

32-bit Arm<sup>®</sup> Cortex<sup>®</sup>-M7 550 MHz MCU, 128 KB Flash, 564 KB RAM, 35 comms peripherals and analog interfaces, HW crypto/hash

Datasheet - production data

## Features

### Core

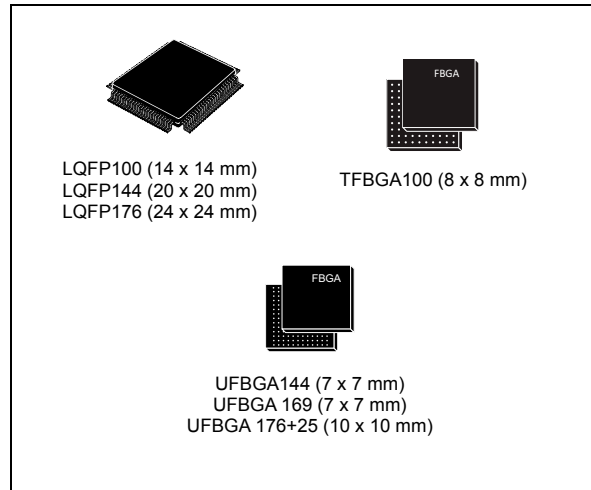
- 32-bit Arm<sup>®</sup> Cortex<sup>®</sup>-M7 CPU with DP-FPU, L1 cache: 32-Kbyte data cache and 32-Kbyte instruction cache allowing 0-wait state execution from embedded Flash memory and external memories, frequency up to 550 MHz, MPU, 1177 DMIPS/2.14 DMIPS/MHz (Dhrystone 2.1), and DSP instructions

### Memories

- 128 Kbytes of embedded Flash memory with ECC
- SRAM: total 564 Kbytes all with ECC, including 128 Kbytes of data TCM RAM for critical real-time data + 432 Kbytes of system RAM (up to 256 Kbytes can remap on instruction TCM RAM for critical real time instructions) + 4 Kbytes of backup SRAM (available in the lowest-power modes)
- Flexible external memory controller with up to 24-bit data bus: SRAM, PSRAM, SDRAM/LPSDR SDRAM, NOR/NAND memories
- 2 x Octo-SPI interface with XiP and on-the-fly decryption support
- 2 x SD/SDIO/MMC interface
- Bootloader with security services support (SFI and SB-SFU)

### Graphics

- Chrom-ART Accelerator graphical hardware accelerator enabling enhanced graphical user interface to reduce CPU load
- LCD-TFT controller supporting up to XGA resolution



### Clock, reset and supply management

- 1.62 V to 3.6 V application supply and I/O
- POR, PDR, PVD and BOR
- Dedicated USB power
- Embedded DCDC and LDO regulator
- Internal oscillators: 64 MHz HSI, 48 MHz HSI48, 4 MHz CSI, 32 kHz LSI
- External oscillators: 4-50 MHz HSE, 32.768 kHz LSE

### Low power

- Sleep, Stop and Standby modes
- V<sub>BAT</sub> supply for RTC, 32×32-bit backup registers

### Analog

- 2×16-bit ADC, up to 3.6 MSPS in 16-bit: up to 22 channels and 7.2 MSPS in double-interleaved mode
- 1 x 12-bit ADC, up to 5 MSPS in 12-bit, up to 12 channels
- 2 x comparators
- 2 x operational amplifier GBW = 8 MHz

- 2× 12-bit D/A converters

#### Digital filters for sigma delta modulator (DFSDM)

- 8 channels/4 filters

#### 4 DMA controllers to offload the CPU

- 1 × MDMA with linked list support
- 2 × dual-port DMAs with FIFO
- 1 × basic DMA with request router capabilities

#### 24 timers

- Seventeen 16-bit (including 5 x low power 16-bit timer available in stop mode) and four 32-bit timers, each with up to 4 IC/OC/PWM or pulse counter and quadrature (incremental) encoder input
- 2x watchdogs, 1x SysTick timer

#### Debug mode

- SWD and JTAG interfaces
- 2-Kbyte embedded trace buffer

#### Up to 128 I/O ports with interrupt capability

#### Up to 35 communication interfaces

- Up to 5 × I2C FM+ interfaces (SMBus/PMBus™)
- Up to 5 USARTs/5 UARTs (ISO7816 interface, LIN, IrDA, modem control) and 1 x LPUART
- Up to 6 SPIs with 4 with muxed duplex I2S for audio class accuracy via internal audio PLL or external clock and up to 5 x SPI (from 5 x USART when configured in synchronous mode)
- 2x SAI (serial audio interface)
- 1× FD/TT-CAN and 2x FD-CAN
- 8- to 14-bit camera interface
- 16-bit parallel slave synchronous interface
- SPDIF-IN interface
- HDMI-CEC
- Ethernet MAC interface with DMA controller
- USB 2.0 high-speed/full-speed device/host/OTG controller with dedicated

DMA, on-chip FS PHY and ULPI for external HS PHY

- SWPMI single-wire protocol master I/F
- MDIO slave interface

#### Mathematical acceleration

- CORDIC for trigonometric functions acceleration
- FMAC: Filter mathematical accelerator

#### Digital temperature sensor

#### Cryptographic/HASH acceleration

- AES 128, 192, 256, TDES, HASH (MD5, SHA-1, SHA-2), HMAC
- 2x OTFDEC AES-128 in CTR mode for Octo-SPI memory encryption/decryption

#### True random number generator

#### CRC calculation unit

#### RTC with sub-second accuracy and hardware calendar

#### ROP, PC-ROP, tamper detection, secure firmware upgrade support

#### 96-bit unique ID

#### All packages are ECOPACK2 compliant

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# 1 Introduction

This document provides information on STM32H730xB microcontrollers, such as description, functional overview, pin assignment and definition, packaging, and ordering information.

This document should be read in conjunction with the STM32H730xB reference manual (RM0468), available from the STMicroelectronics website [www.st.com](http://www.st.com).

For information on the Arm<sup>®(a)</sup> Cortex<sup>®</sup>-M7 core, refer to the Cortex<sup>®</sup>-M7 Technical Reference Manual, available from the <http://www.arm.com> website.

The logo for Arm, consisting of the word "arm" in a bold, lowercase, sans-serif font.

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a. Arm is a registered trademark of Arm Limited (or its subsidiaries) in the US and/or elsewhere.

## 2 Description

STM32H730xB devices are based on the high-performance Arm® Cortex®-M7 32-bit RISC core operating at up to 550 MHz. The Cortex® -M7 core features a floating point unit (FPU) which supports Arm® double-precision (IEEE 754 compliant) and single-precision data-processing instructions and data types. The Cortex -M7 core includes 32 Kbytes of instruction cache and 32 Kbytes of data cache. STM32H730xB devices support a full set of DSP instructions and a memory protection unit (MPU) to enhance application security.

STM32H730xB devices incorporate high-speed embedded memories with 128 Kbytes of Flash memory, up to 564 Kbytes of RAM (including 192 Kbytes that can be shared between ITCM and AXI, plus 64 Kbytes exclusively ITCM, plus 128 Kbytes exclusively AXI, 128 Kbyte DTCM, 48 Kbytes AHB and 4 Kbytes of backup RAM), as well as an extensive range of enhanced I/Os and peripherals connected to APB buses, AHB buses, 2x32-bit multi-AHB bus matrix and a multi layer AXI interconnect supporting internal and external memory access. To improve application robustness, all memories feature error code correction (one error correction, two error detections).

The devices embed peripherals allowing mathematical/arithmetic function acceleration (CORDIC co-processor for trigonometric functions and FMAC unit for filter functions). All the devices offer three ADCs, two DACs, two operational amplifiers, two ultra-low power comparators, a low-power RTC, 4 general-purpose 32-bit timers, 12 general-purpose 16-bit timers including two PWM timers for motor control, five low-power timers, a true random number generator (RNG), and a cryptographic acceleration cell, and a HASH processor. The devices support four digital filters for external sigma-delta modulators (DFSDM). They also feature standard and advanced communication interfaces.

- Standard peripherals
  - Five I<sup>2</sup>Cs
  - Five USARTs, five UARTs and one LPUART
  - Six SPIs, four I<sup>2</sup>Ss in Half-duplex mode. To achieve audio class accuracy, the I<sup>2</sup>S peripherals can be clocked by a dedicated internal audio PLL or by an external clock to allow synchronization. (Note that the five USARTs also provide SPI slave capability.)
  - Two SAI serial audio interfaces
  - One SPDIFRX interface with four inputs
  - One SWPMI (Single Wire Protocol Master Interface)
  - Management Data Input/Output (MDIO) slaves
  - Two SDMMC interfaces
  - A USB OTG high-speed interface with full-speed capability (with the ULPI)
  - Two FDCANs plus one TT-FDCAN interface
  - An Ethernet interface
  - Chrom-ART Accelerator
  - HDMI-CEC



- Advanced peripherals including
  - A flexible memory control (FMC) interface
  - Two Octo-SPI memory interfaces with on-the-fly decryption (OTFDEC)
  - A camera interface for CMOS sensors
  - An LCD-TFT display controller

Refer to [Table 1: STM32H730xB features and peripheral counts](#) for the list of peripherals available on each part number.

To reduce the power consumption some STM32H730xB devices include an optional step-down converter that can be used either for internal or external supply, or both.

STM32H730xB devices operate in the  $-40$  to  $+85$  °C ambient temperature range from a 1.62 to 3.6 V power supply. The supply voltage can drop down to 1.62 V by using an external power supervisor (see [Section 3.8.2: Power supply supervisor](#)) and connecting the PDR\_ON pin to  $V_{SS}$ . Otherwise the supply voltage must stay above 1.71 V with the embedded power voltage detector enabled.

Dedicated supply inputs for USB are available to allow a greater power supply choice.

A comprehensive set of power-saving modes allows the design of low-power applications.

STM32H730xB devices are offered in several packages ranging from 100 to 176 pins/balls. The set of included peripherals changes with the device chosen.

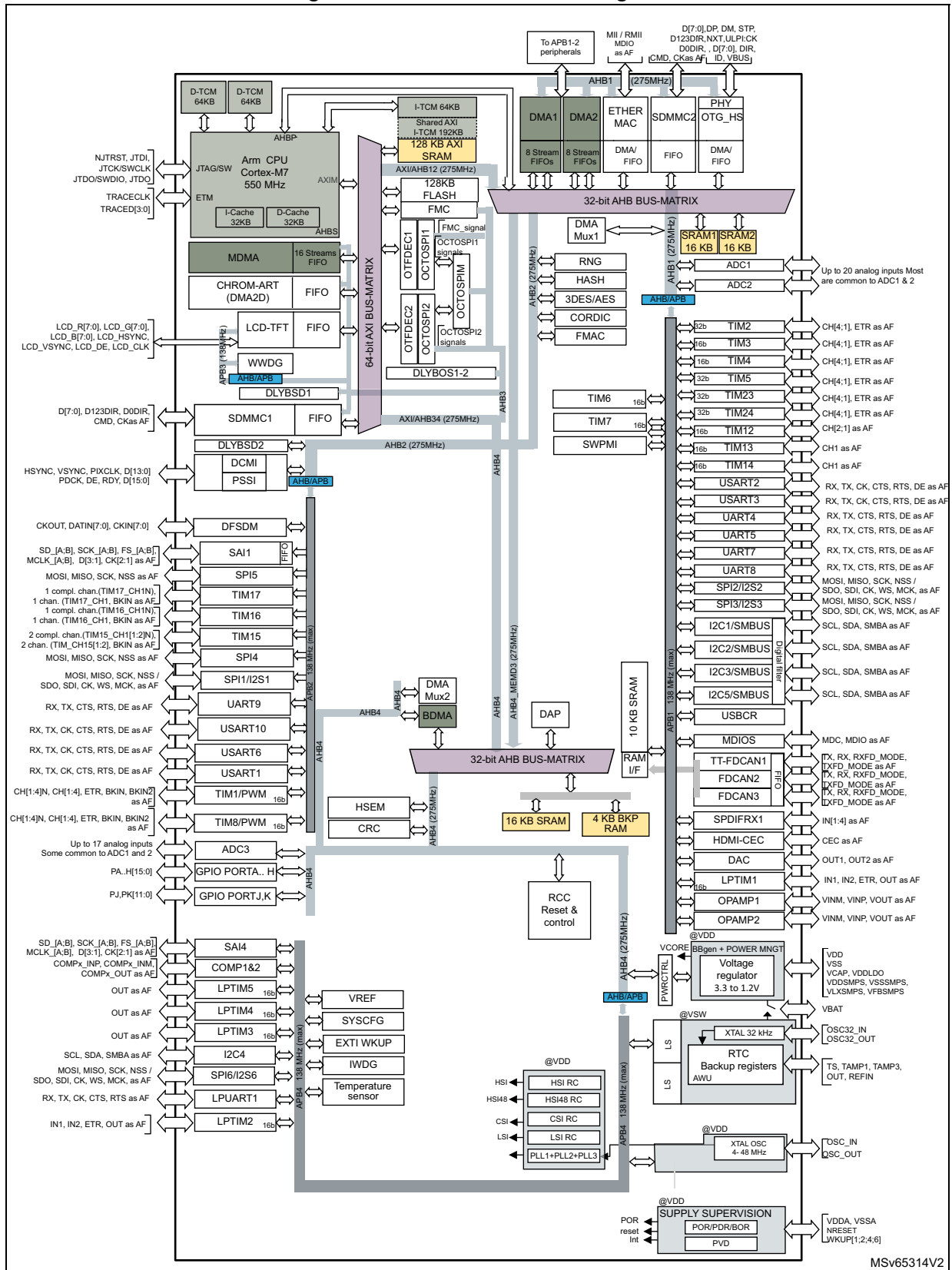
These features make STM32H730xB microcontrollers suitable for a wide range of applications:

- Motor drive and application control
- Medical equipment
- Industrial applications: PLC, inverters, circuit breakers
- Printers, and scanners
- Alarm systems, video intercom, and HVAC
- Home audio appliances
- Mobile applications, Internet of Things
- Wearable devices: smart watches.

[Figure 1](#) shows the device block diagram.



Figure 1. STM32H730xB block diagram



MSV65314V2



Table 1. STM32H730xB features and peripheral counts

Peripherals		no SMPS				SMPS		
		STM32H730VBT6	STM32H730VBH6	STM32H730ZBT6	STM32H730ZBI6	STM32H730ABI6Q	STM32H730IBK6Q	STM32H730IBT6Q
Flash memory (Kbytes)		128						
SRAM (Kbytes)	SRAM mapped onto AXI bus	128						
	SRAM1 (D2 domain)	16						
	SRAM2 (D2 domain)	16						
	SRAM4 (D3 domain)	16						
RAM shared between ITCM and AXI (Kbytes)		192						
TCM RAM in Kbytes	ITCM RAM (instruction)	64						
	DTCM RAM (data)	128						
Backup SRAM (Kbytes)		4						
FMC	Interface	1						
	NOR Flash memory/RAM controller	-	-	yes	yes	yes	yes	yes
	Multiplexed I/O NOR Flash memory	yes	yes	yes	yes	yes	yes	yes
	16-bit NAND Flash memory	yes	yes	yes	yes	yes	yes	yes
	16-bit SDRAM controller	-	-	yes	yes	yes	yes	yes
	24-bit SDRAM controller <sup>(1)</sup>	-	-	-	-	-	yes	-
GPIO		80		112	114	121	128	119

Table 1. STM32H730xB features and peripheral counts (continued)

Peripherals		no SMPS				SMPS		
		STM32H730VBT6	STM32H730VBH6	STM32H730ZBT6	STM32H730ZBI6	STM32H730ABI6Q	STM32H730IBK6Q	STM32H730IBT6Q
Octo-SPI interface		2 <sup>(2)</sup>	2 <sup>(2)</sup>	2	2	2	2	2
OTFDEC		yes						
Cordic		yes						
FMAC		yes						
Timers	General purpose 32 bits	2	2	2	2	2	2	2
	General purpose 16 bits	10	10	10	10	10	10	10
	Advanced control (PWM)	2	2	2	2	2	2	2
	Basic	2	2	2	2	2	2	2
	Low-power	5	5	5	5	5	5	5
	RTC	1	1	1	1	1	1	1
	Window watchdog / independent watchdog	2	2	2	2	2	2	2
Wakeup pins		4	4	4	4	4	4	4
Tamper pins		2	2	2	2	2	2	2
Random number generator		yes						
Cryptographic accelerator		yes						

Table 1. STM32H730xB features and peripheral counts (continued)

Peripherals		no SMPS				SMPS		
		STM32H730VBT6	STM32H730VBH6	STM32H730ZBT6	STM32H730ZBI6	STM32H730ABI6Q	STM32H730IBK6Q	STM32H730IBT6Q
Communication interfaces	SPI / I2S	5/4	5/4	6/4	6/4	4/4	6/4	6/4
	I2C	5	5	5	5	5	5	5
	USART/UART/ LPUART	5/5/1	5/5/1	5/5/1	5/5/1	5/5/1	5/5/1	5/5/1
	SAI/PDM	2/1 <sup>(3)</sup>	2/1 <sup>(3)</sup>	2/1	2/1	2/1	2/1	2/1
	SPDIFRX	1						
	HDMI-CEC	1						
	SWPMI	1						
	MDIO	1						
	SDMMC	2						
	FDCAN/TT- FDCAN	2/1	2/1	2/1	2/1	2/1	2/1	2/1
	USB [OTG_HS(ULPI)/ FS(PHY)]	1 [1/1]	1 [1/1]	1 [1/1]	1 [1/1]	1 [1/1]	1 [1/1]	1 [1/1]
Ethernet [MII/RMII]	1 [1/1]	1 [1/1]	1 [1/1]	1 [1/1]	1 [1/1]	1 [1/1]	1 [1/1]	
Camera interface/PSSI	yes							
LCD-TFT	yes							
Chrom-ART Accelerator (DMA2D)	yes							
16-bit ADCs	Number of ADCs	2						
	Number of Direct channels ADC1/ADC2	0	2/2	0	2/2	2/2	2/2	0
	Number of Fast channels ADC1/ADC2	3/2	3/2	4/3	4/3	6/5	6/5	4/3
	Number of Slow channels ADC1/ADC2	11/10	9/8	12/11	12/11	12/11	12/11	12/11

Table 1. STM32H730xB features and peripheral counts (continued)

Peripherals		no SMPS				SMPS		
		STM32H730VBT6	STM32H730VBH6	STM32H730ZBT6	STM32H730ZBI6	STM32H730ABI6Q	STM32H730IBK6Q	STM32H730IBT6Q
12-bit ADCs	Number of ADCs	1						
	Number of Direct channels	2	2	2	2	2	2	2
	Number of Fast channels	2	6	6	6	6	6	6
	Number of Slow channels	0	9	4	9	9	9	4
12-bit DAC	Present in IC	yes						
	Number of channels	2						
Comparators		2						
Operational amplifiers		2						
DFSDM	Present in IC	yes						
Maximum CPU frequency		550 MHz						
USB separate supply pad		-	yes	yes	yes	yes	yes	yes
USB internal regulator		-	-	-	-	yes	yes	yes
LDO		yes						
SMPS step-down converter		no				yes		
Operating voltage		1.71 to 3.6 V	1.62 to 3.6 V					
Operating temperature		-40°C to +85°C						
Package		LQFP 100	TFBGA 100	LQFP 144	UFBGA 144	UFBGA 169	UFBGA 176+25	LQFP176

1. The 24-bit SDRAM controller is a 32-bit controller with only a 24-bit data bus and without NBL2-3. It can be used for graphical purposes to access aligned 32-bit words ignoring upper 8 bits.
2. The two Octo-SPI/Quad-SPI interfaces are available only in Muxed mode.
3. For limitations on peripheral features depending on packages, check the available pins/balls in [Table 7: STM32H730xB pin and ball descriptions](#).

## 3 Functional overview

### 3.1 Arm<sup>®</sup> Cortex<sup>®</sup>-M7 with FPU

The Arm<sup>®</sup> Cortex<sup>®</sup>-M7 with double-precision FPU processor is the latest generation of Arm processors for embedded systems. It was developed to provide a low-cost platform that meets the needs of MCU implementation, with a reduced pin count and optimized power consumption, while delivering outstanding computational performance and low interrupt latency.

The Cortex<sup>®</sup>-M7 processor is a highly efficient high-performance featuring:

- Six-stage dual-issue pipeline
- Dynamic branch prediction
- Harvard architecture with L1 caches (32 Kbytes of I-cache and 32 Kbytes of D-cache)
- 64-bit AXI interface
- 64-bit ITCM interface
- 2x32-bit DTCM interfaces

The following memory interfaces are supported:

- Separate Instruction and Data buses (Harvard Architecture) to optimize CPU latency
- Tightly Coupled Memory (TCM) interface designed for fast and deterministic SRAM accesses
- AXI Bus interface to optimize Burst transfers
- Dedicated low-latency AHB-Lite peripheral bus (AHBP) to connect to peripherals.

The processor supports a set of DSP instructions which allow efficient signal processing and complex algorithm execution.

It also supports single and double precision FPU (floating point unit) speeds up software development by using metalanguage development tools, while avoiding saturation.

*Figure 1* shows the general block diagram of the STM32H730xB family.

### 3.2 Memory protection unit (MPU)

The memory protection unit (MPU) manages the CPU access rights and the attributes of the system resources. It has to be programmed and enabled before use. Its main purposes are to prevent an untrusted user program to accidentally corrupt data used by the OS and/or by a privileged task, but also to protect data processes or read-protect memory regions.

The MPU defines access rules for privileged accesses and user program accesses. It allows defining up to 16 protected regions that can in turn be divided into up to 8 independent subregions, where region address, size, and attributes can be configured. The protection area ranges from 32 bytes to 4 Gbytes of addressable memory.

When an unauthorized access is performed, a memory management exception is generated.

## 3.3 Memories

### 3.3.1 Embedded Flash memory

The STM32H730xB devices embed 128 Kbytes of Flash memory that can be used for storing programs and data.

The Flash memory is organized as 266-bit Flash words memory that can be used for storing both code and data constants. Each word consists of:

- one Flash word (8 words, 32 bytes or 256 bits)
- 10 ECC bits (single-error correction and double-error detection).

The Flash memory is organized as follows:

- One sector of 128 Kbytes of user Flash memory (4 K Flash memory words)
- 128 Kbytes of system Flash memory from which the device can boot
- 2 Kbytes (64 Flash words) of user option bytes for user configuration

### 3.3.2 Embedded SRAM

All devices feature:

- from 128 to 320 Kbytes of AXI-SRAM mapped onto the AXI bus on D1 domain
- SRAM1 mapped on D2 domain: 16 Kbytes
- SRAM2 mapped on D2 domain: 16 Kbytes
- SRAM4 mapped on D3 domain: 16 Kbytes
- 4 Kbytes of backup SRAM

The content of this area is protected against possible unwanted write accesses, and can be retained in Standby or  $V_{BAT}$  mode.

- RAM mapped to TCM interface (ITCM and DTCM):

Both ITCM and DTCM RAMs are 0 wait state memories. They can be accessed either from the CPU or the MDMA (even in Sleep mode) through a specific AHB slave of the Cortex®-M7CPU(AHBSAHBP):

- 64 to 256 Kbytes of ITCM-RAM (instruction RAM)

This RAM is connected to ITCM 64-bit interface designed for execution of critical real-times routines by the CPU.

- 128 Kbytes of DTCM-RAM (2x 64-Kbyte DTCM-RAMs on 2x32-bit DTCM ports)

The DTCM-RAM could be used for critical real-time data, such as interrupt service routines or stack/heap memory. Both DTCM-RAMs can be used in parallel (for load/store operations) thanks to the Cortex®-M7 dual issue capability.

The MDMA can be used to load code or data in ITCM or DTCM RAMs. As reflected above, 192 Kbyte of RAM can be used either for AXI SRAM or ITCM, with a 64Kbyte granularity.

### Error code correction (ECC)

Over the product lifetime, and/or due to external events such as radiations, invalid bits in memories may occur. They can be detected and corrected by ECC. This is an expected behavior that has to be managed at final-application software level in order to ensure data integrity through ECC algorithms implementation.

SRAM data are protected by ECC:

- 7 ECC bits are added per 32-bit word.
- 8 ECC bits are added per 64-bit word for AXI-SRAM and ITCM-RAM.

The ECC mechanism is based on the SECDED algorithm. It supports single-error correction and double-error detection.

## 3.4 Secure access mode

In addition to other typical memory protection mechanism (RDP, PCROP), STM32H730xB devices introduce the Secure access mode, a new enhanced security feature. This mode allows developing user-defined secure services by ensuring, on the one hand code and data protection and on the other hand code safe execution.

Two types of secure services are available:

- **STMicroelectronics Root Secure Services:**  
These services are embedded in System memory. They provide a secure solution for firmware and third-party modules installation. These services rely on cryptographic algorithms based on a device unique private key.
- **User-defined secure services:**  
These services are embedded in user Flash memory. Examples of user secure services are proprietary user firmware update solution, secure Flash integrity check or any other sensitive applications that require a high level of protection.  
The secure firmware is embedded in specific user Flash memory areas configured through option bytes.

Secure services are executed just after a reset and preempt all other applications to guarantee protected and safe execution. Once executed, the corresponding code and data are no more accessible.

The above secure services is activated for the next reset exits through an option bit.



## 3.5 Boot modes

At startup, the boot memory space is selected by the BOOT pin and BOOT\_ADDx option bytes, allowing to program any boot memory address from 0x0000 0000 to 0x3FFF FFFF which includes:

- All Flash address space
- All RAM address space: ITCM, DTCM RAMs and SRAMs
- The System memory bootloader

The boot loader is located in non-user System memory. It is used to reprogram the Flash memory through a serial interface (USART, I2C, SPI, FDCAN, USB-DFU). Refer to application note AN2606 “*STM32 microcontroller System memory Boot mode*” for details.

## 3.6 CORDIC co-processor (CORDIC)

The CORDIC co-processor provides hardware acceleration of certain mathematical functions, notably trigonometric, commonly used in motor control, metering, signal processing and many other applications.

It speeds up the calculation of these functions compared to a software implementation, allowing a lower operating frequency, or freeing up processor cycles in order to perform other tasks.

The filter mathematical accelerator unit performs arithmetic operations on vectors. It comprises a multiplier/accumulator (MAC) unit, together with address generation logic, which allows it to index vector elements held in local memory.

The unit includes support for circular buffers on input and output, which allows digital filters to be implemented. Both finite and infinite impulse response filters can be realized.

The unit allows frequent or lengthy filtering operations to be offloaded from the CPU, freeing up the processor for other tasks. In many cases it can accelerate such calculations compared to a software implementation, resulting in a speed-up of time critical tasks.

### CORDIC features

- 24-bit CORDIC rotation engine
- Circular and Hyperbolic modes
- Rotation and Vectoring modes
- Functions: Sine, Cosine, Sinh, Cosh, Atan, Atan2, Atanh, Modulus, Square root, Natural logarithm
- Programmable precision up to 20-bit
- Fast convergence: 4 bits per clock cycle
- Supports 16-bit and 32-bit fixed point input and output formats
- Low latency AHB slave interface
- Results can be read as soon as ready without polling or interrupt
- DMA read and write channels

## 3.7 Filter mathematical accelerator (FMAC)

The filter mathematical accelerator unit performs arithmetic operations on vectors. It comprises a multiplier/accumulator (MAC) unit, together with address generation logic, which allows it to index vector elements held in local memory.

The unit includes support for circular buffers on input and output, which allows digital filters to be implemented. Both finite and infinite impulse response filters can be realized.

The unit allows frequent or lengthy filtering operations to be offloaded from the CPU, freeing up the processor for other tasks. In many cases it can accelerate such calculations compared to a software implementation, resulting in a speed-up of time critical tasks.

### FMAC features

- 16 x 16-bit multiplier
- 24+2-bit accumulator with addition and subtraction
- 16-bit input and output data
- 256 x 16-bit local memory
- Up to three areas can be defined in memory for data buffers (two input, one output), defined by programmable base address pointers and associated size registers
- Input and output sample buffers can be circular
- Buffer “watermark” feature reduces overhead in interrupt mode
- Filter functions: FIR, IIR (direct form 1)
- AHB slave interface
- DMA read and write data channels

## 3.8 Power supply management

### 3.8.1 Power supply scheme

STM32H730xB power supply voltages are the following:

- $V_{DD}$  = 1.62 to 3.6 V: external power supply for I/Os, provided externally through  $V_{DD}$  pins.
- $V_{DDLDO}$  = 1.62 to 3.6 V: supply voltage for the internal regulator supplying  $V_{CORE}$
- $V_{DDA}$  = 1.62 to 3.6 V: external analog power supplies for ADC, DAC, COMP and OPAMP.
- $V_{DD33USB}$ : allows the support of a  $V_{DD}$  supply different from 3.3 V while powering the USB transceiver with 3.3V on  $V_{DD33USB}$ .
- $V_{DD50USB}$  can be supplied through the USB cable to generate the  $V_{DD33USB}$  via the USB internal regulator. This allows support of a  $V_{DD}$  supply different to 3.3 V.  
The USB regulator can be bypassed to supply directly  $V_{DD33USB}$  if  $V_{DD} = 3.3$  V.
- $V_{BAT}$  = 1.2 to 3.6 V: power supply for the  $V_{SW}$  domain when  $V_{DD}$  is not present.
- $V_{CAP}$ :  $V_{CORE}$  supply voltage, which values depend on voltage scaling (1.0 V, 1.1 V, 1.2 V or 1.35 V). They are configured through VOS bits in PWR\_D3CR register. The

V<sub>CORE</sub> domain is split into the following power domains that can be independently switch off.

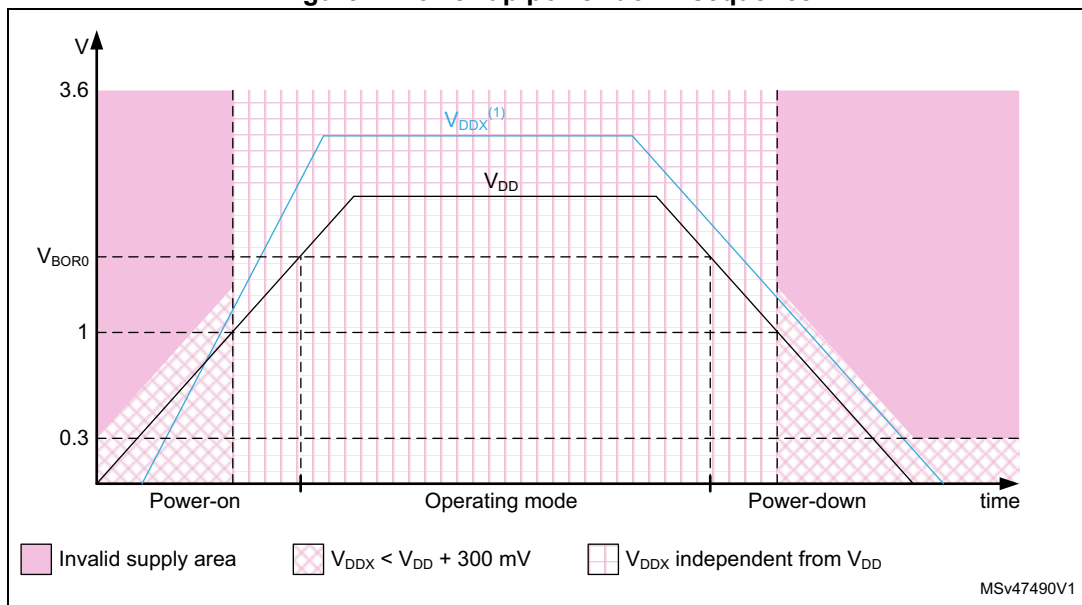
- D1 domain containing some peripherals and the Cortex<sup>®</sup>-M7 core
- D2 domain containing a large part of the peripherals
- D3 domain containing some peripherals and the system control
- VDDSMPS= 1.62 V to 3.6 V: SMPS step-down converter power supply VDDSMPS must be kept at the same voltage level as VDD
- VLXSMPS = SMPS step-down converter output coupled to an inductor
- VFBSMPS = V<sub>CORE</sub> or 1.8 V or 2.5 V external SMPS step-down converter feedback voltage sense input.

During power-up and power-down phases, the following power sequence requirements must be respected (see [Figure 2](#)):

- When V<sub>DD</sub> is below 1 V, other power supplies (V<sub>DDA</sub>, V<sub>DD33USB</sub>, V<sub>DD50USB</sub>) must remain below V<sub>DD</sub> + 300 mV.
- When V<sub>DD</sub> is above 1 V, all power supplies are independent.

During the power-down phase, V<sub>DD</sub> can temporarily become lower than other supplies only if the energy provided to the microcontroller remains below 1 mJ. This allows external decoupling capacitors to be discharged with different time constants during the power-down transient phase.

**Figure 2. Power-up/power-down sequence**



1. V<sub>DDx</sub> refers to any power supply among V<sub>DDA</sub>, V<sub>DD33USB</sub>, V<sub>DD50USB</sub>.

### 3.8.2 Power supply supervisor

The devices have an integrated power-on reset (POR)/ power-down reset (PDR) circuitry coupled with a Brownout reset (BOR) circuitry:

- Power-on reset (POR)  
The POR supervisor monitors  $V_{DD}$  power supply and compares it to a fixed threshold. The devices remain in Reset mode when  $V_{DD}$  is below this threshold,
- Power-down reset (PDR)  
The PDR supervisor monitors  $V_{DD}$  power supply. A reset is generated when  $V_{DD}$  drops below a fixed threshold.  
The PDR supervisor can be enabled/disabled through PDR\_ON pin.
- Brownout reset (BOR)  
The BOR supervisor monitors  $V_{DD}$  power supply. Three BOR thresholds (from 2.1 to 2.7 V) can be configured through option bytes. A reset is generated when  $V_{DD}$  drops below this threshold.

### 3.8.3 Voltage regulator

The same voltage regulator supplies the 3 power domains (D1, D2 and D3). D1 and D2 can be independently switched off.

Voltage regulator output can be adjusted according to application needs through 6 power supply levels:

- Run mode (VOS0 to VOS3)
  - Scale 0: boosted performance (available only with LDO regulator)
  - Scale 1: high performance
  - Scale 2: medium performance and consumption
  - Scale 3: optimized performance and low-power consumption
- Stop mode (SVOS3 to SVOS5)
  - Scale 3: peripheral with wakeup from Stop mode capabilities (UART, SPI, I2C, LPTIM) are operational
  - Scale 4 and 5 where the peripheral with wakeup from Stop mode is disabled. The peripheral functionality is disabled but wakeup from Stop mode is possible through GPIO or asynchronous interrupt.

## 3.9 Low-power strategy

There are several ways to reduce power consumption on STM32H730xB:

- Decrease the dynamic power consumption by slowing down the system clocks even in Run mode and by individually clock gating the peripherals that are not used.
- Save power when the CPU is idle, by selecting among the available low-power modes according to the user application needs. This allows the best compromise between short startup time and low power consumption to be achieved, according to the available wakeup sources.

The devices feature several low-power modes:

- CSleep (CPU clock stopped)
- CStop (CPU sub-system clock stopped)
- DStop (Domain bus matrix clock stopped)
- Stop (System clock stopped)
- DStandby (Domain powered down)
- Standby (System powered down)

CSleep and CStop low-power modes are entered by the MCU when executing the WFI (Wait for Interrupt) or WFE (Wait for Event) instructions, or when the SLEEPONEXIT bit of the Cortex<sup>®</sup>-Mx core is set after returning from an interrupt service routine.

A domain can enter low-power mode (DStop or DStandby) when the processor, its subsystem and the peripherals allocated in the domain enter low-power mode.

If part of the domain is not in low-power mode, the domain remains in the current mode.

Finally the system can enter Stop or Standby when all EXTI wakeup sources are cleared and the power domains are in DStop or DStandby mode.

Table 2. System versus domain low-power mode

System power mode	D1 domain power mode	D2 domain power mode	D3 domain power mode
Run	DRun/DStop/DStandby	DRun/DStop/DStandby	DRun
Stop	DStop/DStandby	DStop/DStandby	DStop
Standby	DStandby	DStandby	DStandby

## 3.10 Reset and clock controller (RCC)

The clock and reset controller is located in D3 domain. The RCC manages the generation of all the clocks, as well as the clock gating and the control of the system and peripheral resets. It provides a high flexibility in the choice of clock sources and allows to apply clock ratios to improve the power consumption. In addition, on some communication peripherals that are capable to work with two different clock domains (either a bus interface clock or a kernel peripheral clock), thus the system frequency can be changed without modifying the baudrate.

### 3.10.1 Clock management

The devices embed four internal oscillators, two oscillators with external crystal or resonator, two internal oscillators with fast startup time and three PLLs.

The RCC receives the following clock source inputs:

- Internal oscillators:
  - 64 MHz HSI clock
  - 48 MHz RC oscillator
  - 4 MHz CSI clock
  - 32 kHz LSI clock
- External oscillators:
  - HSE clock: 4-50 MHz (generated from an external source) or 4-48 MHz (generated from a crystal/ceramic resonator)
  - LSE clock: 32.768 kHz

The RCC provides three PLLs: one for system clock, two for kernel clocks.

The system starts on the HSI clock. The user application can then select the clock configuration.

### 3.10.2 System reset sources

Power-on reset initializes all registers while system reset reinitializes the system except for the debug, part of the RCC and power controller status registers, as well as the backup power domain.

A system reset is generated in the following cases:

- Power-on reset (pwr\_por\_rst)
- Brownout reset
- Low level on NRST pin (external reset)
- Window watchdog
- Independent watchdog
- Software reset
- Low-power mode security reset
- Exit from Standby

### 3.11 General-purpose input/outputs (GPIOs)

Each of the GPIO pins can be configured by software as output (push-pull or open-drain, with or without pull-up or pull-down), as input (floating, with or without pull-up or pull-down) or as peripheral alternate function. Most of the GPIO pins are shared with digital or analog alternate functions. All GPIOs are high-current-capable and have speed selection to better manage internal noise, power consumption and electromagnetic emission.

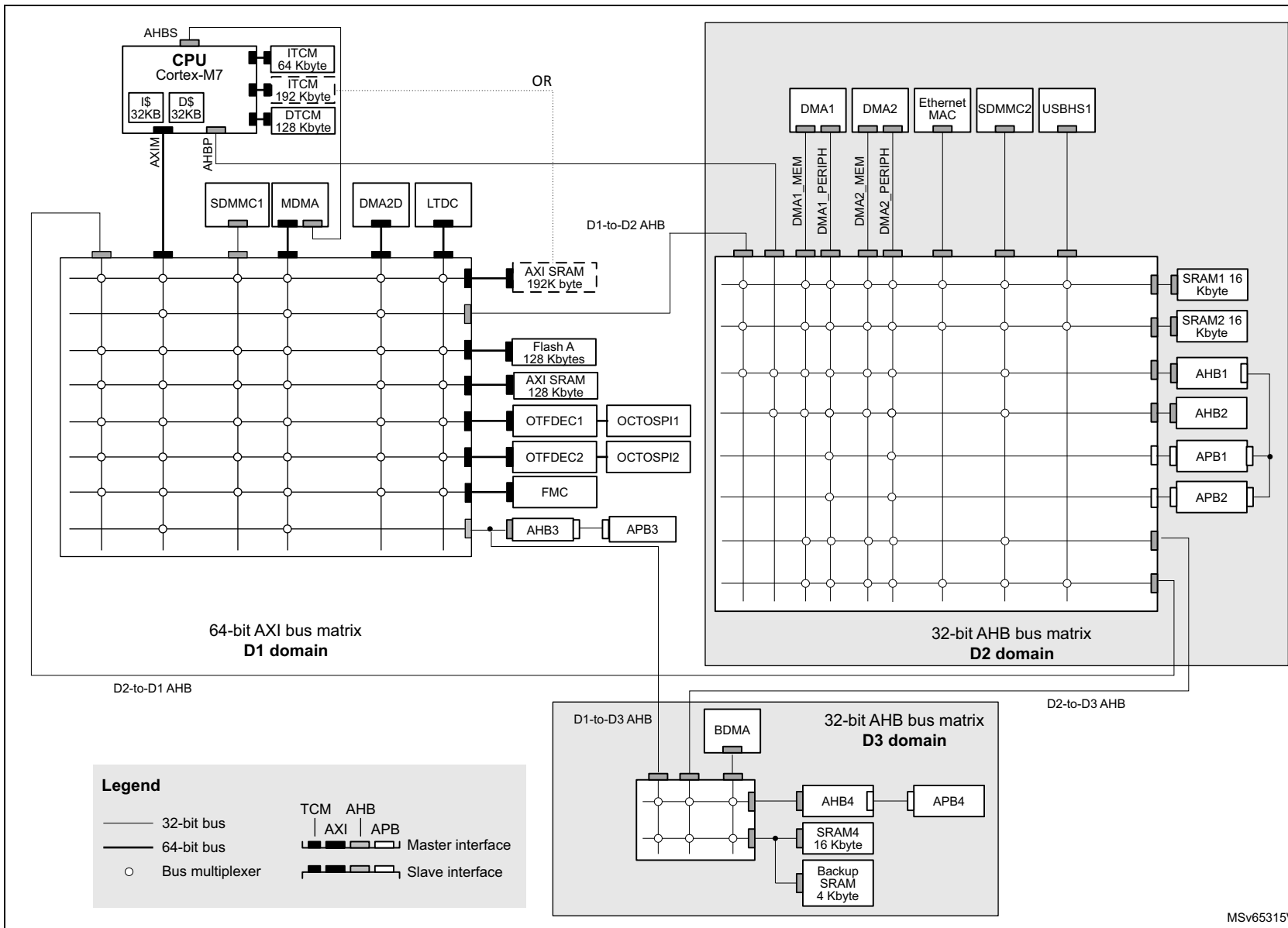
After reset, all GPIOs (except debug pins) are in Analog mode to reduce power consumption (refer to GPIOs register reset values in the device reference manual).

The I/O configuration can be locked if needed by following a specific sequence in order to avoid spurious writing to the I/Os registers.

### 3.12 Bus-interconnect matrix

The devices feature an AXI bus matrix, two AHB bus matrices and bus bridges that allow the interconnection of bus masters with bus slaves (see [Figure 3](#)).

Figure 3. STM32H730xB bus matrix



MSv65315V1



### 3.13 DMA controllers

The devices feature four DMA instances and a DMA request router to unload CPU activity:

- A master direct memory access (MDMA)  
The MDMA is a high-speed DMA controller, which is in charge of all types of memory transfers (peripheral to memory, memory to memory, memory to peripheral), without any CPU action. It features a master AXI interface and a dedicated AHB interface to access Cortex<sup>®</sup>-M7 TCM memories.  
The MDMA is located in D1 domain. It is able to interface with the other DMA controllers located in D2 domain to extend the standard DMA capabilities, or can manage peripheral DMA requests directly.  
Each of the 16 channels can perform single block transfers, repeated block transfers and linked list transfers.
- Two dual-port DMAs (DMA1, DMA2) located in D2 domain, with FIFO and request router capabilities.
- One basic DMA (BDMA) located in D3 domain, with request router capabilities.
- A DMA request multiplexer (DMAMUX)  
The DMA request router could be considered as an extension of the DMA controller. It routes the DMA peripheral requests to the DMA controller itself. This allowing managing the DMA requests with a high flexibility, maximizing the number of DMA requests that run concurrently, as well as generating DMA requests from peripheral output trigger or DMA event.

### 3.14 Chrom-ART Accelerator (DMA2D)

The Chrom-Art Accelerator (DMA2D) is a specialized DMA dedicated to image manipulation. It can perform the following operations:

- Filling a part or the whole of a destination image with a specific color
- Copying a part or the whole of a source image into a part or the whole of a destination image
- Copying a part or the whole of a source image into a part or the whole of a destination image with a pixel format conversion
- Blending a part and/or two complete source images with different pixel format and copy the result into a part or the whole of a destination image with a different color format.
- All the classical color coding schemes are supported from 4-bit up to 32-bit per pixel with indexed or direct color mode, including block based YCbCr to handle JPEG decoder output.
- The DMA2D has its own dedicated memories for CLUTs (color look-up tables).

An interrupt can be generated when an operation is complete or at a programmed watermark.

All the operations are fully automated and are running independently from the CPU or the DMAs.

### 3.15 Nested vectored interrupt controller (NVIC)

The devices embed a nested vectored interrupt controller which is able to manage 16 priority levels, and handle up to 140 maskable interrupt channels plus the 16 interrupt lines of the Cortex<sup>®</sup>-M7 with FPU core.

- Closely coupled NVIC gives low-latency interrupt processing
- Interrupt entry vector table address passed directly to the core
- Allows early processing of interrupts
- Processing of late arriving, higher-priority interrupts
- Support tail chaining
- Processor context automatically saved on interrupt entry, and restored on interrupt exit with no instruction overhead

This hardware block provides flexible interrupt management features with minimum interrupt latency.

### 3.16 Extended interrupt and event controller (EXTI)

The EXTI controller performs interrupt and event management. In addition, it can wake up the processor, power domains and/or D3 domain from Stop mode.

The EXTI handles up to 80 independent event/interrupt lines split as 26 configurable events and 54 direct events.

Configurable events have dedicated pending flags, active edge selection, and software trigger capable.

Direct events provide interrupts or events from peripherals having a status flag.

### 3.17 Cyclic redundancy check calculation unit (CRC)

The CRC (cyclic redundancy check) calculation unit is used to get a CRC code using a programmable polynomial.

Among other applications, CRC-based techniques are used to verify data transmission or storage integrity. In the scope of the EN/IEC 60335-1 standard, they offer a means of verifying the Flash memory integrity. The CRC calculation unit helps compute a signature of the software during runtime, to be compared with a reference signature generated at link-time and stored at a given memory location.

### 3.18 Flexible memory controller (FMC)

The FMC controller main features are the following:

- Interface with static-memory mapped devices including:
  - Static random access memory (SRAM)
  - NOR Flash memory/OneNAND Flash memory
  - PSRAM (4 memory banks)
  - NAND Flash memory with ECC hardware to check up to 8 Kbytes of data
- Interface with synchronous DRAM (SDRAM/Mobile LPDDR SDRAM) memories
- 8-, 16-, 24-bit data bus width
- Independent Chip Select control for each memory bank
- Independent configuration for each memory bank
- Write FIFO
- Read FIFO for SDRAM controller
- The maximum FMC\_CLK/FMC\_SDCLK frequency for synchronous accesses is the FMC kernel clock divided by 2.

### 3.19 Octo-SPI memory interface (OCTOSPI)

The OCTOSPI is a specialized communication interface targeting single, dual, quad or octal SPI memories. The STM32H730xB embeds two separate Octo-SPI interfaces.

Each OCTOSPI instance supports single/dual/quad/octal SPI formats. Multiplexing of single/dual/quad/octal SPI over the same bus can be achieved using the integrated Octo-SPI I/O manager (OCTOSPIM).

The OCTOSPI can operate in any of the three following modes:

- Indirect mode: all the operations are performed using the OCTOSPI registers
- Status-polling mode: the external memory status register is periodically read and an interrupt can be generated in case of flag setting
- Memory-mapped mode: the external memory is memory mapped and it is seen by the system as if it was an internal memory supporting both read and write operations.

The OCTOSPI supports two frame formats supported by most external serial memories such as serial PSRAMs, serial NAND and serial NOR Flash memories, Hyper RAMs and Hyper Flash memories.

Multi chip package (MCP) combining any of the above mentioned memory types can also be supported.

- The classical frame format with the command, address, alternate byte, dummy cycles and data phase
- The HyperBus™ frame format.

### 3.20 Analog-to-digital converters (ADCs)

STM32H730xB devices embed three analog-to-digital converters, two of 16-bit resolution, and the third of 12-bit resolution. The 16-bit resolution ADCs can be configured as 16, 14, 12, 10 or 8 bits. The 12-bit resolution ADC can be configured to 12, 10 or 8 bits.

Each ADC shares up to 20 external channels, performing conversions in Single-shot or Scan mode. In Scan mode, automatic conversion is performed on a selected group of analog inputs.

Additional logic functions embedded in the ADC interface allow:

- simultaneous sample and hold
- Interleaved sample and hold

The ADC can be served by the DMA controller, thus allowing automatic transfer of ADC converted values to a destination location without any software action.

In addition, an analog watchdog feature can accurately monitor the converted voltage of one, some, or all selected channels. An interrupt is generated when the converted voltage is outside the programmed thresholds.

To synchronize A/D conversion and timers, the ADCs can be triggered by any of the TIM1, TIM2, TIM3, TIM4, TIM6, TIM8, TIM15, TIM23, TIM24, and LPTIM1 timers.

### 3.21 Temperature sensor

STM32H730xB devices embed a temperature sensor that generates a voltage ( $V_{TS}$ ) that varies linearly with the temperature. This temperature sensor is internally connected to ADC3\_IN17. The conversion range is between 1.7 V and 3.6 V. It can measure the device junction temperature ranging from  $-40$  to  $+125^{\circ}\text{C}$ .

The temperature sensor have a good linearity, but it has to be calibrated to obtain a good overall accuracy of the temperature measurement. As the temperature sensor offset varies from chip to chip due to process variation, the uncalibrated internal temperature sensor is suitable for applications that detect temperature changes only. To improve the accuracy of the temperature sensor measurement, each device is individually factory-calibrated by ST. The temperature sensor factory calibration data are stored by ST in the System memory area, which is accessible in Read-only mode.

### 3.22 Digital temperature sensor (DTS)

STM32H730xB devices embed a sensor that converts the temperature into a square wave the frequency of which is proportional to the temperature. The PCLK or the LSE clock can be used as the reference clock for the measurements. A formula given in the product reference manual allows calculation of the temperature according to the measured frequency stored in the DTS\_DR register.

### 3.23 V<sub>BAT</sub> operation

The V<sub>BAT</sub> power domain contains the RTC, the backup registers and the backup SRAM.

To optimize battery duration, this power domain is supplied by V<sub>DD</sub> when available or by the voltage applied on VBAT pin (when V<sub>DD</sub> supply is not present). V<sub>BAT</sub> power is switched when the PDR detects that V<sub>DD</sub> dropped below the PDR level.

The voltage on the VBAT pin could be provided by an external battery, a supercapacitor or directly by V<sub>DD</sub>, in which case, the V<sub>BAT</sub> mode is not functional.

V<sub>BAT</sub> operation is activated when V<sub>DD</sub> is not present.

The V<sub>BAT</sub> pin supplies the RTC, the backup registers and the backup SRAM.

*Note:* When the microcontroller is supplied from V<sub>BAT</sub>, external interrupts and RTC alarm/events do not exit it from V<sub>BAT</sub> operation.

*When PDR\_ON pin is connected to V<sub>SS</sub> (Internal Reset OFF), the V<sub>BAT</sub> functionality is no more available and V<sub>BAT</sub> pin should be connected to V<sub>DD</sub>.*

### 3.24 Digital-to-analog converters (DAC)

The two 12-bit buffered DAC channels can be used to convert two digital signals into two analog voltage signal outputs.

This dual digital Interface supports the following features:

- two DAC converters: one for each output channel
- 8-bit or 12-bit monotonic output
- left or right data alignment in 12-bit mode
- synchronized update capability
- noise-wave generation
- triangular-wave generation
- dual DAC channel independent or simultaneous conversions
- DMA capability for each channel including DMA underrun error detection
- external triggers for conversion
- input voltage reference V<sub>REF+</sub> or internal VREFBUF reference.

The DAC channels are triggered through the timer update outputs that are also connected to different DMA streams.

### 3.25 Ultra-low-power comparators (COMP)

STM32H730xB devices embed two rail-to-rail comparators (COMP1 and COMP2). They feature programmable reference voltage (internal or external), hysteresis and speed (low speed for low-power) as well as selectable output polarity.

The reference voltage can be one of the following:

- An external I/O
- A DAC output channel
- An internal reference voltage or submultiple (1/4, 1/2, 3/4).

All comparators can wake up from Stop mode, generate interrupts and breaks for the timers, and be combined into a window comparator.

### 3.26 Operational amplifiers (OPAMP)

STM32H730xB devices embed two rail-to-rail operational amplifiers (OPAMP1 and OPAMP2) with external or internal follower routing and PGA capability.

The operational amplifier main features are:

- PGA with a non-inverting gain ranging of 2, 4, 8 or 16 or inverting gain ranging of -1, -3, -7 or -15
- One positive input connected to DAC
- Output connected to internal ADC
- Low input bias current down to 1 nA
- Low input offset voltage down to 1.5 mV
- Gain bandwidth up to 7.3 MHz

The devices embeds two operational amplifiers (OPAMP1 and OPAMP2) with two inputs and one output each. These three I/Os can be connected to the external pins, thus enabling any type of external interconnections. The operational amplifiers can be configured internally as a follower, as an amplifier with a non-inverting gain ranging from 2 to 16 or with inverting gain ranging from -1 to -15.

### 3.27 Digital filter for sigma-delta modulators (DFSDM)

The devices embed one DFSDM with 4 digital filters modules and 8 external input serial channels (transceivers) or alternately 8 internal parallel inputs support.

The DFSDM peripheral is dedicated to interface the external  $\Sigma\Delta$  modulators to microcontroller and then to perform digital filtering of the received data streams (which represent analog value on  $\Sigma\Delta$  modulators inputs). DFSDM can also interface PDM (Pulse Density Modulation) microphones and perform PDM to PCM conversion and filtering in hardware. DFSDM features optional parallel data stream inputs from internal ADC peripherals or microcontroller memory (through DMA/CPU transfers into DFSDM).

DFSDM transceivers support several serial interface formats (to support various  $\Sigma\Delta$  modulators). DFSDM digital filter modules perform digital processing according user selected filter parameters with up to 24-bit final ADC resolution.

The DFSDM peripheral supports:

- 8 multiplexed input digital serial channels:
  - configurable SPI interface to connect various SD modulator(s)
  - configurable Manchester coded 1 wire interface support
  - PDM (Pulse Density Modulation) microphone input support
  - maximum input clock frequency up to 20 MHz (10 MHz for Manchester coding)
  - clock output for SD modulator(s): 0..20 MHz
- alternative inputs from 8 internal digital parallel channels (up to 16 bit input resolution):
  - internal sources: ADC data or memory data streams (DMA)
- 4 digital filter modules with adjustable digital signal processing:
  - Sinc<sup>x</sup> filter: filter order/type (1..5), oversampling ratio (up to 1..1024)
  - integrator: oversampling ratio (1..256)
- up to 24-bit output data resolution, signed output data format
- automatic data offset correction (offset stored in register by user)
- continuous or single conversion
- start-of-conversion triggered by:
  - software trigger
  - internal timers
  - external events
  - start-of-conversion synchronously with first digital filter module (DFSDM0)
- analog watchdog feature:
  - low value and high value data threshold registers
  - dedicated configurable Sinc<sup>x</sup> digital filter (order = 1..3, oversampling ratio = 1..32)
  - input from final output data or from selected input digital serial channels
  - continuous monitoring independently from standard conversion
- short circuit detector to detect saturated analog input values (bottom and top range):
  - up to 8-bit counter to detect 1..256 consecutive 0's or 1's on serial data stream
  - monitoring continuously each input serial channel
- break signal generation on analog watchdog event or on short circuit detector event

- extremes detector:
  - storage of minimum and maximum values of final conversion data
  - refreshed by software
- DMA capability to read the final conversion data
- interrupts: end of conversion, overrun, analog watchdog, short circuit, input serial channel clock absence
- “regular” or “injected” conversions:
  - “regular” conversions can be requested at any time or even in Continuous mode without having any impact on the timing of “injected” conversions
  - “injected” conversions for precise timing and with high conversion priority
- Pulse skipper feature to support beamforming applications (delay-line like behavior).

**Table 3. DFSDM implementation**

DFSDM features	DFSDM1
Number of filters	4
Number of input transceivers/channels	8
Internal ADC parallel input	X
Number of external triggers	16
Regular channel information in identification register	X



### 3.28 Digital camera interface (DCMI)

The devices embed a camera interface that can connect with camera modules and CMOS sensors through an 8-bit to 14-bit parallel interface, to receive video data. The camera interface can achieve a data transfer rate up to 140 Mbyte/s using a 80 MHz pixel clock. It features:

- Programmable polarity for the input pixel clock and synchronization signals
- Parallel data communication can be 8-, 10-, 12- or 14-bit
- Supports 8-bit progressive video monochrome or raw bayer format, YCbCr 4:2:2 progressive video, RGB 565 progressive video or compressed data (like JPEG)
- Supports Continuous mode or Snapshot (a single frame) mode
- Capability to automatically crop the image

### 3.29 PSSI

The PSSI is a generic synchronous 8-/16-bit parallel data input/output slave interface. It allows the transmitter to send a data valid signal to indicate when the data is valid, and the receiver to output a flow control signal to indicate when it is ready to sample the data.

The main PSSI features are:

- Slave mode operation
- 8- or 16-bit parallel data input or output
- 8-word (32-byte) FIFO
- Data enable (DE) alternate function input and Ready (RDY) alternate function output.

When enabled, these signals can either allow the transmitter to indicate when the data is valid or, the receiver to indicate when it is ready to sample the data, or both.

The PSSI shares most of its circuitry with the digital camera interface (DCMI). It therefore cannot be used simultaneously with the DCMI.

### 3.30 LCD-TFT controller

The LCD-TFT display controller provides a 24-bit parallel digital RGB (Red, Green, Blue) and delivers all signals to interface directly to a broad range of LCD and TFT panels up to XGA (1024 x 768) resolution with the following features:

- 2 display layers with dedicated FIFO (64x64-bit)
- Color Look-Up table (CLUT) up to 256 colors (256x24-bit) per layer
- Up to 8 input color formats selectable per layer
- Flexible blending between two layers using alpha value (per pixel or constant)
- Flexible programmable parameters for each layer
- Color keying (transparency color)
- Up to 4 programmable interrupt events
- AXI master interface with burst of 16 words

### 3.31 True random number generator (RNG)

The RNG is a true random number generator that provides full entropy outputs to the application as 32-bit samples. It is composed of a live entropy source (analog) and an internal conditioning component.

The RNG can be used to construct a Non-deterministic Random Bit Generator (NDRBG), as a NIST SP 800-90B compliant entropy source.

The RNG true random number generator has been tested using German BSI statistical tests of AIS-31 (T0 to T8), and NIST SP800-90B statistical test suite.

### 3.32 Cryptographic acceleration (CRYP and HASH)

The devices embed a cryptographic processor that supports the advanced cryptographic algorithms usually required to ensure confidentiality, authentication, data integrity and non-repudiation when exchanging messages

with a peer:

- Encryption/Decryption
  - DES/TDES (data encryption standard/triple data encryption standard): ECB (electronic codebook) and CBC (cipher block chaining) chaining algorithms, 64-, 128- or 192-bit key
  - AES (advanced encryption standard): ECB, CBC, GCM, CCM, and CTR (counter mode) chaining algorithms, 128, 192 or 256-bit key
- Universal HASH
  - – SHA-1 and SHA-2 (secure HASH algorithms)
  - – MD5
  - – HMAC

The cryptographic accelerator supports DMA request generation.

### 3.33 On-the-fly decryption engine (OTFDEC)

The embedded OTFDEC decrypts in real-time the encrypted content stored in the external Octo-SPI memories used in Memory-mapped mode.

The OTFDEC uses the AES-128 algorithm in counter mode (CTR).

Code execution on external Octo-SPI memories can be protected against fault injection thanks to

STMicroelectronics enhanced encryption mode (refer to RM0468 for details).

The OTFDEC main features are as follow:

- On-the-fly 128-bit decryption during STM32 Octo-SPI read operations (single or multiple).
  - AES-CTR algorithm with keystream FIFO (depth= 4)
  - Support for any read size
- Up to four independent encrypted regions
  - Region definition granularity: 4096 bytes
  - Region configuration write locking mechanism
  - Two optional decryption modes: execute-only and execute-never
- 128-bit key for each region, two-byte firmware version, and eight-byte application-defined nonce
- Encryption keys confidentiality and integrity protection
  - Write only registers with software locking mechanism
  - Availability of 8-bit CRC as public key information
- Support for STM32 Octo-SPI prefetching mechanism.

### 3.34 Timers and watchdogs

The devices include two advanced-control timers, twelve general-purpose timers, two basic timers, five low-power timers, two watchdogs and a SysTick timer.

All timer counters can be frozen in Debug mode.

[Table 4](#) compares the features of the advanced-control, general-purpose and basic timers.

**Table 4. Timer feature comparison**

Timer type	Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary output	Max interface clock (MHz)	Max timer clock (MHz) <sup>(1)</sup>
Advanced-control	TIM1, TIM8	16-bit	Up, Down, Up/down	Any integer between 1 and 65536	Yes	4	Yes	137.5	275
General purpose	TIM2, TIM5, TIM23, TIM24	32-bit	Up, Down, Up/down	Any integer between 1 and 65536	Yes	4	No	137.5	275
	TIM3, TIM4	16-bit	Up, Down, Up/down	Any integer between 1 and 65536	Yes	4	No	137.5	275
	TIM12	16-bit	Up	Any integer between 1 and 65536	No	2	No	137.5	275
	TIM13, TIM14	16-bit	Up	Any integer between 1 and 65536	No	1	No	137.5	275
	TIM15	16-bit	Up	Any integer between 1 and 65536	Yes	2	1	137.5	275
	TIM16, TIM17	16-bit	Up	Any integer between 1 and 65536	Yes	1	1	137.5	275

Table 4. Timer feature comparison (continued)

Timer type	Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary output	Max interface clock (MHz)	Max timer clock (MHz) <sup>(1)</sup>
Basic	TIM6, TIM7	16-bit	Up	Any integer between 1 and 65536	Yes	0	No	137.5	275
Low-power timer	LPTIM1, LPTIM2, LPTIM3, LPTIM4, LPTIM5	16-bit	Up	1, 2, 4, 8, 16, 32, 64, 128	No	0	No	137.5	275

1. The maximum timer clock is up to 550 MHz depending on theTIMPRE bit in the RCC\_CFGFR register and D2PRE1/2 bits in RCC\_D2CFGR register.

### 3.34.1 Advanced-control timers (TIM1, TIM8)

The advanced-control timers (TIM1, TIM8) can be seen as three-phase PWM generators multiplexed on 6 channels. They have complementary PWM outputs with programmable inserted dead times. They can also be considered as complete general-purpose timers. Their 4 independent channels can be used for:

- Input capture
- Output compare
- PWM generation (Edge- or Center-aligned modes)
- One-pulse mode output

If configured as standard 16-bit timers, they have the same features as the general-purpose TIMx timers. If configured as 16-bit PWM generators, they have full modulation capability (0-100%).

The advanced-control timer can work together with the TIMx timers via the Timer Link feature for synchronization or event chaining.

TIM1 and TIM8 support independent DMA request generation.

### 3.34.2 General-purpose timers (TIMx)

There are ten synchronizable general-purpose timers embedded in the STM32H730xB devices (see [Table 4: Timer feature comparison](#) for differences).

- **TIM2, TIM3, TIM4, TIM5, TIM23, TIM24**

The devices include 4 full-featured general-purpose timers: TIM2, TIM3, TIM4, TIM5, TIM23 and TIM24. TIM2, TIM5, TIM23 and TIM24 are based on a 32-bit auto-reload up/downcounter and a 16-bit prescaler while TIM3 and TIM4 are based on a 16-bit auto-reload up/downcounter and a 16-bit prescaler. All timers feature 4 independent channels for input capture/output compare, PWM or One-pulse mode output. This gives up to 24 input capture/output compare/PWMs on the largest packages.

TIM2, TIM3, TIM4, TIM5, TIM23 and TIM24 general-purpose timers can work together, or with the other general-purpose timers and the advanced-control timers TIM1 and TIM8 via the Timer Link feature for synchronization or event chaining.

Any of these general-purpose timers can be used to generate PWM outputs.

TIM2, TIM3, TIM4, TIM5, TIM23, and TIM24 all have independent DMA request generation. They are capable of handling quadrature (incremental) encoder signals and the digital outputs from 1 to 4 hall-effect sensors.

- **TIM12, TIM13, TIM14, TIM15, TIM16, TIM17**

These timers are based on a 16-bit auto-reload upcounter and a 16-bit prescaler. TIM13, TIM14, TIM16 and TIM17 feature one independent channel, whereas TIM12 and TIM15 have two independent channels for input capture/output compare, PWM or One-pulse mode output. They can be synchronized with the TIM2, TIM3, TIM4, TIM5, TIM23, and TIM24 full-featured general-purpose timers or used as simple time bases.

### 3.34.3 Basic timers TIM6 and TIM7

These timers are mainly used for DAC trigger and waveform generation. They can also be used as a generic 16-bit time base.

TIM6 and TIM7 support independent DMA request generation.

### 3.34.4 Low-power timers (LPTIM1, LPTIM2, LPTIM3, LPTIM4, LPTIM5)

The low-power timers have an independent clock and is running also in Stop mode if it is clocked by LSE, LSI or an external clock. It is able to wakeup the devices from Stop mode.

This low-power timer supports the following features:

- 16-bit up counter with 16-bit autoreload register
- 16-bit compare register
- Configurable output: pulse, PWM
- Continuous / One-shot mode
- Selectable software / hardware input trigger
- Selectable clock source:
  - Internal clock source: LSE, LSI, HSI or APB clock
  - External clock source over LPTIM input (working even with no internal clock source running, used by the Pulse Counter Application)
- Programmable digital glitch filter
- Encoder mode

### 3.34.5 Independent watchdog

The independent watchdog is based on a 12-bit downcounter and 8-bit prescaler. It is clocked from an independent 32 kHz internal RC and as it operates independently from the main clock, it can operate in Stop and Standby modes. It can be used either as a watchdog to reset the device when a problem occurs, or as a free-running timer for application timeout management. It is hardware- or software-configurable through the option bytes.

A window option allows the device to be reset when a reload operation is made too early after the previous reload.

### 3.34.6 Window watchdog

The window watchdog is based on a 7-bit downcounter that can be set as free-running. It can be used as a watchdog to reset the device when a problem occurs. It is clocked from the main clock. It has an early warning interrupt capability and the counter can be frozen in Debug mode.

### 3.34.7 SysTick timer

This timer is dedicated to real-time operating systems, but could also be used as a standard down counter. It features:

- A 24-bit down counter
- Autoreload capability
- Maskable system interrupt generation when the counter reaches 0
- Programmable clock source.

### 3.35 Real-time clock (RTC), backup SRAM and backup registers

The RTC is an independent BCD timer/counter. It supports the following features:

- Calendar with subsecond, seconds, minutes, hours (12 or 24 format), week day, date, month, year, in BCD (binary-coded decimal) format.
- Automatic correction for 28, 29 (leap year), 30, and 31 days of the month.
- Two programmable alarms.
- On-the-fly correction from 1 to 32767 RTC clock pulses. This can be used to synchronize it with a master clock.
- Reference clock detection: a more precise second source clock (50 or 60 Hz) can be used to enhance the calendar precision.
- Digital calibration circuit with 0.95 ppm resolution, to compensate for quartz crystal inaccuracy.
- Three anti-tamper detection pins with programmable filter.
- Timestamp feature which can be used to save the calendar content. This function can be triggered by an event on the timestamp pin, or by a tamper event, or by a switch to  $V_{BAT}$  mode.
- 17-bit auto-reload wakeup timer (WUT) for periodic events with programmable resolution and period.

The RTC and the 32 backup registers are supplied through a switch that takes power either from the  $V_{DD}$  supply when present or from the  $V_{BAT}$  pin.

The backup registers are 32-bit registers used to store 128 bytes of user application data when  $V_{DD}$  power is not present. They are not reset by a system or power reset, or when the device wakes up from Standby mode.

The RTC clock sources can be:

- A 32.768 kHz external crystal (LSE)
- An external resonator or oscillator (LSE)
- The internal low-power RC oscillator (LSI, with typical frequency of 32 kHz)
- The high-speed external clock (HSE) divided by 32.

The RTC is functional in  $V_{BAT}$  mode and in all low-power modes when it is clocked by the LSE. When clocked by the LSI, the RTC is not functional in  $V_{BAT}$  mode, but is functional in all low-power modes.

All RTC events (Alarm, Wakeup Timer, Timestamp or Tamper) can generate an interrupt and wakeup the device from the low-power modes.



### 3.36 Inter-integrated circuit interface (I2C)

STM32H730xB devices embed five I<sup>2</sup>C interfaces.

The I<sup>2</sup>C bus interface handles communications between the microcontroller and the serial I<sup>2</sup>C bus. It controls all I<sup>2</sup>C bus-specific sequencing, protocol, arbitration and timing.

The I2C peripheral supports:

- I<sup>2</sup>C-bus specification and user manual rev. 5 compatibility:
  - Slave and Master modes, multimaster capability
  - Standard-mode (Sm), with a bitrate up to 100 kbit/s
  - Fast-mode (Fm), with a bitrate up to 400 kbit/s
  - Fast-mode Plus (Fm+), with a bitrate up to 1 Mbit/s and 20 mA output drive I/Os
  - 7-bit and 10-bit addressing mode, multiple 7-bit slave addresses
  - Programmable setup and hold times
  - Optional clock stretching
- System Management Bus (SMBus) specification rev 2.0 compatibility:
  - Hardware PEC (Packet Error Checking) generation and verification with ACK control
  - Address resolution protocol (ARP) support
  - SMBus alert
- Power System Management Protocol (PMBus™) specification rev 1.1 compatibility
- Independent clock: a choice of independent clock sources allowing the I2C communication speed to be independent from the PCLK reprogramming.
- Wakeup from Stop mode on address match
- Programmable analog and digital noise filters
- 1-byte buffer with DMA capability

### 3.37 Universal synchronous/asynchronous receiver transmitter (USART)

STM32H730xB devices have five embedded universal synchronous receiver transmitters (USART1, USART2, USART3, USART6, and USART10) and five universal asynchronous receiver transmitters (UART4, UART5, UART7, UART8, and UART9). Refer to [Table 5: USART features](#) for a summary of USARTx and UARTx features.

These interfaces provide asynchronous communication, IrDA SIR ENDEC support, multiprocessor communication mode, single-wire Half-duplex communication mode and have LIN Master/Slave capability. They provide hardware management of the CTS and RTS signals, and RS485 Driver Enable. They are able to communicate at speeds of up to 12.5 Mbit/s.

USART1, USART2, USART3, USART6, and USART10 also provide Smartcard mode (ISO 7816 compliant) and SPI-like communication capability.

The USARTs embed a Transmit FIFO (TXFIFO) and a Receive FIFO (RXFIFO). FIFO mode is enabled by software and is disabled by default.

All USART have a clock domain independent from the CPU clock, allowing the USARTx to wake up the MCU from Stop mode. The wakeup from Stop mode is programmable and can be done on:

- Start bit detection
- Any received data frame
- A specific programmed data frame
- Specific TXFIFO/RXFIFO status when FIFO mode is enabled.

All USART interfaces can be served by the DMA controller.

**Table 5. USART features**

USART modes/features <sup>(1)</sup>	USART1/2/3/6/10	UART4/5/7/8/9
Hardware flow control for modem	X	X
Continuous communication using DMA	X	X
Multiprocessor communication	X	X
Synchronous mode (Master/Slave)	X	-
Smartcard mode	X	-
Single-wire Half-duplex communication	X	X
IrDA SIR ENDEC block	X	X
LIN mode	X	X
Dual clock domain and wakeup from low power mode	X	X
Receiver timeout interrupt	X	X
Modbus communication	X	X
Auto baud rate detection	X	X
Driver Enable	X	X
USART data length	7, 8 and 9 bits	
Tx/Rx FIFO	X	X
Tx/Rx FIFO size	16	

1. X = supported.

### 3.38 Low-power universal asynchronous receiver transmitter (LPUART)

The device embeds one Low-Power UART (LPUART1). The LPUART supports asynchronous serial communication with minimum power consumption. It supports half duplex single wire communication and modem operations (CTS/RTS). It allows multiprocessor communication.

The LPUARTs embed a Transmit FIFO (TXFIFO) and a Receive FIFO (RXFIFO). FIFO mode is enabled by software and is disabled by default.

The LPUART has a clock domain independent from the CPU clock, and can wakeup the system from Stop mode. The wakeup from Stop mode are programmable and can be done on:

- Start bit detection
- Any received data frame
- A specific programmed data frame
- Specific TXFIFO/RXFIFO status when FIFO mode is enabled.

Only a 32.768 kHz clock (LSE) is needed to allow LPUART communication up to 9600 baud. Therefore, even in Stop mode, the LPUART can wait for an incoming frame while having an extremely low energy consumption. Higher speed clock can be used to reach higher baudrates.

LPUART interface can be served by the DMA controller.

### 3.39 Serial peripheral interface (SPI)/inter- integrated sound interfaces (I2S)

The devices feature up to six SPIs (SPI2S1, SPI2S2, SPI2S3, SPI4, SPI5 and SPI2S6) that allow communicating up to 150 Mbits/s in Master and Slave modes, in Half-duplex, Full-duplex and Simplex modes. The 3-bit prescaler gives 8 master mode frequencies and the frame is configurable from 4 to 16 bits. All SPI interfaces support NSS pulse mode, TI mode, Hardware CRC calculation and 8x 8-bit embedded Rx and Tx FIFOs with DMA capability.

Four standard I<sup>2</sup>S interfaces (multiplexed with SPI1, SPI2, SPI3 and SPI6) are available. They can be operated in Master or Slave mode, in Simplex communication modes, and can be configured to operate as a 16-/32-bit resolution input or output channel (except SPI2S6 which is limited to 16 bits). Audio sampling frequencies from 8 kHz up to 192 kHz are supported. When either or both of the I<sup>2</sup>S interfaces is/are configured in Master mode, the master clock can be output to the external DAC/CODEC at 256 times the sampling frequency. All I<sup>2</sup>S interfaces support 16x 8-bit embedded Rx and Tx FIFOs with DMA capability.

### 3.40 Serial audio interfaces (SAI)

The devices embed 2 SAIs (SAI1, and SAI4) that allow designing many stereo or mono audio protocols such as I2S, LSB or MSB-justified, PCM/DSP, TDM or AC'97. An SPDIF output is available when the audio block is configured as a transmitter. To bring this level of flexibility and reconfigurability, the SAI contains two independent audio sub-blocks. Each block has its own clock generator and I/O line controller.

Audio sampling frequencies up to 192 kHz are supported.

In addition, up to 8 microphones can be supported thanks to an embedded PDM interface. The SAI can work in master or slave configuration. The audio sub-blocks can be either receiver or transmitter and can work synchronously or asynchronously (with respect to the other one). The SAI can be connected with other SAIs to work synchronously.

### 3.41 SPDIFRX Receiver Interface (SPDIFRX)

The SPDIFRX peripheral is designed to receive an S/PDIF flow compliant with IEC-60958 and IEC-61937. These standards support simple stereo streams up to high sample rate, and compressed multi-channel surround sound, such as those defined by Dolby or DTS (up to 5.1).

The main SPDIFRX features are the following:

- Up to 4 inputs available
- Automatic symbol rate detection
- Maximum symbol rate: 12.288 MHz
- Stereo stream from 32 to 192 kHz supported
- Supports Audio IEC-60958 and IEC-61937, consumer applications
- Parity bit management
- Communication using DMA for audio samples
- Communication using DMA for control and user channel information
- Interrupt capabilities

The SPDIFRX receiver provides all the necessary features to detect the symbol rate, and decode the incoming data stream. The user can select the wanted SPDIF input, and when a valid signal will be available, the SPDIFRX will re-sample the incoming signal, decode the Manchester stream, recognize frames, sub-frames and blocks elements. It delivers to the CPU decoded data, and associated status flags.

The SPDIFRX also offers a signal named `spdif_frame_sync`, which toggles at the S/PDIF sub-frame rate that will be used to compute the exact sample rate for clock drift algorithms.

### 3.42 Single wire protocol master interface (SWPMI)

The Single wire protocol master interface (SWPMI) is the master interface corresponding to the Contactless Frontend (CLF) defined in the ETSI TS 102 613 technical specification. The main features are:

- Full-duplex communication mode
- automatic SWP bus state management (active, suspend, resume)
- configurable bitrate up to 2 Mbit/s
- automatic SOF, EOF and CRC handling

SWPMI can be served by the DMA controller.

### 3.43 Management data input/output (MDIO) slaves

The devices embed an MDIO slave interface it includes the following features:

- 32 MDIO Registers addresses, each of which is managed using separate input and output data registers:
  - 32 x 16-bit firmware read/write, MDIO read-only output data registers
  - 32 x 16-bit firmware read-only, MDIO write-only input data registers
- Configurable slave (port) address
- Independently maskable interrupts/events:
  - MDIO Register write
  - MDIO Register read
  - MDIO protocol error
- Able to operate in and wake up from Stop mode

### 3.44 SD/SDIO/MMC card host interfaces (SDMMC)

Two SDMMC host interfaces are available. They support *MultiMediaCard System Specification Version 4.51* in three different databus modes: 1 bit (default), 4 bits and 8 bits.

Both interfaces support the *SD memory card specifications version 4.1*. and the *SDIO card specification version 4.0*. in two different databus modes: 1 bit (default) and 4 bits.

Each SDMMC host interface supports only one SD/SDIO/MMC card at any one time and a stack of MMC Version 4.51 or previous.

The SDMMC host interface embeds a dedicated DMA controller allowing high-speed transfers between the interface and the SRAM.

### 3.45 Controller area network (FDCAN1, FDCAN2, FDCAN3)

The controller area network (CAN) subsystem consists of two CAN modules, a shared message RAM memory and a clock calibration unit.

All CAN modules (FDCAN1, FDCAN2, and FDCAN3) are compliant with ISO 11898-1 (CAN protocol specification version 2.0 part A, B) and CAN FD protocol specification version 1.0.

FDCAN1 supports time triggered CAN (TT-FDCAN) specified in ISO 11898-4, including event synchronized time-triggered communication, global system time, and clock drift compensation. The FDCAN1 contains additional registers, specific to the time triggered feature. The CAN FD option can be used together with event-triggered and time-triggered CAN communication.

A 10-Kbyte message RAM memory implements filters, receive FIFOs, receive buffers, transmit event FIFOs, transmit buffers (and triggers for TT-FDCAN). This message RAM is shared between the three modules - FDCAN1 FDCAN2 and FDCAN3.

The common clock calibration unit is optional. It can be used to generate a calibrated clock for FDCAN1, FDCAN2 and FDCAN3 from the HSI internal RC oscillator and the PLL, by evaluating CAN messages received by the FDCAN1.

### 3.46 Universal serial bus on-the-go high-speed (OTG\_HS)

The devices embed an USB OTG high-speed (up to 480 Mbit/s) device/host/OTG peripheral that supports both full-speed and high-speed operations. It integrates the transceivers for full-speed operation (12 Mbit/s) and a UTMI low-pin interface (ULPI) for high-speed operation (480 Mbit/s). When using the USB OTG\_HS interface in HS mode, an external PHY device connected to the ULPI is required.

The USB OTG\_HS peripheral is compliant with the USB 2.0 specification and with the OTG 2.0 specification. It features software-configurable endpoint setting and supports suspend/resume. The USB OTG\_HS controller requires a dedicated 48 MHz clock that is generated by a PLL connected to the HSE oscillator.

The main features are:

- Combined Rx and Tx FIFO size of 4 Kbytes with dynamic FIFO sizing
- Supports the session request protocol (SRP) and host negotiation protocol (HNP)
- 8 bidirectional endpoints
- 16 host channels with periodic OUT support
- Software configurable to OTG1.3 and OTG2.0 modes of operation
- USB 2.0 LPM (Link Power Management) support
- Battery Charging Specification Revision 1.2 support
- Internal FS OTG PHY support
- External HS or HS OTG operation supporting ULPI in SDR mode The OTG PHY is connected to the microcontroller ULPI port through 12 signals. It can be clocked using the 60 MHz output.
- Internal USB DMA
- HNP/SNP/IP inside (no need for any external resistor)
- For OTG/Host modes, a power switch is needed in case bus-powered devices are connected

### 3.47 Ethernet MAC interface with dedicated DMA controller (ETH)

The devices provide an IEEE-802.3-2002-compliant media access controller (MAC) for ethernet LAN communications through an industry-standard medium-independent interface (MII) or a reduced medium-independent interface (RMII). The microcontroller requires an external physical interface device (PHY) to connect to the physical LAN bus (twisted-pair, fiber, etc.). The PHY is connected to the device MII port using 17 signals for MII or 9 signals for RMII, and can be clocked using the 25 MHz (MII) from the microcontroller.

The devices include the following features:

- Supports 10 and 100 Mbit/s rates
- Dedicated DMA controller allowing high-speed transfers between the dedicated SRAM and the descriptors
- Tagged MAC frame support (VLAN support)
- Half-duplex (CSMA/CD) and full-duplex operation
- MAC control sublayer (control frames) support
- 32-bit CRC generation and removal
- Several address filtering modes for physical and multicast address (multicast and group addresses)
- 32-bit status code for each transmitted or received frame
- Internal FIFOs to buffer transmit and receive frames. The transmit FIFO and the receive FIFO are both 2 Kbytes.
- Supports hardware PTP (precision time protocol) in accordance with IEEE 1588 2008 (PTP V2) with the time stamp comparator connected to the TIM2 input
- Triggers interrupt when system time becomes greater than target time

### 3.48 High-definition multimedia interface (HDMI) - consumer electronics control (CEC)

The devices embed a HDMI-CEC controller that provides hardware support for the Consumer Electronics Control (CEC) protocol (Supplement 1 to the HDMI standard).

This protocol provides high-level control functions between all audiovisual products in an environment. It is specified to operate at low speeds with minimum processing and memory overhead. It has a clock domain independent from the CPU clock, allowing the HDMI-CEC controller to wakeup the MCU from Stop mode on data reception.

### 3.49 Debug infrastructure

The devices offer a comprehensive set of debug and trace features to support software development and system integration.

- Breakpoint debugging
- Code execution tracing
- Software instrumentation
- JTAG debug port
- Serial-wire debug port
- Trigger input and output
- Serial-wire trace port
- Trace port
- Arm® CoreSight™ debug and trace components

The debug can be controlled via a JTAG/Serial-wire debug access port, using industry standard debugging tools. The trace port performs data capture for logging and analysis.

## 4 Memory mapping

Refer to the product line reference manual for details on the memory mapping as well as the boundary addresses for all peripherals.



## 5 Pinouts, pin descriptions and alternate functions

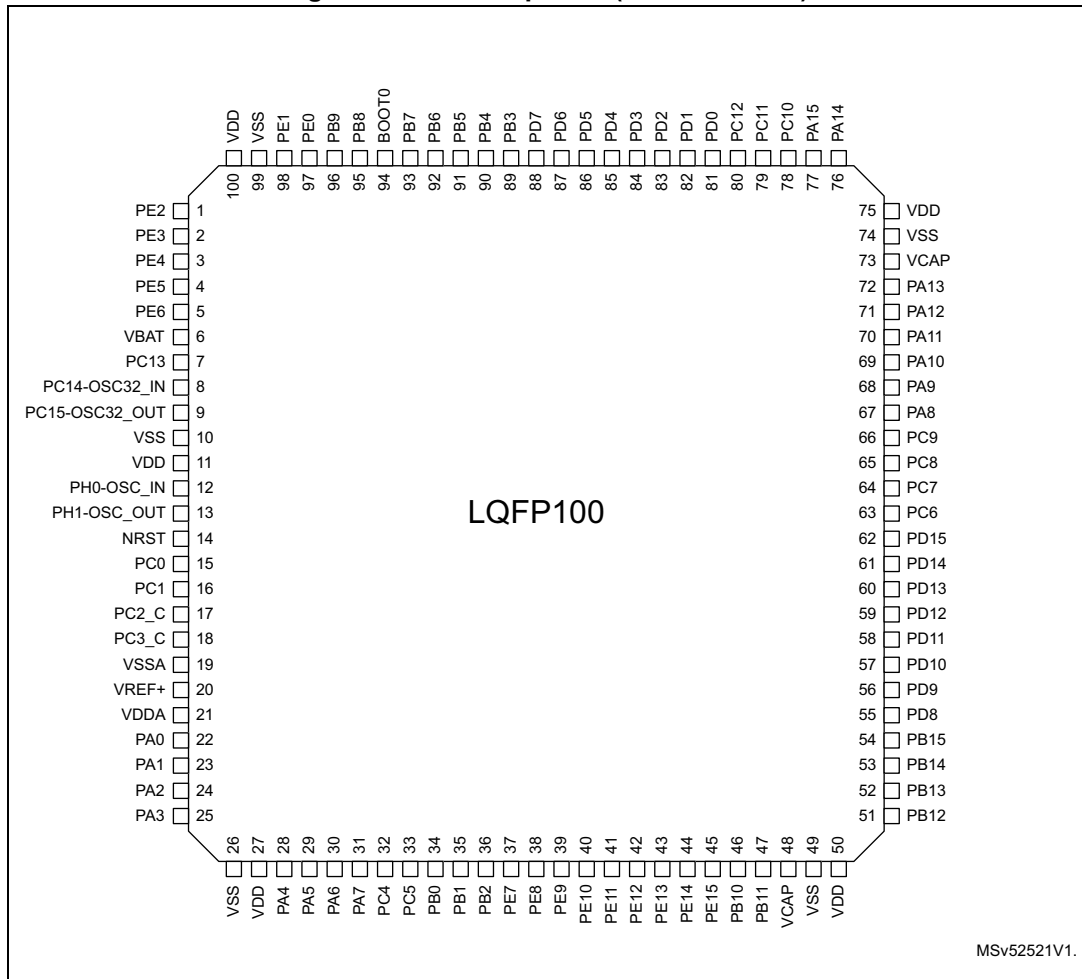
Figure 4. TFBGA100 pinout (without SMPS)

	1	2	3	4	5	6	7	8	9	10
A	PC14-OSC32_IN	PC13	PE2	PB9	PB7	PB4	PB3	PA15	PA14	PA13
B	PC15-OSC32_OUT	VBAT	PE3	PB8	PB6	PD5	PD2	PC11	PC10	PA12
C	PH0-OSC_IN	VSS	PE4	PE1	PB5	PD6	PD3	PC12	PA9	PA11
D	PH1-OSC_OUT	VDD	PE5	PE0	BOOT0	PD7	PD4	PD0	PA8	PA10
E	NRST	PC2_C	PE6	VSS	VSS	VSS	VCAP	PD1	PC9	PC7
F	PC0	PC1	PC3_C	VDD	VDD	VDD33USB	PDR_ON	VCAP	PC8	PC6
G	VSSA	PA0	PA4	PC4	PB2	PE10	PE14	PD15	PD11	PB15
H	VDDA	PA1	PA5	PC5	PE7	PE11	PE15	PD14	PD10	PB14
J	VSS	PA2	PA6	PB0	PE8	PE12	PB10	PB13	PD9	PD13
K	VDD	PA3	PA7	PB1	PE9	PE13	PB11	PB12	PD8	PD12

MSv52520V1.

1. The above figure shows the package top view.

Figure 5. LQFP100 pinout (without SMPS)



1. The above figure shows the package top view.

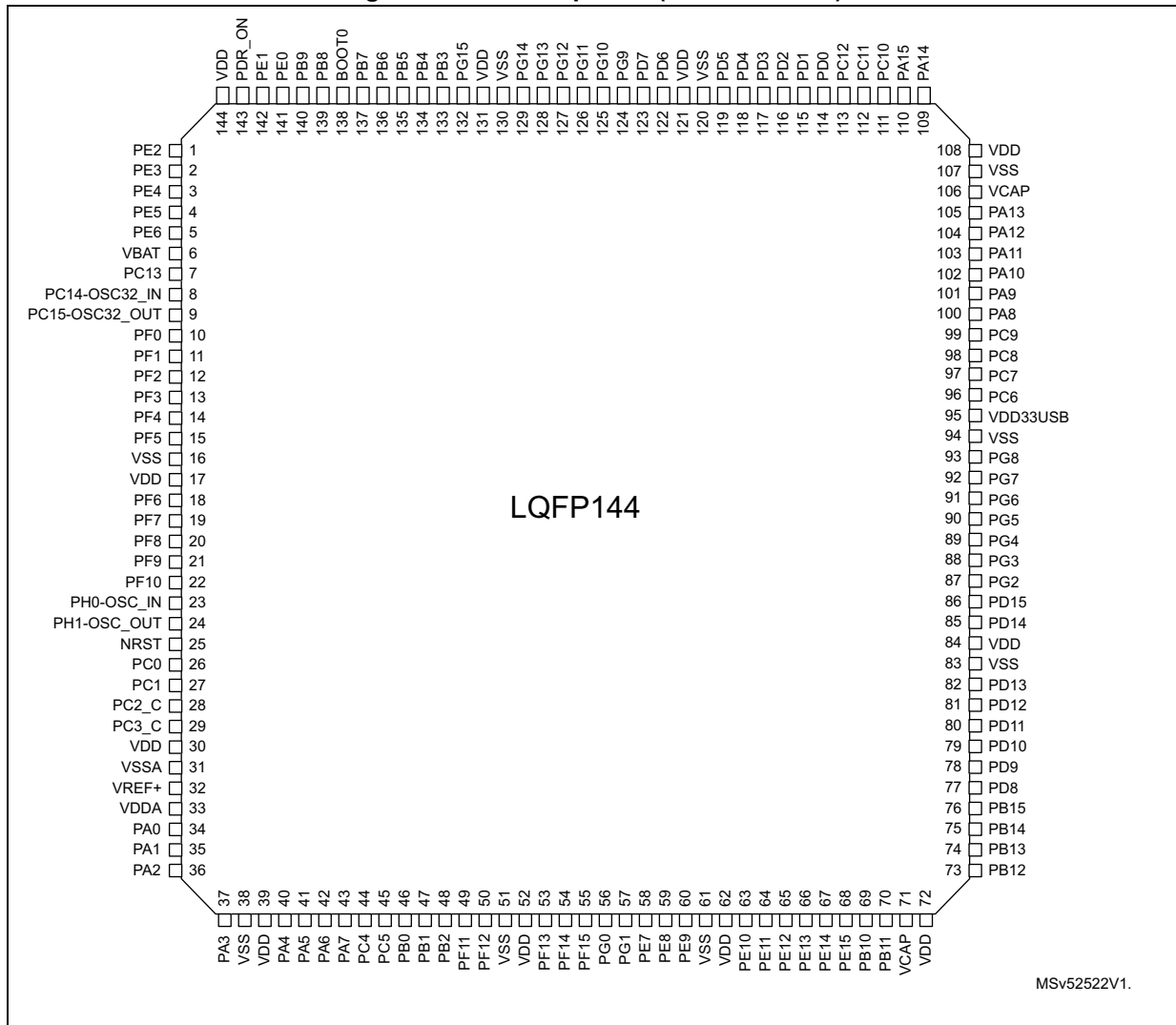
Figure 6. TFBGA144 ballout (without SMPS)

	1	2	3	4	5	6	7	8	9	10	11	12
A	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12
B	B1	B2	B3	B4	B5	B6	B7	B8	B9	B10	B11	B12
C	C1	C2	C3	C4	C5	C6	C7	C8	C9	C10	C11	C12
D	D1	D2	D3	D4	D5	D6	D7	D8	D9	D10	D11	D12
E	E1	E2	E3	E4	E5	E6	E7	E8	E9	E10	E11	E12
F	F1	F2	F3	F4	F5	F6	F7	F8	F9	F10	F11	F12
G	G1	G2	G3	G4	G5	G6	G7	G8	G9	G10	G11	G12
H	H1	H2	H3	H4	H5	H6	H7	H8	H9	H10	H11	H12
J	J1	J2	J3	J4	J5	J6	J7	J8	J9	J10	J11	J12
K	K1	K2	K3	K4	K5	K6	K7	K8	K9	K10	K11	K12
L	L1	L2	L3	L4	L5	L6	L7	L8	L9	L10	L11	L12
M	M1	M2	M3	M4	M5	M6	M7	M8	M9	M10	M11	M12

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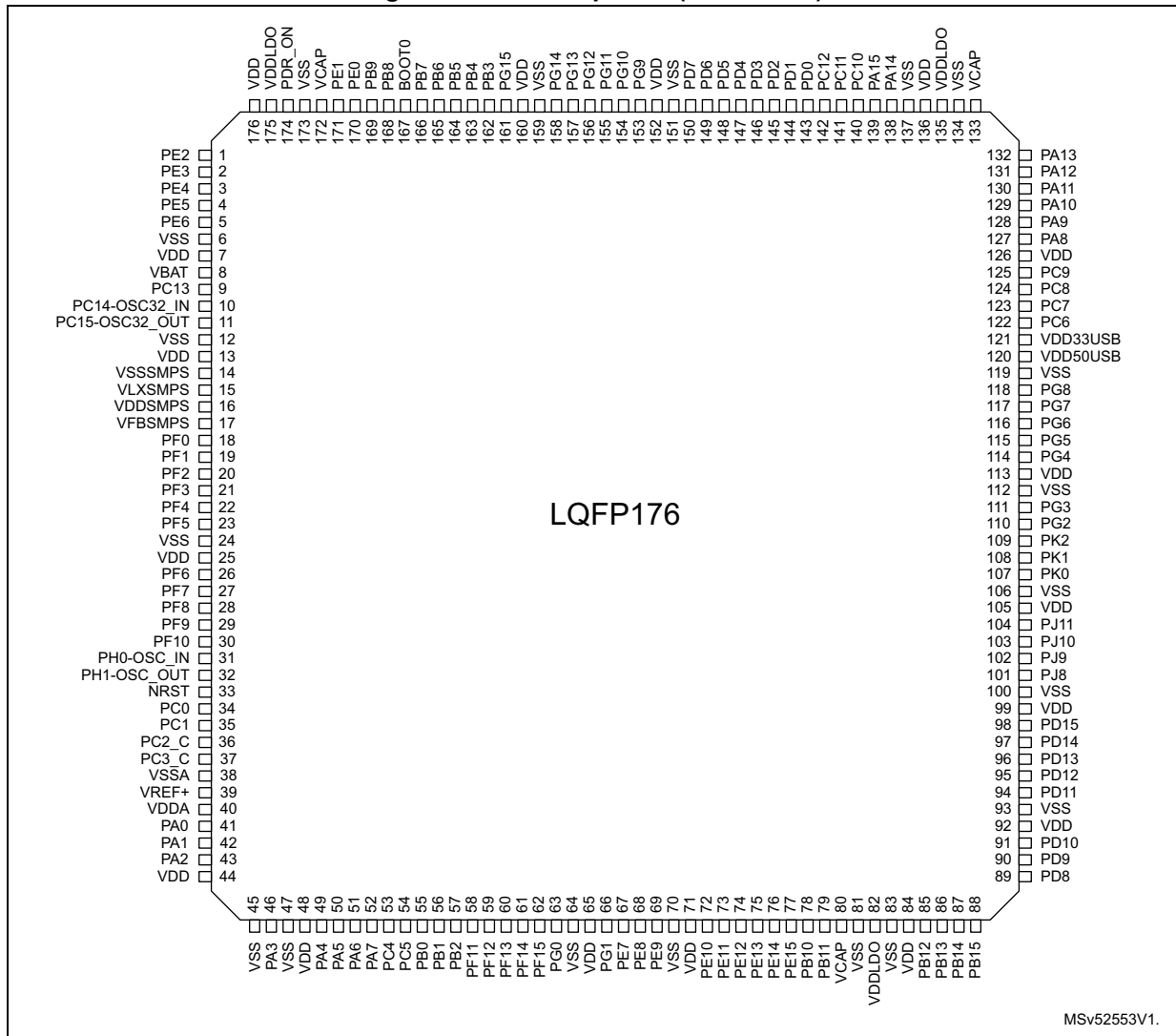
1. The above figure shows the package top view.

Figure 7. LQFP144 pinout (without SMPS)



1. The above figure shows the package top view.

Figure 8. LQFP176 pinout (with SMPS)



1. The above figure shows the package top view.

Figure 9. UFBGA169 ballout (with SMPS)

	1	2	3	4	5	6	7	8	9	10	11	12	13
A	PE4	PE2	VDD	VCAP	PB6	VDD	VDD	PG10	PD5	VDD	PC12	PC10	PH14
B	PC15-OSC32_OUT	PE3	VSS	VDDLDO	PB8	PB4	VSS	PG11	PD6	VSS	PC11	PA14	PH13
C	PC14-OSC32_IN	PE6	PE5	PDR_ON	PB9	PB5	PG14	PG9	PD4	PD1	PA15	VSS	VDD
D	VDD	VSS	PC13	PE1	PE0	PB7	PG13	PD7	PD3	PD0	PA13	VDDLDO	VCAP
E	VLXSMPS	VSSMPS	VBAT	PF1	PF3	BOOT0	PG15	PG12	PD2	PA10	PA9	PA8	PA12
F	VDDSMPS	VFBSMPS	PF0	PF2	PF5	PF7	PB3	PG4	PC6	PC7	PC9	PC8	PA11
G	VDD	VSS	PF4	PF6	PF9	NRST	PF13	PE7	PG6	PG7	PG8	VDD50USB	VDD33USB
H	PH0-OSC_IN	PH1-OSC_OUT	PF10	PF8	PC2	PA4	PF14	PE8	PG2	PG3	PG5	VSS	VDD
J	PC0	PC1	VSSA	PC3	PA0	PA7	PF15	PE9	PE14	PD11	PD13	PD15	PD14
K	PC3_C	PC2_C	PA0_C	PA1	PA6	PC4	PG0	PE13	PH10	PH12	PD9	PD10	PD12
L	VDDA	VREF+	PA1_C	PA5	PB1	PB2	PG1	PE12	PB10	PH11	PB13	VSS	VDD
M	VDD	VSS	PH3	VSS	PB0	PF11	VSS	PE10	PB11	VDDLDO	VSS	PD8	PB15
N	PA2	PH2	PA3	VDD	PC5	PF12	VDD	PE11	PE15	VCAP	VDD	PB12	PB14

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1. The above figure shows the package top view.

Figure 10. UFBGA176+25 ballout (with SMPS)

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15																														
A	VSS	PB8	VDDLDO	VCAP	PB6	PB3	PG11	PG9	PD3	PD1	PA15	PA14	VDDLDO	VCAP	VSS																														
B	PE4	PE3	PB9	PE0	PB7	PB4	PG13	PD7	PD5	PD2	PC12	PH14	PA13	PA8	PA12																														
C	PC13	VSS	PE2	PE1	BOOT0	PB5	PG14	PG10	PD4	PD0	PC11	PC10	PH13	PA10	PA11																														
D	PC15-OSC32_OUT	PC14-OSC32_IN	PE5	PDR_ON	VDD	VSS	PG15	PG12	PD6	VSS	VDD	PH15	PA9	PC8	PC7																														
E	VSS	VBAT	PE6	VDD	<table border="1" style="margin: auto;"> <tr><td>VSS</td><td>VSS</td><td>VSS</td><td>VSS</td><td>VSS</td></tr> <tr><td>VSS</td><td>VSS</td><td>VSS</td><td>VSS</td><td>VSS</td></tr> <tr><td>VSS</td><td>VSS</td><td>VSS</td><td>VSS</td><td>VSS</td></tr> <tr><td>VSS</td><td>VSS</td><td>VSS</td><td>VSS</td><td>VSS</td></tr> <tr><td>VSS</td><td>VSS</td><td>VSS</td><td>VSS</td><td>VSS</td></tr> <tr><td>VSS</td><td>VSS</td><td>VSS</td><td>VSS</td><td>VSS</td></tr> </table>							VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDD	PC9	PC6	VDD50USB
VSS	VSS	VSS	VSS	VSS																																									
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F	VLXSMPS	VSSMPS	PF1	PF0	VSS	VDD33USB	PG6	PG5																																					
G	VDDSMPS	VFBSMPS	PF2	VDD	VSS	PG8	PG7	PG4	PG2																																				
H	PF6	PF4	PF5	PF3	VSS	VDD	PG3	PD14	PD13																																				
J	PH0-OSC_IN	PF8	PF7	PF9	VSS	PD15	PD11	VSS	PD12																																				
K	PH1-OSC_OUT	VSS	PF10	VDD	VSS	VSS	PD9	PB15	PB14																																				
L	NRST	PC0	PC1	VREF-	VDD	PD10	PD8	PB13																																					
M	PC2	PC3	VREF+	VDDA	VDD	VSS	PC5	PB1	VDD	VSS	PH7	PE14	PH11	PH9	PB12																														
N	PC2_C	PC3_C	VSSA	PH2	PA3	PA7	PF11	PE8	PG1	PF15	PF13	PB10	PH8	PH10	PH12																														
P	PA0	PA1	PA1_C	PH4	PA4	PA5	PB2	PG0	PE7	PB11	PF12	PE12	PE13	PE15	PH6																														
R	VSS	PA2	PA0_C	PH3	PH5	PC4	PA6	PB0	PE10	PF14	PE9	PE11	VCAP	VDDLDO	VSS																														

MSv52552V1.

1. The above figure shows the package top view.

**Table 6. Legend/abbreviations used in the pinout table**

Name		Abbreviation	Definition
Pin name		Unless otherwise specified in brackets below the pin name, the pin function during and after reset is the same as the actual pin name	
Pin type		S	Supply pin
		I	Input only pin
		I/O	Input / output pin
		ANA	Analog-only Input
I/O structure		FT	5 V tolerant I/O
		TT	3.3 V tolerant I/O
		B	Dedicated BOOT0 pin
		RST	Bidirectional reset pin with embedded weak pull-up resistor
		<b>Option for TT and FT I/Os</b>	
		_f	I2C FM+ option
		_a	analog option (supplied by V <sub>DDA</sub> )
		_u	USB option (supplied by V <sub>DD33USB</sub> )
		_h	High-speed low-voltage I/O
Notes		Unless otherwise specified by a note, all I/Os are set as floating inputs during and after reset.	
Pin functions	Alternate functions	Functions selected through GPIOx_AFR registers	
	Additional functions	Functions directly selected/enabled through peripheral registers	

Table 7. STM32H730xB pin and ball descriptions

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
A3	1	1	A3	A2	C3	1	PE2	I/O	FT_h	-	TRACECLK, SAI1_CK1, USART10_RX, SPI4_SCK, SAI1_MCLK_A, SAI4_MCLK_A, OCTOSPIM_P1_IO2, SAI4_CK1, ETH_MII_TXD3, FMC_A23, EVENTOUT	-
B3	2	2	A2	B2	B2	2	PE3	I/O	FT_h	-	TRACED0, TIM15_BKIN, SAI1_SD_B, SAI4_SD_B, USART10_TX, FMC_A19, EVENTOUT	-
C3	3	3	B2	A1	B1	3	PE4	I/O	FT_h	-	TRACED1, SAI1_D2, DFSDM1_DATIN3, TIM15_CH1N, SPI4_NSS, SAI1_FS_A, SAI4_FS_A, SAI4_D2, FMC_A20, DCMI_D4/PSSI_D4, LCD_B0, EVENTOUT	-
D3	4	4	B3	C3	D3	4	PE5	I/O	FT_h	-	TRACED2, SAI1_CK2, DFSDM1_CKIN3, TIM15_CH1, SPI4_MISO, SAI1_SCK_A, SAI4_SCK_A, SAI4_CK2, FMC_A21, DCMI_D6/PSSI_D6, LCD_G0, EVENTOUT	-
E3	5	5	B4	C2	E3	5	PE6	I/O	FT_h	-	TRACED3, TIM1_BKIN2, SAI1_D1, TIM15_CH2, SPI4_MOSI, SAI1_SD_A, SAI4_SD_A, SAI4_D1, SAI4_MCLK_B, TIM1_BKIN2_COMP12, FMC_A22, DCMI_D7/PSSI_D7, LCD_G1, EVENTOUT	-
-	-	-	-	-	-	6	VSS	S	-	-	-	-
-	-	-	-	-	-	7	VDD	S	-	-	-	-
B2	6	6	C2	E3	E2	8	VBAT	S	-	-	-	-
A2	7	7	A1	D3	C1	9	PC13	I/O	FT	-	EVENTOUT	RTC_TAMP1/ RTC_TS, WKUP4
A1	8	8	B1	C1	D2	10	PC14-OSC32_IN	I/O	FT	-	EVENTOUT	OSC32_IN



Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
B1	9	9	C1	B1	D1	11	PC15- OSC32_OUT	I/O	FT	-	EVENTOUT	OSC32_OUT
-	-	-	-	-	-	12	VSS	S	-	-	-	-
-	-	-	-	-	-	13	VDD	S	-	-	-	-
-	-	-	-	E2	F2	14	VSSSMPS	S	-	-	-	-
-	-	-	-	E1	F1	15	VLXSMPS	S	-	-	-	-
-	-	-	-	F1	G1	16	VDDSMPS	S	-	-	-	-
-	-	-	-	F2	G2	17	VFBSMPS	S	-	-	-	-
-	-	10	C3	F3	F4	18	PF0	I/O	FT _fn	-	I2C2_SDA(boot), I2C5_SDA, OCTOSPIM_P2_IO0, FMC_A0, TIM23_CH1, EVENTOUT	-
-	-	11	C4	E4	F3	19	PF1	I/O	FT _fn	-	I2C2_SCL(boot), I2C5_SCL, OCTOSPIM_P2_IO1, FMC_A1, TIM23_CH2, EVENTOUT	-
-	-	12	D4	F4	G3	20	PF2	I/O	FT _h	-	I2C2_SMBA, I2C5_SMBA, OCTOSPIM_P2_IO2, FMC_A2, TIM23_CH3, EVENTOUT	-
-	-	13	E2	E5	H4	21	PF3	I/O	FT _ha	-	OCTOSPIM_P2_IO3, FMC_A3, TIM23_CH4, EVENTOUT	ADC3_INP5
-	-	14	E3	G3	H2	22	PF4	I/O	FT _ha	-	OCTOSPIM_P2_CLK, FMC_A4, EVENTOUT	ADC3_INN5, ADC3_INP9
-	-	15	E4	F5	H3	23	PF5	I/O	FT _ha	-	OCTOSPIM_P2_NCLK, FMC_A5, EVENTOUT	ADC3_INP4
-	10	16	-	-	-	24	VSS	S	-	-	-	-
-	11	17	-	-	-	25	VDD	S	-	-	-	-
-	-	18	F3	G4	H1	26	PF6	I/O	FT _ha	-	TIM16_CH1, FDCAN3_RX, SPI5_NSS, SAI1_SD_B, UART7_RX, SAI4_SD_B, OCTOSPIM_P1_IO3, TIM23_CH1, EVENTOUT	ADC3_INN4, ADC3_INP8

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
-	-	19	F2	F6	J3	27	PF7	I/O	FT _ha	-	TIM17_CH1, FDCAN3_TX, SPI5_SCK, SAI1_MCLK_B, UART7_TX, SAI4_MCLK_B, OCTOSPIM_P1_IO2, TIM23_CH2, EVENTOUT	ADC3_INP3
-	-	20	G3	H4	J2	28	PF8	I/O	FT _ha	-	TIM16_CH1N, SPI5_MISO, SAI1_SCK_B, UART7_RTS/UART7_DE, SAI4_SCK_B, TIM13_CH1, OCTOSPIM_P1_IO0, TIM23_CH3, EVENTOUT	ADC3_INN3, ADC3_INP7
-	-	21	G2	G5	J4	29	PF9	I/O	FT _ha	-	TIM17_CH1N, SPI5_MOSI, SAI1_FS_B, UART7_CTS, SAI4_FS_B, TIM14_CH1, OCTOSPIM_P1_IO1, TIM23_CH4, EVENTOUT	ADC3_INP2
-	-	22	G1	H3	K3	30	PF10	I/O	FT _ha	-	TIM16_BKIN, SAI1_D3, PSSI_D15, OCTOSPIM_P1_CLK, SAI4_D3, DCMI_D11/PSSI_D11, LCD_DE, EVENTOUT	ADC3_INN2, ADC3_INP6
C1	12	23	D1	H1	J1	31	PH0-OSC_IN	I/O	FT	-	EVENTOUT	OSC_IN
D1	13	24	E1	H2	K1	32	PH1-OSC_OUT	I/O	FT	-	EVENTOUT	OSC_OUT
E1	14	25	F1	G6	L1	33	NRST	I/O	RS T	-	-	-
F1	15	26	H1	J1	L2	34	PC0	I/O	FT _ha	-	FMC_D12/FMC_AD12, DFSDM1_CKIN0, DFSDM1_DATIN4, SAI4_FS_B, FMC_A25, OTG_HS_ULPI_STP, LCD_G2, FMC_SDNWE, LCD_R5, EVENTOUT	ADC123_INP10
F2	16	27	H2	J2	L3	35	PC1	I/O	FT _ha	-	TRACED0, SAI4_D1, SAI1_D1, DFSDM1_DATIN0, DFSDM1_CKIN4, SPI2_MOSI/I2S2_SDO, SAI1_SD_A, SAI4_SD_A, SDMMC2_CK, OCTOSPIM_P1_IO4, ETH_MDC, MDIOS_MDC, LCD_G5, EVENTOUT	ADC123_INN10, ADC123_INP11, RTC_TAMP3, WKUP6

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
-	-	-	H3	H5	M1	-	PC2	I/O	FT_a	-	PWR_DEEPSLEEP, DFSDM1_CKIN1, OCTOSPIM_P1_IO5, SPI2_MISO/I2S2_SDI, DFSDM1_CKOUT, OCTOSPIM_P1_IO2, OTG_HS_ULPI_DIR, ETH_MII_TXD2, FMC_SDNE0, EVENTOUT	ADC123_INN11, ADC123_INP12
E2	17	28	-	K2	N1	36	PC2_C	AN A	TT_a	-	-	ADC3_INN1, ADC3_INP0
-	-	-	H4	J4	M2	-	PC3	I/O	FT_a	-	PWR_SLEEP, DFSDM1_DATIN1, OCTOSPIM_P1_IO6, SPI2_MOSI/I2S2_SDO, OCTOSPIM_P1_IO0, OTG_HS_ULPI_NXT, ETH_MII_TX_CLK, FMC_SDCKE0, EVENTOUT	ADC12_INN12, ADC12_INP13
F3	18	29	-	K1	N2	37	PC3_C	AN A	TT_a	-	-	ADC3_INP1
-	-	30	-	-	-	-	VDD	S	-	-	-	-
G1	19	31	J1	J3	N3	38	VSSA	S	-	-	-	-
-	-	-	K1	-	L4	-	VREF-	S	-	-	-	-
-	20	32	L1	L2	M3	39	VREF+	S	-	-	-	-
H1	21	33	M1	L1	M4	40	VDDA	S	-	-	-	-
G2	22	34	J2	J5	P1	41	PA0	I/O	FT_ha	-	TIM2_CH1/TIM2_ETR, TIM5_CH1, TIM8_ETR, TIM15_BKIN, SPI6_NSS/I2S6_WS, USART2_CTS/USART2_NSS, UART4_TX, SDMMC2_CMD, SAI4_SD_B, ETH_MII_CRS, FMC_A19, EVENTOUT	ADC1_INP16, WKUP1
-	-	-	-	K3	R3	-	PA0_C	AN A	TT_a	-	-	ADC12_INN1, ADC12_INP0

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
H2	23	35	K2	K4	P2	42	PA1	I/O	FT _ha	-	TIM2_CH2, TIM5_CH2, LPTIM3_OUT, TIM15_CH1N, USART2_RTS/USART2_DE, UART4_RX, OCTOSPIM_P1_IO3, SAI4_MCLK_B, ETH_MII_RX_CLK/ETH_RMII _REF_CLK, OCTOSPIM_P1_DQS, LCD_R2, EVENTOUT	ADC1_INN16, ADC1_INP17
-	-	-	-	L3	P3	-	PA1_C	AN A	TT _a	-	-	ADC12_INP1
J2	24	36	L2	N1	R2	43	PA2	I/O	FT _ha	-	TIM2_CH3, TIM5_CH3, LPTIM4_OUT, TIM15_CH1, OCTOSPIM_P1_IO0, USART2_TX(boot), SAI4_SCK_B, ETH_MDIO, MDIOS_MDIO, LCD_R1, EVENTOUT	ADC12_INP14, WKUP2
-	-	-	-	N2	N4	-	PH2	I/O	FT _ha	-	LPTIM1_IN2, OCTOSPIM_P1_IO4, SAI4_SCK_B, ETH_MII_CRIS, FMC_SDCKE0, LCD_R0, EVENTOUT	ADC3_INP13
-	-	-	-	-	-	44	VDD	S	-	-	-	-
-	-	-	-	-	-	45	VSS	S	-	-	-	-
-	-	-	-	M3	R4	-	PH3	I/O	FT _ha	-	OCTOSPIM_P1_IO5, SAI4_MCLK_B, ETH_MII_COL, FMC_SDNE0, LCD_R1, EVENTOUT	ADC3_INN13, ADC3_INP14
-	-	-	-	-	P4	-	PH4	I/O	FT _fa	-	I2C2_SCL, LCD_G5, OTG_HS_ULPI_NXT, PSSI_D14, LCD_G4, EVENTOUT	ADC3_INN14, ADC3_INP15
-	-	-	-	-	R5	-	PH5	I/O	FT _fa	-	I2C2_SDA, SPI5_NSS, FMC_SDNWE, EVENTOUT	ADC3_INN15, ADC3_INP16

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
K2	25	37	M2	N3	N5	46	PA3	I/O	FT _ha	-	TIM2_CH4, TIM5_CH4, LPTIM5_OUT, TIM15_CH2, I2S6_MCK, OCTOSPIM_P1_IO2, USART2_RX(boot), LCD_B2, OTG_HS_ULPI_D0, ETH_MII_COL, OCTOSPIM_P1_CLK, LCD_B5, EVENTOUT	ADC12_INP15
-	26	38	-	-	-	47	VSS	S	-	-	-	-
-	27	39	-	-	-	48	VDD	S	-	-	-	-
G3	28	40	J3	H6	P5	49	PA4	I/O	TT _ha	-	D1PWREN, TIM5_ETR, SPI1_NSS(boot)/I2S1_WS, SPI3_NSS/I2S3_WS, USART2_CK, SPI6_NSS/I2S6_WS, FMC_D8/FMC_AD8, DCMI_HSYNC/PSSI_DE, LCD_VSYNC, EVENTOUT	ADC12_INP18, DAC1_OUT1
H3	29	41	K3	L4	P6	50	PA5	I/O	TT _ha	-	D2PWREN, TIM2_CH1/TIM2_ETR, TIM8_CH1N, SPI1_SCK(boot)/I2S1_CK, SPI6_SCK/I2S6_CK, OTG_HS_ULPI_CK, FMC_D9/FMC_AD9, PSSI_D14, LCD_R4, EVENTOUT	ADC12_INN18, ADC12_INP19, DAC1_OUT2
J3	30	42	L3	K5	R7	51	PA6	I/O	FT _ha	-	TIM1_BKIN, TIM3_CH1, TIM8_BKIN, SPI1_MISO(boot)/I2S1_SDI, OCTOSPIM_P1_IO3, SPI6_MISO/I2S6_SDI, TIM13_CH1, TIM8_BKIN_COMP12, MDIOS_MDC, TIM1_BKIN_COMP12, DCMI_PIXCLK/PSSI_PDCK, LCD_G2, EVENTOUT	ADC12_INP3

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
K3	31	43	M3	J6	N6	52	PA7	I/O	TT _ha	-	TIM1_CH1N, TIM3_CH2, TIM8_CH1N, SPI1_MOSI(boot)/I2S1_SDO, SPI6_MOSI/I2S6_SDO, TIM14_CH1, OCTOSPIM_P1_IO2, ETH_MII_RX_DV/ETH_RMII_ CRS_DV, FMC_SDNWE, LCD_VSYNC, EVENTOUT	ADC12_INN3, ADC12_INP7, OPAMP1_VINM
G4	32	44	J4	K6	R6	53	PC4	I/O	TT _ha	-	PWR_DEEPSLEEP, FMC_A22, DFSDM1_CKIN2, I2S1_MCK, SPDIFRX1_IN3, SDMMC2_CKIN, ETH_MII_RXD0/ETH_RMII_R XD0, FMC_SDNE0, LCD_R7, EVENTOUT	ADC12_INP4, OPAMP1_VOUT, COMP1_INM
H4	33	45	K4	N5	M7	54	PC5	I/O	TT _ha	-	PWR_SLEEP, SAI4_D3, SAI1_D3, DFSDM1_DATIN2, PSSI_D15, SPDIFRX1_IN4, OCTOSPIM_P1_DQS, ETH_MII_RXD1/ETH_RMII_R XD1, FMC_SDCKE0, COMP1_OUT, LCD_DE, EVENTOUT	ADC12_INN4, ADC12_INP8, OPAMP1_VINM
J4	34	46	L4	M5	R8	55	PB0	I/O	TT _ha	-	TIM1_CH2N, TIM3_CH3, TIM8_CH2N, OCTOSPIM_P1_IO1, DFSDM1_CKOUT, UART4_CTS, LCD_R3, OTG_HS_ULPI_D1, ETH_MII_RXD2, LCD_G1, EVENTOUT	ADC12_INN5, ADC12_INP9, OPAMP1_VINP, COMP1_INP
K4	35	47	M4	L5	M8	56	PB1	I/O	FT _ha	-	TIM1_CH3N, TIM3_CH4, TIM8_CH3N, OCTOSPIM_P1_IO0, DFSDM1_DATIN1, LCD_R6, OTG_HS_ULPI_D2, ETH_MII_RXD3, LCD_G0, EVENTOUT	ADC12_INP5, COMP1_INM

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
G5	36	48	J5	L6	P7	57	PB2	I/O	FT _ha	-	RTC_OUT, SAI4_D1, SAI1_D1, DFSDM1_CKIN1, SAI1_SD_A, SPI3_MOSI/I2S3_SDO, SAI4_SD_A, OCTOSPIM_P1_CLK, OCTOSPIM_P1_DQS, ETH_TX_ER, TIM23_ETR, EVENTOUT	COMP1_INP
-	-	49	M5	M6	N7	58	PF11	I/O	FT _ha	-	SPI5_MOSI, OCTOSPIM_P1_NCLK, SAI4_SD_B, FMC_NRAS, DCMI_D12/PSSI_D12, TIM24_CH1, EVENTOUT	ADC1_INP2
-	-	50	L5	N6	P11	59	PF12	I/O	FT _ha	-	OCTOSPIM_P2_DQS, FMC_A6, TIM24_CH2, EVENTOUT	ADC1_INN2, ADC1_INP6
-	-	51	-	-	-	-	VSS	S	-	-	-	-
-	-	52	-	-	-	-	VDD	S	-	-	-	-
-	-	53	K5	G7	N11	60	PF13	I/O	FT _ha	-	DFSDM1_DATIN6, I2C4_SMBA, FMC_A7, TIM24_CH3, EVENTOUT	ADC2_INP2
-	-	54	M6	H7	R10	61	PF14	I/O	FT _fa	-	DFSDM1_CKIN6, I2C4_SCL, FMC_A8, TIM24_CH4, EVENTOUT	ADC2_INN2, ADC2_INP6
-	-	55	L6	J7	N10	62	PF15	I/O	FT _fh	-	I2C4_SDA, FMC_A9, EVENTOUT	-
-	-	56	K6	K7	P8	63	PG0	I/O	FT _h	-	OCTOSPIM_P2_IO4, UART9_RX, FMC_A10, EVENTOUT	-
-	-	-	-	-	-	64	VSS	S	-	-	-	-
-	-	-	-	-	-	65	VDD	S	-	-	-	-
-	-	57	J6	L7	N9	66	PG1	I/O	TT _h	-	OCTOSPIM_P2_IO5, UART9_TX, FMC_A11, EVENTOUT	OPAMP2_VINM
H5	37	58	M7	G8	P9	67	PE7	I/O	TT _ha	-	TIM1_ETR, DFSDM1_DATIN2, UART7_RX, OCTOSPIM_P1_IO4, FMC_D4/FMC_AD4, EVENTOUT	OPAMP2_VOUT, COMP2_INM

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
J5	38	59	L7	H8	N8	68	PE8	I/O	TT _ha	-	TIM1_CH1N, DFSDM1_CKIN2, UART7_TX, OCTOSPIM_P1_IO5, FMC_D5/FMC_AD5, COMP2_OUT, EVENTOUT	OPAMP2_VINM
K5	39	60	K7	J8	R11	69	PE9	I/O	TT _ha	-	TIM1_CH1, DFSDM1_CKOUT, UART7_RTS/UART7_DE, OCTOSPIM_P1_IO6, FMC_D6/FMC_AD6, EVENTOUT	OPAMP2_VINP, COMP2_INP
-	-	61	-	-	-	70	VSS	S	-	-	-	-
-	-	62	-	-	-	71	VDD	S	-	-	-	-
G6	40	63	J7	M8	R9	72	PE10	I/O	FT _ha	-	TIM1_CH2N, DFSDM1_DATIN4, UART7_CTS, OCTOSPIM_P1_IO7, FMC_D7/FMC_AD7, EVENTOUT	COMP2_INM
H6	41	64	H8	N8	R12	73	PE11	I/O	FT _ha	-	TIM1_CH2, DFSDM1_CKIN4, SPI4_NSS(boot), SAI4_SD_B, OCTOSPIM_P1_NCS, FMC_D8/FMC_AD8, LCD_G3, EVENTOUT	COMP2_INP
J6	42	65	J8	L8	P12	74	PE12	I/O	FT _h	-	TIM1_CH3N, DFSDM1_DATIN5, SPI4_SCK(boot), SAI4_SCK_B, FMC_D9/FMC_AD9, COMP1_OUT, LCD_B4, EVENTOUT	-
K6	43	66	K8	K8	P13	75	PE13	I/O	FT _h	-	TIM1_CH3, DFSDM1_CKIN5, SPI4_MISO(boot), SAI4_FS_B, FMC_D10/FMC_AD10, COMP2_OUT, LCD_DE, EVENTOUT	-
G7	44	67	L8	J9	M12	76	PE14	I/O	FT _h	-	TIM1_CH4, SPI4_MOSI(boot), SAI4_MCLK_B, FMC_D11/FMC_AD11, LCD_CLK, EVENTOUT	-



Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
H7	45	68	M8	N9	P14	77	PE15	I/O	FT_h	-	TIM1_BKIN, USART10_CK, FMC_D12/FMC_AD12, TIM1_BKIN_COMP12, LCD_R7, EVENTOUT	-
J7	46	69	M9	L9	N12	78	PB10	I/O	FT_fh	-	TIM2_CH3, LPTIM2_IN1, I2C2_SCL, SPI2_SCK/I2S2_CK, DFSDM1_DATIN7, USART3_TX(boot), OCTOSPIM_P1_NCS, OTG_HS_ULPI_D3, ETH_MII_RX_ER, LCD_G4, EVENTOUT	-
K7	47	70	M10	M9	P10	79	PB11	I/O	FT_f	-	TIM2_CH4, LPTIM2_ETR, I2C2_SDA, DFSDM1_CKIN7, USART3_RX(boot), OTG_HS_ULPI_D4, ETH_MII_TX_EN/ETH_RMII_TX_EN, LCD_G5, EVENTOUT	-
F8	48	71	H7	N10	R13	80	VCAP	S	-	-	-	-
-	49	-	-	-	-	81	VSS	S	-	-	-	-
-	-	-	-	M10	R14	82	VDDLDO	S	-	-	-	-
-	50	72	-	-	-	-	VDD	S	-	-	-	-
-	-	-	-	-	P15	-	PH6	I/O	FT_h	-	TIM12_CH1, I2C2_SMBA, SPI5_SCK, ETH_MII_RXD2, FMC_SDNE1, DCMI_D8/PSSI_D8, EVENTOUT	-
-	-	-	-	-	M11	-	PH7	I/O	FT_fh	-	I2C3_SCL, SPI5_MISO, ETH_MII_RXD3, FMC_SDCKE1, DCMI_D9/PSSI_D9, EVENTOUT	-
-	-	-	-	-	N13	-	PH8	I/O	FT_fh	-	TIM5_ETR, I2C3_SDA, FMC_D16, DCMI_HSYNC/PSSI_DE, LCD_R2, EVENTOUT	-
-	-	-	-	-	M14	-	PH9	I/O	FT_h	-	TIM12_CH2, I2C3_SMBA, FMC_D17, DCMI_D0/PSSI_D0, LCD_R3, EVENTOUT	-

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
-	-	-	-	K9	N14	-	PH10	I/O	FT_h	-	TIM5_CH1, I2C4_SMBA, FMC_D18, DCMI_D1/PSSI_D1, LCD_R4, EVENTOUT	-
-	-	-	-	L10	M13	-	PH11	I/O	FT_fh	-	TIM5_CH2, I2C4_SCL, FMC_D19, DCMI_D2/PSSI_D2, LCD_R5, EVENTOUT	-
-	-	-	-	-	-	83	VSS	S	-	-	-	-
-	-	-	-	-	-	84	VDD	S	-	-	-	-
-	-	-	-	K10	N15	-	PH12	I/O	FT_fh	-	TIM5_CH3, I2C4_SDA, FMC_D20, DCMI_D3/PSSI_D3, LCD_R6, EVENTOUT	-
K8	51	73	M11	N12	M15	85	PB12	I/O	FT_h	-	TIM1_BKIN, OCTOSPIM_P1_NCLK, I2C2_SMBA, SPI2_NSS/I2S2_WS, DFSDM1_DATIN1, USART3_CK, FDCAN2_RX, OTG_HS_ULPI_D5, ETH_MII_TXD0/ETH_RMII_TX D0, OCTOSPIM_P1_IO0, TIM1_BKIN_COMP12, UART5_RX, EVENTOUT	-
J8	52	74	M12	L11	L15	86	PB13	I/O	FT_h	-	TIM1_CH1N, LPTIM2_OUT, OCTOSPIM_P1_IO2, SPI2_SCK/I2S2_CK, DFSDM1_CKIN1, USART3_CTS/USART3_NSS, FDCAN2_TX, OTG_HS_ULPI_D6, ETH_MII_TXD1/ETH_RMII_TX D1, SDMMC1_D0, DCMI_D2/PSSI_D2, UART5_TX, EVENTOUT	-

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
H10	53	75	L11	N13	K15	87	PB14	I/O	FT_h	-	TIM1_CH2N, TIM12_CH1, TIM8_CH2N, USART1_TX, SPI2_MISO/I2S2_SDI, DFSDM1_DATIN2, USART3_RTS/USART3_DE, UART4_RTS/UART4_DE, SDMMC2_D0, FMC_D10/FMC_AD10, LCD_CLK, EVENTOUT	-
G10	54	76	L12	M13	K14	88	PB15	I/O	FT_h	-	RTC_REFIN, TIM1_CH3N, TIM12_CH2, TIM8_CH3N, USART1_RX, SPI2_MOSI/I2S2_SDO, DFSDM1_CKIN2, UART4_CTS, SDMMC2_D1, FMC_D11/FMC_AD11, LCD_G7, EVENTOUT	-
K9	55	77	L9	M12	L14	89	PD8	I/O	FT_h	-	DFSDM1_CKIN3, USART3_TX(boot), SPDIFRX1_IN2, FMC_D13/FMC_AD13, EVENTOUT	-
J9	56	78	K9	K11	K13	90	PD9	I/O	FT_h	-	DFSDM1_DATIN3, USART3_RX(boot), FMC_D14/FMC_AD14, EVENTOUT	-
H9	57	79	J9	K12	L13	91	PD10	I/O	FT_h	-	DFSDM1_CKOUT, USART3_CK, FMC_D15/FMC_AD15, LCD_B3, EVENTOUT	-
-	-	-	-	-	-	92	VDD	S	-	-	-	-
-	-	-	-	-	-	93	VSS	S	-	-	-	-
G9	58	80	H9	J10	J13	94	PD11	I/O	FT_h	-	LPTIM2_IN2, I2C4_SMBA, USART3_CTS/USART3_NSS, OCTOSPIM_P1_IO0, SAI4_SD_A, FMC_A16/FMC_CLE, EVENTOUT	-

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
K10	59	81	L10	K13	J15	95	PD12	I/O	FT _fn	-	LPTIM1_IN1, TIM4_CH1, LPTIM2_IN1, I2C4_SCL, FDCAN3_RX, USART3_RTS/USART3_DE, OCTOSPIM_P1_IO1, SAI4_FS_A, FMC_A17/FMC_ALE, DCMI_D12/PSSI_D12, EVENTOUT	-
J10	60	82	K10	J11	H15	96	PD13	I/O	FT _fn	-	LPTIM1_OUT, TIM4_CH2, I2C4_SDA, FDCAN3_TX, OCTOSPIM_P1_IO3, SAI4_SCK_A, UART9_RTS/UART9_DE, FMC_A18, DCMI_D13/PSSI_D13, EVENTOUT	-
-	-	83	-	-	-	-	VSS	S	-	-	-	-
-	-	84	-	-	-	-	VDD	S	-	-	-	-
H8	61	85	K11	J13	H14	97	PD14	I/O	FT _h	-	TIM4_CH3, UART8_CTS, UART9_RX, FMC_D0/FMC_AD0, EVENTOUT	-
G8	62	86	K12	J12	J12	98	PD15	I/O	FT _h	-	TIM4_CH4, UART8_RTS/UART8_DE, UART9_TX, FMC_D1/FMC_AD1, EVENTOUT	-
-	-	-	-	-	-	99	VDD	S	-	-	-	-
-	-	-	-	-	-	100	VSS	S	-	-	-	-
-	-	-	-	-	-	101	PJ8	I/O	FT	-	TIM1_CH3N, TIM8_CH1, UART8_TX, LCD_G1, EVENTOUT	-
-	-	-	-	-	-	102	PJ9	I/O	FT	-	TIM1_CH3, TIM8_CH1N, UART8_RX, LCD_G2, EVENTOUT	-
-	-	-	-	-	-	103	PJ10	I/O	FT	-	TIM1_CH2N, TIM8_CH2, SPI5_MOSI, LCD_G3, EVENTOUT	-

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
-	-	-	-	-	-	104	PJ11	I/O	FT	-	TIM1_CH2, TIM8_CH2N, SPI5_MISO, LCD_G4, EVENTOUT	-
-	-	-	-	-	-	105	VDD	S	-	-	-	-
-	-	-	-	-	-	106	VSS	S	-	-	-	-
-	-	-	-	-	-	107	PK0	I/O	FT	-	TIM1_CH1N, TIM8_CH3, SPI5_SCK, LCD_G5, EVENTOUT	-
-	-	-	-	-	-	108	PK1	I/O	FT	-	TIM1_CH1, TIM8_CH3N, SPI5_NSS, LCD_G6, EVENTOUT	-
-	-	-	-	-	-	109	PK2	I/O	FT	-	TIM1_BKIN, TIM8_BKIN, TIM8_BKIN_COMP12, TIM1_BKIN_COMP12, LCD_G7, EVENTOUT	-
-	-	87	J12	H9	G15	110	PG2	I/O	FT_h	-	TIM8_BKIN, TIM8_BKIN_COMP12, FMC_A12, TIM24_ETR, EVENTOUT	-
-	-	88	J11	H10	H13	111	PG3	I/O	FT_h	-	TIM8_BKIN2, TIM8_BKIN2_COMP12, FMC_A13, TIM23_ETR, EVENTOUT	-
-	-	-	-	-	-	112	VSS	S	-	-	-	-
-	-	-	-	-	-	113	VDD	S	-	-	-	-
-	-	89	J10	F8	G14	114	PG4	I/O	FT_h	-	TIM1_BKIN2, TIM1_BKIN2_COMP12, FMC_A14/FMC_BA0, EVENTOUT	-
-	-	90	H12	H11	F15	115	PG5	I/O	FT_h	-	TIM1_ETR, FMC_A15/FMC_BA1, EVENTOUT	-
-	-	91	H11	G9	F14	116	PG6	I/O	FT_h	-	TIM17_BKIN, OCTOSPIM_P1_NCS, FMC_NE3, DCMI_D12/PSSI_D12, LCD_R7, EVENTOUT	-

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
-	-	92	H10	G10	G13	117	PG7	I/O	FT_h	-	SAI1_MCLK_A, USART6_CK, OCTOSPIM_P2_DQS, FMC_INT, DCMI_D13/PSSI_D13, LCD_CLK, EVENTOUT	-
-	-	93	G11	G11	G12	118	PG8	I/O	FT_h	-	TIM8_ETR, SPI6_NSS/I2S6_WS, USART6_RTS/USART6_DE, SPDIFRX1_IN3, ETH_PPS_OUT, FMC_SDCLK, LCD_G7, EVENTOUT	-
-	-	94	-	-	-	119	VSS	S	-	-	-	-
-	-	-	-	G12	E15	120	VDD50USB	S	-	-	-	-
F6	-	95	C11	G13	F13	121	VDD33USB	S	-	-	-	-
F10	63	96	G12	F9	E14	122	PC6	I/O	FT_h	-	TIM3_CH1, TIM8_CH1, DFSDM1_CKIN3, I2S2_MCK, USART6_TX, SDMMC1_D0DIR, FMC_NWAIT, SDMMC2_D6, SDMMC1_D6, DCMI_D0/PSSI_D0, LCD_HSYNC, EVENTOUT	SWPMI_IO
E10	64	97	F12	F10	D15	123	PC7	I/O	FT_h	-	DBTRGIO, TIM3_CH2, TIM8_CH2, DFSDM1_DATIN3, I2S3_MCK, USART6_RX, SDMMC1_D123DIR, FMC_NE1, SDMMC2_D7, SWPMI_TX, SDMMC1_D7, DCMI_D1/PSSI_D1, LCD_G6, EVENTOUT	-
F9	65	98	F11	F12	D14	124	PC8	I/O	FT_h	-	TRACED1, TIM3_CH3, TIM8_CH3, USART6_CK, UART5_RTS/UART5_DE, FMC_NE2/FMC_NCE, FMC_INT, SWPMI_RX, SDMMC1_D0, DCMI_D2/PSSI_D2, EVENTOUT	-

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
E9	66	99	E11	F11	E13	125	PC9	I/O	FT _fh	-	MCO2, TIM3_CH4, TIM8_CH4, I2C3_SDA(boot), I2S_CKIN, I2C5_SDA, UART5_CTS, OCTOSPIM_P1_IO0, LCD_G3, SWPMI_SUSPEND, SDMMC1_D1, DCMI_D3/PSSI_D3, LCD_B2, EVENTOUT	-
-	-	-	-	-	-	126	VDD	S	-	-	-	-
D9	67	100	E12	E12	B14	127	PA8	I/O	FT _fh	-	MCO1, TIM1_CH1, TIM8_BKIN2, I2C3_SCL(boot), I2C5_SCL, USART1_CK, OTG_HS_SOF, UART7_RX, TIM8_BKIN2_COMP12, LCD_B3, LCD_R6, EVENTOUT	-
C9	68	101	D12	E11	D13	128	PA9	I/O	FT _u	-	TIM1_CH2, LPUART1_TX, I2C3_SMBA, SPI2_SCK/I2S2_CK, I2C5_SMBA, USART1_TX(boot), ETH_TX_ER, DCMI_D0/PSSI_D0, LCD_R5, EVENTOUT	OTG_HS_VBUS
D10	69	102	D11	E10	C14	129	PA10	I/O	FT _u	-	TIM1_CH3, LPUART1_RX, USART1_RX(boot), OTG_HS_ID, MDIOS_MDIO, LCD_B4, DCMI_D1/PSSI_D1, LCD_B1, EVENTOUT	-
C10	70	103	C12	F13	C15	130	PA11	I/O	FT _u	-	TIM1_CH4, LPUART1_CTS, SPI2_NSS/I2S2_WS, UART4_RX, USART1_CTS/USART1_NSS, FDCAN1_RX, LCD_R4, EVENTOUT	OTG_HS_DM (boot)

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
B10	71	104	B12	E13	B15	131	PA12	I/O	FT_u	-	TIM1_ETR, LPUART1_RTS/LPUART1_DE, SPI2_SCK/I2S2_CK, UART4_TX, USART1_RTS/USART1_DE, SAI4_FS_B, FDCAN1_TX, TIM1_BKIN2, LCD_R5, EVENTOUT	OTG_HS_DP (boot)
A10	72	105	A12	D11	B13	132	PA13(JTMS/ SWDIO)	I/O	FT	-	JTMS/SWDIO, EVENTOUT	-
E7	73	106	G9	D13	A14	133	VCAP	S	-	-	-	-
-	74	107	-	-	-	134	VSS	S	-	-	-	-
-	-	-	-	D12	A13	135	VDDLDO	S	-	-	-	-
-	75	108	-	-	-	136	VDD	S	-	-	-	-
-	-	-	-	B13	C13	-	PH13	I/O	FT_h	-	TIM8_CH1N, UART4_TX, FDCAN1_TX(boot), FMC_D21, LCD_G2, EVENTOUT	-
-	-	-	-	A13	B12	-	PH14	I/O	FT_h	-	TIM8_CH2N, UART4_RX, FDCAN1_RX(boot), FMC_D22, DCMI_D4/PSSI_D4, LCD_G3, EVENTOUT	-
-	-	-	-	-	D12	-	PH15	I/O	FT_h	-	TIM8_CH3N, FMC_D23, DCMI_D11/PSSI_D11, LCD_G4, EVENTOUT	-
-	-	-	-	-	-	137	VSS	S	-	-	-	-
A9	76	109	A11	B12	A12	138	PA14(JTCK/ SWCLK)	I/O	FT	-	JTCK/SWCLK, EVENTOUT	-
A8	77	110	A10	C11	A11	139	PA15(JTDI)	I/O	FT	-	JTDI, TIM2_CH1/TIM2_ETR, CEC, SPI1_NSS/I2S1_WS, SPI3_NSS/I2S3_WS, SPI6_NSS/I2S6_WS, UART4_RTS/UART4_DE, LCD_R3, UART7_TX, LCD_B6, EVENTOUT	-



Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
B9	78	111	B11	A12	C12	140	PC10	I/O	FT _fh	-	DFSDM1_CKIN5, I2C5_SDA, SPI3_SCK(boot)/I2S3_CK, USART3_TX, UART4_TX, OCTOSPIM_P1_IO1, LCD_B1, SWPMI_RX, SDMMC1_D2, DCMI_D8/PSSI_D8, LCD_R2, EVENTOUT	-
B8	79	112	B10	B11	C11	141	PC11	I/O	FT _fh	-	DFSDM1_DATIN5, I2C5_SCL, SPI3_MISO(boot)/I2S3_SDI, USART3_RX, UART4_RX, OCTOSPIM_P1_NCS, SDMMC1_D3, DCMI_D4/PSSI_D4, LCD_B4, EVENTOUT	-
C8	80	113	C10	A11	B11	142	PC12	I/O	FT _h	-	TRACED3, FMC_D6/FMC_AD6, TIM15_CH1, I2C5_SMBA, SPI6_SCK/I2S6_CK, SPI3_MOSI(boot)/I2S3_SDO, USART3_CK, UART5_TX, SDMMC1_CK, DCMI_D9/PSSI_D9, LCD_R6, EVENTOUT	-
D8	81	114	E10	D10	C10	143	PD0	I/O	FT _h	-	DFSDM1_CKIN6, UART4_RX, FDCAN1_RX(boot), UART9_CTS, FMC_D2/FMC_AD2, LCD_B1, EVENTOUT	-
E8	82	115	D10	C10	A10	144	PD1	I/O	FT _h	-	DFSDM1_DATIN6, UART4_TX, FDCAN1_TX(boot), FMC_D3/FMC_AD3, EVENTOUT	-
B7	83	116	E9	E9	B10	145	PD2	I/O	FT _h	-	TRACED2, FMC_D7/FMC_AD7, TIM3_ETR, TIM15_BKIN, UART5_RX, LCD_B7, SDMMC1_CMD, DCMI_D11/PSSI_D11, LCD_B2, EVENTOUT	-

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
C7	84	117	D9	D9	A9	146	PD3	I/O	FT_h	-	DFSDM1_CKOUT, SPI2_SCK/I2S2_CK, USART2_CTS/USART2_NSS, FMC_CLK, DCMI_D5/PSSI_D5, LCD_G7, EVENTOUT	-
D7	85	118	C9	C9	C9	147	PD4	I/O	FT_h	-	USART2_RTS/USART2_DE, OCTOSPIM_P1_IO4, FMC_NOE, EVENTOUT	-
B6	86	119	B9	A9	B9	148	PD5	I/O	FT_h	-	USART2_TX, OCTOSPIM_P1_IO5, FMC_NWE, EVENTOUT	-
-	-	120	-	-	-	-	VSS	S	-	-	-	-
-	-	121	-	-	-	-	VDD	S	-	-	-	-
C6	87	122	A8	B9	D9	149	PD6	I/O	FT_h	-	SAI4_D1, SAI1_D1, DFSDM1_CKIN4, DFSDM1_DATIN1, SPI3_MOSI/I2S3_SDO, SAI1_SD_A, USART2_RX, SAI4_SD_A, OCTOSPIM_P1_IO6, SDMMC2_CK, FMC_NWAIT, DCMI_D10/PSSI_D10, LCD_B2, EVENTOUT	-
D6	88	123	A9	D8	B8	150	PD7	I/O	FT_h	-	DFSDM1_DATIN4, SPI1_MOSI/I2S1_SDO, DFSDM1_CKIN1, USART2_CK, SPDIFRX1_IN1, OCTOSPIM_P1_IO7, SDMMC2_CMD, FMC_NE1, EVENTOUT	-
-	-	-	-	-	-	151	VSS	S	-	-	-	-
-	-	-	-	-	-	152	VDD	S	-	-	-	-
-	-	124	E8	C8	A8	153	PG9	I/O	FT_h	-	FDCAN3_TX, SPI1_MISO/I2S1_SDI, USART6_RX, SPDIFRX1_IN4, OCTOSPIM_P1_IO6, SAI4_FS_B, SDMMC2_D0, FMC_NE2/FMC_NCE, DCMI_VSYNC/PSSI_RDY, EVENTOUT	-

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
-	-	125	D8	A8	C8	154	PG10	I/O	FT_h	-	FDCAN3_RX, OCTOSPIM_P2_IO6, SPI1_NSS/I2S1_WS, LCD_G3, SAI4_SD_B, SDMMC2_D1, FMC_NE3, DCMI_D2/PSSI_D2, LCD_B2, EVENTOUT	-
-	-	126	C8	B8	A7	155	PG11	I/O	FT_h	-	LPTIM1_IN2, USART10_RX, SPI1_SCK/I2S1_CK, SPDIFRX1_IN1, OCTOSPIM_P2_IO7, SDMMC2_D2, ETH_MII_TX_EN/ETH_RMII_T X_EN, DCMI_D3/PSSI_D3, LCD_B3, EVENTOUT	-
-	-	127	B8	E8	D8	156	PG12	I/O	FT_h	-	LPTIM1_IN1, OCTOSPIM_P2_NCS, USART10_TX, SPI6_MISO/I2S6_SDI, USART6_RTS/USART6_DE, SPDIFRX1_IN2, LCD_B4, SDMMC2_D3, ETH_MII_TXD1/ETH_RMII_TX D1, FMC_NE4, TIM23_CH1, LCD_B1, EVENTOUT	-
-	-	128	D7	D7	B7	157	PG13	I/O	FT_h	-	TRACED0, LPTIM1_OUT, USART10_CTS/USART10_NS S, SPI6_SCK/I2S6_CK, USART6_CTS/USART6_NSS, SDMMC2_D6, ETH_MII_TXD0/ETH_RMII_TX D0, FMC_A24, TIM23_CH2, LCD_R0, EVENTOUT	-
-	-	129	C7	C7	C7	158	PG14	I/O	FT_h	-	TRACED1, LPTIM1_ETR, USART10_RTS/USART10_DE , SPI6_MOSI/I2S6_SDO, USART6_TX, OCTOSPIM_P1_IO7, SDMMC2_D7, ETH_MII_TXD1/ETH_RMII_TX D1, FMC_A25, TIM23_CH3, LCD_B0, EVENTOUT	-
-	-	130	-	-	-	159	VSS	S	-	-	-	-

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
-	-	131	-	-	-	160	VDD	S	-	-	-	-
-	-	132	B7	E7	D7	161	PG15	I/O	FT_h	-	USART6_CTS/USART6_NSS, OCTOSPIM_P2_DQS, USART10_CK, FMC_NCAS, DCMI_D13/PSSI_D13, EVENTOUT	-
A7	89	133	A7	F7	A6	162	PB3(JTDO/TRACESWO)	I/O	FT_h	-	JTDO/TRACESWO, TIM2_CH2, SPI1_SCK/I2S1_CK, SPI3_SCK/I2S3_CK, SPI6_SCK/I2S6_CK, SDMMC2_D2, CRS_SYNC, UART7_RX, TIM24_ETR, EVENTOUT	-
A6	90	134	A6	B6	B6	163	PB4(NJTRST)	I/O	FT_h	-	NJTRST, TIM16_BKIN, TIM3_CH1, SPI1_MISO/I2S1_SDI, SPI3_MISO/I2S3_SDI, SPI2_NSS/I2S2_WS, SPI6_MISO/I2S6_SDI, SDMMC2_D3, UART7_TX, EVENTOUT	-
C5	91	135	B6	C6	C6	164	PB5	I/O	FT_h	-	TIM17_BKIN, TIM3_CH2, LCD_B5, I2C1_SMBA, SPI1_MOSI/I2S1_SDO, I2C4_SMBA, SPI3_MOSI/I2S3_SDO, SPI6_MOSI/I2S6_SDO, FDCAN2_RX, OTG_HS_ULPI_D7, ETH_PPS_OUT, FMC_SDCKE1, DCMI_D10/PSSI_D10, UART5_RX, EVENTOUT	-
B5	92	136	C6	A5	A5	165	PB6	I/O	FT_fh	-	TIM16_CH1N, TIM4_CH1, I2C1_SCL(boot), CEC, I2C4_SCL, USART1_TX, LPUART1_TX, FDCAN2_TX, OCTOSPIM_P1_NCS, DFSDM1_DATIN5, FMC_SDNE1, DCMI_D5/PSSI_D5, UART5_TX, EVENTOUT	-

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
A5	93	137	D6	D6	B5	166	PB7	I/O	FT_fa	-	TIM17_CH1N, TIM4_CH2, I2C1_SDA, I2C4_SDA, USART1_RX, LPUART1_RX, DFSDM1_CKIN5, FMC_NL, DCMI_VSYNC/PSSI_RDY, EVENTOUT	PVD_IN
D5	94	138	D5	E6	C5	167	BOOT0	I	B	-	-	VPP
B4	95	139	C5	B5	A2	168	PB8	I/O	FT_fh	-	TIM16_CH1, TIM4_CH3, DFSDM1_CKIN7, I2C1_SCL, I2C4_SCL, SDMMC1_CKIN, UART4_RX, FDCAN1_RX, SDMMC2_D4, ETH_MII_TXD3, SDMMC1_D4, DCMI_D6/PSSI_D6, LCD_B6, EVENTOUT	-
A4	96	140	B5	C5	B3	169	PB9	I/O	FT_fh	-	TIM17_CH1, TIM4_CH4, DFSDM1_DATIN7, I2C1_SDA(boot), SPI2_NSS/I2S2_WS, I2C4_SDA, SDMMC1_CDIR, UART4_TX, FDCAN1_TX, SDMMC2_D5, I2C4_SMBA, SDMMC1_D5, DCMI_D7/PSSI_D7, LCD_B7, EVENTOUT	-
D4	97	141	A5	D5	B4	170	PE0	I/O	FT_h	-	LPTIM1_ETR, TIM4_ETR, LPTIM2_ETR, UART8_RX, SAI4_MCLK_A, FMC_NBL0, DCMI_D2/PSSI_D2, LCD_R0, EVENTOUT	-
C4	98	142	A4	D4	C4	171	PE1	I/O	FT_h	-	LPTIM1_IN2, UART8_TX, FMC_NBL1, DCMI_D3/PSSI_D3, LCD_R6, EVENTOUT	-
-	-	-	-	A4	A4	172	VCAP	S	-	-	-	-
-	99	-	-	-	-	173	VSS	S	-	-	-	-
F7	-	143	E5	C4	D4	174	PDR_ON	S	-	-	-	-
-	-	-	-	B4	A3	175	VDDLDO	S	-	-	-	-
-	100	144	-	-	-	-	VDD	S	-	-	-	-

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
-	-	-	-	-	-	176	VDD	S	-	-	-	-
C2	-	-	D2	B3	A1	-	VSS	S	-	-	-	-
E6	-	-	E6	B7	A15	-	VSS	S	-	-	-	-
J1	-	-	E7	B10	C2	-	VSS	S	-	-	-	-
E4	-	-	G4	C12	D10	-	VSS	S	-	-	-	-
E5	-	-	G8	D2	D6	-	VSS	S	-	-	-	-
-	-	-	G10	G2	E1	-	VSS	S	-	-	-	-
-	-	-	H5	H12	F10	-	VSS	S	-	-	-	-
-	-	-	H6	L12	F12	-	VSS	S	-	-	-	-
-	-	-	-	M2	F6	-	VSS	S	-	-	-	-
-	-	-	-	M4	F7	-	VSS	S	-	-	-	-
-	-	-	-	M7	F8	-	VSS	S	-	-	-	-
-	-	-	-	M11	F9	-	VSS	S	-	-	-	-
-	-	-	-	-	G10	-	VSS	S	-	-	-	-
-	-	-	-	-	G6	-	VSS	S	-	-	-	-
-	-	-	-	-	G7	-	VSS	S	-	-	-	-
-	-	-	-	-	G8	-	VSS	S	-	-	-	-
-	-	-	-	-	G9	-	VSS	S	-	-	-	-
-	-	-	-	-	H10	-	VSS	S	-	-	-	-
-	-	-	-	-	H6	-	VSS	S	-	-	-	-
-	-	-	-	-	H7	-	VSS	S	-	-	-	-
-	-	-	-	-	H8	-	VSS	S	-	-	-	-
-	-	-	-	-	H9	-	VSS	S	-	-	-	-
-	-	-	-	-	J10	-	VSS	S	-	-	-	-
-	-	-	-	-	J14	-	VSS	S	-	-	-	-
-	-	-	-	-	J6	-	VSS	S	-	-	-	-
-	-	-	-	-	J7	-	VSS	S	-	-	-	-
-	-	-	-	-	J8	-	VSS	S	-	-	-	-
-	-	-	-	-	J9	-	VSS	S	-	-	-	-
-	-	-	-	-	K10	-	VSS	S	-	-	-	-

Table 7. STM32H730xB pin and ball descriptions (continued)

Pin Number							Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
TFBGA100	LQFP100	LQFP144	UFBGA144	UFBGA169	UFBGA176+25	LQFP176						
-	-	-	-	-	K12	-	VSS	S	-	-	-	-
-	-	-	-	-	K2	-	VSS	S	-	-	-	-
-	-	-	-	-	K6	-	VSS	S	-	-	-	-
-	-	-	-	-	K7	-	VSS	S	-	-	-	-
-	-	-	-	-	K8	-	VSS	S	-	-	-	-
-	-	-	-	-	K9	-	VSS	S	-	-	-	-
-	-	-	-	-	M10	-	VSS	S	-	-	-	-
-	-	-	-	-	M6	-	VSS	S	-	-	-	-
-	-	-	-	-	R1	-	VSS	S	-	-	-	-
-	-	-	-	-	R15	-	VSS	S	-	-	-	-
D2	-	-	D3	A3	D5	-	VDD	S	-	-	-	-
F5	-	-	F4	A6	D11	-	VDD	S	-	-	-	-
K1	-	-	F5	A7	E4	-	VDD	S	-	-	-	-
F4	-	-	F6	A10	E12	-	VDD	S	-	-	-	-
-	-	-	F7	C13	G4	-	VDD	S	-	-	-	-
-	-	-	F8	D1	H12	-	VDD	S	-	-	-	-
-	-	-	F9	G1	K4	-	VDD	S	-	-	-	-
-	-	-	F10	H13	L12	-	VDD	S	-	-	-	-
-	-	-	G5	L13	M5	-	VDD	S	-	-	-	-
-	-	-	G6	M1	M9	-	VDD	S	-	-	-	-
-	-	-	G7	N4	-	-	VDD	S	-	-	-	-
-	-	-	-	N7	-	-	VDD	S	-	-	-	-
-	-	-	-	N11	-	-	VDD	S	-	-	-	-



Table 8. STM32H730xB pin alternate functions

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15	
	SYS	FMC/ LPTIM1/ SAI4/ TIM16/17 /TIM1x/ TIM2x	FDCAN3 /PDM_ SAI1/ TIM3/4/5 /12/15	DFSDM1/ LCD/ LPTIM2/3/ 4/5/ LPUART1 /OCTO SPI_M_P1/ 2/TIM8	CEC/DCMI/ PSSI/ DFSDM1/ I2C1/2/3/4/5 /LPTIM2/ OCTOSPIM _P1/TIM15/ USART1/10	CEC/ FDCAN3/ SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/5/6	DFSDM1/ I2C4/5/ OCTO SPI_M_P1/ SAI1/SPI3/ I2S3/ UART4	SDMMC1/ SPI2/I2S2 /SPI3/I2S 3/SPI6/ UART7 /USART1/ 2/3/6	LPUART1 /SAI4/ SDMMC1/ SPDIFRX 1/SPI6/ UART4/5/ 8	FDCAN1/2/ FMC/LCD/ OCTOSPIM _P1/2/SAI4 /SDMMC2/ SPDIFRX1/ TIM13/14	CRS/FMC/ LCD/OCT OSPIM_P1 /OTG1_FS/ OTG1_HS/ SAI4/ SDMMC2/ TIM8	DFSDM1/ ETH/I2C4/ LCD/MDIOS /OCTOSPIM _P1/SDMMC 2/SWPM11/ TIM1x/TIM8/ UART7/9/ USART10	FMC/LCD /MDIOS/ OCTOSPI M_P1/ SDMMC1 /TIM1x/ TIM8	COMP/ DCMI/ PSSI/ LCD/ TIM1x/ TIM23	LCD/ TIM24/ UART5	SYS	
Port A	PA0	-	TIM2_ CH1/TIM 2_ETR	TIM5_ CH1	TIM8_ ETR	TIM15_ BKIN	SPI6_NSS /I2S6_WS	-	USART2_ CTS/ USART2_ NSS	UART4_ TX	SDMMC2_ CMD	SAI4_SD_ B	ETH_MII_ CRS	FMC_A19	-	-	EVENT OUT
	PA1	-	TIM2_CH 2	TIM5_ CH2	LPTIM3_ OUT	TIM15_CH1 N	-	-	USART2_ RTS/ USART2_ DE	UART4_ RX	OCTOSPIM _P1_IO3	SAI4_ MCLK_B	ETH_MII_ RX_CLK/ ETH_RMII_ REF_CLK	OCTOSPI M_P1_ DQS	-	LCD_R 2	EVENT OUT
	PA2	-	TIM2_CH 3	TIM5_ CH3	LPTIM4_ OUT	TIM15_CH1	-	OCTOSPI M_P1_IO0	USART2_ TX	SAI4_ SCK_B	-	-	ETH_MDIO	MDIOS_ MDIO	-	LCD_R 1	EVENT OUT
	PA3	-	TIM2_CH 4	TIM5_ CH4	LPTIM5_ OUT	TIM15_CH2	I2S6_MCK	OCTOSPI M_P1_IO2	USART2_ RX	-	LCD_B2	OTG_HS_ ULPI_D0	ETH_MII_ COL	OCTOSPI M_P1_ CLK	-	LCD_B 5	EVENT OUT
	PA4	D1PW REN	-	TIM5_ ETR	-	-	SPI1_NSS /I2S1_WS	SPI3_NSS/ I2S3_WS	USART2_ CK	SPI6_NS S/I2S6_ WS	-	-	-	FMC_D8/ FMC_AD 8	DCMI_ HSYNC /PSSI_ DE	LCD_V SYNC	EVENT OUT
	PA5	D2PW REN	TIM2_CH 1/TIM2_ ETR	-	TIM8_ CH1N	-	SPI1_SCK /I2S1_CK	-	-	SPI6_SC K/I2S6_ CK	-	OTG_HS_ ULPI_CK	-	FMC_D9/ FMC_AD 9	PSSI_ D14	LCD_R 4	EVENT OUT
	PA6	-	TIM1_ BKIN	TIM3_C H1	TIM8_ BKIN	-	SPI1_ MISO/I2S 1_SDI	OCTOSPI M_P1_IO3	-	SPI6_MIS O/I2S6_ S DI	TIM13_CH 1	TIM8_BKIN _COMP12	MDIOS_ MDC	TIM1_ BKIN_ COMP12	DCMI_ PIXCL K/PSSI_ _PDCK	LCD_G 2	EVENT OUT
	PA7	-	TIM1_CH 1N	TIM3_ CH2	TIM8_CH 1N	-	SPI1_ MOSI/I2S 1_SDO	-	-	SPI6_ MOSI/I2S 6_SDO	TIM14_CH 1	OCTOSPI M_P1_IO2	ETH_MII_ RX_DV/ETH _RMII_CRS _DV	FMC_SD NWE	-	LCD_V SYNC	EVENT OUT
	PA8	MCO1	TIM1_CH 1	-	TIM8_ BKIN2	I2C3_SCL	-	I2C5_SCL	USART1_ CK	-	-	OTG_HS_ SOF	UART7_RX	TIM8_ BKIN2_ COMP12	LCD_B 3	LCD_R 6	EVENT OUT





Table 8. STM32H730xB pin alternate functions (continued)

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
	SYS	FMC/ LPTIM1/ SAI4/ TIM16/17 /TIM1x/ TIM2x	FDCAN3 /PDM_ SAI1/ TIM3/4/5 /12/15	DFSDM1/ LCD/ LPTIM2/3/ 4/5/ LPUART1 /OCTO SPIM_P1/ 2/TIM8	CEC/DCMI/ PSSI/ DFSDM1/ I2C1/2/3/4/5 /LPTIM2/ OCTOSPIM _P1/TIM15/ USART1/10	CEC/ FDCAN3/ SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/5/6	DFSDM1/ I2C4/5/ OCTO SPIM_P1/ SAI1/SPI3/ I2S3/ UART4	SDMMC1/ SPI2/I2S2 /SPI3/I2S 3/SPI6/ UART7 /USART1/ 2/3/6	LPUART1 /SAI4/ SDMMC1/ SPDIFRX 1/SPI6/ UART4/5/ 8	FDCAN1/2/ FMC/LCD/ OCTOSPIM _P1/2/SAI4 /SDMMC2/ SPDIFRX1/ TIM13/14	CRS/FMC/ LCD/OCT OSPIM_P1 /OTG1_FS/ OTG1_HS/ SAI4/ SDMMC2/ TIM8	DFSDM1/ ETH/I2C4/ LCD/MDIOS /OCTOSPIM _P1/SDMMC 2/SWPMI1/ TIM1x/TIM8/ UART7/9/ USART10	FMC/LCD /MDIOS/ OCTOSPI M_P1/ SDMMC1 /TIM1x/ TIM8	COMP/ DCMI/ PSSI/ LCD/ TIM1x/ TIM23	LCD/ TIM24/ UART5	SYS
PA9	-	TIM1_CH 2	-	LPUART1 _TX	I2C3_ SMBA	SPI2_SCK /I2S2_CK	I2C5_ SMBA	USART1_ TX	-	-	-	ETH_TX_ER	-	DCMI_ D0/ PSSI_ D0	LCD_R 5	EVENT OUT
PA10	-	TIM1_CH 3	-	LPUART1 _RX	-	-	-	USART1_ RX	-	-	OTG_HS_ ID	MDIOS_ MDIO	LCD_B4	DCMI_ D1/ PSSI_ D1	LCD_B 1	EVENT OUT
PA11	-	TIM1_CH 4	-	LPUART1 _CTS	-	SPI2_NSS /I2S2_WS	UART4_RX	USART1_ CTS/ USART1_ NSS	-	FDCAN1_ RX	-	-	-	-	LCD_R 4	EVENT OUT
PA12	-	TIM1_ ETR	-	LPUART1 _RTS/ LPUART1 _DE	-	SPI2_SCK /I2S2_CK	UART4_TX	USART1_ RTS/ USART1_ DE	SAI4_FS_ B	FDCAN1_ TX	-	-	TIM1_ BKin2	-	LCD_R 5	EVENT OUT
PA13	JTMS/ SWDI O	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
PA14	JTCK/ SWCLK	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
PA15	JTDI	TIM2_CH 1/TIM2_ ETR	-	-	CEC	SPI1_NSS /I2S1_WS	SPI3_NSS/ I2S3_WS	SPI6_NS S/I2S6_W S	UART4_R TS/UART 4_DE	LCD_R3	-	UART7_TX	-	-	LCD_B 6	EVENT OUT

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Table 8. STM32H730xB pin alternate functions (continued)

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
	SYS	FMC/ LPTIM1/ SAI4/ TIM16/17 /TIM1x/ TIM2x	FDCAN3 /PDM_ SAI1/ TIM3/4/5 /12/15	DFSDM1/ LCD/ LPTIM2/3/ 4/5/ LPUART1 /OCTO SPIM_P1/ 2/TIM8	CEC/DCMI/ PSSI/ DFSDM1/ I2C1/2/3/4/5 /LPTIM2/ OCTOSPIM _P1/TIM15/ USART1/10	CEC/ FDCAN3/ SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/5/6	DFSDM1/ I2C4/5/ OCTO SPIM_P1/ SAI1/SPI3/ I2S3/ UART4	SDMMC1/ SPI2/I2S2 /SPI3/I2S 3/SPI6/ UART7 /USART1/ 2/3/6	LPUART1 /SAI4/ SDMMC1/ SPDIFRX 1/SPI6/ UART4/5/ 8	FDCAN1/2/ FMC/LCD/ OCTOSPIM _P1/2/SAI4 /SDMMC2/ SPDIFRX1/ TIM13/14	CRS/FMC/ LCD/OCT OSPIM_P1 /OTG1_FS/ OTG1_HS/ SAI4/ SDMMC2/ TIM8	DFSDM1/ ETH/I2C4/ LCD/MDIOS /OCTOSPIM _P1/SDMMC 2/SWP11/ TIM1x/TIM8/ UART7/9/ USART10	FMC/LCD /MDIOS/ OCTOSPI M_P1/ SDMMC1 /TIM1x/ TIM8	COMP/ DCMI/ PSSI/ LCD/ TIM1x/ TIM23	LCD/ TIM24/ UART5	SYS
PB0	-	TIM1_ CH2N	TIM3_ CH3	TIM8_ CH2N	OCTOSPIM _P1_IO1	-	DFSDM1_ CKOUT	-	UART4_ CTS	LCD_R3	OTG_HS_ ULPI_D1	ETH_MII_ RXD2	-	-	LCD_G 1	EVENT OUT
PB1	-	TIM1_ CH3N	TIM3_ CH4	TIM8_CH 3N	OCTOSPIM _P1_IO0	-	DFSDM1_ DATIN1	-	-	LCD_R6	OTG_HS_ ULPI_D2	ETH_MII_ RXD3	-	-	LCD_G 0	EVENT OUT
PB2	RTC_ OUT	SAI4_D1	SAI1_D1	-	DFSDM1_ CKIN1	-	SAI1_SD_ A	SPI3_ MOSI/I2S 3_SDO	SAI4_SD_ A	OCTOSPIM _P1_CLK	OCTOSPI M_P1_ DQS	ETH_TX_ER	-	TIM23_ ETR	-	EVENT OUT
PB3	JTDO/ TRAC ESWO	TIM2_CH 2	-	-	-	SPI1_SCK /I2S1_CK	SPI3_SCK/ I2S3_CK	-	SPI6_ SCK/I2S6 _CK	SDMMC2_ D2	CRS_ SYNC	UART7_RX	-	-	TIM24_ ETR	EVENT OUT
PB4	NJT RST	TIM16_ BKIN	TIM3_ CH1	-	-	SPI1_ MISO/I2S 1_SDI	SPI3_ MISO/I2S3 _SDI	SPI2_ NSS/I2S2 _WS	SPI6_ MISO/I2S 6_SDI	SDMMC2_ D3	-	UART7_TX	-	-	-	EVENT OUT
PB5	-	TIM17_ BKIN	TIM3_ CH2	LCD_B5	I2C1_ SMBA	SPI1_ MOSI/I2S 1_SDO	I2C4_SMB A	SPI3_ MOSI/I2S 3_SDO	SPI6_ MOSI/I2S 6_SDO	FDCAN2_ RX	OTG_HS_ ULPI_D7	ETH_PPS_ OUT	FMC_SD CKE1	DCMI_ D10/ PSSI_ D10	UART5_ RX	EVENT OUT
PB6	-	TIM16_ CH1N	TIM4_ CH1	-	I2C1_SCL	CEC	I2C4_SCL	USART1_ TX	LPUART1 _TX	FDCAN2_ TX	OCTOSPI M_P1_ NCS	DFSDM1_ DATIN5	FMC_SD NE1	DCMI_ D5/ PSSI_ D5	UART5_ TX	EVENT OUT
PB7	-	TIM17_ CH1N	TIM4_ CH2	-	I2C1_SDA	-	I2C4_SDA	USART1_ RX	LPUART1 _RX	-	-	DFSDM1_ CKIN5	FMC_NL	DCMI_ VSYNC /PSSI_ RDY	-	EVENT OUT
PB8	-	TIM16_ CH1	TIM4_ CH3	DFSDM1_ CKIN7	I2C1_SCL	-	I2C4_SCL	SDMMC1 _CKIN	UART4_ RX	FDCAN1_ RX	SDMMC2_ D4	ETH_MII_ TXD3	SDMMC1 _D4	DCMI_ D6/ PSSI_ D6	LCD_B 6	EVENT OUT
PB9	-	TIM17_ CH1	TIM4_ CH4	DFSDM1_ DATIN7	I2C1_SDA	SPI2_NSS /I2S2_WS	I2C4_SDA	SDMMC1 _CDIR	UART4_ TX	FDCAN1_ TX	SDMMC2_ D5	I2C4_SMB A	SDMMC1 _D5	DCMI_ D7/ PSSI_ D7	LCD_B 7	EVENT OUT

Port B



**Table 8. STM32H730xB pin alternate functions (continued)**

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15	
	SYS	FMC/ LPTIM1/ SAI4/ TIM16/17 /TIM1x/ TIM2x	FDCAN3 /PDM_ SAI1/ TIM3/4/5 /12/15	DFSDM1/ LCD/ LPTIM2/3/ 4/5/ LPUART1 /OCTO SPI_M_P1/ 2/TIM8	CEC/DCMI/ PSSI/ DFSDM1/ I2C1/2/3/4/5 /LPTIM2/ OCTOSPIM _P1/TIM15/ USART1/10	CEC/ FDCAN3/ SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/5/6	DFSDM1/ I2C4/5/ OCTO SPI_M_P1/ SAI1/SPI3/ I2S3/ UART4	SDMMC1/ SPI2/I2S2 /SPI3/I2S 3/SPI6/ UART7 /USART1/ 2/3/6	LPUART1 /SAI4/ SDMMC1/ SPDIFRX 1/SPI6/ UART4/5/ 8	FDCAN1/2/ FMC/LCD/ OCTOSPIM _P1/2/SAI4 /SDMMC2/ SPDIFRX1/ TIM13/14	CRS/FMC/ LCD/OCT OSPIM_P1 /OTG1_FS/ OTG1_HS/ SAI4/ SDMMC2/ TIM8	DFSDM1/ ETH/I2C4/ LCD/MDIOS /OCTOSPIM _P1/SDMMC 2/SWPMM1/ TIM1x/TIM8/ UART7/9/ USART10	FMC/LCD /MDIOS/ OCTOSPI M_P1/ SDMMC1 /TIM1x/ TIM8	COMP/ DCMI/ PSSI/ LCD/ TIM1x/ TIM23	LCD/ TIM24/ UART5	SYS	
P r o t o b	PB10	-	TIM2_ CH3	-	LPTIM2_ IN1	I2C2_SCL	SPI2_SCK /I2S2_CK	DFSDM1_ DATIN7	USART3_ TX	-	OCTOSPIM _P1_NCS	OTG_HS_ ULPI_D3	ETH_MII_ RX_ER	-	-	LCD_G 4	EVENT OUT
	PB11	-	TIM2_ CH4	-	LPTIM2_ ETR	I2C2_SDA	-	DFSDM1_ CKIN7	USART3_ RX	-	-	OTG_HS_ ULPI_D4	ETH_MII_TX _EN/ETH_ RMII_TX_ EN	-	-	LCD_G 5	EVENT OUT
	PB12	-	TIM1_ BKIN	-	OCTOSPI M_P1_ NCLK	I2C2_ SMBA	SPI2_NSS /I2S2_WS	DFSDM1_ DATIN1	USART3_ CK	-	FDCAN2_ RX	OTG_HS_ ULPI_D5	ETH_MII_TX D0/ETH_ RMII_TXD0	OCTOSPI M_P1_IO 0	TIM1_ BKIN_ COMP 12	UART5 _RX	EVENT OUT
	PB13	-	TIM1_ CH1N	-	LPTIM2_ OUT	OCTOSPIM _P1_IO2	SPI2_SCK /I2S2_CK	DFSDM1_ CKIN1	USART3_ CTS/ USART3_ NSS	-	FDCAN2_ TX	OTG_HS_ ULPI_D6	ETH_MII_TX D1/ETH_ RMII_TXD1	SDMMC1 _D0	DCMI_ D2/P SSI_D2	UART5 _TX	EVENT OUT
	PB14	-	TIM1_ CH2N	TIM12_ CH1	TIM8_ CH2N	USART1_ TX	SPI2_ MISO/ I2S2_SDI	DFSDM1_ DATIN2	USART3_ RTS/ USART3_ DE	UART4_ RTS /UART4_ DE	SDMMC2_ D0	-	-	FMC_D1 0/FMC_ AD10	-	LCD_ CLK	EVENT OUT
	PB15	RTC_ REFIN	TIM1_ CH3N	TIM12_ CH2	TIM8_ CH3N	USART1_ RX	SPI2_MO SI/I2S2_ SDO	DFSDM1_ CKIN2	-	UART4_ CTS	SDMMC2_ D1	-	-	FMC_D11 /FMC_AD 11	-	LCD_G 7	EVENT OUT



Table 8. STM32H730xB pin alternate functions (continued)

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
	SYS	FMC/ LPTIM1/ SAI4/ TIM16/17 /TIM1x/ TIM2x	FDCAN3 /PDM_ SAI1/ TIM3/4/5 /12/15	DFSDM1/ LCD/ LPTIM2/3/ 4/5/ LPUART1 /OCTO SPI_P1/ 2/TIM8	CEC/DCMI/ PSSI/ DFSDM1/ I2C1/2/3/4/5 /LPTIM2/ OCTOSPIM _P1/TIM15/ USART1/10	CEC/ FDCAN3/ SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/5/6	DFSDM1/ I2C4/5/ OCTO SPI_P1/ SAI1/SPI3/ I2S3/ UART4	SDMMC1/ SPI2/I2S2 /SPI3/I2S 3/SPI6/ UART7 /USART1/ 2/3/6	LPUART1 /SAI4/ SDMMC1/ SPDIFRX 1/SPI6/ UART4/5/ 8	FDCAN1/2/ FMC/LCD/ OCTOSPIM _P1/2/SAI4 /SDMMC2/ SPDIFRX1/ TIM13/14	CRS/FMC/ LCD/OCT OSPIM_P1 /OTG1_FS/ OTG1_HS/ SAI4/ SDMMC2/ TIM8	DFSDM1/ ETH/I2C4/ LCD/MDIOS /OCTOSPIM _P1/SDMMC 2/SWPIM1/ TIM1x/TIM8/ UART7/9/ USART10	FMC/LCD /MDIOS/ OCTOSPIM _P1/ SDMMC1 /TIM1x/ TIM8	COMP/ DCMI/ PSSI/ LCD/ TIM1x/ TIM23	LCD/ TIM24/ UART5	SYS
PC0	-	FMC_D1 2/FMC_ AD12	-	DFSDM1_ CKIN0	-	-	DFSDM1_ DATIN4	-	SAI4_FS_ B	FMC_A25	OTG_HS_ ULPI_STP	LCD_G2	FMC_ SDNWE	-	LCD_R 5	EVENT OUT
PC1	TRA CED0	SAI4_D1	-	DFSDM1_ DATIN0	DFSDM1_C KIN4	SPI2_MO SI/I2S2_S DO	SAI1_SD_ A	-	SAI4_SD_ A	SDMMC2_ CK	OCTOSPI M_P1_IO4	ETH_MDC	MDIOS_ MDC	-	LCD_G 5	EVENT OUT
PC2	PWR_ DEEP SLEEP	-	-	DFSDM1_ CKIN1	OCTOSPIM _P1_IO5	SPI2_MIS O/I2S2_S DI	DFSDM1_ CKOUT	-	-	OCTOSPIM _P1_IO2	OTG_HS_ ULPI_DIR	ETH_MIL_ TXD2	FMC_SD NE0	-	-	EVENT OUT
PC3	PWR_ SLEEP	-	-	DFSDM1_ DATIN1	OCTOSPIM _P1_IO6	SPI2_MO SI/I2S2_S DO	-	-	-	OCTOSPIM _P1_IO0	OTG_HS_ ULPI_NXT	ETH_MIL_ TX_CLK	FMC_SD CKE0	-	-	EVENT OUT
PC4	PWR_ DEEP SLEEP	FMC_A2 2	-	DFSDM1_ CKIN2	-	I2S1_MCK	-	-	-	SPDIFRX1 _IN3	SDMMC2_ CKIN	ETH_MIL_ RXD0/ETH_ RMII_RXD0	FMC_SD NE0	-	LCD_R 7	EVENT OUT
PC5	PWR_ SLEEP	SAI4_D3	SAI1_D3	DFSDM1_ DATIN2	PSSI_D15	-	-	-	-	SPDIFRX1 _IN4	OCTOSPI M_P1_ DQS	ETH_MIL_ RXD1/ETH_ RMII_RXD1	FMC_SD CKE0	COMP 1_OUT	LCD_ DE	EVENT OUT
PC6	-	-	TIM3_ CH1	TIM8_CH 1	DFSDM1_ CKIN3	I2S2_MCK	-	USART6_ TX	SDMMC1 _D0DIR	FMC_ NWAIT	SDMMC2_ D6	-	SDMMC1 _D6	DCMI_ D0/ PSSI_ D0	LCD_ HSYNC	EVENT OUT
PC7	DBTR GIO	-	TIM3_ CH2	TIM8_CH 2	DFSDM1_ DATIN3	-	I2S3_MCK	USART6_ RX	SDMMC1 _D123DIR	FMC_NE1	SDMMC2_ D7	SWPIM1_TX	SDMMC1 _D7	DCMI_ D1/PS SI_D1	LCD_G 6	EVENT OUT
PC8	TRA CED1	-	TIM3_ CH3	TIM8_CH 3	-	-	-	USART6_ CK	UART5_ RTS/ UART5_ DE	FMC_NE2/ FMC_NCE	FMC_INT	SWPIM1_RX	SDMMC1 _D0	DCMI_ D2/PS SI_D2	-	EVENT OUT
PC9	MCO2	-	TIM3_C H4	TIM8_CH 4	I2C3_SDA	I2S_CKIN	I2C5_SDA	-	UART5_ CTS	OCTOSPIM _P1_IO0	LCD_G3	SWPIM1_SU SPEND	SDMMC1 _D1	DCMI_ D3/PS SI_D3	LCD_B 2	EVENT OUT

Prot C



Table 8. STM32H730xB pin alternate functions (continued)

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15		
	SYS	FMC/ LPTIM1/ SAI4/ TIM16/17 /TIM1x/ TIM2x	FDCAN3 /PDM_ SAI1/ TIM3/4/5 /12/15	DFSDM1/ LCD/ LPTIM2/3/ 4/5/ LPUART1 /OCTO SPIM_P1/ 2/TIM8	CEC/DCMI/ PSSI/ DFSDM1/ I2C1/2/3/4/5 /LPTIM2/ OCTOSPIM _P1/TIM15/ USART1/10	CEC/ FDCAN3/ SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/5/6	DFSDM1/ I2C4/5/ OCTO SPIM_P1/ SAI1/SPI3/ I2S3/ UART4	SDMMC1/ SPI2/I2S2 /SPI3/I2S 3/SPI6/ UART7 /USART1/ 2/3/6	LPUART1 /SAI4/ SDMMC1/ SPDIFRX 1/SPI6/ UART4/5/ 8	FDCAN1/2/ FMC/LCD/ OCTOSPIM _P1/2/SAI4 /SDMMC2/ SPDIFRX1/ TIM13/14	CRS/FMC/ LCD/OCT OSPIM_P1 /OTG1_FS/ OTG1_HS/ SAI4/ SDMMC2/ TIM8	DFSDM1/ ETH/I2C4/ LCD/MDIOS /OCTOSPIM _P1/SDMMC 2/SWPMI1/ TIM1x/TIM8/ UART7/9/ USART10	FMC/LCD /MDIOS/ OCTOSPI M_P1/ SDMMC1 /TIM1x/ TIM8	COMP/ DCMI/ PSSI/ LCD/ TIM1x/ TIM23	LCD/ TIM24/ UART5	SYS		
Port C	PC10	-	-	-	DFSDM1_ CKIN5	I2C5_SDA	-	SPI3_SCK/ I2S3_CK	USART3_ TX	UART4_ TX	OCTOSPIM _P1_IO1	LCD_B1	SWPMI_RX	SDMMC1 _D2	DCMI_ D8/ PSSI_ D8	LCD_R 2	EVENT OUT	
	PC11	-	-	-	DFSDM1_ DATIN5	I2C5_SCL	-	SPI3 MISO/I2S3 _SDI	USART3_ RX	UART4_ RX	OCTOSPIM _P1_NCS	-	-	SDMMC1 _D3	DCMI_ D4/ PSSI_ D4	LCD_B 4	EVENT OUT	
	PC12	TRAC ED3	FMC_D6/ FMC_AD 6	TIM15_ CH1	-	I2C5_SMB A	SPI6_SCK /I2S6_CK	SPI3 MOSI/I2S3 _SDO	USART3_ CK	UART5_ TX	-	-	-	SDMMC1 _CK	DCMI_ D9/ PSSI_ D9	LCD_R 6	EVENT OUT	
	PC13	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PC14	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PC15	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT

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Table 8. STM32H730xB pin alternate functions (continued)

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15	
	SYS	FMC/ LPTIM1/ SAI4/ TIM16/17 /TIM1x/ TIM2x	FDCAN3 /PDM_ SAI1/ TIM3/4/5 /12/15	DFSDM1/ LCD/ LPTIM2/3/ 4/5/ LPUART1 /OCTO SPI_M_P1/ 2/TIM8	CEC/DCMI/ PSSI/ DFSDM1/ I2C1/2/3/4/5 /LPTIM2/ OCTOSPI _P1/TIM15/ USART1/10	CEC/ FDCAN3/ SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/5/6	DFSDM1/ I2C4/5/ OCTO SPIM_P1/ SAI1/SPI3/ I2S3/ UART4	SDMMC1/ SPI2/I2S2 /SPI3/I2S 3/SPI6/ UART7 /USART1/ 2/3/6	LPUART1 /SAI4/ SDMMC1/ SPDIFRX 1/SPI6/ UART4/5/ 8	FDCAN1/2/ FMC/LCD/ OCTOSPI _P1/2/SAI4 /SDMMC2/ SPDIFRX1/ TIM13/14	CRS/FMC/ LCD/OCT OSPIM_P1 /OTG1_FS/ OTG1_HS/ SAI4/ SDMMC2/ TIM8	DFSDM1/ ETH/I2C4/ LCD/MDIOS /OCTOSPI _P1/SDMMC 2/SWPMI1/ TIM1x/TIM8/ UART7/9/ USART10	FMC/LCD /MDIOS/ OCTOSPI _M_P1/ SDMMC1 /TIM1x/ TIM8	COMP/ DCMI/ PSSI/ LCD/ TIM1x/ TIM23	LCD/ TIM24/ UART5	SYS	
Port D	PD0	-	-	-	DFSDM1_ CKIN6	-	-	-	-	UART4_ RX	FDCAN1_ RX	-	UART9_CTS	FMC_D2/ FMC_AD 2	-	LCD_B 1	EVENT OUT
Port D	PD1	-	-	-	DFSDM1_ DATIN6	-	-	-	-	UART4_ TX	FDCAN1_ TX	-	-	FMC_D3/ FMC_AD 3	-	-	EVENT OUT
Port D	PD2	TRAC ED2	FMC_D7/ FMC_AD 7	TIM3_ ETR	-	TIM15_ BKIN	-	-	-	UART5_ RX	LCD_B7	-	-	SDMMC1 _CMD	DCMI_ D11/ PSSI_ D11	LCD_B 2	EVENT OUT
Port D	PD3	-	-	-	DFSDM1_ CKOUT	-	SPI2_SCK /I2S2_CK	-	USART2_ CTS/ USART2_ NSS	-	-	-	-	FMC_ CLK	DCMI_ D5/ PSSI_ D5	LCD_G 7	EVENT OUT
Port D	PD4	-	-	-	-	-	-	-	USART2_ RTS/ USART2_ DE	-	-	OCTOSPI M_P1_IO4	-	FMC_ NOE	-	-	EVENT OUT
Port D	PD5	-	-	-	-	-	-	-	USART2_ TX	-	-	OCTOSPI M_P1_IO5	-	FMC_NW E	-	-	EVENT OUT
Port D	PD6	-	SAI4_D1	SAI1_D1	DFSDM1_ CKIN4	DFSDM1_ DATIN1	SPI3_ MOSI/I2S 3_SDO	SAI1_SD_ A	USART2_ RX	SAI4_SD_ A	-	OCTOSPI M_P1_IO6	SDMMC2_ CK	FMC_ NWAIT	DCMI_ D10/ PSSI_ D10	LCD_B 2	EVENT OUT
Port D	PD7	-	-	-	DFSDM1_ DATIN4	-	SPI1_ MOSI/I2S 1_SDO	DFSDM1_ CKIN1	USART2_ CK	-	SPDIFRX1 _IN1	OCTOSPI M_P1_IO7	SDMMC2_ CMD	FMC_NE 1	-	-	EVENT OUT
Port D	PD8	-	-	-	DFSDM1_ CKIN3	-	-	-	USART3_ TX	-	SPDIFRX1 _IN2	-	-	FMC_D1 3/FMC_A D13	-	-	EVENT OUT
Port D	PD9	-	-	-	DFSDM1_ DATIN3	-	-	-	USART3_ RX	-	-	-	-	FMC_D1 4/FMC_ AD14	-	-	EVENT OUT



Table 8. STM32H730xB pin alternate functions (continued)

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15	
	SYS	FMC/ LPTIM1/ SAI4/ TIM16/17 /TIM1x/ TIM2x	FDCAN3 /PDM_ SAI1/ TIM3/4/5 /12/15	DFSDM1/ LCD/ LPTIM2/3/ 4/5/ LPUART1 /OCTO SPIM_P1/ 2/TIM8	CEC/DCMI/ PSSI/ DFSDM1/ I2C1/2/3/4/5 /LPTIM2/ OCTOSPIM _P1/TIM15/ USART1/10	CEC/ FDCAN3/ SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/5/6	DFSDM1/ I2C4/5/ OCTO SPIM_P1/ SAI1/SPI3/ I2S3/ UART4	SDMMC1/ SPI2/I2S2 /SPI3/I2S 3/SPI6/ UART7 /USART1/ 2/3/6	LPUART1 /SAI4/ SDMMC1/ SPDIFRX 1/SPI6/ UART4/5/ 8	FDCAN1/2/ FMC/LCD/ OCTOSPIM _P1/2/SAI4 /SDMMC2/ SPDIFRX1/ TIM13/14	CRS/FMC/ LCD/OCT OSPIM_P1 /OTG1_FS/ OTG1_HS/ SAI4/ SDMMC2/ TIM8	DFSDM1/ ETH/I2C4/ LCD/MDIOS /OCTOSPIM _P1/SDMMC 2/SWPMI1/ TIM1x/TIM8/ UART7/9/ USART10	FMC/LCD /MDIOS/ OCTOSPI M_P1/ SDMMC1 /TIM1x/ TIM8	COMP/ DCMI/ PSSI/ LCD/ TIM1x/ TIM23	LCD/ TIM24/ UART5	SYS	
Port D	PD10	-	-	-	DFSDM1_ CKOUT	-	-	-	USART3_ CK	-	-	-	-	FMC_D1 5/FMC_A D15	-	LCD_B 3	EVENT OUT
	PD11	-	-	-	LPTIM2_I N2	I2C4_SMB A	-	-	USART3_ CTS/USA RT3_NSS	-	OCTOSPIM _P1_IO0	SAI4_SD_ A	-	FMC_A16 /FMC_CL E	-	-	EVENT OUT
	PD12	-	LPTIM1_ IN1	TIM4_C H1	LPTIM2_I N1	I2C4_SCL	FDCAN3_ RX	-	USART3_ RTS/USA RT3_DE	-	OCTOSPIM _P1_IO1	SAI4_FS_ A	-	FMC_A17 /FMC_AL E	DCMI_ D12/PS SI_D12	-	EVENT OUT
	PD13	-	LPTIM1_ OUT	TIM4_C H2	-	I2C4_SDA	FDCAN3_ TX	-	-	-	OCTOSPIM _P1_IO3	SAI4_SCK _A	UART9_RTS /UART9_DE	FMC_A18	DCMI_ D13/PS SI_D13	-	EVENT OUT
	PD14	-	-	TIM4_C H3	-	-	-	-	-	UART8_C TS	-	-	UART9_RX	FMC_D0/ FMC_AD 0	-	-	EVENT OUT
	PD15	-	-	TIM4_C H4	-	-	-	-	-	UART8_R TS/UART 8_DE	-	-	UART9_TX	FMC_D1/ FMC_AD 1	-	-	EVENT OUT

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Table 8. STM32H730xB pin alternate functions (continued)

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
	SYS	FMC/ LPTIM1/ SAI4/ TIM16/17 /TIM1x/ TIM2x	FDCAN3 /PDM_ SAI1/ TIM3/4/5 /12/15	DFSDM1/ LCD/ LPTIM2/3/ 4/5/ LPUART1 /OCTO SPIM_P1/ 2/TIM8	CEC/DCMI/ PSSI/ DFSDM1/ I2C1/2/3/4/5 /LPTIM2/ OCTOSPIM _P1/TIM15/ USART1/10	CEC/ FDCAN3/ SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/5/6	DFSDM1/ I2C4/5/ OCTO SPIM_P1/ SAI1/SPI3/ I2S3/ UART4	SDMMC1/ SPI2/I2S2 /SPI3/I2S 3/SPI6/ UART7 /USART1/ 2/3/6	LPUART1 /SAI4/ SDMMC1/ SPDIFRX 1/SPI6/ UART4/5/ 8	FDCAN1/2/ FMC/LCD/ OCTOSPIM _P1/2/SAI4 /SDMMC2/ SPDIFRX1/ TIM13/14	CRS/FMC/ LCD/OCT OSPIM_P1 /OTG1_FS/ OTG1_HS/ SAI4/ SDMMC2/ TIM8	DFSDM1/ ETH/I2C4/ LCD/MDIOS /OCTOSPIM _P1/SDMMC 2/SWPIM1/ TIM1x/TIM8/ UART7/9/ USART10	FMC/LCD /MDIOS/ OCTOSPI M_P1/ SDMMC1 /TIM1x/ TIM8	COMP/ DCMI/ PSSI/ LCD/ TIM1x/ TIM23	LCD/ TIM24/ UART5	SYS
PE0	-	LPTIM1_ETR	TIM4_ETR	-	LPTIM2_ETR	-	-	-	UART8_RX	-	SAI4_MCLK_A	-	FMC_NBL0	DCMI_D2/PSI_D2	LCD_R0	EVENT OUT
PE1	-	LPTIM1_IN2	-	-	-	-	-	-	UART8_TX	-	-	-	FMC_NBL1	DCMI_D3/PSI_D3	LCD_R6	EVENT OUT
PE2	TRAC ECLK	-	SAI1_CK1	-	USART10_RX	SPI4_SCK	SAI1_MCLK_A	-	SAI4_MCLK_A	OCTOSPIM_P1_IO2	SAI4_CK1	ETH_MII_TXD3	FMC_A23	-	-	EVENT OUT
PE3	TRAC ED0	-	-	-	TIM15_BKIN	-	SAI1_SDB	-	SAI4_SDB	-	-	USART10_TX	FMC_A19	-	-	EVENT OUT
PE4	TRAC ED1	-	SAI1_D2	DFSDM1_DATIN3	TIM15_CH1N	SPI4_NSS	SAI1_FS_A	-	SAI4_FS_A	-	SAI4_D2	-	FMC_A20	DCMI_D4/PSI_D4	LCD_B0	EVENT OUT
PE5	TRAC ED2	-	SAI1_CK2	DFSDM1_CKIN3	TIM15_CH1	SPI4_MISO	SAI1_SCK_A	-	SAI4_SCK_A	-	SAI4_CK2	-	FMC_A21	DCMI_D6/PSI_D6	LCD_G0	EVENT OUT
PE6	TRAC ED3	TIM1_BKIN2	SAI1_D1	-	TIM15_CH2	SPI4_MOSI	SAI1_SDA	-	SAI4_SDA	SAI4_D1	SAI4_MCLK_B	TIM1_BKIN2_COMP12	FMC_A22	DCMI_D7/PSI_D7	LCD_G1	EVENT OUT
PE7	-	TIM1_ETR	-	DFSDM1_DATIN2	-	-	-	UART7_RX	-	-	OCTOSPIM_P1_IO4	-	FMC_D4/ FMC_AD4	-	-	EVENT OUT
PE8	-	TIM1_CH1N	-	DFSDM1_CKIN2	-	-	-	UART7_TX	-	-	OCTOSPIM_P1_IO5	-	FMC_D5/ FMC_AD5	COMP2_OUT	-	EVENT OUT
PE9	-	TIM1_CH1	-	DFSDM1_CKOUT	-	-	-	UART7_RTS/UART7_DE	-	-	OCTOSPIM_P1_IO6	-	FMC_D6/ FMC_AD6	-	-	EVENT OUT
PE10	-	TIM1_CH2N	-	DFSDM1_DATIN4	-	-	-	UART7_CTS	-	-	OCTOSPIM_P1_IO7	-	FMC_D7/ FMC_AD7	-	-	EVENT OUT

Port E





Table 8. STM32H730xB pin alternate functions (continued)

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
	SYS	FMC/ LPTIM1/ SAI4/ TIM16/17 /TIM1x/ TIM2x	FDCAN3 /PDM_ SAI1/ TIM3/4/5 /12/15	DFSDM1/ LCD/ LPTIM2/3/ 4/5/ LPUART1 /OCTO SPIM_P1/ 2/TIM8	CEC/DCMI/ PSSI/ DFSDM1/ I2C1/2/3/4/5 /LPTIM2/ OCTOSPIM _P1/TIM15/ USART1/10	CEC/ FDCAN3/ SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/5/6	DFSDM1/ I2C4/5/ OCTO SPIM_P1/ SAI1/SPI3/ I2S3/ UART4	SDMMC1/ SPI2/I2S2 /SPI3/I2S 3/SPI6/ UART7 /USART1/ 2/3/6	LPUART1 /SAI4/ SDMMC1/ SPDIFRX 1/SPI6/ UART4/5/ 8	FDCAN1/2/ FMC/LCD/ OCTOSPIM _P1/2/SAI4 /SDMMC2/ SPDIFRX1/ TIM13/14	CRS/FMC/ LCD/OCT OSPIM_P1 /OTG1_FS/ OTG1_HS/ SAI4/ SDMMC2/ TIM8	DFSDM1/ ETH/I2C4/ LCD/MDIOS /OCTOSPIM _P1/SDMMC 2/SWPMI1/ TIM1x/TIM8/ UART7/9/ USART10	FMC/LCD /MDIOS/ OCTOSPI M_P1/ SDMMC1 /TIM1x/ TIM8	COMP/ DCMI/ PSSI/ LCD/ TIM1x/ TIM23	LCD/ TIM24/ UART5	SYS
Port E	PE11	-	TIM1_CH 2	-	DFSDM1_ CKIN4	-	SPI4_NSS	-	-	-	SAI4_SD_ B	OCTOSPIM _P1_NCS	FMC_D8/ FMC_AD 8	-	LCD_G 3	EVENT OUT
	PE12	-	TIM1_CH 3N	-	DFSDM1_ DATIN5	-	SPI4_SCK	-	-	-	SAI4_SCK _B	-	FMC_D9/ FMC_AD 9	COMP 1_OUT	LCD_B 4	EVENT OUT
	PE13	-	TIM1_CH 3	-	DFSDM1_ CKIN5	-	SPI4_MIS O	-	-	-	SAI4_FS_ B	-	FMC_D1 0/FMC_A D10	COMP 2_OUT	LCD_D E	EVENT OUT
	PE14	-	TIM1_CH 4	-	-	-	SPI4_MO SI	-	-	-	SAI4_MCL K_B	-	FMC_D11 /FMC_AD 11	-	LCD_C LK	EVENT OUT
	PE15	-	TIM1_BKI N	-	-	-	-	-	-	-	-	USART10_C K	FMC_D1 2/FMC_A D12	TIM1_B KIN_C OMP12	LCD_R 7	EVENT OUT



Table 8. STM32H730xB pin alternate functions (continued)

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
	SYS	FMC/ LPTIM1/ SAI4/ TIM16/17 /TIM1x/ TIM2x	FDCAN3 /PDM_ SAI1/ TIM3/4/5 /12/15	DFSDM1/ LCD/ LPTIM2/3/ 4/5/ LPUART1 /OCTO SPI_M_P1/ 2/TIM8	CEC/DCMI/ PSSI/ DFSDM1/ I2C1/2/3/4/5 /LPTIM2/ OCTOSPIM _P1/TIM15/ USART1/10	CEC/ FDCAN3/ SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/5/6	DFSDM1/ I2C4/5/ OCTO SPI_M_P1/ SAI1/SPI3/ I2S3/ UART4	SDMMC1/ SPI2/I2S2 /SPI3/I2S 3/SPI6/ UART7 /USART1/ 2/3/6	LPUART1 /SAI4/ SDMMC1/ SPDIFRX 1/SPI6/ UART4/5/ 8	FDCAN1/2/ FMC/LCD/ OCTOSPIM _P1/2/SAI4 /SDMMC2/ SPDIFRX1/ TIM13/14	CRS/FMC/ LCD/OCT OSPIM_P1 /OTG1_FS/ OTG1_HS/ SAI4/ SDMMC2/ TIM8	DFSDM1/ ETH/I2C4/ LCD/MDIOS /OCTOSPIM _P1/SDMMC 2/SWPMI1/ TIM1x/TIM8/ UART7/9/ USART10	FMC/LCD /MDIOS/ OCTOSPI M_P1/ SDMMC1 /TIM1x/ TIM8	COMP/ DCMI/ PSSI/ LCD/ TIM1x/ TIM23	LCD/ TIM24/ UART5	SYS
PF0	-	-	-	-	I2C2_SDA	-	I2C5_SDA	-	-	OCTOSPIM _P2_IO0	-	-	FMC_A0	TIM23_ CH1	-	EVENT OUT
PF1	-	-	-	-	I2C2_SCL	-	I2C5_SCL	-	-	OCTOSPIM _P2_IO1	-	-	FMC_A1	TIM23_ CH2	-	EVENT OUT
PF2	-	-	-	-	I2C2_SMB A	-	I2C5_SMB A	-	-	OCTOSPIM _P2_IO2	-	-	FMC_A2	TIM23_ CH3	-	EVENT OUT
PF3	-	-	-	-	-	-	-	-	-	OCTOSPIM _P2_IO3	-	-	FMC_A3	TIM23_ CH4	-	EVENT OUT
PF4	-	-	-	-	-	-	-	-	-	OCTOSPIM _P2_CLK	-	-	FMC_A4	-	-	EVENT OUT
PF5	-	-	-	-	-	-	-	-	-	OCTOSPIM _P2_NCLK	-	-	FMC_A5	-	-	EVENT OUT
PF6	-	TIM16_C H1	FDCAN3 _RX	-	-	SPI5_NSS	SAI1_SD_ B	UART7_R X	SAI4_SD_ B	-	OCTOSPI M_P1_IO3	-	-	TIM23_ CH1	-	EVENT OUT
PF7	-	TIM17_C H1	FDCAN3 _TX	-	-	SPI5_SCK	SAI1_MCL K_B	UART7_T X	SAI4_MC LK_B	-	OCTOSPI M_P1_IO2	-	-	TIM23_ CH2	-	EVENT OUT
PF8	-	TIM16_C H1N	-	-	-	SPI5_MIS O	SAI1_SCK _B	UART7_R TS/UART 7_DE	SAI4_SC K_B	TIM13_CH 1	OCTOSPI M_P1_IO0	-	-	TIM23_ CH3	-	EVENT OUT

Port F



Table 8. STM32H730xB pin alternate functions (continued)

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15	
	SYS	FMC/ LPTIM1/ SAI4/ TIM16/17 /TIM1x/ TIM2x	FDCAN3 /PDM_ SAI1/ TIM3/4/5 /12/15	DFSDM1/ LCD/ LPTIM2/3/ 4/5/ LPUART1 /OCTO SPIM_P1/ 2/TIM8	CEC/DCMI/ PSSI/ DFSDM1/ I2C1/2/3/4/5 /LPTIM2/ OCTOSPIM _P1/TIM15/ USART1/10	CEC/ FDCAN3/ SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/5/6	DFSDM1/ I2C4/5/ OCTO SPIM_P1/ SAI1/SPI3/ I2S3/ UART4	SDMMC1/ SPI2/I2S2 /SPI3/I2S 3/SPI6/ UART7 /USART1/ 2/3/6	LPUART1 /SAI4/ SDMMC1/ SPDIFRX 1/SPI6/ UART4/5/ 8	FDCAN1/2/ FMC/LCD/ OCTOSPIM _P1/2/SAI4 /SDMMC2/ SPDIFRX1/ TIM13/14	CRS/FMC/ LCD/OCT OSPIM_P1 /OTG1_FS/ OTG1_HS/ SAI4/ SDMMC2/ TIM8	DFSDM1/ ETH/I2C4/ LCD/MDIOS /OCTOSPIM _P1/SDMMC 2/SWPIM1/ TIM1x/TIM8/ UART7/9/ USART10	FMC/LCD /MDIOS/ OCTOSPIM _P1/ SDMMC1 /TIM1x/ TIM8	COMP/ DCMI/ PSSI/ LCD/ TIM1x/ TIM23	LCD/ TIM24/ UART5	SYS	
Port F	PF9	-	TIM17_C H1N	-	-	-	SPI5_MO SI	SAI1_FS_B	UART7_C TS	SAI4_FS_ B	TIM14_CH 1	OCTOSPIM_P1_IO1	-	-	TIM23_ CH4	-	EVENT OUT
	PF10	-	TIM16_B KIN	SAI1_D3	-	PSSI_D15	-	-	-	-	OCTOSPIM _P1_CLK	SAI4_D3	-	-	DCMI D11/PS SI_D11	LCD_D E	EVENT OUT
	PF11	-	-	-	-	-	SPI5_MO SI	-	-	-	OCTOSPIM _P1_NCLK	SAI4_SD_ B	-	FMC_NR AS	DCMI D12/P SI_D12	TIM24_ CH1	EVENT OUT
	PF12	-	-	-	-	-	-	-	-	-	OCTOSPIM _P2_DQS	-	-	FMC_A6	-	TIM24_ CH2	EVENT OUT
	PF13	-	-	-	DFSDM1_ DATIN6	I2C4_SMB A	-	-	-	-	-	-	-	FMC_A7	-	TIM24_ CH3	EVENT OUT
	PF14	-	-	-	DFSDM1_ CKIN6	I2C4_SCL	-	-	-	-	-	-	-	FMC_A8	-	TIM24_ CH4	EVENT OUT
	PF15	-	-	-	-	I2C4_SDA	-	-	-	-	-	-	-	FMC_A9	-	-	EVENT OUT
Port G	PG0	-	-	-	-	-	-	-	-	-	OCTOSPIM _P2_IO4	-	UART9_RX	FMC_A10	-	-	EVENT OUT
	PG1	-	-	-	-	-	-	-	-	-	OCTOSPIM _P2_IO5	-	UART9_TX	FMC_A11	-	-	EVENT OUT
	PG2	-	-	-	TIM8_BKI N	-	-	-	-	-	-	-	TIM8_BKIN_ COMP12	FMC_A12	-	TIM24_ ETR	EVENT OUT
	PG3	-	-	-	TIM8_BKI N2	-	-	-	-	-	-	-	TIM8_BKIN2_ COMP12	FMC_A13	TIM23_ ETR	-	EVENT OUT



Table 8. STM32H730xB pin alternate functions (continued)

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
	SYS	FMC/ LPTIM1/ SAI4/ TIM16/17/ TIM1x/ TIM2x	FDCAN3/ PDM_ SAI1/ TIM3/4/5/ TIM2/15	DFSDM1/ LCD/ LPTIM2/3/ 4/5/ LPUART1 /OCTO SPIM_P1/ 2/TIM8	CEC/DCMI/ PSSI/ DFSDM1/ I2C1/2/3/4/5 /LPTIM2/ OCTOSPIM _P1/TIM15/ USART1/10	CEC/ FDCAN3/ SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/5/6	DFSDM1/ I2C4/5/ OCTO SPIM_P1/ SAI1/SPI3/ I2S3/ UART4	SDMMC1/ SPI2/I2S2 /SPI3/I2S 3/SPI6/ UART7 /USART1/ 2/3/6	LPUART1 /SAI4/ SDMMC1/ SPDIFRX 1/SPI6/ UART4/5/ 8	FDCAN1/2/ FMC/LCD/ OCTOSPIM _P1/2/SAI4 /SDMMC2/ SPDIFRX1/ TIM13/14	CRS/FMC/ LCD/OCT OSPIM_P1 /OTG1_FS/ OTG1_HS/ SAI4/ SDMMC2/ TIM8	DFSDM1/ ETH/I2C4/ LCD/MDIOS /OCTOSPIM _P1/SDMMC 2/SWPMI1/ TIM1x/TIM8/ UART7/9/ USART10	FMC/LCD /MDIOS/ OCTOSPI M_P1/ SDMMC1 /TIM1x/ TIM8	COMP/ DCMI/ PSSI/ LCD/ TIM1x/ TIM23	LCD/ TIM24/ UART5	SYS
PG4	-	TIM1_BK1 N2	-	-	-	-	-	-	-	-	-	TIM1_BKIN2 _COMP12	FMC_A14 /FMC_BA 0	-	-	EVENT OUT
PG5	-	TIM1_ET R	-	-	-	-	-	-	-	-	-	-	FMC_A15 /FMC_BA 1	-	-	EVENT OUT
PG6	-	TIM17_B KIN	-	-	-	-	-	-	-	-	OCTOSPI M_P1_NC S	-	FMC_NE 3	DCMI_ D12/PS SI_D12	LCD_R 7	EVENT OUT
PG7	-	-	-	-	-	-	SAI1_MCL K_A	USART6_ CK	-	OCTOSPIM _P2_DQS	-	-	FMC_INT	DCMI_ D13/PS SI_D13	LCD_C LK	EVENT OUT
PG8	-	-	-	TIM8_ET R	-	SPI6_NSS /I2S6_WS	-	USART6_ RTS/USA RT6_DE	SPDIFRX 1_IN3	-	-	ETH_PPS_ OUT	FMC_SD CLK	-	LCD_G 7	EVENT OUT
PG9	-	-	FDCAN3 _TX	-	-	SPI1_MIS O/I2S1_S DI	-	USART6_ RX	SPDIFRX 1_IN4	OCTOSPIM _P1_IO6	SAI4_FS_ B	SDMMC2_D 0	FMC_NE 2/FMC_N CE	DCMI_ VSYNC /PSSI_ RDY	-	EVENT OUT
PG10	-	-	FDCAN3 _RX	OCTOSPI M_P2_IO 6	-	SPI1_NSS /I2S1_WS	-	-	-	LCD_G3	SAI4_SD_ B	SDMMC2_D 1	FMC_NE 3	DCMI_ D2/PS SI_D2	LCD_B 2	EVENT OUT
PG11	-	LPTIM1_I N2	-	-	USART10_ RX	SPI1_SCK /I2S1_CK	-	-	SPDIFRX 1_IN1	OCTOSPIM _P2_IO7	SDMMC2_ D2	ETH_MII_TX _EN/ETH_R MII_TX_EN	-	DCMI_ D3/PS SI_D3	LCD_B 3	EVENT OUT
PG12	-	LPTIM1_I N1	-	OCTOSPI M_P2_NC S	USART10_ TX	SPI6_MIS O/I2S6_S DI	-	USART6_ RTS/USA RT6_DE	SPDIFRX 1_IN2	LCD_B4	SDMMC2_ D3	ETH_MII_TX D1/ETH_RM II_TXD1	FMC_NE 4	TIM23_ CH1	LCD_B 1	EVENT OUT
PG13	TRAC ED0	LPTIM1_ OUT	-	-	USART10_ CTS/USAR T10_NSS	SPI6_SCK /I2S6_CK	-	USART6_ CTS/USA RT6_NSS	-	-	SDMMC2_ D6	ETH_MII_TX D0/ETH_RM II_TXD0	FMC_A24	TIM23_ CH2	LCD_R 0	EVENT OUT

Port G



Table 8. STM32H730xB pin alternate functions (continued)

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15	
	SYS	FMC/ LPTIM1/ SAI4/ TIM16/17 /TIM1x/ TIM2x	FDCAN3 /PDM_ SAI1/ TIM3/4/5 /12/15	DFSDM1/ LCD/ LPTIM2/3/ 4/5/ LPUART1 /OCTO SPI_P1/ 2/TIM8	CEC/DCMI/ PSSI/ DFSDM1/ I2C1/2/3/4/5 /LPTIM2/ OCTOSPIM _P1/TIM15/ USART1/10	CEC/ FDCAN3/ SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/5/6	DFSDM1/ I2C4/5/ OCTO SPI_P1/ SAI1/SPI3/ I2S3/ UART4	SDMMC1/ SPI2/I2S2 /SPI3/I2S 3/SPI6/ UART7 /USART1/ 2/3/6	LPUART1 /SAI4/ SDMMC1/ SPDIFRX 1/SPI6/ UART4/5/ 8	FDCAN1/2/ FMC/LCD/ OCTOSPIM _P1/2/SAI4 /SDMMC2/ SPDIFRX1/ TIM13/14	CRS/FMC/ LCD/OCT OSPIM_P1 /OTG1_FS/ OTG1_HS/ SAI4/ SDMMC2/ TIM8	DFSDM1/ ETH/I2C4/ LCD/MDIOS /OCTOSPIM _P1/SDMMC 2/SWPIM1/ TIM1x/TIM8/ UART7/9/ USART10	FMC/LCD /MDIOS/ OCTOSPI M_P1/ SDMMC1 /TIM1x/ TIM8	COMP/ DCMI/ PSSI/ LCD/ TIM1x/ TIM23	LCD/ TIM24/ UART5	SYS	
Port G	PG14	TRAC ED1	LPTIM1_ ETR	-	-	USART10_ RTS/USAR T10_DE	SPI6_MO SI/I2S6_S DO	-	USART6_ TX	-	OCTOSPIM _P1_IO7	SDMMC2_ D7	ETH_MII_TX D1/ETH_RM II_TXD1	FMC_A25	TIM23_ CH3	LCD_B 0	EVENT OUT
	PG15	-	-	-	-	-	-	-	USART6_ CTS/USA RT6_NSS	-	OCTOSPIM _P2_DQS	-	USART10_C K	FMC_NC AS	DCMI_ D13/PS SI_D13	-	EVENT OUT
Port H	PH0	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PH1	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PH2	-	LPTIM1_ N2	-	-	-	-	-	-	-	OCTOSPIM _P1_IO4	SAI4_SCK _B	ETH_MII_C RS	FMC_SD CKE0	-	LCD_R 0	EVENT OUT
	PH3	-	-	-	-	-	-	-	-	-	OCTOSPIM _P1_IO5	SAI4_MCL K_B	ETH_MII_C OL	FMC_SD NE0	-	LCD_R 1	EVENT OUT
	PH4	-	-	-	-	I2C2_SCL	-	-	-	-	LCD_G5	OTG_HS_ ULPI_NXT	-	-	PSSI_ D14	LCD_G 4	EVENT OUT
	PH5	-	-	-	-	I2C2_SDA	SPI5_NSS	-	-	-	-	-	-	FMC_SD NWE	-	-	EVENT OUT
	PH6	-	-	TIM12_ CH1	-	I2C2_SMB A	SPI5_SCK	-	-	-	-	-	ETH_MII_R XD2	FMC_SD NE1	DCMI_ D8/PS SI_D8	-	EVENT OUT
	PH7	-	-	-	-	I2C3_SCL	SPI5_MIS O	-	-	-	-	-	ETH_MII_R XD3	FMC_SD CKE1	DCMI_ D9/PS SI_D9	-	EVENT OUT
	PH8	-	-	TIM5_E TR	-	I2C3_SDA	-	-	-	-	-	-	-	FMC_D1 6	DCMI_ HSYNC /PSSI_ DE	LCD_R 2	EVENT OUT
PH9	-	-	TIM12_ CH2	-	I2C3_SMB A	-	-	-	-	-	-	-	FMC_D1 7	DCMI_ D0/PS SI_D0	LCD_R 3	EVENT OUT	

Table 8. STM32H730xB pin alternate functions (continued)

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15	
	SYS	FMC/ LPTIM1/ SAI4/ TIM16/17 /TIM1x/ TIM2x	FDCAN3 /PDM_ SAI1/ TIM3/4/5 /12/15	DFSDM1/ LCD/ LPTIM2/3/ 4/5/ LPUART1 /OCTO SPI_P1/ 2/TIM8	CEC/DCMI/ PSSI/ DFSDM1/ I2C1/2/3/4/5 /LPTIM2/ OCTOSPIM _P1/TIM15/ USART1/10	CEC/ FDCAN3/ SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/5/6	DFSDM1/ I2C4/5/ OCTO SPI_P1/ SAI1/SPI3/ I2S3/ UART4	SDMMC1/ SPI2/I2S2 /SPI3/I2S 3/SPI6/ UART7 /USART1/ 2/3/6	LPUART1 /SAI4/ SDMMC1/ SPDIFRX 1/SPI6/ UART4/5/ 8	FDCAN1/2/ FMC/LCD/ OCTOSPIM _P1/2/SAI4 /SDMMC2/ SPDIFRX1/ TIM13/14	CRS/FMC/ LCD/OCT OSPIM_P1 /OTG1_FS/ OTG1_HS/ SAI4/ SDMMC2/ TIM8	DFSDM1/ ETH/I2C4/ LCD/MDIOS /OCTOSPIM _P1/SDMMC 2/SWPIM1/ TIM1x/TIM8/ UART7/9/ USART10	FMC/LCD /MDIOS/ OCTOSPI M_P1/ SDMMC1 /TIM1x/ TIM8	COMP/ DCMI/ PSSI/ LCD/ TIM1x/ TIM23	LCD/ TIM24/ UART5	SYS	
Port H	PH10	-	-	TIM5_C H1	-	I2C4_SMB A	-	-	-	-	-	-	FMC_D1 8	DCMI_ D1/PS SI_D1	LCD_R 4	EVENT OUT	
	PH11	-	-	TIM5_C H2	-	I2C4_SCL	-	-	-	-	-	-	FMC_D1 9	DCMI_ D2/PS SI_D2	LCD_R 5	EVENT OUT	
	PH12	-	-	TIM5_C H3	-	I2C4_SDA	-	-	-	-	-	-	FMC_D2 0	DCMI_ D3/PS SI_D3	LCD_R 6	EVENT OUT	
	PH13	-	-	-	TIM8_CH 1N	-	-	-	-	UART4_T X	FDCAN1_T X	-	-	FMC_D2 1	-	LCD_G 2	EVENT OUT
	PH14	-	-	-	TIM8_CH 2N	-	-	-	-	UART4_R X	FDCAN1_R X	-	-	FMC_D2 2	DCMI_ D4/PS SI_D4	LCD_G 3	EVENT OUT
	PH15	-	-	-	TIM8_CH 3N	-	-	-	-	-	-	-	-	FMC_D2 3	DCMI_ D11/PS SI_D11	LCD_G 4	EVENT OUT
Port J	PJ8	-	TIM1_CH 3N	-	TIM8_CH 1	-	-	-	-	UART8_T X	-	-	-	-	LCD_G 1	EVENT OUT	
	PJ9	-	TIM1_CH 3	-	TIM8_CH 1N	-	-	-	-	UART8_R X	-	-	-	-	LCD_G 2	EVENT OUT	
	PJ10	-	TIM1_CH 2N	-	TIM8_CH 2	-	SPI5_MO SI	-	-	-	-	-	-	-	LCD_G 3	EVENT OUT	
	PJ11	-	TIM1_CH 2	-	TIM8_CH 2N	-	SPI5_MIS O	-	-	-	-	-	-	-	LCD_G 4	EVENT OUT	

## 6 Electrical characteristics

### 6.1 Parameter conditions

Unless otherwise specified, all voltages are referenced to  $V_{SS}$ .

#### 6.1.1 Minimum and maximum values

Unless otherwise specified the minimum and maximum values are guaranteed in the worst conditions of junction temperature, supply voltage and frequencies by tests in production on 100% of the devices with an junction temperature at  $T_J = 25\text{ }^\circ\text{C}$  and  $T_J = T_{Jmax}$  (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in the table footnotes. Based on characterization, the minimum and maximum values refer to sample tests and represent the mean value plus or minus three times the standard deviation ( $\text{mean} \pm 3\sigma$ ).

#### 6.1.2 Typical values

Unless otherwise specified, typical data are based on  $T_J = 25\text{ }^\circ\text{C}$ ,  $V_{DD} = 3.3\text{ V}$  (for the  $1.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$  voltage range). They are given only as design guidelines and are not tested.

Typical ADC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range, where 95% of the devices have an error less than or equal to the value indicated ( $\text{mean} \pm 2\sigma$ ).

#### 6.1.3 Typical curves

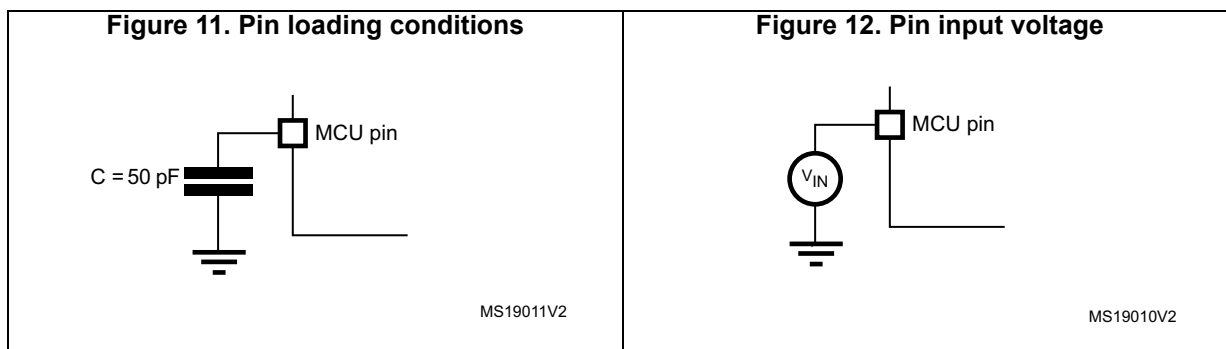
Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

#### 6.1.4 Loading capacitor

The loading conditions used for pin parameter measurement are shown in [Figure 11](#).

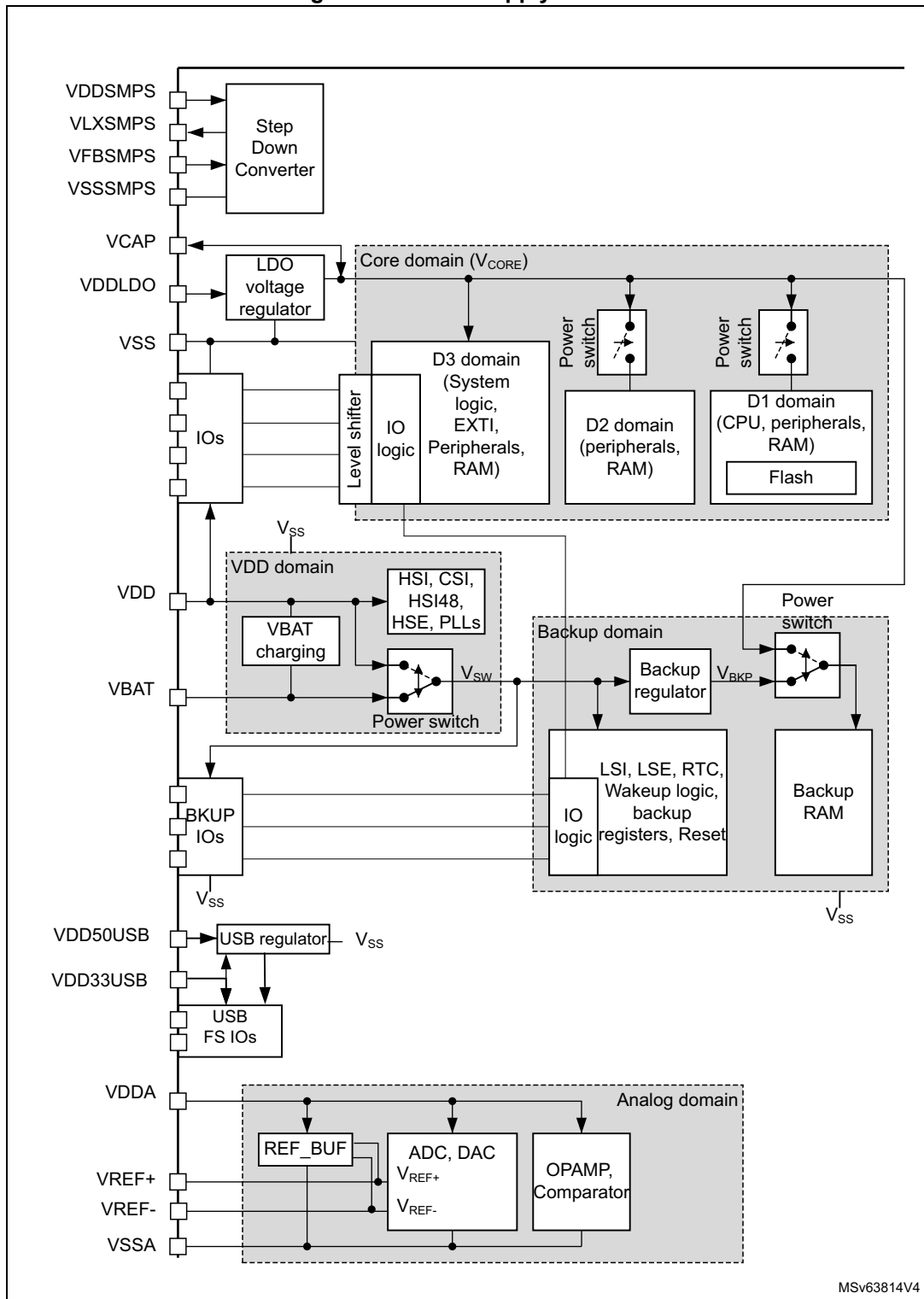
#### 6.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in [Figure 12](#).



6.1.6 Power supply scheme

Figure 13. Power supply scheme



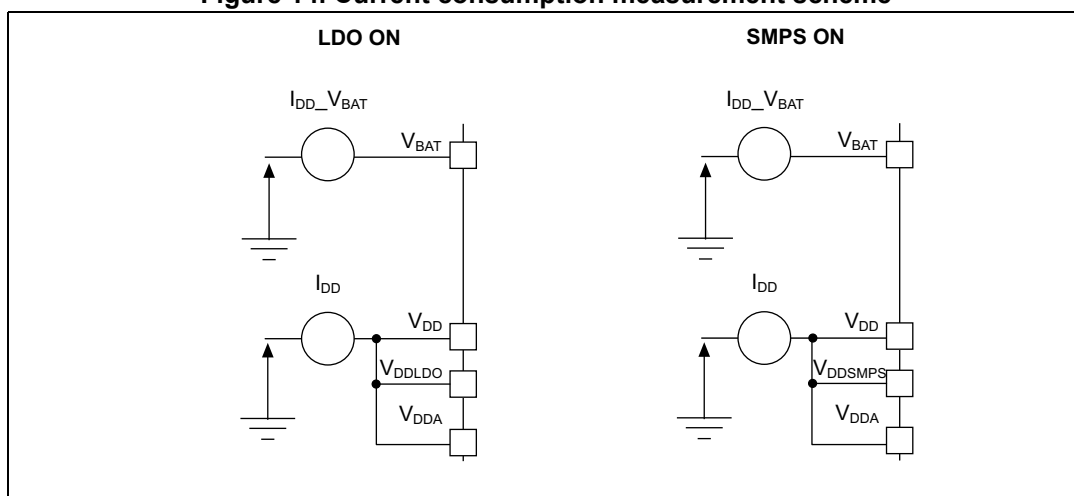
MSv63814V4

1. Refer to application note AN5419 "Getting started with STM32H723/733, STM32H725/735 and STM32H730 Value Line hardware development" for the possible power scheme and connected capacitors.



### 6.1.7 Current consumption measurement

Figure 14. Current consumption measurement scheme



## 6.2 Absolute maximum ratings

Stresses above the absolute maximum ratings listed in [Table 9: Voltage characteristics](#), [Table 10: Current characteristics](#), and [Table 11: Thermal characteristics](#) may cause permanent damage to the device. These are stress ratings only and the functional operation of the device at these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. Device mission profile (application conditions) is compliant with JEDEC JESD47 Qualification Standard, extended mission profiles are available on demand.

Table 9. Voltage characteristics

Symbols	Ratings	Min	Max	Unit
$V_{DDX} - V_{SS}^{(1)}$	External main supply voltage (including $V_{DD}$ , $V_{DDLDO}$ , $V_{DDSMPS}$ , $V_{DDA}$ , $V_{DD33USB}$ , $V_{BAT}$ )	-0.3	4.0	V
$V_{IN}^{(2)}$	Input voltage on FT_XXX pins	$V_{SS}-0.3$	$\text{Min}(V_{DD}, V_{DDA}, V_{DD33USB}, V_{BAT}) + 4.0^{(3)(4)}$	V
	Input voltage on TT_XX pins	$V_{SS}-0.3$	4.0	V
	Input voltage on BOOT0 pin	$V_{SS}$	9.0	V
	Input voltage on any other pins	$V_{SS}-0.3$	4.0	V
$ \Delta V_{DDX} $	Variations between different $V_{DDX}$ power pins of the same domain	-	50	mV
$ V_{SSx}-V_{SS} $	Variations between all the different ground pins	-	50	mV

- All main power ( $V_{DD}$ ,  $V_{DDA}$ ,  $V_{DD33USB}$ ,  $V_{DDSMPS}$ ,  $V_{BAT}$ ) and ground ( $V_{SS}$ ,  $V_{SSA}$ ) pins must always be connected to the external power supply, in the permitted range.
- $V_{IN}$  maximum must always be respected.
- This formula has to be applied on power supplies related to the IO structure described by the pin definition table.

- To sustain a voltage higher than 4V the internal pull-up/pull-down resistors must be disabled.

**Table 10. Current characteristics**

Symbols	Ratings	Max	Unit
$\Sigma I_{V_{DD}}$	Total current into sum of all $V_{DD}$ power lines (source) <sup>(1)</sup>	620	mA
$\Sigma I_{V_{SS}}$	Total current out of sum of all $V_{SS}$ ground lines (sink) <sup>(1)</sup>	620	
$I_{V_{DD}}$	Maximum current into each $V_{DD}$ power pin (source) <sup>(1)</sup>	100	
$I_{V_{SS}}$	Maximum current out of each $V_{SS}$ ground pin (sink) <sup>(1)</sup>	100	
$I_{IO}$	Output current sunk by any I/O and control pin, except Px_C	20	
	Output current sunk by Px_C pins	1	
$\Sigma I_{(PIN)}$	Total output current sunk by sum of all I/Os and control pins <sup>(2)</sup>	140	
	Total output current sourced by sum of all I/Os and control pins <sup>(2)</sup>	140	
$I_{INJ(PIN)}^{(3)(4)}$	Injected current on FT_xxx, TT_xx, RST and B pins except PA4, PA5	-5/+0	
	Injected current on PA4, PA5	-0/0	
$\Sigma I_{INJ(PIN)}$	Total injected current (sum of all I/Os and control pins) <sup>(5)</sup>	±25	

- All main power ( $V_{DD}$ ,  $V_{DDA}$ ,  $V_{DD33USB}$ ) and ground ( $V_{SS}$ ,  $V_{SSA}$ ) pins must always be connected to the external power supplies, in the permitted range.
- This current consumption must be correctly distributed over all I/Os and control pins. The total output current must not be sunk/sourced between two consecutive power supply pins referring to high pin count QFP packages.
- Positive injection is not possible on these I/Os and does not occur for input voltages lower than the specified maximum value.
- A positive injection is induced by  $V_{IN} > V_{DD}$  while a negative injection is induced by  $V_{IN} < V_{SS}$ .  $I_{INJ(PIN)}$  must never be exceeded. Refer also to [Table 9: Voltage characteristics](#) for the maximum allowed input voltage values.
- When several inputs are submitted to a current injection, the maximum  $\Sigma I_{INJ(PIN)}$  is the absolute sum of the positive and negative injected currents (instantaneous values).

**Table 11. Thermal characteristics**

Symbol	Ratings		Value	Unit
$T_{STG}$	Storage temperature range		- 65 to +150	°C
$T_J$	Maximum junction temperature	Industrial temperature range 6	125	

### 6.3 Operating conditions

#### 6.3.1 General operating conditions

Table 12. General operating conditions

Symbol	Parameter	Operating conditions	Min	Typ	Max	Unit
V <sub>DD</sub>	Standard operating voltage	-	1.62 <sup>(1)</sup>	-	3.6	V
V <sub>DDLDO</sub>	Supply voltage for the internal regulator	V <sub>DDLDO</sub> ≤ V <sub>DD</sub>	1.62 <sup>(1)</sup>	-	3.6	
V <sub>DDSMPS</sub>	Supply voltage for the internal SMPS Step-down converter	V <sub>DDSMPS</sub> = V <sub>DD</sub>	1.62 <sup>(1)</sup>	-	3.6	
V <sub>DD50USB</sub>	-	USB regulator ON	4	5	5.5	
		USB regulator OFF	-	V <sub>DD33USB</sub>	-	
V <sub>DD33USB</sub>	Standard operating voltage, USB domain	USB used	3.0	-	3.6	
		USB not used	0	-	3.6	
V <sub>DDA</sub>	Analog operating voltage	ADC or COMP used	1.62	-	3.6	
		DAC used	1.8	-		
		OPAMP used	2.0	-		
		VREFBUF used	1.8	-		
		ADC, DAC, OPAMP, COMP, VREFBUF not used	0	-		
V <sub>IN</sub>	I/O Input voltage	TT_xx I/O	-0.3	-	V <sub>DD</sub> +0.3	
		BOOT0	0	-	9	
		All I/O except BOOT0 and TT_xx	-0.3	-	Min(V <sub>DD</sub> , V <sub>DDA</sub> , V <sub>DD33USB</sub> ) +3.6V < 5.5V <sup>(2)</sup>	
V <sub>CORE</sub>	Internal regulator ON (LDO or SMPS) <sup>(3)</sup>	VOS3	0.95	1.0	1.05	V
		VOS2	1.05	1.10	1.15	
		VOS1	1.15	1.21	1.26	
		VOS0	1.30	1.36	1.40	
	Regulator OFF: external V <sub>CORE</sub> voltage must be supplied from external regulator on VCAP pins	VOS3	0.98	1.03	1.08	
		VOS2	1.08	1.13	1.18	
		VOS1	1.18	1.23	1.28	
		VOS0	1.33	1.38	1.40	

Table 12. General operating conditions (continued)

Symbol	Parameter	Operating conditions	Min	Typ	Max	Unit
f <sub>CPU</sub>	Arm® Cortex®-M7 clock frequency	VOS3	-	-	170	MHz
		VOS2	-	-	300	
		VOS1	-	-	400	
		VOS0	-	-	520	
		VOS0 and CPU_FREQ_BOOST	-	-	550	
f <sub>ACLK</sub>	AXI clock frequency	VOS3	-	-	85	
		VOS2	-	-	150	
		VOS1	-	-	200	
		VOS0	-	-	275	
f <sub>HCLK</sub>	AHB clock frequency	VOS3	-	-	85	
		VOS2	-	-	150	
		VOS1	-	-	200	
		VOS0	-	-	275	
f <sub>PCLK</sub>	APB clock frequency	VOS3	-	-	42.5 <sup>(4)</sup>	
		VOS2	-	-	75	
		VOS1	-	-	100	
		VOS0	-	-	137.5	
T <sub>A</sub> <sup>(5)</sup>	Ambient temperature for temperature range 3	Maximum power dissipation	-40		125	°C
	Ambient temperature for temperature range 6	Maximum power dissipation	-40		85	
		Low-power dissipation <sup>(6)</sup>	-40		105	

1. When RESET is released, the functionality is guaranteed down to V<sub>PDRmax</sub> or down to the specified V<sub>DDmin</sub> when the PDR is OFF. The PDR can only be switched OFF though the PDR\_ON pin that not available in all packages.
2. This formula has to be applied on power supplies related to the I/O structure described by the pin definition table.
3. At startup, the external V<sub>CORE</sub> voltage must remain higher or equal to 1.10 V before disabling the internal regulator (LDO).
4. This value corresponds to the maximum APB clock frequency when at least one peripheral is enabled.
5. The device junction temperature must be kept below maximum T<sub>J</sub> indicated in [Table 13: Supply voltage and maximum temperature configuration](#) and the maximum temperature.
6. In low-power dissipation state, T<sub>A</sub> can be extended to this range as long as T<sub>J</sub> does not exceed T<sub>Jmax</sub> (see [Section 7.8: Thermal characteristics](#)).

Table 13. Supply voltage and maximum temperature configuration

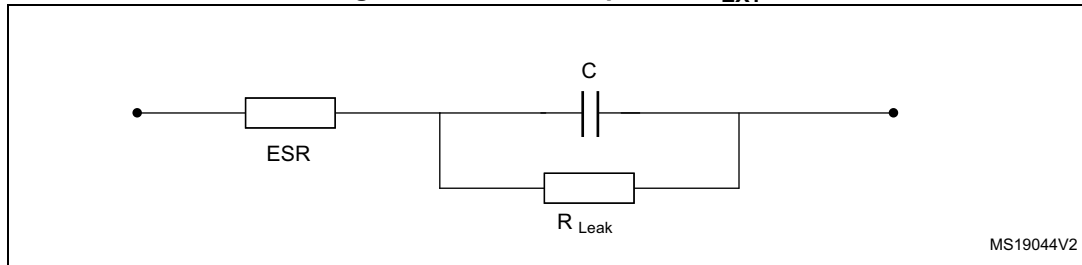
Power scale	V <sub>CORE</sub> source	Max. T <sub>J</sub> (°C) <sup>(1)</sup>	Min. V <sub>DD</sub> (V)	Min. V <sub>DDLDO</sub> (V)
VOS0	SMPS	105	2.2	-
	LDO		1.7	1.7
	SMPS supplies LDO		3 <sup>(2)</sup>	1.7
	External (Bypass)		1.62	1.62
VOS1	SMPS	140	2.2	-
		125	1.62	-
	LDO		1.62	1.62
	SMPS supplies LDO		2.3	-
External (Bypass)	1.62		-	
VOS2	SMPS	140	1.62	-
	LDO	125	1.62	1.62
	SMPS supplies LDO		2.3	-
	External (Bypass)		1.62	-
VOS3	SMPS		140	1.62
	LDO	125	1.62	1.62
	SMPS supplies LDO		2.3	-
	external (Bypass)E		1.62	-
SVOS4/SVOS5	SMPS		140	1.62
	LDO	125	2	2
		105	1.62	1.62
	SMPS supplies LDO	125	3 <sup>(2)</sup>	2
		105	2.3	-
External (Bypass)	125	1.62	-	

- 140 °C can be reached only for part numbers in temperature range 3. For part numbers in temperature range 6, this value must be decreased to 125 °C.
- The SMPS must be configured to output 2,5 V.

### 6.3.2 VCAP external capacitor

Stabilization for the main regulator is achieved by connecting an external capacitor  $C_{EXT}$  to the VCAP pin.  $C_{EXT}$  is specified in [Table 14](#). Two external capacitors can be connected to VCAP pins.

Figure 15. External capacitor  $C_{EXT}$



1. Legend: ESR is the equivalent series resistance.

Table 14. VCAP operating conditions<sup>(1)</sup>

Symbol	Parameter	Conditions
C <sub>EXT</sub>	Capacitance of external capacitor	2.2 μF <sup>(2)(3)</sup>
ESR	ESR of external capacitor	< 100 mΩ

1. When bypassing the voltage regulator, the two 2.2 μF V<sub>CAP</sub> capacitors are not required and should be replaced by two 100 nF decoupling capacitors.
2. This value corresponds to C<sub>EXT</sub> typical value. A variation of +/-20% is tolerated.
3. If a third VCAP pin is available on the package, it must be connected to the other VCAP pins but no additional capacitor is required.

### 6.3.3 SMPS step-down converter

The devices embed a high power efficiency SMPS step-down converter. SMPS characteristics for external usage are given in [Table 16](#). The SMPS step-down converter requires external components that are specified in [Figure 16](#) and [Table 15](#).

Figure 16. External components for SMPS step-down converter

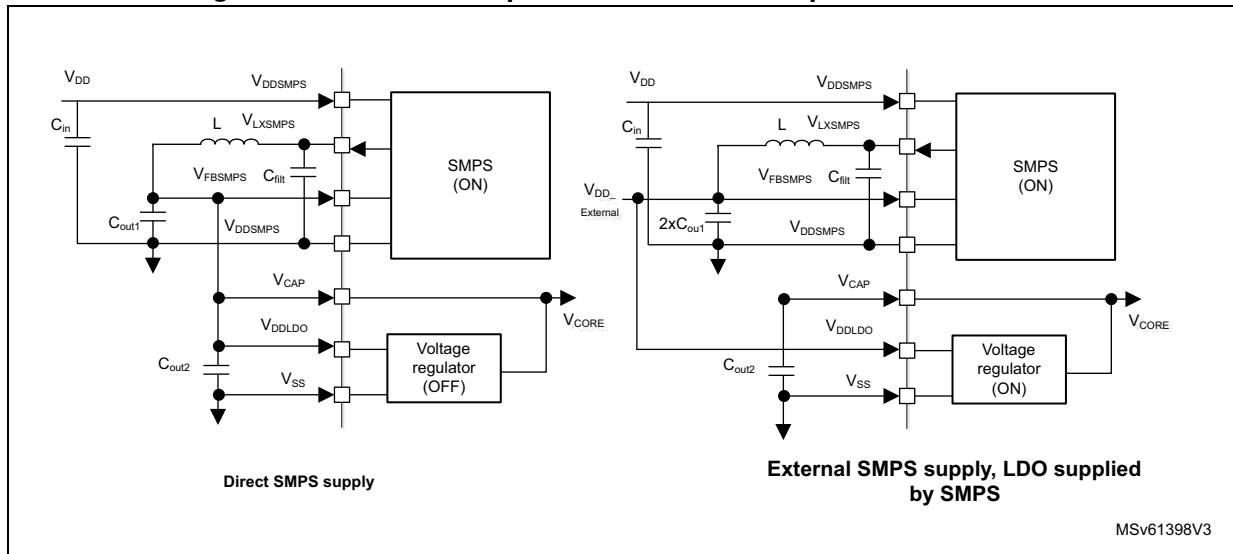


Table 15. Characteristics of SMPS step-down converter external components

Symbol	Parameter	Conditions
$C_{in}$	Capacitance of external capacitor on $V_{DDSMPS}$	4.7 $\mu F$
	ESR of external capacitor	100 m $\Omega$
$C_{filt}$	Capacitance of external capacitor on $V_{LXSMPS}$ pin	220 pF
$C_{OUT}$	Capacitance of external capacitor on $V_{FBSMPS}$ pin	10 $\mu F$
	ESR of external capacitor	20 m $\Omega$
L	Inductance of external Inductor on $V_{LXSMPS}$ pin	2.2 $\mu H$
-	Serial DC resistor	150 m $\Omega$
$I_{SAT}$	DC current at which the inductance drops 30% from its value without current.	1.7 A
$I_{RMS}$	Average current for a 40 °C rise: rated current for which the temperature of the inductor is raised 40°C by DC current	1.4 A

Table 16. SMPS step-down converter characteristics for external usage

Parameters	Conditions	Min	Typ	Max	Unit
$V_{DDSMPS}^{(1)}$	$V_{OUT} = 1.8 V$	2.3	-	3.6	V
	$V_{OUT} = 2.5 V$	3	-	3.6	
$V_{OUT}^{(2)}$	$I_{out}=600 mA$	2.25	2.5	2.75	V
		1.62	1.8	1.98	
$I_{OUT}$	internal and external usage	-	-	600	mA
	External usage only <sup>(3)</sup>	-	-	600	
$RDS_{ON}$	-	-	100	120	m $\Omega$

**Table 16. SMPS step-down converter characteristics for external usage (continued)**

Parameters	Conditions	Min	Typ	Max	Unit
$I_{DDSMPS\_Q}$	Quiescent current	-	220	-	$\mu A$
$T_{SMPS\_START}$	$V_{OUT} = 1.8 V$	-	270	405	$\mu s$
	$V_{OUT} = 2.5 V$	-	360	540	

1. The switching frequency is 2.4 MHz±10%
2. Including line transient and load transient.
3. These characteristics are given for SDEXTHP bit is set in the PWR\_CR3 register.

**Table 17. Inrush current and inrush electric charge characteristics for LDO and SMPS<sup>(1)(2)</sup>**

Symbol	Parameter	Conditions	-	Min	Typ	Max	Unit
$I_{RUSH}$	Inrush current on voltage regulator power-on (POR or wakeup from Standby)	on $V_{DDLDO}^{(3)}$	-	-	55	96 <sup>(4)</sup>	mA
		on $V_{DDSMPS}^{(5)}$	SMPS supplies the $V_{DDCORE}$	-	100	420 <sup>(6)</sup>	
	Inrush current on voltage regulator power-on (POR)	on $V_{DDSMPS}^{(5)}$	SMPS supplies internal LDO, $V_{OUT} = 1.8 V^{(7)}$	-	130	400 <sup>(6)</sup>	
			SMPS supplies internal LDO, $V_{OUT} = 2.5 V^{(7)}$	-	-	300 <sup>(6)</sup>	
			SMPS supplies external circuit, $V_{OUT} = 1.8 V^{(7)}$	-	100	320 <sup>(6)</sup>	
			SMPS supplies external circuit, $V_{OUT} = 2.5 V^{(7)}$	-	-	240 <sup>(6)</sup>	
	Inrush current on voltage regulator power-on (wakeup from Standby)	on $V_{DDSMPS}^{(5)}$	SMPS supplies internal LDO, $V_{OUT} = 1.8 V$	-	170	530 <sup>(6)</sup>	
			SMPS supplies internal LDO, $V_{OUT} = 2.5 V$	-	240	550 <sup>(6)</sup>	



**Table 17. Inrush current and inrush electric charge characteristics for LDO and SMPS<sup>(1)(2)</sup> (continued)**

Symbol	Parameter	Conditions	-	Min	Typ	Max	Unit
Q <sub>RUSH</sub>	Inrush current on voltage regulator power-on (POR or wakeup from Standby)	on V <sub>DDLDO</sub> <sup>(3)</sup>	-	-	4.4	5.3 <sup>(4)</sup>	μC
		on V <sub>DDSMPS</sub> <sup>(5)</sup>	SMPS supplies the V <sub>DDCORE</sub>	-	7.3	18 <sup>(6)</sup>	
	Inrush current on voltage regulator power-on (POR)	on V <sub>DDSMPS</sub> <sup>(5)</sup>	SMPS supplies internal LDO, V <sub>OUT</sub> = 1.8 V <sup>(7)</sup>	-	8.8	17 <sup>(6)</sup>	
			SMPS supplies internal LDO, V <sub>OUT</sub> = 2.5 V <sup>(7)</sup>	-		13 <sup>(6)</sup>	
			SMPS supplies external circuit, V <sub>OUT</sub> = 1.8 V <sup>(7)</sup>	-	7.3	13.7 <sup>(6)</sup>	
			SMPS supplies external circuit, V <sub>OUT</sub> = 2.5 V <sup>(7)</sup>	-		10.5 <sup>(6)</sup>	
	Inrush current on voltage regulator power-on (wakeup from Standby)	on V <sub>DDSMPS</sub> <sup>(5)</sup>	SMPS supplies internal LDO, V <sub>OUT</sub> = 1.8 V	-	15.0	28 <sup>(6)</sup>	
			SMPS supplies internal LDO, V <sub>OUT</sub> = 2.5 V	-	28.0	39 <sup>(6)</sup>	

1. The typical values are given for V<sub>DDLDO</sub> = V<sub>DDSMPS</sub> = 3.3 V and for typical decoupling capacitor values of C<sub>EXT</sub> and C<sub>OUT</sub>.
2. The product consumption (on V<sub>DDCORE</sub>) is not taken into account in the inrush current and inrush electric charges.
3. The inrush current and inrush electric charge on V<sub>DDLDO</sub> are not present in Bypass mode or when the SMPS supplies the V<sub>DDCORE</sub>.
4. The maximum value is given for the maximum decoupling capacitor C<sub>EXT</sub>.
5. The inrush current and inrush electric charges on V<sub>DDSMPS</sub> are not present if the external component (L or C<sub>OUT</sub>) is not present that is if the SMPS is not used.
6. The maximum value is given for the maximum decoupling capacitor C<sub>OUT</sub> and the minimum V<sub>DDSMPS</sub> voltage.
7. The inrush current due to transition from 1.2 V to the final V<sub>OUT</sub> Value (1.8 V or 2.5 V) is not taken into account.

### 6.3.4 Operating conditions at power-up / power-down

Subject to general operating conditions for  $T_A$ .

**Table 18. Operating conditions at power-up / power-down (regulator ON)**

Symbol	Parameter	Min	Max	Unit
$t_{VDD}$	$V_{DD}$ rise time rate	0	$\infty$	$\mu\text{s/V}$
	$V_{DD}$ fall time rate	10	$\infty$	
$t_{VDDA}$	$V_{DDA}$ rise time rate	0	$\infty$	
	$V_{DDA}$ fall time rate	10	$\infty$	
$t_{VDDUSB}$	$V_{DDUSB}$ rise time rate	0	$\infty$	
	$V_{DDUSB}$ fall time rate	10	$\infty$	

### 6.3.5 Embedded reset and power control block characteristics

The parameters given in [Table 19](#) are derived from tests performed under ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 12: General operating conditions](#).

**Table 19. Reset and power control block characteristics**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$t_{RSTTEMPO}^{(1)}$	Reset temporization after BOR0 released	-	-	377	550	$\mu s$
$V_{POR/PDR}$	Power-on/power-down reset threshold	Rising edge <sup>(1)</sup>	1.62	1.67	1.71	V
		Falling edge	1.58	1.62	1.68	
$V_{BOR1}$	Brown-out reset threshold 1	Rising edge	2.04	2.10	2.15	
		Falling edge	1.95	2.00	2.06	
$V_{BOR2}$	Brown-out reset threshold 2	Rising edge	2.34	2.41	2.47	
		Falling edge	2.25	2.31	2.37	
$V_{BOR3}$	Brown-out reset threshold 3	Rising edge	2.63	2.70	2.78	
		Falling edge	2.54	2.61	2.68	
$V_{PVD0}$	Programmable Voltage Detector threshold 0	Rising edge	1.90	1.96	2.01	
		Falling edge	1.81	1.86	1.91	
$V_{PVD1}$	Programmable Voltage Detector threshold 1	Rising edge	2.05	2.10	2.16	
		Falling edge	1.96	2.01	2.06	
$V_{PVD2}$	Programmable Voltage Detector threshold 2	Rising edge	2.19	2.26	2.32	
		Falling edge	2.10	2.15	2.21	
$V_{PVD3}$	Programmable Voltage Detector threshold 3	Rising edge	2.35	2.41	2.47	
		Falling edge	2.25	2.31	2.37	
$V_{PVD4}$	Programmable Voltage Detector threshold 4	Rising edge	2.49	2.56	2.62	
		Falling edge	2.39	2.45	2.51	
$V_{PVD5}$	Programmable Voltage Detector threshold 5	Rising edge	2.64	2.71	2.78	
		Falling edge	2.55	2.61	2.68	
$V_{PVD6}$	Programmable Voltage Detector threshold 6	Rising edge	2.78	2.86	2.94	
		Falling edge in Run mode	2.69	2.76	2.83	
$V_{POR/PDR}$	Hysteresis voltage for Power-on/power-down reset	Hysteresis in Run mode	-	43.00	-	mV
$V_{hyst\_BOR\_PVD}$	Hysteresis voltage for BOR	Hysteresis in Run mode	-	100	-	
$I_{DD\_BOR\_PVD}^{(1)}$	BOR and PVD consumption from $V_{DD}$	-	-	-	0.630	$\mu A$
$I_{DD\_POR\_PVD}$	POR and PVD consumption from $V_{DD}$	-	0.8	-	1.200	

Table 19. Reset and power control block characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
V <sub>AVM_0</sub>	Analog voltage detector for V <sub>DDA</sub> threshold 0	Rising edge	1.66	1.71	1.76	V	
		Falling edge	1.56	1.61	1.66		
V <sub>AVM_1</sub>	Analog voltage detector for V <sub>DDA</sub> threshold 1	Rising edge	2.06	2.12	2.19		
		Falling edge	1.96	2.02	2.08		
V <sub>AVM_2</sub>	Analog voltage detector for V <sub>DDA</sub> threshold 2	Rising edge	2.42	2.50	2.58		
		Falling edge	2.35	2.42	2.49		
V <sub>AVM_3</sub>	Analog voltage detector for V <sub>DDA</sub> threshold 3	Rising edge	2.74	2.83	2.91		
		Falling edge	2.64	2.72	2.80		
V <sub>hyst_VDDA</sub>	Hysteresis of V <sub>DDA</sub> voltage detector	-	-	100	-		mV
I <sub>DD_PVM</sub>	PVM consumption from V <sub>DD(1)</sub>	-	-	-	0.25		μA
I <sub>DD_VDDA</sub>	Voltage detector consumption on V <sub>DDA</sub> <sup>(1)</sup>	Resistor bridge	-	-	2.5	μA	

1. Guaranteed by design.

### 6.3.6 Embedded reference voltage characteristics

The parameters given in [Table 20](#) are derived from tests performed under ambient temperature and V<sub>DD</sub> supply voltage conditions summarized in [Table 12: General operating conditions](#).

Table 20. Embedded reference voltage

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V <sub>REFINT</sub>	Internal reference voltages	-40°C < T <sub>J</sub> < T <sub>Jmax</sub>	1.180	1.216	1.255	V
t <sub>S_vrefint</sub> <sup>(1)(2)(3)</sup>	ADC sampling time when reading the internal reference voltage	-	4.3	-	-	μs
t <sub>S_vbat</sub> <sup>(2)</sup>	VBAT sampling time when reading the internal VBAT reference voltage	-	9	-	-	
t <sub>start_vrefint</sub> <sup>(2)</sup>	Start time of reference voltage buffer when ADC is enable	-	-	-	4.4	
I <sub>refbuf</sub> <sup>(2)</sup>	Reference Buffer consumption for ADC	V <sub>DD</sub> = 3.3 V	9	13.5	23	μA
ΔV <sub>REFINT</sub> <sup>(2)</sup>	Internal reference voltage spread over the temperature range	-40°C < T <sub>J</sub> < T <sub>Jmax</sub>	-	5	15	mV
T <sub>coeff</sub> <sup>(2)</sup>	Average temperature coefficient	Average temperature coefficient	-	20	70	ppm/°C
V <sub>DDcoeff</sub> <sup>(2)</sup>	Average Voltage coefficient	3.0 V < V <sub>DD</sub> < 3.6 V	-	10	1370	ppm/V

**Table 20. Embedded reference voltage (continued)**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V <sub>REFINT_DIV1</sub>	1/4 reference voltage	-	-	25	-	% V <sub>REFINT</sub>
V <sub>REFINT_DIV2</sub>	1/2 reference voltage	-	-	50	-	
V <sub>REFINT_DIV3</sub>	3/4 reference voltage	-	-	75	-	

1. The shortest sampling time for the application can be determined by multiple iterations.
2. Guaranteed by design.
3. Guaranteed by design. and tested in production at 3.3 V.

**Table 21. Internal reference voltage calibration values**

Symbol	Parameter	Memory address
V <sub>REFIN_CAL</sub>	Raw data acquired at temperature of 30 °C, V <sub>DDA</sub> = 3.3 V	1FF1 E860 - 1FF1 E861

### 6.3.7 Embedded USB regulator characteristics

The parameters given in [Table 22](#) are derived from tests performed under ambient temperature and V<sub>DD</sub> supply voltage conditions summarized in [Table 12: General operating conditions](#).

**Table 22. USB regulator characteristics**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V <sub>DD50USB</sub>	Supply voltage	-	4	5	5.5	V
I <sub>DD50USB</sub>	Current consumption	-	-	14	-	µA
V <sub>REGOUTV33V</sub>	Regulated output voltage	-	3	-	3.6	V
I <sub>OUT</sub>	Output current load sinked by USB block	-	-	-	20	mA
T <sub>WKUP</sub>	Wakeup time	-	-	120	170	us

### 6.3.8 Supply current characteristics

The current consumption is a function of several parameters and factors such as the operating voltage, ambient temperature, I/O pin loading, device software configuration, operating frequencies, I/O pin switching rate, program location in memory and executed binary code.

The current consumption is measured as described in [Figure 14: Current consumption measurement scheme](#).

All the run-mode current consumption measurements given in this section are performed with a CoreMark code.

### Typical and maximum current consumption

The MCU is placed under the following conditions:

- All I/O pins are in analog input mode.
- All peripherals are disabled except when explicitly mentioned.
- The Flash memory access time is adjusted with the minimum wait states number, depending on the  $f_{\text{ACLK}}$  frequency (refer to the table “Number of wait states according to CPU clock ( $f_{\text{rcc\_c\_ck}}$ ) frequency and  $V_{\text{CORE}}$  range” available in the reference manual).
- When the peripherals are enabled, the AHB clock frequency is the CPU frequency divided by 2 and the APB clock frequency is AHB clock frequency divided by 2.

The parameters given in the below tables are derived from tests performed under ambient temperature and supply voltage conditions summarized in [Table 12: General operating conditions](#).

**Table 23. Typical and maximum current consumption in Run mode, code with data processing running from ITCM<sup>(1)</sup>**

Symbol	Parameter	Conditions	f <sub>rcc_c_ck</sub> (MHz)	Typ LDO regulator ON	Typ SMPS ON	Max LDO regulator ON <sup>(2)</sup>				Max SMPS ON <sup>(3)</sup>	Unit	
						T <sub>J</sub> = 25 °C	T <sub>J</sub> = 85 °C	T <sub>J</sub> = 105 °C	T <sub>J</sub> = 125 °C			T <sub>J</sub> = 140 °C
I <sub>DD</sub>	Supply current in Run mode	All peripherals disabled	VOS0 <sup>(4)</sup>	550	145	81	170	260	330	-	-	mA
				520	135	76	160	260	320	-	-	
			VOS0	520	135	76	160	260	320	-	-	
				480	125	72.5	150	250	310	-	-	
				450	115	67.5	150	240	300	-	-	
			VOS1	400	105	60	130	230	290	-	-	
				400	90.5	47	110	170	220	280	160	
			VOS2	300	69.5	36.5	84	150	200	260	150	
				300	63	31.5	74	130	170	220	110	
			VOS3	280	58	29	69	120	160	210	110	
				216	45.5	22.5	56	110	150	200	110	
				200	42	21	53	110	140	200	110	
			VOS3	170	32.5	15	40	80	110	160	74	
				168	32	15	40	79	110	160	74	
				144	28	13.5	36	75	110	150	74	
		60		13.5	6.7	21	61	90	140	67		
		25		6.9	3.6	14	54	83	130	67		
		All peripherals enabled	VOS0 <sup>(4)</sup>	550	215	125	250	360	430	-	-	
				520	205	120	240	350	420	-	-	
			VOS0	520	205	120	240	350	420	-	-	
				400	160	92.5	190	300	370	-	-	
			VOS1	400	135	72	160	230	290	360	200	
				300	105	54.5	130	200	250	330	180	
			VOS2	300	95	46.5	110	170	210	280	140	
				280	88	43	100	160	210	270	140	
			VOS3	170	49	22.5	58	110	140	190	93	

1. Data are in DTCM for best computation performance, the cache has no influence on consumption in this case.
2. Guaranteed by characterization results, unless otherwise specified. Refer to [Section 6.3.3: SMPS step-down converter](#) for the SMPS maximum consumption.
3. The parameter values given in the above table for the SMPS regulator are extrapolated from the LDO consumption and typical SMPS efficiency factors.
4. CPU\_FREQ\_BOOST is enabled.

**Table 24. Typical and maximum current consumption in Run mode, code with data processing running from Flash memory, cache ON<sup>(1)</sup>**

Symbol	Parameter	Conditions	f <sub>rcc_c_ck</sub> (MHz)	Typ LDO regulator ON	Typ SMPS ON	Max LDO regulator ON <sup>(2)</sup>				Max SMPS ON <sup>(3)</sup>	Unit	
						T <sub>J</sub> = 25 °C	T <sub>J</sub> = 85 °C	T <sub>J</sub> = 105 °C	T <sub>J</sub> = 125 °C			T <sub>J</sub> = 140 °C
I <sub>DD</sub>	Supply current in Run mode	All peripherals disabled	VOS0 <sup>(4)</sup>	550	145	83.5	170	270	330	-	-	mA
				520	140	78.5	170	260	320	-	-	
			VOS0	520	140	78.5	170	260	320	-	-	
				400	110	62	140	230	290	-	-	
			VOS1	400	92	48.5	110	180	220	290	160	
				300	71	37.5	86	150	200	260	150	
			VOS2	300	64	32	75	130	170	220	110	
				280	59	29.5	70	120	160	210	110	
				216	46.5	23	-	-	-	-	-	
				200	42.5	21.5	53	110	140	200	110	
			VOS3	180	36	17	43	83	120	160	85	
				170	33.5	15.5	41	81	110	160	74	
				168	33	15.5	-	-	-	-	-	
				144	29	13.5	-	-	-	-	-	
		60		14	6.85	-	-	-	-	-		
		All peripherals enabled	VOS0 <sup>(4)</sup>	550	220	130	250	360	430	-	-	
				520	210	120	240	350	420	-	-	
			VOS0	520	210	120	240	350	420	-	-	
				400	160	94.5	190	300	370	-	-	
			VOS1	400	140	73	160	240	290	360	200	
				300	105	55.5	130	200	250	330	180	
			VOS2	300	96	47	110	170	210	280	140	
				280	89	43.5	110	160	210	270	140	
			VOS3	170	50	23	59	110	140	190	93	

1. Data are in DTCM for best computation performance, the cache has no influence on consumption in this case.
2. Guaranteed by characterization results, unless otherwise specified. Refer to [Section 6.3.3: SMPS step-down converter](#) for the SMPS maximum consumption.
3. The parameter values given in the above table for the SMPS regulator are extrapolated from the LDO consumption and typical SMPS efficiency factors.
4. CPU\_FREQ\_BOOST is enabled.



**Table 25. Typical and maximum current consumption in Run mode, code with data processing running from Flash memory, cache OFF<sup>(1)</sup>**

Symbol	Parameter	Conditions	f <sub>rcc_c_ck</sub> (MHz)	Typ LDO regulator ON	Typ SMPS ON	Unit	
I <sub>DD</sub>	Supply current in Run mode	All peripherals disabled	VOS0 <sup>(2)</sup>	550	99	59.5	mA
				520	95	56	
			VOS0	520	95	56	
				400	76.5	47	
			VOS1	400	66.5	38	
				300	51.5	30	
			VOS2	300	47.5	26	
				280	43.5	24	
		VOS3	170	24.5	13		
		All peripherals enabled	VOS0 <sup>(2)</sup>	550	170	100	
				520	165	95.5	
			VOS0	520	165	95.5	
				400	130	77.5	
			VOS1	400	115	62	
				300	87	47.5	
			VOS2	300	79	41.5	
280	73.5			38			
VOS3	170	41	20.5				

1. Data are in DTCM for best computation performance, the cache has no influence on consumption in this case.
2. CPU\_FREQ\_BOOST is enabled.

**Table 26. Typical consumption in Run mode and corresponding performance versus code position**

Symbol	Parameter	Conditions		f <sub>rcc_c_ck</sub> (MHz)	Coremark	Typ LDO regulator ON	Typ SMPS ON	Unit	LDO I <sub>DD</sub> /Coremark	SMPS I <sub>DD</sub> /Coremark	Unit
		Peripheral	Code								
I <sub>DD</sub>	Supply current in Run mode	All peripherals disabled, cache ON	ITCM	550	2777	145	81	mA	52.2	29.2	μA/ Coremark
			FLASH	550	2777	145	83.5		52.2	30.1	
			AXI SRAM	550	2777	145	83.5		52.2	30.1	
			SRAM 1	550	2777	150	86		54.0	31.0	
			SRAM 4	550	2777	145	83.5		52.2	30.1	
		All peripherals disabled cache OFF	FLASH	550	923	99	59.5		107.3	64.5	
			AXI SRAM	550	1271	105	60.5		82.6	47.6	
			SRAM 1	550	790	96.5	54.5		122.2	69.0	
			SRAM 4	550	723	89.5	50.5		123.8	69.8	

**Table 27. Typical current consumption in Autonomous mode**

Symbol	Parameter	Conditions	f <sub>rcc_c_ck</sub> (MHz)	Typ LDO regulator ON	Typ SMPS ON	Unit	
I <sub>DD</sub>	Supply current in Autonomous mode	Run, D1Stop, D2Stop	VOS3	64	3.6	2.2	mA
		Run, D1Standby, D2Standby	VOS3	64	2.6	1.6	

**Table 28. Typical current consumption in Sleep mode**

Symbol	Parameter	Conditions	f <sub>rcc_c_ck</sub> (MHz)	Typ LDO regulator ON	Typ SMPS ON	Max LDO regulator ON <sup>(1)(2)</sup>					Max SMPS ON <sup>(3)</sup>	Unit
						T <sub>J</sub> = 25 °C	T <sub>J</sub> = 85 °C	T <sub>J</sub> = 105 °C	T <sub>J</sub> = 125 °C	T <sub>J</sub> = 140 °C		
I <sub>DD(Sleep)</sub>	Supply current in Sleep mode	All peripherals disabled	VOS0 <sup>(4)</sup>	550	36	20.5	-	-	-	-	-	mA
				520	33.5	19.5	60	170	240	-	-	
			VOS0	520	33.5	19.5	60	170	240	-	-	
				400	27	16	52	160	230	-	-	
			VOS1	400	22.5	12.5	39	110	170	240	140	
				300	18.5	10.5	34	110	160	240	140	
			VOS2	300	16.5	8.75	28	85	130	190	110	
				170	9.7	5.2	21	78	120	190	110	
			VOS3	170	8.5	4.35	17	61	96	150	74	

1. Guaranteed by characterization results.
2. Refer to [Section 6.3.3: SMPS step-down converter](#) for the SMPS maximum consumption.
3. The parameter values given in the above table for the SMPS regulator are extrapolated from the LDO consumption and typical SMPS efficiency factors.
4. CPU\_FREQ\_BOOST is enabled.

**Table 29. Typical current consumption in System Stop mode**

Symbol	Parameter	Conditions	Typ LDO regulator ON	Typ SMPS ON	Max LDO regulator ON <sup>(1)(2)</sup>					Max SMPS ON <sup>(3)</sup>	Unit
					T <sub>J</sub> = 25 °C	T <sub>J</sub> = 85 °C	T <sub>J</sub> = 105 °C	T <sub>J</sub> = 125 °C	T <sub>J</sub> = 140 °C		
I <sub>DD(Stop)</sub>	Supply current in Stop and DStop modes	Flash memory in low power mode	SVOS5	0.52	0.2	3.7	26	44	72	50	mA
			SVOS4	0.81	0.35	6.1	39	64	110	70	
			SVOS3	1.15	0.515	8.6	51	82	130	100	
		Flash memory in normal mode	SVOS5	0.535	0.205	3.7	26	44	72	50	
			SVOS4	0.96	0.475	6.2	39	64	110	75	
			SVOS3	1.45	0.645	8.8	51	83	130	100	

1. Guaranteed by characterization results.
2. Refer to [Section 6.3.3: SMPS step-down converter](#) for the SMPS maximum consumption.
3. The parameter values given in the above table for the SMPS regulator are extrapolated from the LDO consumption and typical SMPS efficiency factors.

**Table 30. Typical current consumption in Standby mode**

Symbol	Parameter	Conditions		Typ <sup>(1)</sup>				Max at 3.6 V with LDO regulator ON <sup>(2)</sup>				Max at 3.6 V with SMPS ON <sup>(3)</sup>	Unit
		Backup SRAM	RTC and LSE <sup>(4)</sup>	1.65 V	2.4 V	3 V	3.3 V	T <sub>J</sub> = 25 °C	T <sub>J</sub> = 85 °C	T <sub>J</sub> = 105 °C	T <sub>J</sub> = 125 °C		
I <sub>DD</sub> (Standby)	Supply current in Standby mode, IWDG OFF	OFF	OFF	2.2	2.35	2.5	2.8	-	-	-	-	-	µA
		ON	OFF	3.5	3.7	4	4.3	-	-	-	-		
		OFF	ON	2.2	2.4	2.85	3.25	4.5	15	30	64	96	
		ON	ON	3.5	3.8	4.35	4.75	8.3	39	75	140	180	

1. These values are given for PDR OFF. When the PDR is ON, the typical current consumption is increased (refer to [Table 19: Reset and power control block characteristics](#)).
2. Guaranteed by characterization results.
3. The parameter values given in the above table for the SMPS regulator are extrapolated from the LDO consumption and typical SMPS efficiency factors.
4. The LSE is in Low-drive mode.

Table 31. Typical and maximum current consumption in V<sub>BAT</sub> mode

Symbol	Parameter	Conditions		Typ				Max at 3.6 V with LDO regulator ON <sup>(1)(2)</sup>				Max at 3.6 V with SMPS ON <sup>(1)(2)</sup>	Unit
		Back-up SRAM	RTC and LSE <sup>(3)</sup>	1.2 V	2 V	3 V	3.3 V	T <sub>J</sub> = 25 °C	T <sub>J</sub> = 85 °C	T <sub>J</sub> = 105 °C	T <sub>J</sub> = 125 °C	T <sub>J</sub> = 140 °C	
I <sub>DD</sub> (VBAT)	Supply current in VBAT mode	OFF	OFF	0.008	0.01	0.025	0.05	0.3	3.1	7.4	18	34	µA
		ON	OFF	1.5	1.7	1.9	1.9	4	28	53	91	110	
		OFF	ON	0.4	0.5	0.75	0.8	-	-	-	-	-	
		ON	ON	1.8	2.1	2.8	3.2	-	-	-	-	-	

1. Guaranteed by characterization results.
2. The LDO regulator is used before switching to V<sub>BAT</sub> mode.
3. The LSE is in Low-drive mode.

Typical SMPS efficiency versus load current and temperature

Figure 17. Typical SMPS efficiency (%) vs load current (A) in Run mode at T<sub>J</sub> = 30 °C

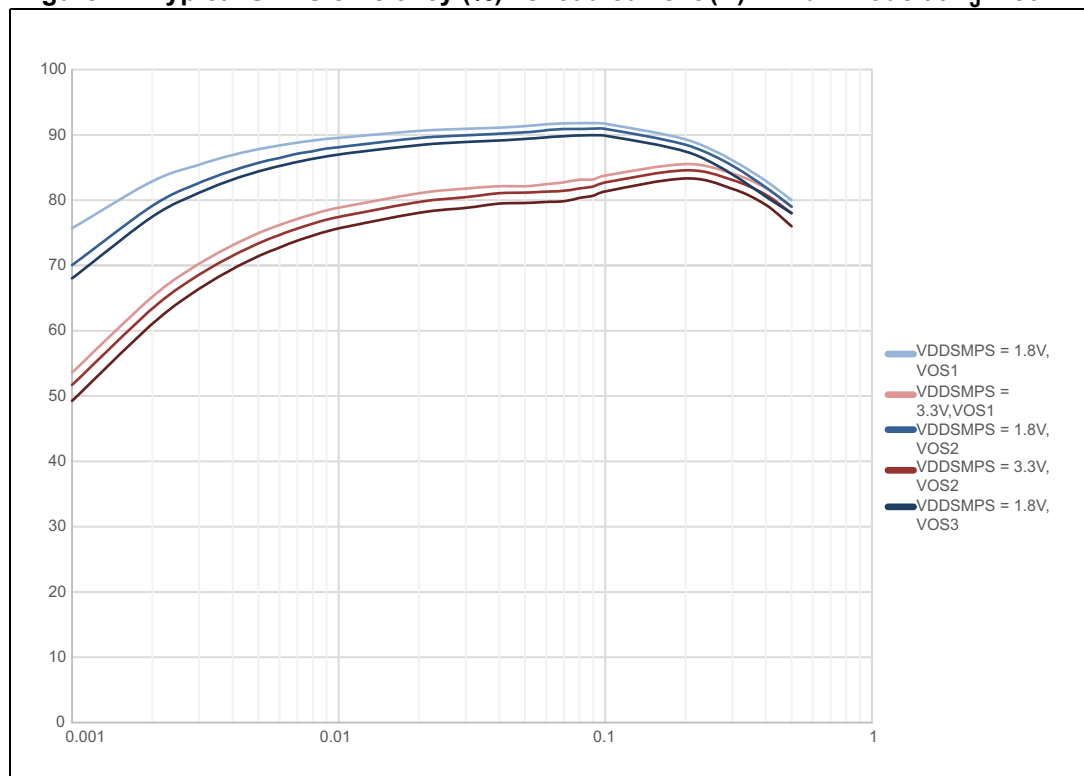


Figure 18. Typical SMPS efficiency (%) vs load current (A) in Run mode at  $T_J = T_{Jmax}$

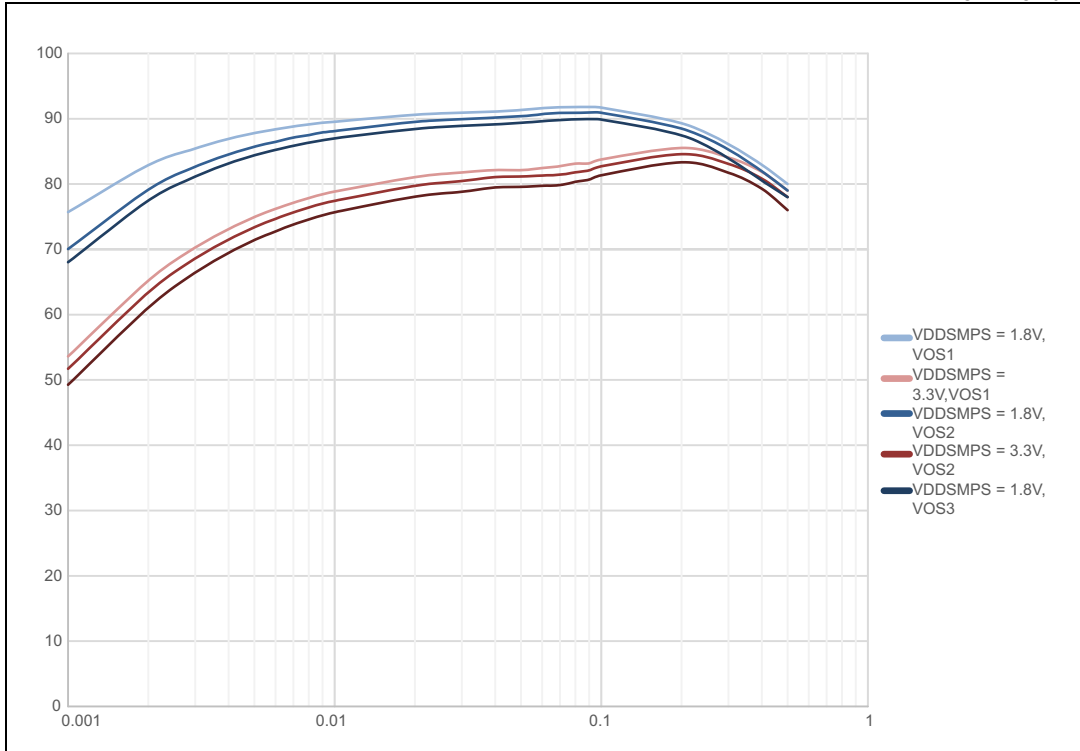
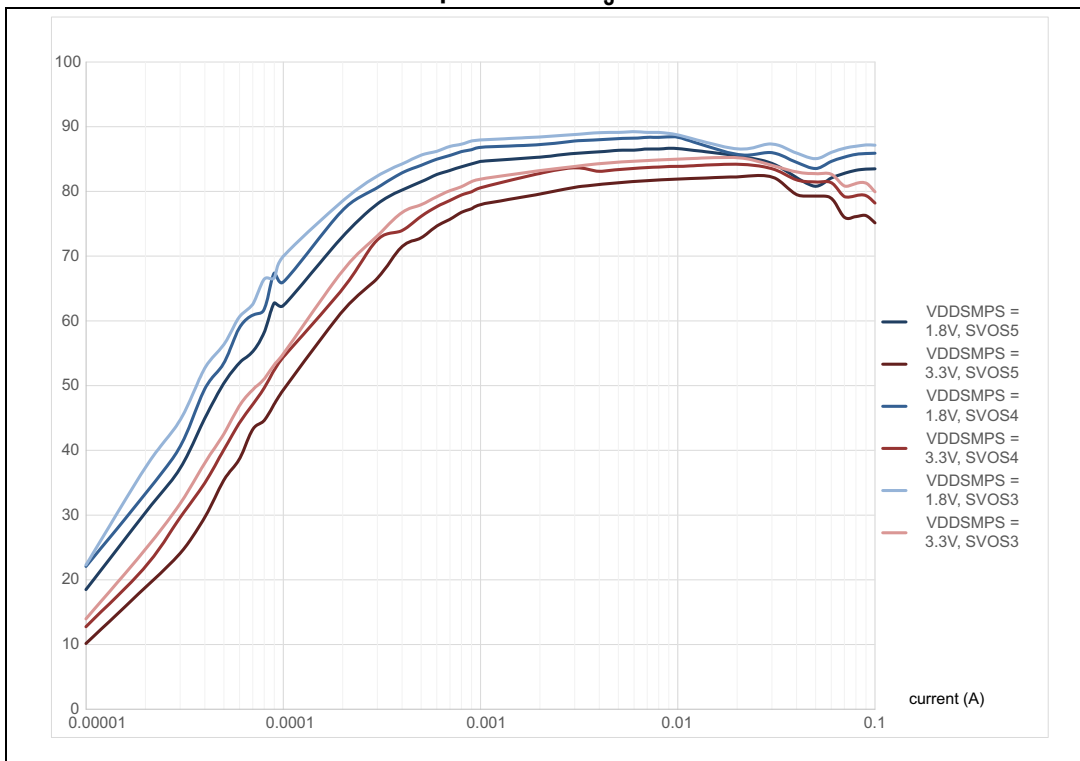
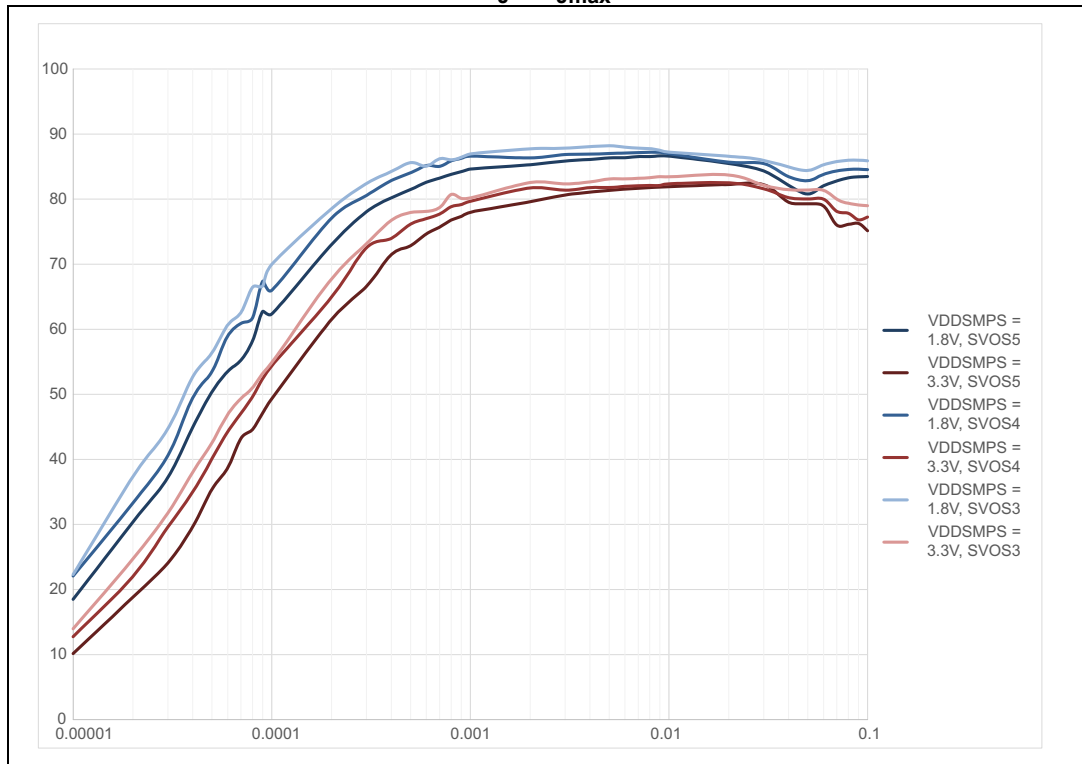


Figure 19. Typical SMPS efficiency (%) vs load current (A) in Stop and DStop modes at  $T_J = 30\text{ }^\circ\text{C}$



**Figure 20. Typical SMPS efficiency (%) vs load current (A) in low-power mode at  $T_J = T_{Jmax}$**



**I/O system current consumption**

The current consumption of the I/O system has two components: static and dynamic.

**I/O static current consumption**

All the I/Os used as inputs with pull-up generate a current consumption when the pin is externally held low. The value of this current consumption can be simply computed by using the pull-up/pull-down resistors values given in [Table 53: I/O static characteristics](#).

For the output pins, any external pull-down or external load must also be considered to estimate the current consumption.

An additional I/O current consumption is due to I/Os configured as inputs if an intermediate voltage level is externally applied. This current consumption is caused by the input Schmitt trigger circuits used to discriminate the input value. Unless this specific configuration is required by the application, this supply current consumption can be avoided by configuring these I/Os in analog mode. This is notably the case of ADC input pins which should be configured as analog inputs.

**Caution:** Any floating input pin can also settle to an intermediate voltage level or switch inadvertently, as a result of external electromagnetic noise. To avoid a current consumption related to floating pins, they must either be configured in analog mode, or forced internally to a definite digital value. This can be done either by using pull-up/down resistors or by configuring the pins in output mode.

**I/O dynamic current consumption**

In addition to the internal peripheral current consumption, the I/Os used by an application also contribute to the current consumption. When an I/O pin switches, it uses the current from the MCU supply voltage to supply the I/O pin circuitry and to charge/discharge the capacitive load (internal or external) connected to the pin:

$$I_{SW} = V_{DDX} \times f_{SW} \times C_L$$

where

$I_{SW}$  is the current sunk by a switching I/O to charge/discharge the capacitive load

$V_{DDX}$  is the MCU supply voltage

$f_{SW}$  is the I/O switching frequency

$C_L$  is the total capacitance seen by the I/O pin:  $C = C_{INT} + C_{EXT}$

The test pin is configured in push-pull output mode and is toggled by software at a fixed frequency.

### 6.3.9 Wakeup time from low-power modes

The wakeup times given in [Table 32](#) are measured starting from the wakeup event trigger up to the first instruction executed by the CPU:

- For Stop or Sleep modes: the wakeup event is WFE.
- WKUP (PC1) pin is used to wakeup from Standby, Stop and Sleep modes.

All timings are derived from tests performed under ambient temperature and  $V_{DD}=3.3$  V.

**Table 32. Low-power mode wakeup timings**

Symbol	Parameter	Conditions	Typ <sup>(1)</sup>	Max <sup>(1)</sup> (2)	Unit
$t_{WUSLEEP}^{(3)}$	Wakeup from Sleep	-	14.00	15.00	CPU clock cycles
$t_{WUSTOP}^{(3)}$	Wakeup from Stop mode	SVOS3, HSI, Flash memory in Normal mode	4.6	6.2	μs
		SVOS3, HSI, Flash memory in low-power mode	12.4	17.4	
		SVOS4, HSI, Flash memory in Normal mode	15.5	21.1	
		SVOS4, HSI, Flash memory in low-power mode	23.3	31.8	
		SVOS5, HSI, Flash memory in Normal mode	39.1	52.6	
		SVOS5, HSI, Flash memory in low-power mode	39.1	52.7	
		SVOS3, CSI, Flash memory in Normal mode	30.0	41.6	
		SVOS3, CSI, Flash memory in low power mode	40.6	55.0	
		SVOS4, CSI, Flash memory in Normal mode	41.0	55.4	
		SVOS4, CSI, Flash memory in low-power mode	51.5	68.8	
		SVOS5, CSI, Flash memory in Normal mode	67.3	89.5	
		SVOS5, CSI, Flash memory in low-power mode	67.2	89.5	
$t_{WUSTDBY}^{(3)}$	Wakeup from Standby mode	-	400.0	504.3	

1. Guaranteed by characterization results.
2. The maximum values have been measured at -40 °C, in worst conditions.
3. The wakeup times are measured from the wakeup event to the point in which the application code reads the first



### 6.3.10 External clock source characteristics

#### High-speed external user clock generated from an external source

In bypass mode the HSE oscillator is switched off and the input pin is a standard I/O.

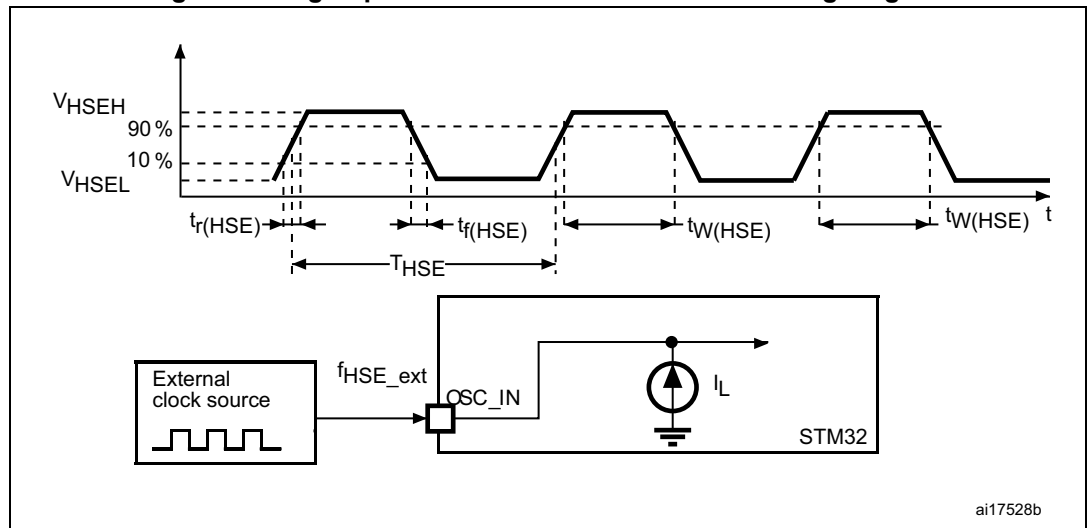
The external clock signal has to respect the [Table 53: I/O static characteristics](#). However, the recommended clock input waveform is shown in [Figure 21](#).

**Table 33. High-speed external user clock characteristics<sup>(1)</sup>**

Symbol	Parameter	Min	Typ	Max	Unit
$f_{HSE\_ext}$	User external clock source frequency	4	25	50	MHz
$V_{SW}$ ( $V_{HSEH} - V_{HSEL}$ )	OSC_IN amplitude	$0.7V_{DD}$	-	$V_{DD}$	V
$V_{DC}$	OSC_IN input voltage	$V_{SS}$	-	$0.3V_{SS}$	
$t_{W(HSE)}$	OSC_IN high or low time	7	-	-	ns

1. Guaranteed by design.

**Figure 21. High-speed external clock source AC timing diagram**



**Low-speed external user clock generated from an external source**

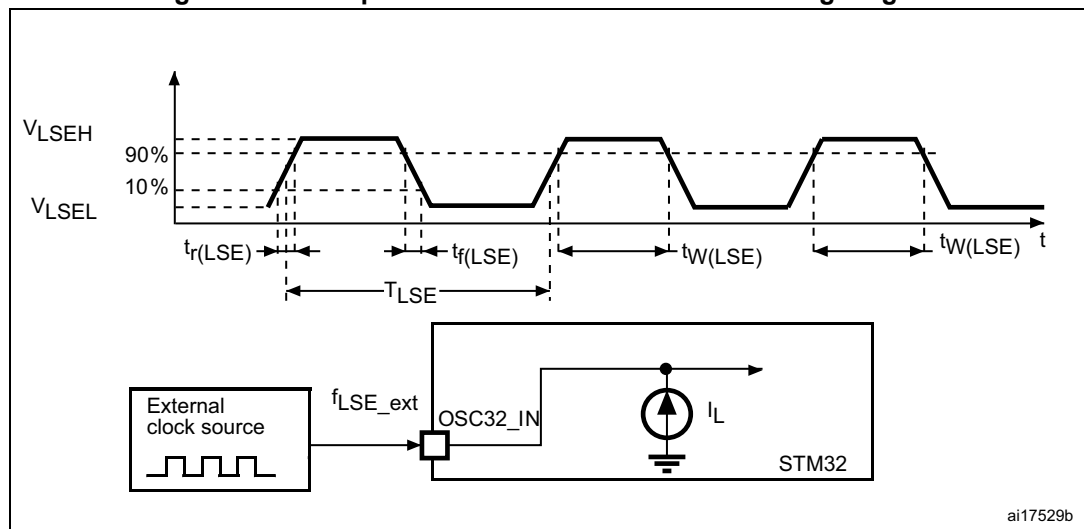
In bypass mode the LSE oscillator is switched off and the input pin is a standard I/O. The external clock signal has to respect the [Table 53: I/O static characteristics](#). However, the recommended clock input waveform is shown in [Figure 22](#).

**Table 34. Low-speed external user clock characteristics<sup>(1)</sup>**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{LSE\_ext}$	User external clock source frequency	-	-	32.768	1000	kHz
$V_{LSEH}$	OSC32_IN input pin high level voltage	-	$0.7 V_{DD}$	-	$V_{DD}$	V
$V_{LSEL}$	OSC32_IN input pin low level voltage	-	$V_{SS}$	-	$0.3 V_{DD}$	
$t_{w(LSEH)}$ $t_{w(LSEL)}$	OSC32_IN high or low time	-	250	-	-	ns

1. Guaranteed by design.

**Figure 22. Low-speed external clock source AC timing diagram**



### High-speed external clock generated from a crystal/ceramic resonator

The high-speed external (HSE) clock can be supplied with a 4 to 50 MHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on characterization results obtained with typical external components specified in [Table 35](#). In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

**Table 35. 4-50 MHz HSE oscillator characteristics<sup>(1)</sup>**

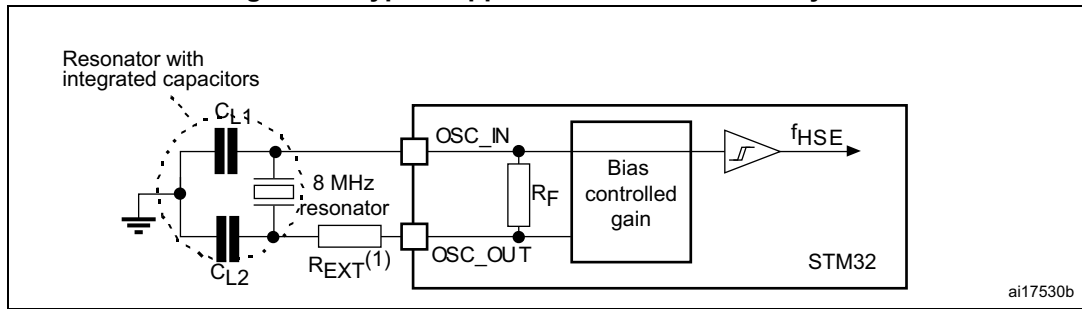
Symbol	Parameter	Operating conditions <sup>(2)</sup>	Min	Typ	Max	Unit
F	Oscillator frequency	-	4	-	50	MHz
R <sub>F</sub>	Feedback resistor	-	-	200	-	kΩ
I <sub>DD(HSE)</sub>	HSE current consumption	During startup <sup>(3)</sup>	-	-	4	mA
		V <sub>DD</sub> =3 V, R <sub>m</sub> =30 Ω C <sub>L</sub> =10 pF at 4 MHz	-	0.35	-	
		V <sub>DD</sub> =3 V, R <sub>m</sub> =30 Ω C <sub>L</sub> =10 pF at 8 MHz	-	0.40	-	
		V <sub>DD</sub> =3 V, R <sub>m</sub> =30 Ω C <sub>L</sub> =10 pF at 16 MHz	-	0.45	-	
		V <sub>DD</sub> =3 V, R <sub>m</sub> =30 Ω C <sub>L</sub> =10 pF at 32 MHz	-	0.65	-	
		V <sub>DD</sub> =3 V, R <sub>m</sub> =30 Ω C <sub>L</sub> =10 pF at 48 MHz	-	0.95	-	
G <sub>m</sub> <sub>critmax</sub>	Maximum critical crystal gm	Startup	-	-	1.5	mA/V
t <sub>SU</sub> <sup>(4)</sup>	Start-up time	V <sub>DD</sub> is stabilized	-	2	-	ms

1. Guaranteed by design.
2. Resonator characteristics given by the crystal/ceramic resonator manufacturer.
3. This consumption level occurs during the first 2/3 of the t<sub>SU(HSE)</sub> startup time.
4. t<sub>SU(HSE)</sub> is the startup time measured from the moment it is enabled (by software) to a stabilized 8 MHz oscillation is reached. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer.

For C<sub>L1</sub> and C<sub>L2</sub>, it is recommended to use high-quality external ceramic capacitors in the 5 pF to 25 pF range (typical), designed for high-frequency applications, and selected to match the requirements of the crystal or resonator (see [Figure 23](#)). C<sub>L1</sub> and C<sub>L2</sub> are usually the same size. The crystal manufacturer typically specifies a load capacitance which is the series combination of C<sub>L1</sub> and C<sub>L2</sub>. The PCB and MCU pin capacitance must be included (10 pF can be used as a rough estimate of the combined pin and board capacitance) when sizing C<sub>L1</sub> and C<sub>L2</sub>.

**Note:** For information on selecting the crystal, refer to application note AN2867 "Oscillator design guide for ST microcontrollers" available from the ST website [www.st.com](http://www.st.com).

Figure 23. Typical application with an 8 MHz crystal



1.  $R_{EXT}$  value depends on the crystal characteristics.

**Low-speed external clock generated from a crystal/ceramic resonator**

The low-speed external (LSE) clock can be supplied with a 32.768 kHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on characterization results obtained with typical external components specified in [Table 36](#). In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

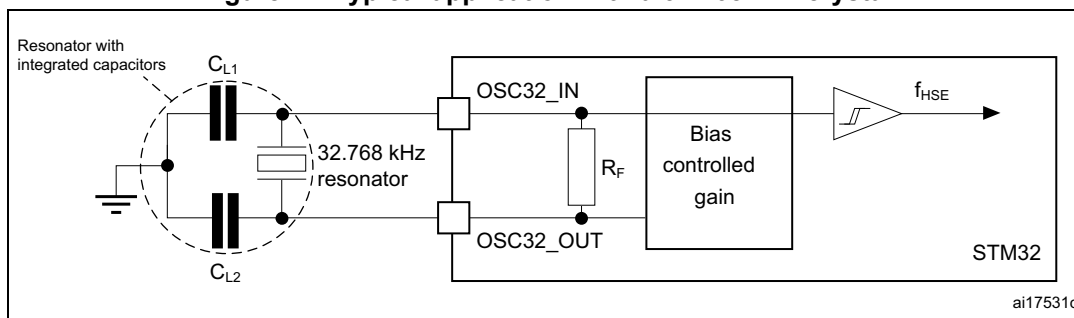
Table 36. Low-speed external user clock characteristics<sup>(1)</sup>

Symbol	Parameter	Operating conditions <sup>(2)</sup>	Min	Typ	Max	Unit
F	Oscillator frequency	-	-	32.768	-	kHz
$I_{DD}$	LSE current consumption	LSEDRV[1:0] = 00, Low drive capability	-	290	-	nA
		LSEDRV[1:0] = 01, Medium Low drive capability	-	390	-	
		LSEDRV[1:0] = 10, Medium high drive capability	-	550	-	
		LSEDRV[1:0] = 11, High drive capability	-	900	-	
$G_{m_{critmax}}$	Maximum critical crystal gm	LSEDRV[1:0] = 00, Low drive capability	-	-	0.5	$\mu A/V$
		LSEDRV[1:0] = 01, Medium Low drive capability	-	-	0.75	
		LSEDRV[1:0] = 10, Medium high drive capability	-	-	1.7	
		LSEDRV[1:0] = 11, High drive capability	-	-	2.7	
$t_{SU}^{(3)}$	Startup time	VDD is stabilized	-	2	-	s

1. Guaranteed by design.
2. Refer to the note and caution paragraphs below the table, and to the application note AN2867 "Oscillator design guide for ST microcontrollers".
3.  $t_{SU}$  is the startup time measured from the moment it is enabled (by software) to a stabilized 32.768k Hz oscillation is reached. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer.

Note: For information on selecting the crystal, refer to the application note AN2867 “Oscillator design guide for ST microcontrollers” available from the ST website [www.st.com](http://www.st.com).

Figure 24. Typical application with a 32.768 kHz crystal



1. An external resistor is not required between OSC32\_IN and OSC32\_OUT and it is forbidden to add one.

### 6.3.11 Internal clock source characteristics

The parameters given in [Table 37](#) to [Table 39](#) are derived from tests performed under ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 12: General operating conditions](#).

#### 48 MHz high-speed internal RC oscillator (HSI48)

Table 37. HSI48 oscillator characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{HSI48}$	HSI48 frequency	$V_{DD}=3.3\text{ V}$ , $T_J=30\text{ °C}$	47.5 <sup>(1)</sup>	48	48.5 <sup>(1)</sup>	MHz
TRIM <sup>(2)</sup>	USER trimming step	-	-	0.175	0.250	%
USER TRIM COVERAGE <sup>(3)</sup>	USER TRIMMING coverage	$\pm 32$ steps	$\pm 4.70$	$\pm 5.6$	-	%
DuCy(HSI48) <sup>(2)</sup>	Duty Cycle	-	45	-	55	%
ACCCHSI48_REL <sup>(3)(4)</sup>	Accuracy of the HSI48 oscillator over temperature (factory calibrated)	$T_J=-40$ to $125\text{ °C}$	-4.5	-	3.5	%
$\Delta V_{DD}(\text{HSI48})^{(2)(5)}$	HSI48 oscillator frequency drift with $V_{DD}^{(6)}$ (the reference is 3.3 V)	$V_{DD}=3$ to $3.6\text{ V}$ $V_{DD}=1.62\text{ V}$ to $3.6\text{ V}$	-	0.025 0.05	0.05 0.1	%
$t_{su}(\text{HSI48})^{(2)}$	HSI48 oscillator start-up time	-	-	2.1	4.0	$\mu\text{s}$
$I_{DD}(\text{HSI48})^{(2)}$	HSI48 oscillator power consumption	-	-	350	400	$\mu\text{A}$
$N_T$ jitter <sup>(2)</sup>	Next transition jitter Accumulated jitter on 28 cycles <sup>(7)</sup>	-	-	$\pm 0.15$	-	ns
$P_T$ jitter <sup>(2)</sup>	Paired transition jitter Accumulated jitter on 56 cycles <sup>(7)</sup>	-	-	$\pm 0.25$	-	ns

1. Guaranteed by test in production.
2. Guaranteed by design.
3. Guaranteed by characterization results.
4.  $\Delta f_{HSI} = \text{ACCCHSI48\_REL} + \Delta V_{DD}$ .

5.  $\Delta f_{\text{HSI}} = \text{ACCHSI48\_REL} + \Delta V_{\text{DD}}$ .
6. These values are obtained by using the formula:  $(\text{Freq}(3.6 \text{ V}) - \text{Freq}(3.0 \text{ V})) / \text{Freq}(3.0 \text{ V})$  or  $(\text{Freq}(3.6 \text{ V}) - \text{Freq}(1.62 \text{ V})) / \text{Freq}(1.62 \text{ V})$ .
7. Jitter measurements are performed without clock source activated in parallel.

**64 MHz high-speed internal RC oscillator (HSI)**

**Table 38. HSI oscillator characteristics<sup>(1)</sup>**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{\text{HSI}}$	HSI frequency	$V_{\text{DD}}=3.3 \text{ V}, T_{\text{J}}=30 \text{ }^\circ\text{C}$	63.7 <sup>(2)</sup>	64	64.3 <sup>(2)</sup>	MHz
TRIM	HSI user trimming step	Trimming is not a multiple of 32	-	0.24	0.32	%
		Trimming is 128, 256 and 384	-5.2	-1.8	-	
		Trimming is 64, 192, 320 and 448	-1.4	-0.8	-	
		Other trimming are a multiple of 32 (not including multiple of 64 and 128)	-0.6	-0.25	-	
DuCy(HSI)	Duty cycle	-	45	-	55	%
$\Delta V_{\text{DD}}(\text{HSI})$	HSI oscillator frequency drift over $V_{\text{DD}}$ (the reference is 3.3 V)	$V_{\text{DD}}=1.62 \text{ to } 3.6 \text{ V}$	-0.12	-	0.03	%
$\Delta T_{\text{EMP}}(\text{HSI})$	HSI oscillator frequency drift over temperature (the reference is 64 MHz)	$T_{\text{J}}=-20 \text{ to } 105 \text{ }^\circ\text{C}$	-1 <sup>(3)</sup>	-	1 <sup>(3)</sup>	%
		$T_{\text{J}}=-40 \text{ to } T_{\text{Jmax}} \text{ }^\circ\text{C}$	-2 <sup>(3)</sup>	-	1 <sup>(3)</sup>	
$t_{\text{su}}(\text{HSI})$	HSI oscillator start-up time	-	-	1.4	2	$\mu\text{s}$
$t_{\text{stab}}(\text{HSI})$	HSI oscillator stabilization time	at 1% of target frequency	-	4	8	
		at 5% of target frequency	-	-	4	
$I_{\text{DD}}(\text{HSI})$	HSI oscillator power consumption	-	-	300	400	$\mu\text{A}$

1. Guaranteed by design unless otherwise specified.
2. Guaranteed by test in production.
3. Guaranteed by characterization results.

## 4 MHz low-power internal RC oscillator (CSI)

Table 39. CSI oscillator characteristics<sup>(1)</sup>

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{\text{CSI}}$	CSI frequency	$V_{\text{DD}}=3.3\text{ V}$ , $T_{\text{J}}=30\text{ °C}$	3.96 <sup>(2)</sup>	4	4.04 <sup>(2)</sup>	MHz
TRIM	CSI trimming step	Trimming is not a multiple of 16	-	0.40	0.75	%
		Trimming is a multiple of 32	-4.75	-2.75	0.75	
		Other trimming values not multiple of 16 (excluding multiple of 32)	-0.43	0.00	0.75	
DuCy(CSI)	Duty cycle	-	45	-	55	%
$\Delta_{\text{TEMP}}$ (CSI)	CSI oscillator frequency drift over temperature	$T_{\text{J}} = 0\text{ to }85\text{ °C}$	-3.7 <sup>(3)</sup>	-	4.5 <sup>(3)</sup>	%
		$T_{\text{J}} = -40\text{ to }125\text{ °C}$	-11 <sup>(3)</sup>	-	7.5 <sup>(3)</sup>	
$\Delta_{\text{VDD}}$ (CSI)	CSI oscillator frequency drift over $V_{\text{DD}}$	$V_{\text{DD}} = 1.62\text{ to }3.6\text{ V}$	-0.06	-	0.06	%
$t_{\text{su}}$ (CSI)	CSI oscillator startup time	-	-	1	2	$\mu\text{s}$
$t_{\text{stab}}$ (CSI)	CSI oscillator stabilization time (to reach $\pm 3\%$ of $f_{\text{CSI}}$ )	-	-	-	4	cycle
$I_{\text{DD}}$ (CSI)	CSI oscillator power consumption	-	-	23	30	$\mu\text{A}$

1. Guaranteed by design, unless otherwise specified.
2. Guaranteed by test in production.
3. Guaranteed by characterization results.

## Low-speed internal (LSI) RC oscillator

Table 40. LSI oscillator characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{\text{LSI}}$	LSI frequency	$V_{\text{DD}} = 3.3\text{ V}$ , $T_{\text{J}} = 25\text{ °C}$	31.4 <sup>(1)</sup>	32	32.6 <sup>(1)</sup>	kHz
		$T_{\text{J}} = -40\text{ to }110\text{ °C}$ , $V_{\text{DD}} = 1.62\text{ to }3.6\text{ V}$	29.76 <sup>(2)</sup>	-	33.6 <sup>(2)</sup>	
		$T_{\text{J}} = -40\text{ to }125\text{ °C}$ , $V_{\text{DD}} = 1.62\text{ to }3.6\text{ V}$	29.4 <sup>(2)</sup>	-	33.6 <sup>(2)</sup>	
$t_{\text{su}}$ (LSI) <sup>(3)</sup>	LSI oscillator startup time	-	-	80	130	$\mu\text{s}$
$t_{\text{stab}}$ (LSI) <sup>(3)</sup>	LSI oscillator stabilization time (5% of final value)	-	-	120	170	
$I_{\text{DD}}$ (LSI) <sup>(3)</sup>	LSI oscillator power consumption	-	-	130	280	nA

1. Guaranteed by test in production.
2. Guaranteed by characterization results.
3. Guaranteed by design.

6.3.12 PLL characteristics

The parameters given in [Table 41](#), [Table 44](#) are derived from tests performed under temperature and V<sub>DD</sub> supply voltage conditions summarized in [Table 12: General operating conditions](#).

Table 41. PLL1 characteristics (wide VCO frequency range)<sup>(1)</sup>

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
f <sub>PLL_IN</sub>	PLL input clock	-	2	-	16	MHz	
	PLL input clock duty cycle	-	10	-	90	%	
f <sub>PLL_P_OUT</sub>	PLL multiplier output clock P	VOS0	1.5	-	550 <sup>(2)</sup>	MHz	
		VOS1	1.5	-	400 <sup>(2)</sup>		
		VOS2	1.5	-	300 <sup>(2)</sup>		
		VOS3	1.5	-	170 <sup>(2)</sup>		
f <sub>VCO_OUT</sub>	PLL VCO output	-	192	-	836 <sup>(3)</sup>		
t <sub>LOCK</sub>	PLL lock time	Normal mode	15	50	150 <sup>(3)</sup>	µs	
		Sigma-delta mode (CKIN ≥ 8 MHz)	25	65	170		
Jitter	Cycle-to-cycle jitter <sup>(4)</sup>	f <sub>PLL_OUT</sub> = f <sub>VCO_OUT</sub> /100	f <sub>VCO_OUT</sub> = 192 MHz	-	51	-	ps
			f <sub>VCO_OUT</sub> = 400 MHz	-	19	-	
			f <sub>VCO_OUT</sub> = 560 MHz	-	10	-	
			f <sub>VCO_OUT</sub> = 800 MHz	-	9	-	
	Period jitter		f <sub>VCO_OUT</sub> = 192 MHz	-	38	-	
			f <sub>VCO_OUT</sub> = 560 MHz	-	8	-	
			f <sub>VCO_OUT</sub> = 800 MHz	-	7	-	
			Long term jitter	Normal mode (CKIN = 2 MHz)	f <sub>VCO_OUT</sub> = 192 MHz	-	
	f <sub>VCO_OUT</sub> = 400 MHz	-			0.14	-	
	f <sub>VCO_OUT</sub> = 832 MHz	-			0.16	-	
	Sigma-delta mode (CKIN = 16 MHz)	f <sub>VCO_OUT</sub> = 192 MHz		-	0.17	-	
		f <sub>VCO_OUT</sub> = 500 MHz		-	0.08	-	
f <sub>VCO_OUT</sub> = 836 MHz		-		0.06	-		



**Table 41. PLL1 characteristics (wide VCO frequency range)<sup>(1)</sup> (continued)**

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
I <sub>DD(PLL)</sub>	PLL power consumption	f <sub>VCO_OUT</sub> = 560 MHz	V <sub>DDA</sub>	530	557	670	μA
			V <sub>CORE</sub>	1190	1285	6300	
		f <sub>VCO_OUT</sub> = 192 MHz	V <sub>DDA</sub>	260	286	513	
			V <sub>CORE</sub>	309	377	5700	

1. Guaranteed by design unless otherwise specified.
2. This value must be limited to the maximum frequency due to the product limitation.
3. Guaranteed by characterization results.
4. Integer mode only.

**Table 42. PLL1 characteristics (medium VCO frequency range)<sup>(1)</sup>**

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
f <sub>PLL_IN</sub>	PLL input clock	-		1	-	2	MHz
	PLL input clock duty cycle	-		10	-	90	%
f <sub>PLL_OUT</sub>	PLL multiplier output clock P, Q, R	VOS0		1.17	-	210	MHz
		VOS1		1.17	-	210	
		VOS2		1.17	-	210	
		VOS3		1.17	-	200	
f <sub>VCO_OUT</sub>	PLL VCO output	-		150	-	420	
t <sub>LOCK</sub>	PLL lock time	Normal mode		-	60 <sup>(2)</sup>	100 <sup>(2)</sup>	μs
		Sigma-delta mode		forbidden			
Jitter	Cycle-to-cycle jitter <sup>(3)</sup>	-	f <sub>VCO_OUT</sub> = 150 MHz	-	145	-	±ps
			f <sub>VCO_OUT</sub> = 300 MHz	-	91	-	
			f <sub>VCO_OUT</sub> = 400 MHz	-	64	-	
			f <sub>VCO_OUT</sub> = 420 MHz	-	63	-	
	Period jitter	f <sub>PLL_OUT</sub> = 50 MHz	f <sub>VCO_OUT</sub> = 150 MHz	-	55	-	±ps
			f <sub>VCO_OUT</sub> = 400 MHz	-	30	-	
Long term jitter	Normal mode	f <sub>VCO_OUT</sub> = 400 MHz	-	±0.3	-	%	
I(PLL)	PLL power consumption on V <sub>DD</sub>	f <sub>VCO_OUT</sub> = 420 MHz	VDD	-	440	1150	μA
			V <sub>CORE</sub>	-	530	-	
		f <sub>VCO_OUT</sub> = 150 MHz	VDD	-	180	500	
			V <sub>CORE</sub>	-	200	-	

1. Guaranteed by design unless otherwise specified.
2. Guaranteed by characterization results.
3. Integer mode only.

**Table 43. PLL2 and PLL3 characteristics (wide VCO frequency range)<sup>(1)</sup>**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
f <sub>PLL_IN</sub>	PLL input clock	-	2	-	16	MHz	
	PLL input clock duty cycle	-	10	-	90	%	
f <sub>PLL_OUT</sub>	PLL multiplier output clock P, Q, R	VOS0	1.5	-	550 <sup>(2)</sup>	MHz	
		VOS1	1.5	-	400 <sup>(2)</sup>		
		VOS2	1.5	-	300 <sup>(2)</sup>		
		VOS3	1.5	-	170 <sup>(2)</sup>		
f <sub>VCO_OUT</sub>	PLL VCO output	-	192	-	960 <sup>(3)</sup>		
t <sub>LOCK</sub>	PLL lock time	Normal mode	-	50	150 <sup>(3)</sup>	µs	
		Sigma-delta mode (f <sub>PLL_IN</sub> ≥ 8 MHz)	-	58	166 <sup>(3)</sup>		
Jitter	Cycle-to-cycle jitter <sup>(4)</sup>	f <sub>VCO_OUT</sub> = 192 MHz	-	134	-	±ps	
		f <sub>VCO_OUT</sub> = 200 MHz	-	134	-		
		f <sub>VCO_OUT</sub> = 400 MHz	-	76	-		
		f <sub>VCO_OUT</sub> = 800 MHz	-	39	-		
	Long term jitter	Normal mode (f <sub>PLL_IN</sub> = 2 MHz)	f <sub>VCO_OUT</sub> = 560 MHz	-	±0.2	-	%
		Normal mode (f <sub>PLL_IN</sub> = 16 MHz)	f <sub>VCO_OUT</sub> = 560 MHz	-	±0.8	-	
		Sigma-delta mode (f <sub>PLL_IN</sub> = 2 MHz)	f <sub>VCO_OUT</sub> = 560 MHz	-	±0.2	-	
		Sigma-delta mode (f <sub>PLL_IN</sub> = 16 MHz)	f <sub>VCO_OUT</sub> = 560 MHz	-	±0.8	-	
I <sub>DD(PLL)</sub> <sup>(3)</sup>	PLL power consumption	f <sub>VCO_OUT</sub> = 836 MHz	V <sub>DD</sub>	-	590	1500	µA
			V <sub>CORE</sub>	-	720	-	
		f <sub>VCO_OUT</sub> = 192 MHz	V <sub>DD</sub>	-	180	600	
			V <sub>CORE</sub>	-	280	-	

1. Guaranteed by design unless otherwise specified.
2. This value must be limited to the maximum frequency due to the product limitation.

- 3. Guaranteed by characterization results.
- 4. Integer mode only.

**Table 44. PLL2 and PLL3 characteristics (medium VCO frequency range)<sup>(1)</sup>**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
f <sub>PLL_IN</sub>	PLL input clock	-	1	-	2	MHz	
	PLL input clock duty cycle	-	10	-	90	%	
f <sub>PLL_OUT</sub>	PLL multiplier output clock P, Q, R	VOS0	1.17	-	210	MHz	
		VOS1	1.17	-	210	-	
		VOS2	1.17	-	210	-	
		VOS3	1.17	-	200	-	
f <sub>VCO_OUT</sub>	PLL VCO output	-	150	-	420	-	
t <sub>LOCK</sub>	PLL lock time	Normal mode	-	60	100 <sup>(2)</sup>	μs	
		Sigma-delta mode	forbidden				
Jitter	Cycle-to-cycle jitter <sup>(3)</sup>	f <sub>VCO_OUT</sub> = 150 MHz	-	145	-	±ps	
		f <sub>VCO_OUT</sub> = 200 MHz	-	91	-		
		f <sub>VCO_OUT</sub> = 400 MHz	-	64	-		
		f <sub>VCO_OUT</sub> = 420 MHz	-	63	-		
	Period jitter	f <sub>PLL_OUT</sub> = 50 MHz	f <sub>VCO_OUT</sub> = 150 MHz	-	55	-	±ps
		f <sub>VCO_OUT</sub> = 400 MHz		-	30	-	
Long term jitter	Normal mode	f <sub>VCO_OUT</sub> = 400 MHz	-	±0.3	-	%	
I <sub>DD(PLL)</sub>	PLL power consumption on V <sub>DD</sub>	f <sub>VCO_OUT</sub> = 420 MHz	V <sub>DD</sub>	-	440	1150	μA
			V <sub>CORE</sub>	-	530	-	
		f <sub>VCO_OUT</sub> = 150 MHz	V <sub>DD</sub>	-	180	500	
			V <sub>CORE</sub>	-	200	-	

- 1. Guaranteed by design unless otherwise specified.
- 2. Guaranteed by characterization results.
- 3. Integer mode only.

### 6.3.13 Memory characteristics

#### Flash memory

The characteristics are given at  $T_J = -40$  to  $125$  °C unless otherwise specified.

The devices are shipped to customers with the Flash memory erased.

**Table 45. Flash memory characteristics**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$I_{DD}$	Supply current	Write / Erase 8-bit mode	-	6.5	-	mA
		Write / Erase 16-bit mode	-	11.5	-	
		Write / Erase 32-bit mode	-	20	-	
		Write / Erase 64-bit mode	-	35	-	

**Table 46. Flash memory programming**

Symbol	Parameter	Conditions	Min <sup>(1)</sup>	Typ	Max <sup>(1)</sup>	Unit
$t_{prog}$	Word (266 bits) programming time	Program/erase parallelism x 8	-	290	580 <sup>(2)</sup>	$\mu$ s
		Program/erase parallelism x 16	-	180	360	
		Program/erase parallelism x 32	-	130	260	
		Program/erase parallelism x 64	-	100	200	
$t_{ERASE}$	Sector (128 Kbytes) erase time	Program/erase parallelism x 8	-	2	4	s
		Program/erase parallelism x 16	-	1.8	3.6	
		Program/erase parallelism x 32	-	-	-	
$t_{ME}$	Mass erase time (1 Mbyte)	Program/erase parallelism x 8	-	3	26	
		Program/erase parallelism x 16	-	8	16	
		Program/erase parallelism x 32	-	6	12	
		Program/erase parallelism x 64	-	5	10	
$V_{prog}$	Programming voltage	Program parallelism x 8	1.62	-	3.6	V
		Program parallelism x 16				
		Program parallelism x 32				
		Program parallelism x 64	1.8	-	3.6	

1. Guaranteed by characterization results.
2. The maximum programming time is measured after 10K erase operations.

**Table 47. Flash memory endurance and data retention**

Symbol	Parameter	Conditions	Min <sup>(1)</sup>	Unit
$N_{END}$	Endurance	$T_J = -40$ to $+125$ °C	10	kcycles
$t_{RET}$	Data retention	1 kcycle at $T_A = 85$ °C	30	Years
		10 kcycles at $T_A = 55$ °C	20	

1. Guaranteed by characterization results.

### 6.3.14 EMC characteristics

Susceptibility tests are performed on a sample basis during device characterization.

#### Functional EMS (electromagnetic susceptibility)

While a simple application is executed on the device (toggling 2 LEDs through I/O ports), the device is stressed by two electromagnetic events until a failure occurs. The failure is indicated by the LEDs:

- **Electrostatic discharge (ESD)** (positive and negative) is applied to all device pins until a functional disturbance occurs. This test is compliant with the IEC 61000-4-2 standard.
- **FTB**: A burst of fast transient voltage (positive and negative) is applied to  $V_{DD}$  and  $V_{SS}$  through a 100 pF capacitor, until a functional disturbance occurs. This test is compliant with the IEC 61000-4-4 standard.

A device reset allows normal operations to be resumed.

The test results are given in [Table 48](#). They are based on the EMS levels and classes defined in application note AN1709 “*EMC design guide for STM8, STM32 and Legacy MCUs*”.

**Table 48. EMS characteristics**

Symbol	Parameter	Conditions	Level/Class
$V_{FESD}$	Voltage limits to be applied on any I/O pin to induce a functional disturbance	$V_{DD} = 3.3\text{ V}$ , $T_A = 25\text{ °C}$ , LQFP176, conforming to IEC 61000-4-2	3B
$V_{FTB}$	Fast transient voltage burst limits to be applied through 100 pF on $V_{DD}$ and $V_{SS}$ pins to induce a functional disturbance	$V_{DD} = 3.3\text{ V}$ , $T_A = 25\text{ °C}$ , LQFP176, conforming to IEC 61000-4-4	5A

As a consequence, it is recommended to add a serial resistor (1 k $\Omega$ ) located as close as possible to the MCU to the pins exposed to noise (connected to tracks longer than 50 mm on PCB).

#### Designing hardened software to avoid noise problems

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

#### Software recommendations

The software flowchart must include the management of runaway conditions such as:

- Corrupted program counter
- Unexpected reset
- Critical Data corruption (control registers...)

**Prequalification trials**

Most of the common failures (unexpected reset and program counter corruption) can be reproduced by manually forcing a low state on the NRST pin or the Oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring (see application note AN1015 “Software techniques for improving microcontrollers EMC performance”).

**Electromagnetic Interference (EMI)**

The electromagnetic field emitted by the device are monitored while a simple application, executing EEMBC code, is running. This emission test is compliant with SAE IEC61967-2 standard which specifies the test board and the pin loading.

**Table 49. EMI characteristics**

Symbol	Parameter	Conditions	Monitored frequency band	Max vs. [f <sub>HSE</sub> /f <sub>CPU</sub> ]	Unit
				8/550 MHz	
S <sub>EMI</sub>	Peak level	V <sub>DD</sub> = 3.6 V, T <sub>A</sub> = 25 °C, LQFP176 package, conforming to IEC61967-2	0.1 to 30 MHz	14	dBμV
			30 to 130 MHz	20	
			130 MHz to 1 GHz	27	
			1 GHz to 2 GHz	17	
			EMI Level	4	-

### 6.3.15 Absolute maximum ratings (electrical sensitivity)

Based on three different tests (ESD, LU) using specific measurement methods, the device is stressed in order to determine its performance in terms of electrical sensitivity.

#### Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse) are applied to the pins of each sample according to each pin combination. This test conforms to the ANSI/ESDA/JEDEC JS-001 and ANSI/ESDA/JEDEC JS-002 standards.

**Table 50. ESD absolute maximum ratings**

Symbol	Ratings	Conditions	Packages	Class	Maximum value <sup>(1)</sup>	Unit
V <sub>ESD(HBM)</sub>	Electrostatic discharge voltage (human body model)	T <sub>A</sub> = 25 °C conforming to ANSI/ESDA/JEDEC JS-001	Packages with SMPS	1C	1000 <sup>(2)</sup>	V
			Packages without SMPS	2	2000	
V <sub>ESD(CDM)</sub>	Electrostatic discharge voltage (charge device model)	T <sub>A</sub> = +25 °C conforming to ANSI/ESDA/JEDEC JS-002	All LQFP packages	C1	250	
			All BGA and WLCSP packages	C2a	500	

1. Guaranteed by characterization results.
2. Excluding V<sub>FBSMPS</sub>, the maximum value is 2000 V.

#### Static latchup

Two complementary static tests are required on six parts to assess the latchup performance:

- A supply overvoltage is applied to each power supply pin
- A current injection is applied to each input, output and configurable I/O pin

These tests are compliant with JESD78 IC latchup standard.

**Table 51. Electrical sensitivities**

Symbol	Parameter	Conditions	Class
LU	Static latchup class	Conforming to JESD78, T <sub>J</sub> = T <sub>JMax</sub>	II level A

### 6.3.16 I/O current injection characteristics

As a general rule, a current injection to the I/O pins, due to external voltage below  $V_{SS}$  or above  $V_{DD}$  (for standard, 3.3 V-capable I/O pins) should be avoided during the normal product operation. However, in order to give an indication of the robustness of the microcontroller in cases when an abnormal injection accidentally happens, susceptibility tests are performed on a sample basis during the device characterization.

#### Functional susceptibility to I/O current injection

While a simple application is executed on the device, the device is stressed by injecting current into the I/O pins programmed in floating input mode. While current is injected into the I/O pin, one at a time, the device is checked for functional failures.

The failure is indicated by an out of range parameter: ADC error above a certain limit (higher than 5 LSB TUE), out of conventional limits of induced leakage current on adjacent pins (out of  $-5 \mu A/+0 \mu A$  range), or other functional failure (for example reset, oscillator frequency deviation).

The following tables are the compilation of the SIC1/SIC2 and functional ESD results.

Negative induced A negative induced leakage current is caused by negative injection and positive induced leakage current by positive injection.

**Table 52. I/O current injection susceptibility<sup>(1)</sup>**

Symbol	Description	Functional susceptibility		Unit
		Negative injection	Positive injection	
I <sub>INJ</sub>	PA12, PE8	5	0	mA
	PC4, PE12, PF15, PH0	0	NA	
	PA0, PA0_C, PA1, PA1_C, PC2, PC2_C, PC3, PC3_C, PA4, PA5, PE7, PG1, PH4, PH5, BOOT0	0	0	
	All other I/Os	5	NA	

1. Guaranteed by characterization results.

### 6.3.17 I/O port characteristics

#### General input/output characteristics

Unless otherwise specified, the parameters given in [Table 53: I/O static characteristics](#) are derived from tests performed under the conditions summarized in [Table 12: General operating conditions](#). All I/Os are CMOS and TTL compliant (except for BOOT0).

*Note:* For information on GPIO configuration, refer to application note AN4899 “STM32 GPIO configuration for hardware settings and low-power consumption” available from the ST website [www.st.com](http://www.st.com).



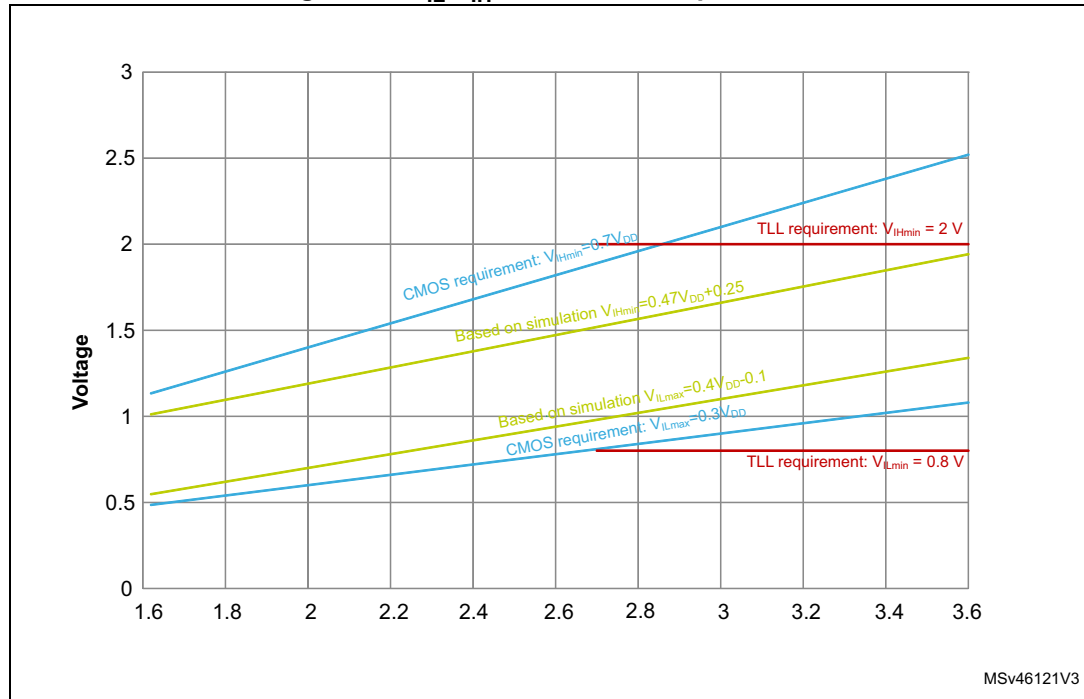
Table 53. I/O static characteristics

Symbol	Parameter	Condition	Min	Typ	Max	Unit
V <sub>IL</sub>	I/O input low level voltage except BOOT0	1.62 V < V <sub>DD</sub> < 3.6 V	-	-	0.3V <sub>DD</sub> <sup>(1)</sup>	V
	I/O input low level voltage except BOOT0		-	-	0.4V <sub>DD</sub> -0.1 <sup>(2)</sup>	
	BOOT0 I/O input low level voltage		-	-	0.19V <sub>DD</sub> +0.1 <sup>(2)</sup>	
V <sub>IH</sub>	I/O input high level voltage except BOOT0	1.62 V < V <sub>DD</sub> < 3.6 V	0.7V <sub>DD</sub> <sup>(1)</sup>	-	-	V
	I/O input high level voltage except BOOT0		0.47V <sub>DD</sub> +0.25 <sup>(2)</sup>	-	-	
	BOOT0 I/O input high level voltage		0.17V <sub>DD</sub> +0.6 <sup>(2)</sup>	-	-	
V <sub>HYS</sub> <sup>(2)</sup>	TT_xx, FT_XXX and NRST I/O input hysteresis	1.62 V < V <sub>DD</sub> < 3.6 V	-	250	-	mV
	BOOT0 I/O input hysteresis		-	200	-	
I <sub>leak</sub> <sup>(3)</sup>	FT_xx Input leakage current <sup>(2)</sup>	0 < V <sub>IN</sub> ≤ Max(V <sub>DDXXX</sub> ) <sup>(8)</sup>	-	-	+/-250	nA
		Max(V <sub>DDXXX</sub> ) < V <sub>IN</sub> ≤ 5.5 V <sup>(4)(5)(8)</sup>	-	-	1500	
	FT_u IO	0 < V <sub>IN</sub> ≤ Max(V <sub>DDXXX</sub> ) <sup>(8)</sup>	-	-	+/- 350	
		Max(V <sub>DDXXX</sub> ) < V <sub>IN</sub> ≤ 5.5 V <sup>(4)(5)(8)</sup>	-	-	5000 <sup>(6)</sup>	
	TT_xx Input leakage current	0 < V <sub>IN</sub> ≤ Max(V <sub>DDXXX</sub> ) <sup>(8)</sup>	-	-	+/-250	
	VPP (BOOT0 alternate function)	0 < V <sub>IN</sub> ≤ V <sub>DD</sub>	-	-	15	
V <sub>DD</sub> < V <sub>IN</sub> ≤ 9 V		-	-	35		
R <sub>PU</sub>	Weak pull-up equivalent resistor <sup>(7)</sup>	V <sub>IN</sub> =V <sub>SS</sub>	30	40	50	kΩ
R <sub>PD</sub>	Weak pull-down equivalent resistor <sup>(7)</sup>	V <sub>IN</sub> =V <sub>DD</sub> <sup>(8)</sup>	30	40	50	
C <sub>IO</sub>	I/O pin capacitance	-	-	5	-	pF

- Compliant with CMOS requirements.
- Guaranteed by design.
- This parameter represents the pad leakage of the I/O itself. The total product pad leakage is provided by the following formula: I<sub>Total\_leak\_max</sub> = 10 μA + [number of I/Os where V<sub>IN</sub> is applied on the pad] × I<sub>lkg(Max)</sub>.
- All FT\_xx IO except FT\_lu, FT\_u and PC3.
- V<sub>IN</sub> must be less than Max(V<sub>DDXXX</sub>) + 3.6 V.
- To sustain a voltage higher than MIN(V<sub>DD</sub>, V<sub>DDA</sub>, V<sub>DD33USB</sub>) + 0.3 V, the internal pull-up and pull-down resistors must be disabled.
- The pull-up and pull-down resistors are designed with a true resistance in series with a switchable PMOS/NMOS. This PMOS/NMOS contribution to the series resistance is minimal (~10% order).
- Max(V<sub>DDXXX</sub>) is the maximum value of all the I/O supplies.

All I/Os are CMOS and TTL compliant (no software configuration required). Their characteristics cover more than the strict CMOS-technology or TTL parameters. The coverage of these requirements for FT I/Os is shown in [Figure 25](#).

**Figure 25.  $V_{IL}/V_{IH}$  for all I/Os except BOOT0**



### Output driving current

The GPIOs (general purpose input/outputs) can sink or source up to  $\pm 8\text{ mA}$ , and sink or source up to  $\pm 20\text{ mA}$  (with a relaxed  $V_{OL}/V_{OH}$ ).

In the user application, the number of I/O pins which can drive current must be limited to respect the absolute maximum rating specified in [Section 6.2](#). In particular:

- The sum of the currents sourced by all the I/Os on  $V_{DD}$ , plus the maximum Run consumption of the MCU sourced on  $V_{DD}$ , cannot exceed the absolute maximum rating  $\Sigma I_{VDD}$  (see [Table 10](#)).
- The sum of the currents sunk by all the I/Os on  $V_{SS}$  plus the maximum Run consumption of the MCU sunk on  $V_{SS}$  cannot exceed the absolute maximum rating  $\Sigma I_{VSS}$  (see [Table 10](#)).

### Output voltage levels

Unless otherwise specified, the parameters given in [Table 54: Output voltage characteristics for all I/Os except PC13, PC14 and PC15](#) and [Table 55: Output voltage characteristics for PC13, PC14 and PC15](#) are derived from tests performed under ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 12: General operating conditions](#). All I/Os are CMOS and TTL compliant.

**Table 54. Output voltage characteristics for all I/Os except PC13, PC14 and PC15<sup>(1)</sup>**

Symbol	Parameter	Conditions <sup>(3)</sup>	Min	Max	Unit
$V_{OL}$	Output low level voltage	CMOS port <sup>(2)</sup> $I_{IO} = 8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	V
$V_{OH}$	Output high level voltage	CMOS port <sup>(2)</sup> $I_{IO} = -8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	$V_{DD}-0.4$	-	
$V_{OL}^{(3)}$	Output low level voltage	TTL port <sup>(2)</sup> $I_{IO} = 8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	
$V_{OH}^{(3)}$	Output high level voltage	TTL port <sup>(2)</sup> $I_{IO} = -8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	2.4	-	
$V_{OL}^{(3)}$	Output low level voltage	$I_{IO} = 20 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	1.3	
$V_{OH}^{(3)}$	Output high level voltage	$I_{IO} = -20 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	$V_{DD}-1.3$	-	
$V_{OL}^{(3)}$	Output low level voltage	$I_{IO} = 4 \text{ mA}$ $1.62 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	
$V_{OH}^{(3)}$	Output high level voltage	$I_{IO} = -4 \text{ mA}$ $1.62 \text{ V} \leq V_{DD} < 3.6 \text{ V}$	$V_{DD}-0.4$	-	
$V_{OLFM+}^{(3)}$	Output low level voltage for an FTf I/O pin in FM+ mode	$I_{IO} = 20 \text{ mA}$ $2.3 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	
		$I_{IO} = 10 \text{ mA}$ $1.62 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	

- The I/O current sourced or sunk by the device must always respect the absolute maximum rating specified in [Table 9: Voltage characteristics](#), and the sum of the currents sourced or sunk by all the I/Os (I/O ports and control pins) must always respect the absolute maximum ratings  $\Sigma I_{IO}$ .
- TTL and CMOS outputs are compatible with JEDEC standards JESD36 and JESD52.
- Guaranteed by design.

Table 55. Output voltage characteristics for PC13, PC14 and PC15<sup>(1)</sup>

Symbol	Parameter	Conditions <sup>(3)</sup>	Min	Max	Unit
$V_{OL}$	Output low level voltage	CMOS port <sup>(2)</sup> $I_{IO} = 3 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	V
$V_{OH}$	Output high level voltage	CMOS port <sup>(2)</sup> $I_{IO} = -3 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	$V_{DD}-0.4$	-	
$V_{OL}^{(3)}$	Output low level voltage	TTL port <sup>(2)</sup> $I_{IO} = 3 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	
$V_{OH}^{(2)}$	Output high level voltage	TTL port <sup>(2)</sup> $I_{IO} = -3 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	2.4	-	
$V_{OL}^{(2)}$	Output low level voltage	$I_{IO} = 1.5 \text{ mA}$ $1.62 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	
$V_{OH}^{(2)}$	Output high level voltage	$I_{IO} = -1.5 \text{ mA}$ $1.62 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	$V_{DD}-0.4$	-	

1. The I/O current sourced or sunk by the device must always respect the absolute maximum rating specified in [Table 9: Voltage characteristics](#), and the sum of the currents sourced or sunk by all the I/Os (I/O ports and control pins) must always respect the absolute maximum ratings  $\Sigma I_{IO}$ .
2. TTL and CMOS outputs are compatible with JEDEC standards JESD36 and JESD52.
3. Guaranteed by design.

**Output buffer timing characteristics (HSLV option disabled)**

The HSLV bit of SYSCFG\_CCCSR register can be used to optimize the I/O speed when the product voltage is below 2.7 V.

**Table 56. Output timing characteristics (HSLV OFF)<sup>(1)</sup>**

Speed	Symbol	Parameter	conditions	Min	Max	Unit
00	$F_{\max}^{(2)}$	Maximum frequency	C=50 pF, 2.7 V ≤ V <sub>DD</sub> ≤ 3.6 V	-	12	MHz
			C=50 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	3	
			C=30 pF, 2.7 V ≤ V <sub>DD</sub> ≤ 3.6 V	-	12	
			C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	3	
			C=10 pF, 2.7 V ≤ V <sub>DD</sub> ≤ 3.6 V	-	16	
			C=10 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	4	
	$t_r/t_f^{(3)}$	Output high to low level fall time and output low to high level rise time	C=50 pF, 2.7 V ≤ V <sub>DD</sub> ≤ 3.6 V	-	16.6	ns
			C=50 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	33.3	
			C=30 pF, 2.7 V ≤ V <sub>DD</sub> ≤ 3.6 V	-	13.3	
			C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	25	
			C=10 pF, 2.7 V ≤ V <sub>DD</sub> ≤ 3.6 V	-	10	
			C=10 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	20	
01	$F_{\max}^{(2)}$	Maximum frequency	C=50 pF, 2.7 V ≤ V <sub>DD</sub> ≤ 3.6 V	-	60	MHz
			C=50 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	15	
			C=30 pF, 2.7 V ≤ V <sub>DD</sub> ≤ 3.6 V	-	80	
			C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	15	
			C=10 pF, 2.7 V ≤ V <sub>DD</sub> ≤ 3.6 V	-	110	
			C=10 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	20	
	$t_r/t_f^{(3)}$	Output high to low level fall time and output low to high level rise time	C=50 pF, 2.7 V ≤ V <sub>DD</sub> ≤ 3.6 V	-	5.2	ns
			C=50 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	10	
			C=30 pF, 2.7 V ≤ V <sub>DD</sub> ≤ 3.6 V	-	4.2	
			C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	7.5	
			C=10 pF, 2.7 V ≤ V <sub>DD</sub> ≤ 3.6 V	-	2.8	
			C=10 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	5.2	

Table 56. Output timing characteristics (HSLV OFF)<sup>(1)</sup> (continued)

Speed	Symbol	Parameter	conditions	Min	Max	Unit
10	F <sub>max</sub> <sup>(2)</sup>	Maximum frequency	C=50 pF, 2.7 V≤V <sub>DD</sub> ≤3.6 V <sup>(4)</sup>	-	85	MHz
			C=50 pF, 1.62 V≤V <sub>DD</sub> ≤2.7 V <sup>(4)</sup>	-	35	
			C=30 pF, 2.7 V≤V <sub>DD</sub> ≤3.6 V <sup>(4)</sup>	-	110	
			C=30 pF, 1.62 V≤V <sub>DD</sub> ≤2.7 V <sup>(4)</sup>	-	40	
			C=10 pF, 2.7 V≤V <sub>DD</sub> ≤3.6 V <sup>(4)</sup>	-	166	
			C=10 pF, 1.62 V≤V <sub>DD</sub> ≤2.7 V <sup>(4)</sup>	-	100	
	t <sub>r</sub> /t <sub>f</sub> <sup>(3)</sup>	Output high to low level fall time and output low to high level rise time	C=50 pF, 2.7 V≤V <sub>DD</sub> ≤3.6 V <sup>(4)</sup>	-	3.8	ns
			C=50 pF, 1.62 V≤V <sub>DD</sub> ≤2.7 V <sup>(4)</sup>	-	6.9	
			C=30 pF, 2.7 V≤V <sub>DD</sub> ≤3.6 V <sup>(4)</sup>	-	2.8	
			C=30 pF, 1.62 V≤V <sub>DD</sub> ≤2.7 V <sup>(4)</sup>	-	5.2	
C=10 pF, 2.7 V≤V <sub>DD</sub> ≤3.6 V <sup>(4)</sup>			-	1.8		
C=10 pF, 1.62 V≤V <sub>DD</sub> ≤2.7 V <sup>(4)</sup>			-	3.3		
11	F <sub>max</sub> <sup>(2)</sup>	Maximum frequency	C=50 pF, 2.7 V≤V <sub>DD</sub> ≤3.6 V <sup>(4)</sup>	-	100	MHz
			C=50 pF, 1.62 V≤V <sub>DD</sub> ≤2.7 V <sup>(4)</sup>	-	50	
			C=30 pF, 2.7 V≤V <sub>DD</sub> ≤3.6 V <sup>(4)</sup>	-	133	
			C=30 pF, 1.62 V≤V <sub>DD</sub> ≤2.7 V <sup>(4)</sup>	-	66	
			C=10 pF, 2.7 V≤V <sub>DD</sub> ≤3.6 V <sup>(4)</sup>	-	220	
			C=10 pF, 1.62 V≤V <sub>DD</sub> ≤2.7 V <sup>(4)</sup>	-	85	
	t <sub>r</sub> /t <sub>f</sub> <sup>(3)</sup>	Output high to low level fall time and output low to high level rise time	C=50 pF, 2.7 V≤V <sub>DD</sub> ≤3.6 V <sup>(4)</sup>	-	3.3	ns
			C=50 pF, 1.62 V≤V <sub>DD</sub> ≤2.7 V <sup>(4)</sup>	-	6.6	
			C=30 pF, 2.7 V≤V <sub>DD</sub> ≤3.6 V <sup>(4)</sup>	-	2.4	
			C=30 pF, 1.62 V≤V <sub>DD</sub> ≤2.7 V <sup>(4)</sup>	-	4.5	
C=10 pF, 2.7 V≤V <sub>DD</sub> ≤3.6 V <sup>(4)</sup>			-	1.5		
C=10 pF, 1.62 V≤V <sub>DD</sub> ≤2.7 V <sup>(4)</sup>			-	2.7		

1. Guaranteed by design.
2. The maximum frequency is defined with the following conditions:  
 (t<sub>r</sub>+t<sub>f</sub>) ≤ 2/3 T  
 Skew ≤ 1/20 T  
 45%<Duty cycle<55%
3. The fall and rise times are defined between 90% and 10% and between 10% and 90% of the output waveform, respectively.
4. Compensation system enabled.

## Output buffer timing characteristics (HSLV option enabled)

Table 57. Output timing characteristics (HSLV ON)<sup>(1)</sup>

Speed	Symbol	Parameter	conditions	Min	Max	Unit
00	F <sub>max</sub> <sup>(2)</sup>	Maximum frequency	C=50 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	10	MHz
			C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	10	
			C=10 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	10	
	t <sub>r</sub> /t <sub>f</sub> <sup>(3)</sup>	Output high to low level fall time and output low to high level rise time	C=50 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	11	ns
			C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	9	
			C=10 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	6.6	
01	F <sub>max</sub> <sup>(2)</sup>	Maximum frequency	C=50 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	50	MHz
			C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	58	
			C=10 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	66	
	t <sub>r</sub> /t <sub>f</sub> <sup>(3)</sup>	Output high to low level fall time and output low to high level rise time	C=50 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	6.6	ns
			C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	4.8	
			C=10 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	3	
10	F <sub>max</sub> <sup>(2)</sup>	Maximum frequency	C=50 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V <sup>(4)</sup>	-	55	MHz
			C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V <sup>(4)</sup>	-	80	
			C=10 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V <sup>(4)</sup>	-	133	
	t <sub>r</sub> /t <sub>f</sub> <sup>(3)</sup>	Output high to low level fall time and output low to high level rise time	C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V <sup>(4)</sup>	-	5.8	ns
			C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V <sup>(4)</sup>	-	4	
			C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V <sup>(4)</sup>	-	2.4	
11	F <sub>max</sub> <sup>(2)</sup>	Maximum frequency	C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V <sup>(4)</sup>	-	60	MHz
			C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V <sup>(4)</sup>	-	90	
			C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V <sup>(4)</sup>	-	175	
	t <sub>r</sub> /t <sub>f</sub> <sup>(3)</sup>	Output high to low level fall time and output low to high level rise time	C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V <sup>(4)</sup>	-	5.3	ns
			C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V <sup>(4)</sup>	-	3.6	
			C=30 pF, 1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V <sup>(4)</sup>	-	1.9	

1. Guaranteed by design.

2. The maximum frequency is defined with the following conditions:  
 $(t_r + t_f) \leq 2/3 T$   
 Skew  $\leq 1/20 T$   
 $45\% < \text{Duty cycle} < 55\%$

3. The fall and rise times are defined between 90% and 10% and between 10% and 90% of the output waveform, respectively.

4. Compensation system enabled.

### Analog switch between ports Pxy\_C and Pxy

PA0\_C, PA1\_C, PC2\_C and PC3\_C can be connected internally to PA0, PA1, PC2 and PC3, respectively (refer to SYSCFG\_PMCR register in RM0468 reference manual). The switch is controlled by  $V_{DDSWITCH}$  voltage level. It is defined through BOOSTVDDSEL bit of SYSCFG\_PMCR. If the switch is closed the switch characteristics are given in the table below.

**Table 58. Pxy\_C and Pxy analog switch characteristics**

Parameter	Conditions	Min	Typ	Max	Unit	
Switch impedance	Switch control boosted		-	-	315	Ω
	Switch control not boosted	$V_{DDSWITCH} > 2.7\text{ V}$	-	-	315	
		$V_{DDSWITCH} > 2.4\text{ V}$	-	-	335	
		$V_{DDSWITCH} > 2.0\text{ V}$	-	-	390	
		$V_{DDSWITCH} > 1.8\text{ V}$	-	-	445	
		$V_{DDSWITCH} > 1.62\text{ V}$	-	-	550	

### 6.3.18 NRST pin characteristics

The NRST pin input driver uses CMOS technology. It is connected to a permanent pull-up resistor,  $R_{PU}$  (see [Table 53: I/O static characteristics](#)).

Unless otherwise specified, the parameters given in [Table 59](#) are derived from tests performed under the ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 12: General operating conditions](#).

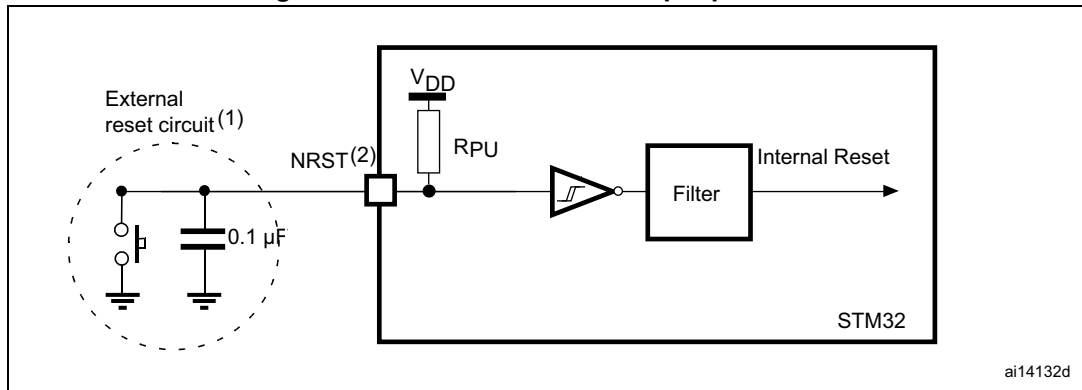
**Table 59. NRST pin characteristics**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{PU}^{(2)}$	Weak pull-up equivalent resistor <sup>(1)</sup>	$V_{IN} = V_{SS}$	30	40	50	kΩ
$V_{F(NRST)}^{(2)}$	NRST Input filtered pulse	$1.71\text{ V} < V_{DD} < 3.6\text{ V}$	-	-	50	ns
$V_{NF(NRST)}^{(2)}$	NRST Input not filtered pulse	$1.71\text{ V} < V_{DD} < 3.6\text{ V}$	350	-	-	
		$1.62\text{ V} < V_{DD} < 3.6\text{ V}$	1000	-	-	

1. The pull-up is designed with a true resistance in series with a switchable PMOS. This PMOS contribution to the series resistance must be minimum (~10% order).
2. Guaranteed by design.



Figure 26. Recommended NRST pin protection



1. The reset network protects the device against parasitic resets.
2. The user must ensure that the level on the NRST pin can go below the  $V_{IL(NRST)}$  max level specified in [Table 53](#). Otherwise the reset is not taken into account by the device.

### 6.3.19 FMC characteristics

Unless otherwise specified, the parameters given in [Table 60](#) to [Table 73](#) for the FMC interface are derived from tests performed under the ambient temperature,  $f_{HCLK}$  frequency and  $V_{DD}$  supply voltage conditions summarized in [Table 12: General operating conditions](#), with the following configuration:

- Output speed is set to  $OSPEEDRy[1:0] = 11$
- Measurement points are done at CMOS levels:  $0.5V_{DD}$
- IO Compensation cell activated.
- HSLV activated when  $V_{DD} \leq 2.7$  V
- VOS level set to VOS0.

Refer to [Section 6.3.17: I/O port characteristics](#) for more details on the input/output alternate function characteristics.

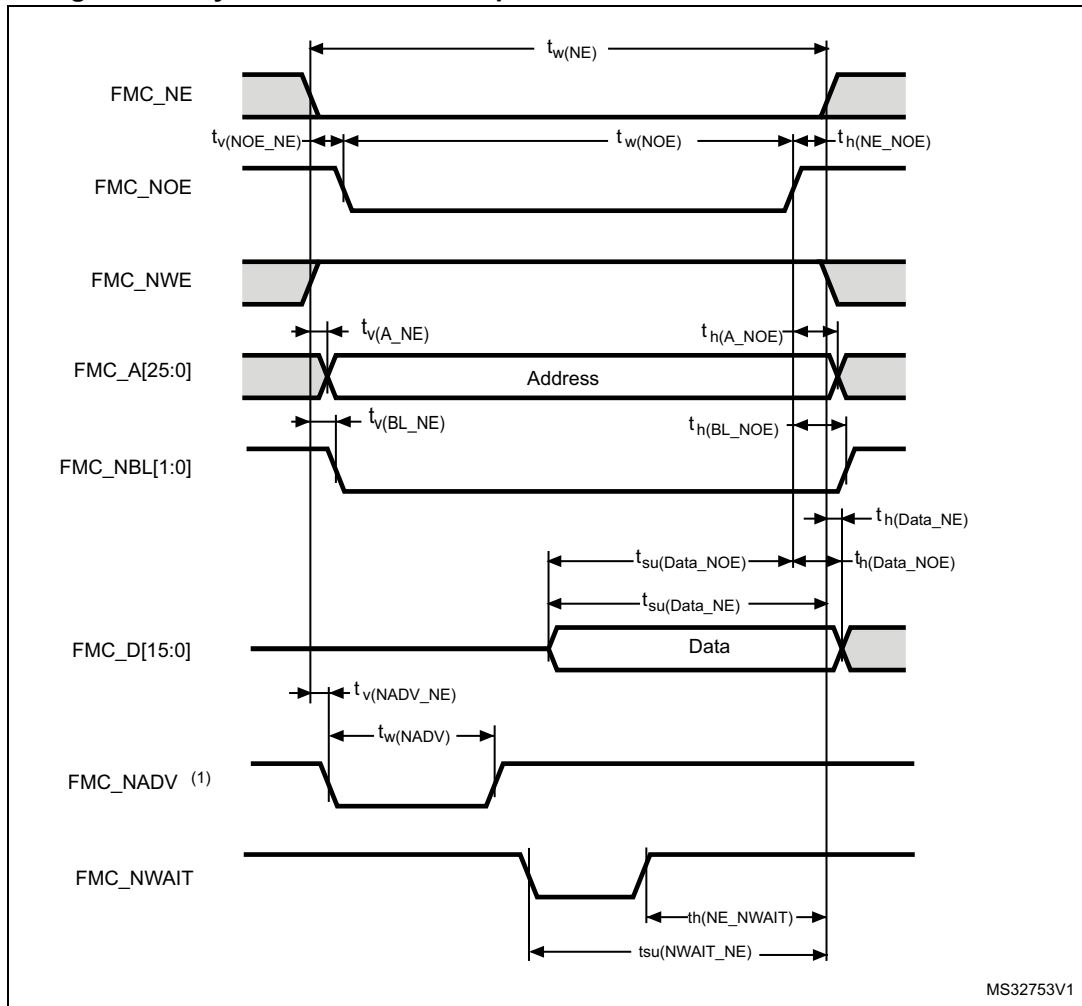
#### Asynchronous waveforms and timings

[Figure 27](#) through [Figure 29](#) represent asynchronous waveforms and [Table 60](#) through [Table 67](#) provide the corresponding timings. The results shown in these tables are obtained with the following FMC configuration:

- AddressSetupTime = 0x1
- AddressHoldTime = 0x1
- DataSetupTime = 0x1 (except for asynchronous NWAIT mode , DataSetupTime = 0x5)
- BusTurnAroundDuration = 0x0
- Capacitive load  $C_L = 30$  pF

In all timing tables, the  $T_{KERCK}$  is the  $f_{mc\_ker\_ck}$  clock period.

Figure 27. Asynchronous non-multiplexed SRAM/PSRAM/NOR read waveforms



1. Mode 2/B, C and D only. In Mode 1, FMC\_NADV is not used.

**Table 60. Asynchronous non-multiplexed SRAM/PSRAM/NOR read timings<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FMC_NE low time	$3T_{fmc\_ker\_ck}-1$	$3T_{fmc\_ker\_ck}+1$	ns
$t_{v(NOEN\_NE)}$	FMC_NEx low to FMC_NOE low	0	0.5	
$t_{w(NOEN)}$	FMC_NOE low time	$2T_{fmc\_ker\_ck}-1$	$2T_{fmc\_ker\_ck}+1$	
$t_{h(NE\_NOEN)}$	FMC_NOE high to FMC_NE high hold time	$T_{fmc\_ker\_ck}$	-	
$t_{v(A\_NE)}$	FMC_NEx low to FMC_A valid	-	0.5	
$t_{h(A\_NOEN)}$	Address hold time after FMC_NOE high	$2T_{fmc\_ker\_ck}$	-	
$t_{su(Data\_NE)}$	Data to FMC_NEx high setup time	$T_{fmc\_ker\_ck}+14$	-	
$t_{su(Data\_NOEN)}$	Data to FMC_NOEx high setup time	13	-	
$t_{h(Data\_NOEN)}$	Data hold time after FMC_NOE high	0	-	
$t_{h(Data\_NE)}$	Data hold time after FMC_NEx high	0	-	
$t_{v(NADV\_NE)}$	FMC_NEx low to FMC_NADV low	-	4	
$t_{w(NADV)}$	FMC_NADV low time	-	$T_{fmc\_ker\_ck}+1$	

1. Guaranteed by characterization results.

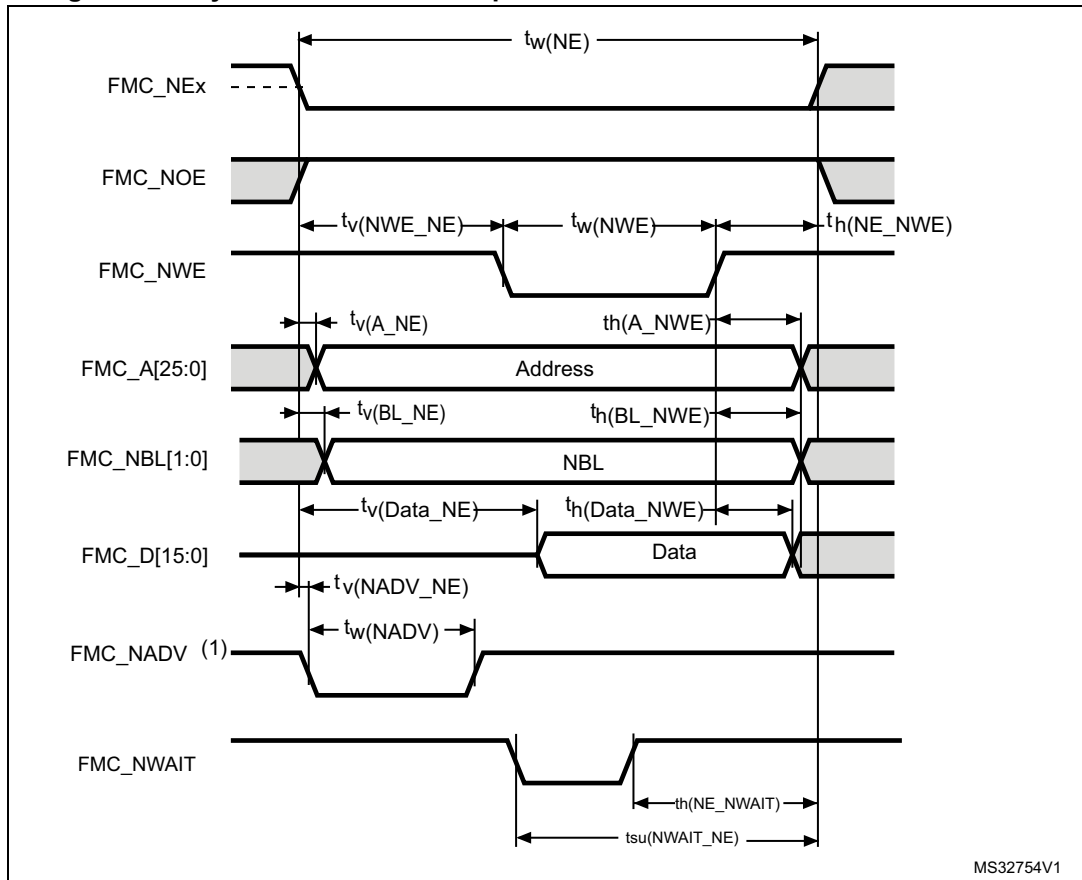
**Table 61. Asynchronous non-multiplexed SRAM/PSRAM/NOR read-NWAIT timings<sup>(1)(2)</sup>**

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FMC_NE low time	$7T_{fmc\_ker\_ck}-1$	$7T_{fmc\_ker\_ck}+1$	ns
$t_{w(NOEN)}$	FMC_NOE low time	$5T_{fmc\_ker\_ck}-1$	$5T_{fmc\_ker\_ck}+1$	
$t_{w(NWAIT)}$	FMC_NWAIT low time	$T_{fmc\_ker\_ck}-0.5$	-	
$t_{su(NWAIT\_NE)}$	FMC_NWAIT valid before FMC_NEx high	$4T_{fmc\_ker\_ck}+9$	-	
$t_{h(NE\_NWAIT)}$	FMC_NEx hold time after FMC_NWAIT invalid	$3T_{fmc\_ker\_ck}+12$	-	

1. Guaranteed by characterization results.

2.  $N_{WAIT}$  pulse width is equal to 1 fmc\_ker\_ck cycle.

Figure 28. Asynchronous non-multiplexed SRAM/PSRAM/NOR write waveforms



1. Mode 2/B, C and D only. In Mode 1, FMC\_NADV is not used.

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**Table 62. Asynchronous non-multiplexed SRAM/PSRAM/NOR write timings<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FMC_NE low time	$3T_{fmc\_ker\_ck} - 1$	$3T_{fmc\_ker\_ck} + 1$	ns
$t_{v(NWE\_NE)}$	FMC_NEx low to FMC_NWE low	$T_{fmc\_ker\_ck} - 1$	$T_{fmc\_ker\_ck}$	
$t_{w(NWE)}$	FMC_NWE low time	$T_{fmc\_ker\_ck} - 0.5$	$T_{fmc\_ker\_ck} + 0.5$	
$t_{h(NE\_NWE)}$	FMC_NWE high to FMC_NE high hold time	$T_{fmc\_ker\_ck}$	-	
$t_{v(A\_NE)}$	FMC_NEx low to FMC_A valid	-	1	
$t_{h(A\_NWE)}$	Address hold time after FMC_NWE high	$T_{fmc\_ker\_ck} - 0.5$	-	
$t_{v(BL\_NE)}$	FMC_NEx low to FMC_BL valid	-	0.5	
$t_{h(BL\_NWE)}$	FMC_BL hold time after FMC_NWE high	$T_{fmc\_ker\_ck} - 0.5$	-	
$t_{v(Data\_NE)}$	Data to FMC_NEx low to Data valid	-	$T_{fmc\_ker\_ck} + 2$	
$t_{h(Data\_NWE)}$	Data hold time after FMC_NWE high	$T_{fmc\_ker\_ck}$	-	
$t_{v(NADV\_NE)}$	FMC_NEx low to FMC_NADV low	-	5	
$t_{w(NADV)}$	FMC_NADV low time	-	$T_{fmc\_ker\_ck} + 1$	

1. Guaranteed by characterization results.

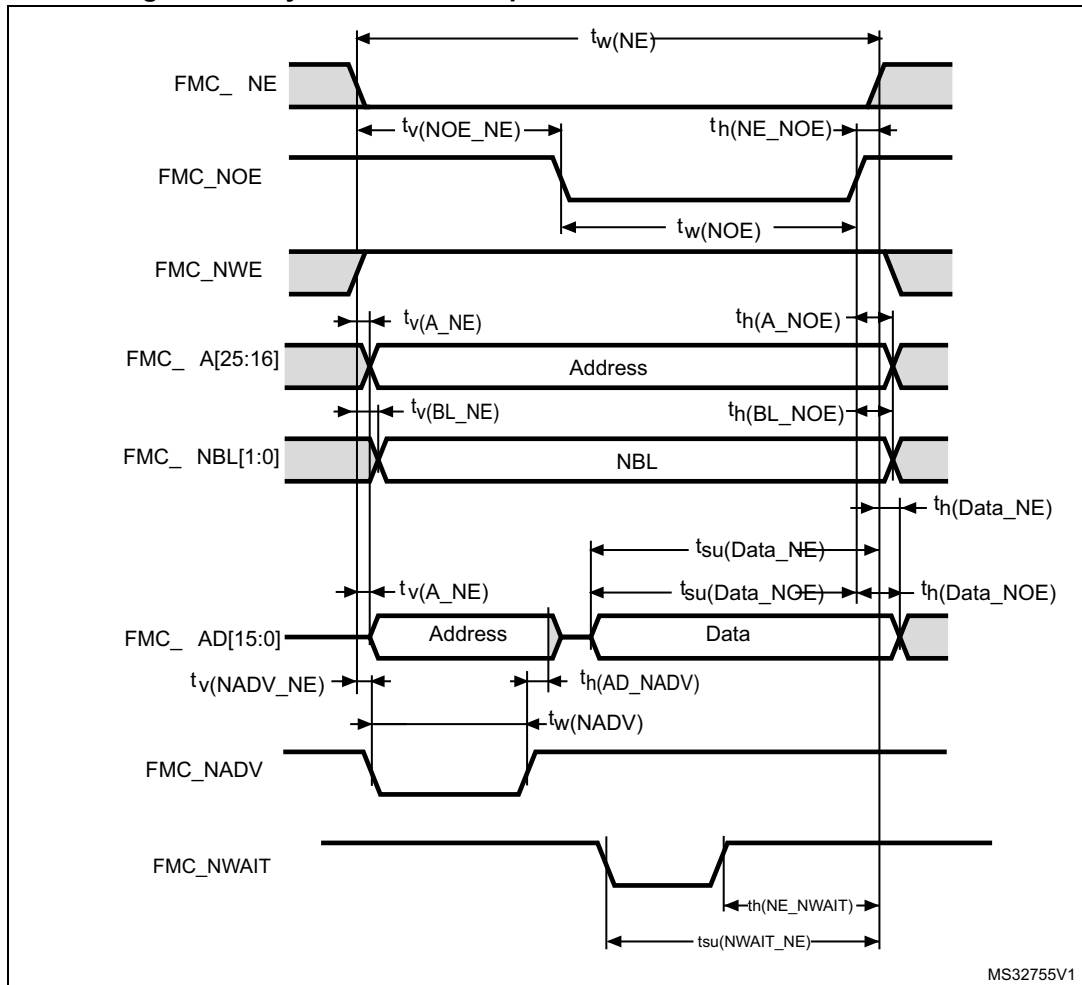
**Table 63. Asynchronous non-multiplexed SRAM/PSRAM/NOR write-NWAIT timings<sup>(1)(2)</sup>**

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FMC_NE low time	$8T_{fmc\_ker\_ck} - 1$	$8T_{fmc\_ker\_ck} + 1$	ns
$t_{w(NWE)}$	FMC_NWE low time	$6T_{fmc\_ker\_ck} - 1$	$6T_{fmc\_ker\_ck} + 1$	
$t_{su(NWAIT\_NE)}$	FMC_NWAIT valid before FMC_NEx high	$5T_{fmc\_ker\_ck} + 13$	-	
$t_{h(NE\_NWAIT)}$	FMC_NEx hold time after FMC_NWAIT invalid	$4T_{fmc\_ker\_ck} + 12$	-	

1. Guaranteed by characterization results.

2.  $N_{WAIT}$  pulse width is equal to 1  $fmc\_ker\_ck$  cycle.

Figure 29. Asynchronous multiplexed PSRAM/NOR read waveforms



**Table 64. Asynchronous multiplexed PSRAM/NOR read timings<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FMC_NE low time	$4T_{fmc\_ker\_ck} - 1$	$4T_{fmc\_ker\_ck} + 1$	ns
$t_{v(NOE\_NE)}$	FMC_NEx low to FMC_NOE low	$2T_{fmc\_ker\_ck}$	$2T_{fmc\_ker\_ck} + 0.5$	
$t_{w(NOE)}$	FMC_NOE low time	$T_{fmc\_ker\_ck} - 1$	$T_{fmc\_ker\_ck} + 1$	
$t_{h(NE\_NOE)}$	FMC_NOE high to FMC_NE high hold time	$T_{fmc\_ker\_ck}$	-	
$t_{v(A\_NE)}$	FMC_NEx low to FMC_A valid	-	0.5	
$t_{v(NADV\_NE)}$	FMC_NEx low to FMC_NADV low	0	4.0	
$t_{w(NADV)}$	FMC_NADV low time	$T_{fmc\_ker\_ck} - 0.5$	$T_{fmc\_ker\_ck} + 1$	
$t_{h(AD\_NADV)}$	FMC_AD(address) valid hold time after FMC_NADV high	$T_{fmc\_ker\_ck} - 4$	-	
$t_{h(A\_NOE)}$	Address hold time after FMC_NOE high	$T_{fmc\_ker\_ck} - 0.5$	-	
$t_{su(Data\_NE)}$	Data to FMC_NEx high setup time	$T_{fmc\_ker\_ck} + 14$	-	
$t_{su(Data\_NOE)}$	Data to FMC_NOE high setup time	13	-	
$t_{h(Data\_NE)}$	Data hold time after FMC_NEx high	0	-	
$t_{h(Data\_NOE)}$	Data hold time after FMC_NOE high	0	-	

1. Guaranteed by characterization results.

**Table 65. Asynchronous multiplexed PSRAM/NOR read-NWAIT timings<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FMC_NE low time	$8T_{fmc\_ker\_ck} - 1$	$8T_{fmc\_ker\_ck} + 1$	ns
$t_{w(NOE)}$	FMC_NWE low time	$5T_{fmc\_ker\_ck} - 1$	$5T_{fmc\_ker\_ck} + 1$	
$t_{su(NWAIT\_NE)}$	FMC_NWAIT valid before FMC_NEx high	$4T_{fmc\_ker\_ck} + 9$	-	
$t_{h(NE\_NWAIT)}$	FMC_NEx hold time after FMC_NWAIT invalid	$3T_{fmc\_ker\_ck} + 12$	-	

1. Guaranteed by characterization results.

**Table 66. Asynchronous multiplexed PSRAM/NOR write timings<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FMC_NE low time	$4T_{fmc\_ker\_ck} - 1$	$4T_{fmc\_ker\_ck}$	ns
$t_{v(NWE\_NE)}$	FMC_NEx low to FMC_NWE low	$T_{fmc\_ker\_ck} - 1$	$T_{fmc\_ker\_ck} + 0.5$	
$t_{w(NWE)}$	FMC_NWE low time	$2T_{fmc\_ker\_ck} - 0.5$	$2T_{fmc\_ker\_ck} + 0.5$	
$t_{h(NE\_NWE)}$	FMC_NWE high to FMC_NE high hold time	$T_{fmc\_ker\_ck} - 0.5$	-	
$t_{v(A\_NE)}$	FMC_NEx low to FMC_A valid	-	1	
$t_{v(NADV\_NE)}$	FMC_NEx low to FMC_NADV low	0	5.0	
$t_{w(NADV)}$	FMC_NADV low time	$T_{fmc\_ker\_ck} - 0.5$	$T_{fmc\_ker\_ck} + 1$	
$t_{h(AD\_NADV)}$	FMC_AD(address) valid hold time after FMC_NADV high)	$T_{fmc\_ker\_ck} - 4.5$	-	
$t_{h(A\_NWE)}$	Address hold time after FMC_NWE high	$T_{fmc\_ker\_ck} - 0.5$	-	
$t_{h(BL\_NWE)}$	FMC_BL hold time after FMC_NWE high	$T_{fmc\_ker\_ck} - 0.5$	-	
$t_{v(BL\_NE)}$	FMC_NEx low to FMC_BL valid	-	0.5	
$t_{v(Data\_NADV)}$	FMC_NADV high to Data valid	-	$T_{fmc\_ker\_ck} + 2$	
$t_{h(Data\_NWE)}$	Data hold time after FMC_NWE high	$T_{fmc\_ker\_ck}$	-	

1. Guaranteed by characterization results.

**Table 67. Asynchronous multiplexed PSRAM/NOR write-NWAIT timings<sup>(1)(2)</sup>**

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FMC_NE low time	$9T_{fmc\_ker\_ck} - 1$	$9T_{fmc\_ker\_ck}$	ns
$t_{w(NWE)}$	FMC_NWE low time	$7T_{fmc\_ker\_ck} - 0.5$	$7T_{fmc\_ker\_ck} + 0.5$	
$t_{su(NWAIT\_NE)}$	FMC_NWAIT valid before FMC_NEx high	$5T_{fmc\_ker\_ck} + 9$	-	
$t_{h(NE\_NWAIT)}$	FMC_NEx hold time after FMC_NWAIT invalid	$4T_{fmc\_ker\_ck} + 12$	-	

1. Guaranteed by characterization results.

2.  $N_{WAIT}$  pulse width is equal to 1 fmc\_ker\_ck cycle.



**Synchronous waveforms and timings**

Figure 30 through Figure 33 represent synchronous waveforms and Table 68 through Table 71 provide the corresponding timings. The results shown in these tables are obtained with the following FMC configuration:

- BurstAccessMode = FMC\_BurstAccessMode\_Enable
- MemoryType = FMC\_MemoryType\_CRAM
- WriteBurst = FMC\_WriteBurst\_Enable
- CLKDivision = 1
- DataLatency = 1 for NOR Flash, DataLatency = 0 for PSRAM,  $C_L = 30$  pF

In all the timing tables, the  $T_{fmc\_ker\_ck}$  is the  $f_{mc\_ker\_ck}$  clock period, with the following FMC\_CLK maximum values:

- For  $2.7 V < V_{DD} < 3.6 V$ : maximum FMC\_CLK = 137 MHz at  $C_L = 20$  pF
- For  $1.8 V < V_{DD} < 1.9 V$ : maximum FMC\_CLK = 100 MHz at  $C_L = 20$  pF
- For  $1.62 V < V_{DD} < 1.8 V$ : maximum FMC\_CLK = 88 MHz at  $C_L = 15$  pF

**Figure 30. Synchronous multiplexed NOR/PSRAM read timings**

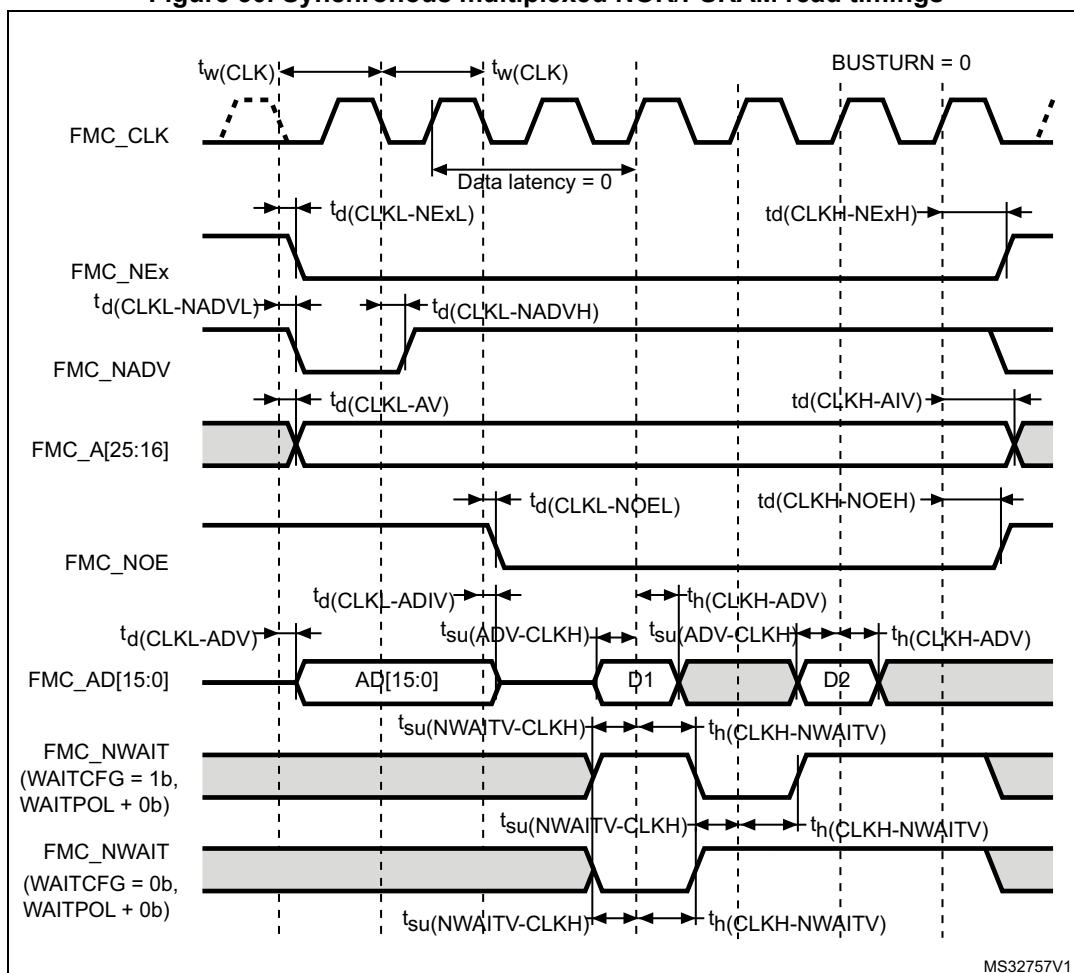
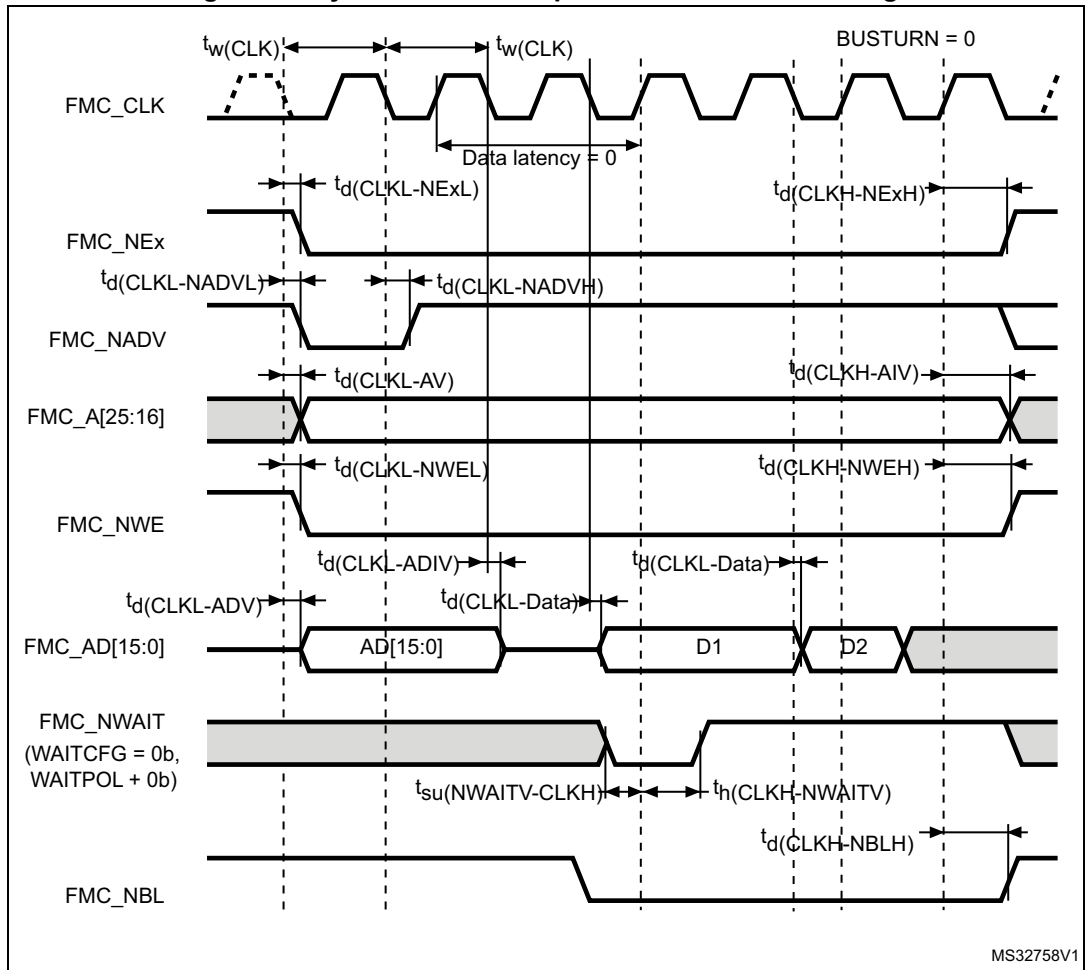


Table 68. Synchronous multiplexed NOR/PSRAM read timings<sup>(1)</sup>

Symbol	Parameter		Min	Max	Unit
$t_w(\text{CLK})$	FMC_CLK period		$2T_{\text{fmc\_ker\_ck}} - 0.5$	-	ns
$t_d(\text{CLKL-NEXL})$	FMC_CLK low to FMC_NEx low (x=0..2)		-	3	
$t_d(\text{CLKH-NExH})$	FMC_CLK high to FMC_NEx high (x= 0...2)		$T_{\text{fmc\_ker\_ck}} + 1.5$	-	
$t_d(\text{CLKL-NADV})$	FMC_CLK low to FMC_NADV low	1.62 V < V <sub>DD</sub> < 3.6 V	-	5.5	
		2.7 V < V <sub>DD</sub> < 3.6 V		2	
$t_d(\text{CLKL-NADVH})$	FMC_CLK low to FMC_NADV high	1.62 V < V <sub>DD</sub> < 3.6 V	1	-	
		2.7 V < V <sub>DD</sub> < 3.6 V		-	
$t_d(\text{CLKL-AV})$	FMC_CLK low to FMC_Ax valid (x=16...25)		-	3	
$t_d(\text{CLKH-AIV})$	FMC_CLK high to FMC_Ax invalid (x=16...25)		$T_{\text{fmc\_ker\_ck}}$	-	
$t_d(\text{CLKL-NOEL})$	FMC_CLK low to FMC_NOE low		-	2.5	
$t_d(\text{CLKH-NOEH})$	FMC_CLK high to FMC_NOE high		$T_{\text{fmc\_ker\_ck}} + 1$	-	
$t_d(\text{CLKL-ADV})$	FMC_CLK low to FMC_AD[15:0] valid		-	3	
$t_d(\text{CLKL-ADIV})$	FMC_CLK low to FMC_AD[15:0] invalid		0	-	
$t_{su}(\text{ADV-CLKH})$	FMC_A/D[15:0] valid data before FMC_CLK high		3	-	
$t_h(\text{CLKH-ADV})$	FMC_A/D[15:0] valid data after FMC_CLK high		0	-	
$t_{su}(\text{NWAIT-CLKH})$	FMC_NWAIT valid before FMC_CLK high		3	-	
$t_h(\text{CLKH-NWAIT})$	FMC_NWAIT valid after FMC_CLK high		2.5	-	

1. Guaranteed by characterization results.

Figure 31. Synchronous multiplexed PSRAM write timings

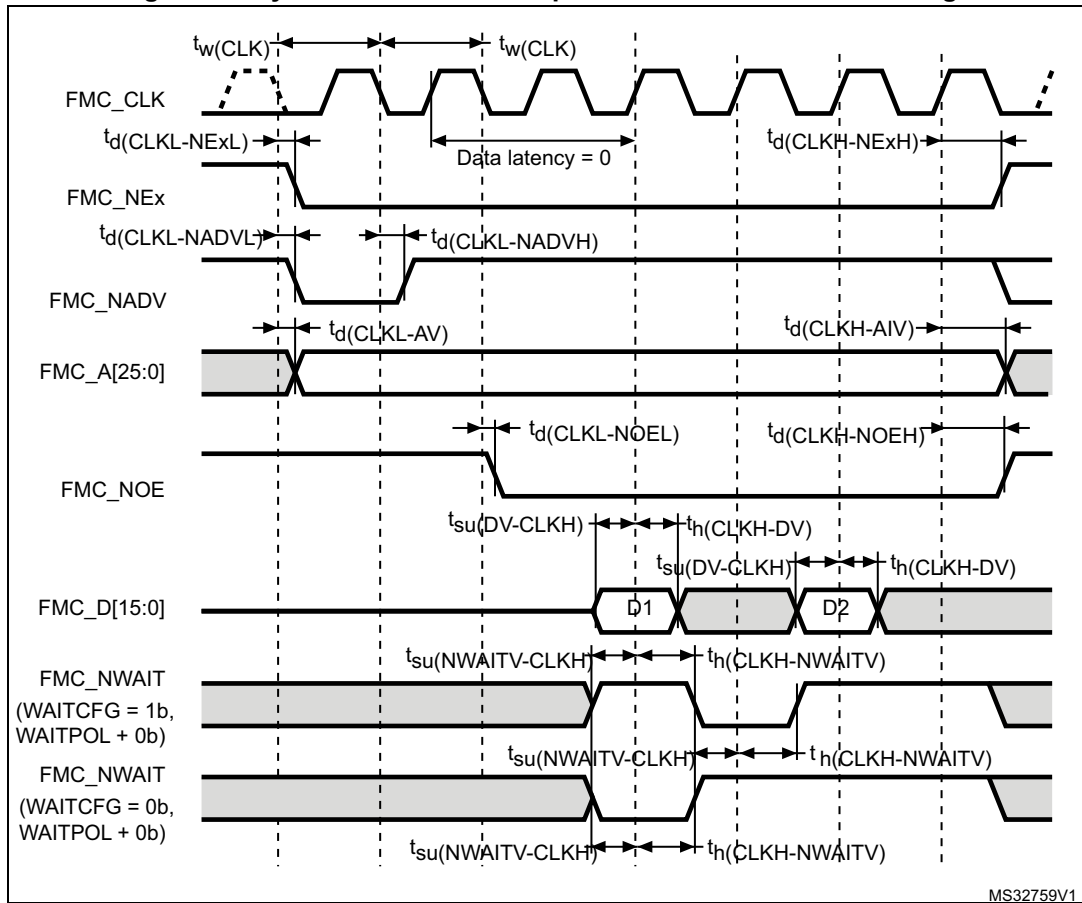


**Table 69. Synchronous multiplexed PSRAM write timings<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit	
$t_w(\text{CLK})$	FMC_CLK period, $V_{DD} = 2.7$ to $3.6$ V	$2T_{fmc\_ker\_ck} - 0.5$	-	ns	
$t_d(\text{CLKL-NExL})$	FMC_CLK low to FMC_NEx low ( $x = 0..2$ )	-	3		
$t_d(\text{CLKH-NExH})$	FMC_CLK high to FMC_NEx high ( $x = 0..2$ )	$T_{fmc\_ker\_ck} + 1.5$	-		
$t_d(\text{CLKL-NADV})$	FMC_CLK low to FMC_NADV low	$1.62 \text{ V} < V_{DD} < 3.6 \text{ V}$	-		5.5
		$2.7 \text{ V} < V_{DD} < 3.6 \text{ V}$	-		2.0
$t_d(\text{CLKL-NADVH})$	FMC_CLK low to FMC_NADV high	$1.62 \text{ V} < V_{DD} < 3.6 \text{ V}$	1		-
		$2.7 \text{ V} < V_{DD} < 3.6 \text{ V}$	-		-
$t_d(\text{CLKL-AV})$	FMC_CLK low to FMC_Ax valid ( $x = 16..25$ )	-	3		
$t_d(\text{CLKH-AIV})$	FMC_CLK high to FMC_Ax invalid ( $x = 16..25$ )	$T_{fmc\_ker\_ck}$	-		
$t_d(\text{CLKL-NWEL})$	FMC_CLK low to FMC_NWE low	-	2.5		
$t_d(\text{CLKH-NWEH})$	FMC_CLK high to FMC_NWE high	$T_{fmc\_ker\_ck} + 1$	-		
$t_d(\text{CLKL-ADV})$	FMC_CLK low to FMC_AD[15:0] valid	-	2.5		
$t_d(\text{CLKL-ADIV})$	FMC_CLK low to FMC_AD[15:0] invalid	0	-		
$t_d(\text{CLKL-DATA})$	FMC_A/D[15:0] valid data after FMC_CLK low	-	3.5		
$t_d(\text{CLKL-NBLL})$	FMC_CLK low to FMC_NBL low	-	2		
$t_d(\text{CLKH-NBLH})$	FMC_CLK high to FMC_NBL high	$T_{fmc\_ker\_ck} + 0.5$	-		
$t_{su}(\text{NWAIT-CLKH})$	FMC_NWAIT valid before FMC_CLK high	3	-		
$t_h(\text{CLKH-NWAIT})$	FMC_NWAIT valid after FMC_CLK high	2.5	-		

1. Guaranteed by characterization results.

Figure 32. Synchronous non-multiplexed NOR/PSRAM read timings

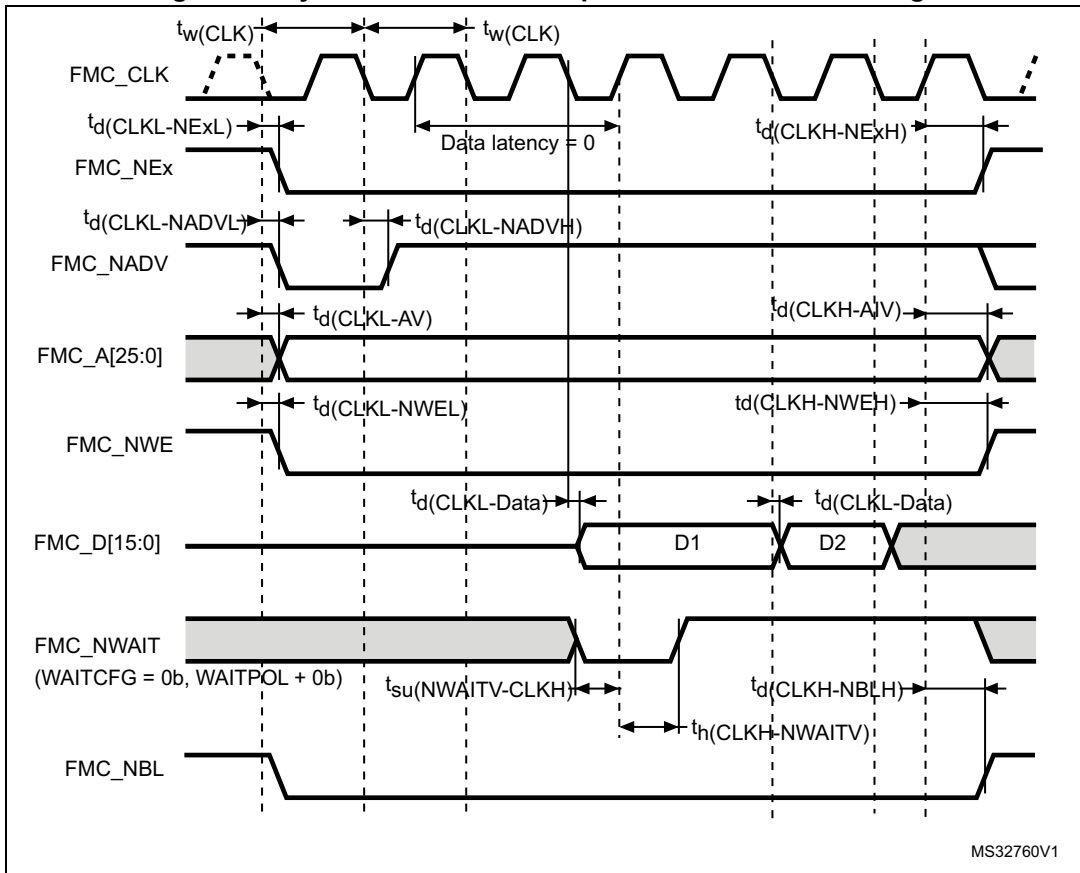


**Table 70. Synchronous non-multiplexed NOR/PSRAM read timings<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit	
$t_w(\text{CLK})$	FMC_CLK period	$2T_{\text{fmc\_ker\_ck}} - 0.5$	-	ns	
$t_{(\text{CLKL-NE}x\text{L})}$	FMC_CLK low to FMC_NEx low (x=0..2)	-	3		
$t_{d(\text{CLKH-NE}x\text{H})}$	FMC_CLK high to FMC_NEx high (x= 0...2)	$T_{\text{fmc\_ker\_ck}} + 1.5$	-		
$t_{d(\text{CLKL-NADV}x\text{L})}$	FMC_CLK low to FMC_NADV low	$1.62 \text{ V} < V_{\text{DD}} < 3.6 \text{ V}$	-		5.5
		$2.7 \text{ V} < V_{\text{DD}} < 3.6 \text{ V}$	-		2.0
$t_{d(\text{CLKL-NADV}x\text{H})}$	FMC_CLK low to FMC_NADV high	$1.62 \text{ V} < V_{\text{DD}} < 3.6 \text{ V}$	1		-
		$2.7 \text{ V} < V_{\text{DD}} < 3.6 \text{ V}$	-		-
$t_{d(\text{CLKL-AV})}$	FMC_CLK low to FMC_Ax valid (x=16...25)	-	3		
$t_{d(\text{CLKH-AIV})}$	FMC_CLK high to FMC_Ax invalid (x=16...25)	$T_{\text{fmc\_ker\_ck}}$	-		
$t_{d(\text{CLKL-NOEL})}$	FMC_CLK low to FMC_NOE low	-	2.5		
$t_{d(\text{CLKH-NOEH})}$	FMC_CLK high to FMC_NOE high	$T_{\text{fmc\_ker\_ck}} + 1$	-		
$t_{\text{su}(\text{DV-CLKH})}$	FMC_D[15:0] valid data before FMC_CLK high	3	-		
$t_{\text{h}(\text{CLKH-DV})}$	FMC_D[15:0] valid data after FMC_CLK high	0	-		
$t_{(\text{NWAIT-CLKH})}$	FMC_NWAIT valid before FMC_CLK high	3	-		
$t_{\text{h}(\text{CLKH-NWAIT})}$	FMC_NWAIT valid after FMC_CLK high	2.5	-		

1. Guaranteed by characterization results.

Figure 33. Synchronous non-multiplexed PSRAM write timings



**Table 71. Synchronous non-multiplexed PSRAM write timings<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit	
$t_{(CLK)}$	FMC_CLK period	$2T_{fmc\_ker\_ck} - 0.5$	-	ns	
$t_{d(CLKL-NExL)}$	FMC_CLK low to FMC_NEx low (x=0..2)	-	3		
$t_{(CLKH-NExH)}$	FMC_CLK high to FMC_NEx high (x= 0...2)	$T_{fmc\_ker\_ck} + 1.5$	-		
$t_{d(CLKL-NADV L)}$	FMC_CLK low to FMC_NADV low	$1.62\text{ V} < V_{DD} < 3.6\text{ V}$	-		5.5
		$2.7\text{ V} < V_{DD} < 3.6\text{ V}$	-		2
$t_{d(CLKL-NADV H)}$	FMC_CLK low to FMC_NADV high	$1.62\text{ V} < V_{DD} < 3.6\text{ V}$	1		-
		$2.7\text{ V} < V_{DD} < 3.6\text{ V}$	-		-
$t_{d(CLKL-AV)}$	FMC_CLK low to FMC_Ax valid (x=16...25)	-	3		
$t_{d(CLKH-AIV)}$	FMC_CLK high to FMC_Ax invalid (x=16...25)	$T_{fmc\_ker\_ck}$	-		
$t_{d(CLKL-NWEL)}$	FMC_CLK low to FMC_NWE low	-	2.5		
$t_{d(CLKH-NWEH)}$	FMC_CLK high to FMC_NWE high	$T_{fmc\_ker\_ck} + 1$	-		
$t_{d(CLKL-Data)}$	FMC_D[15:0] valid data after FMC_CLK low	-	3.5		
$t_{d(CLKL-NBLL)}$	FMC_CLK low to FMC_NBL low	-	2		
$t_{d(CLKH-NBLH)}$	FMC_CLK high to FMC_NBL high	$T_{fmc\_ker\_ck} + 0.5$	-		
$t_{su(NWAIT-CLKH)}$	FMC_NWAIT valid before FMC_CLK high	3	-		
$t_h(CLKH-NWAIT)$	FMC_NWAIT valid after FMC_CLK high	2.5	-		

1. Guaranteed by characterization results.



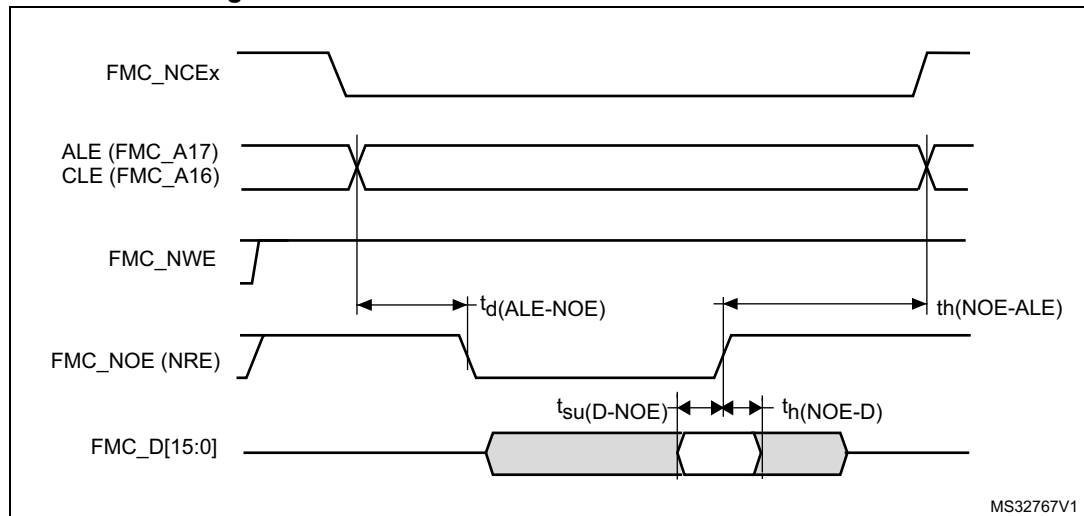
**NAND controller waveforms and timings**

Figure 34 through Figure 37 represent synchronous waveforms, and Table 72 and Table 73 provide the corresponding timings. The results shown in this table are obtained with the following FMC configuration and a capacitive load ( $C_L$ ) of 30 pF:

- COM.FMC\_SetupTime = 0x01
- COM.FMC\_WaitSetupTime = 0x03
- COM.FMC\_HoldSetupTime = 0x02
- COM.FMC\_HiZSetupTime = 0x01
- ATT.FMC\_SetupTime = 0x01
- ATT.FMC\_WaitSetupTime = 0x03
- ATT.FMC\_HoldSetupTime = 0x02
- ATT.FMC\_HiZSetupTime = 0x01
- Bank = FMC\_Bank\_NAND
- MemoryDataWidth = FMC\_MemoryDataWidth\_16b
- ECC = FMC\_ECC\_Enable
- ECCPageSize = FMC\_ECCPageSize\_512Bytes
- TCLRSetupTime = 0
- TARSetupTime = 0

In all timing tables, the  $T_{fmc\_ker\_ck}$  is the `fmc_ker_ck` clock period.

**Figure 34. NAND controller waveforms for read access**



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Figure 35. NAND controller waveforms for write access

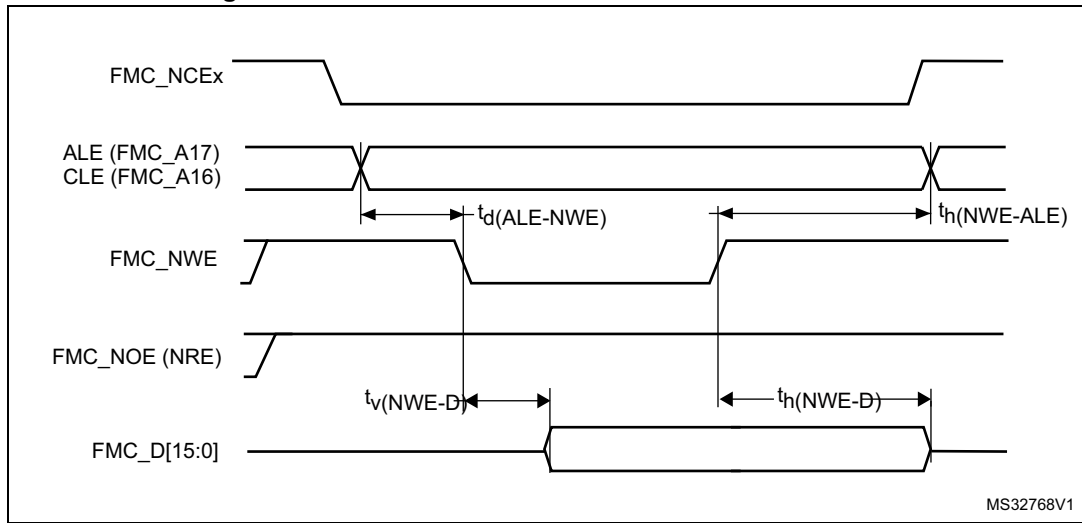


Figure 36. NAND controller waveforms for common memory read access

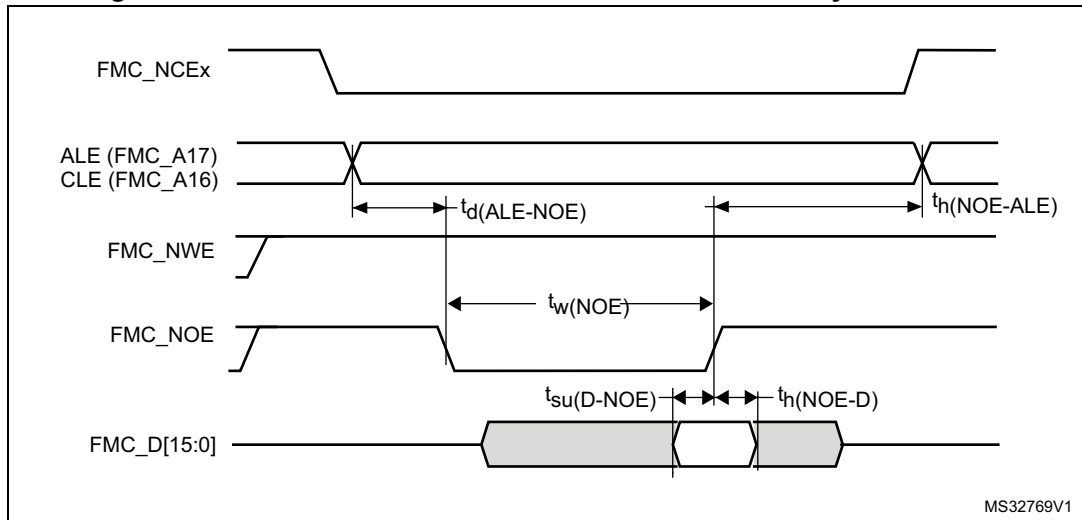


Figure 37. NAND controller waveforms for common memory write access

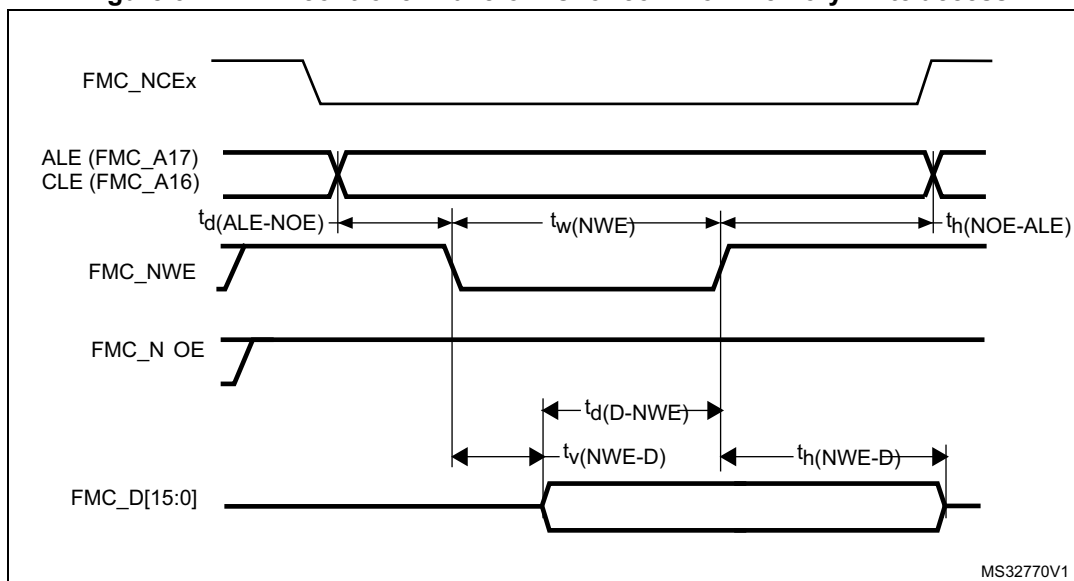


Table 72. Switching characteristics for NAND Flash read cycles<sup>(1)</sup>

Symbol	Parameter	Min	Max	Unit
$t_w(\text{NOE})$	FMC_NOE low width	$4T_{\text{fmc\_ker\_ck}} - 0.5$	$4T_{\text{fmc\_ker\_ck}} + 0.5$	ns
$t_{\text{su}}(\text{D-NOE})$	FMC_D[15-0] valid data before FMC_NOE high	11	-	
$t_h(\text{NOE-D})$	FMC_D[15-0] valid data after FMC_NOE high	0	-	
$t_d(\text{ALE-NOE})$	FMC_ALE valid before FMC_NOE low	-	$3T_{\text{fmc\_ker\_ck}} + 0.5$	
$t_h(\text{NOE-ALE})$	FMC_NWE high to FMC_ALE invalid	$4T_{\text{fmc\_ker\_ck}} - 1$	-	

1. Guaranteed by characterization results.

Table 73. Switching characteristics for NAND Flash write cycles<sup>(1)</sup>

Symbol	Parameter	Min	Max	Unit
$t_w(\text{NWE})$	FMC_NWE low width	$4T_{\text{fmc\_ker\_ck}} - 0.5$	$4T_{\text{fmc\_ker\_ck}} + 0.5$	ns
$t_v(\text{NWE-D})$	FMC_NWE low to FMC_D[15-0] valid	0	-	
$t_h(\text{NWE-D})$	FMC_NWE high to FMC_D[15-0] invalid	$2T_{\text{fmc\_ker\_ck}} + 1.5$	-	
$t_d(\text{D-NWE})$	FMC_D[15-0] valid before FMC_NWE high	$5T_{\text{fmc\_ker\_ck}} - 5$	-	
$t_d(\text{ALE-NWE})$	FMC_ALE valid before FMC_NWE low	-	$3T_{\text{fmc\_ker\_ck}} + 0.5$	
$t_h(\text{NWE-ALE})$	FMC_NWE high to FMC_ALE invalid	$2T_{\text{fmc\_ker\_ck}} - 0.5$	-	

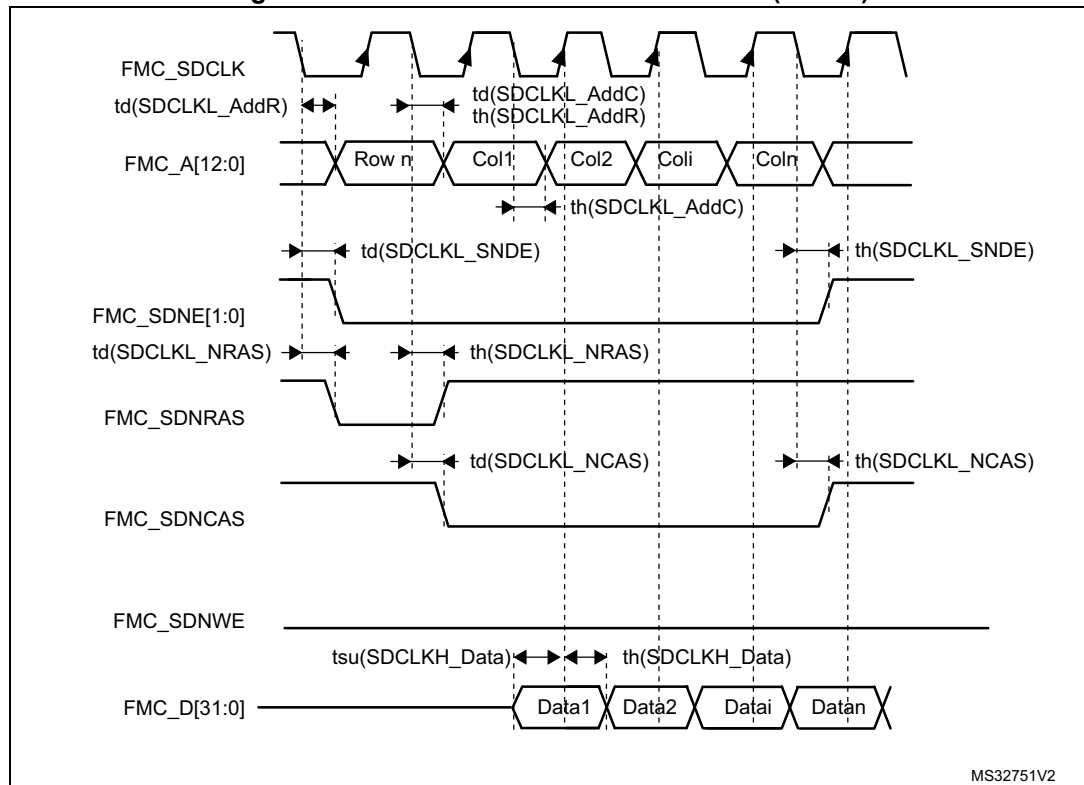
1. Guaranteed by characterization results.

**SDRAM waveforms and timings**

In all timing tables, the TKERCK is the `fmc_ker_ck` clock period, with the following FMC\_SDCLK maximum values:

- For  $2.7\text{ V} < V_{DD} < 3.6\text{ V}$ : maximum FMC\_CLK = 95 MHz at 20 pF
- For  $1.8\text{ V} < V_{DD} < 1.9\text{ V}$ : maximum FMC\_CLK = 90 MHz at 20 pF
- For  $1.62\text{ V} < V_{DD} < 1.8\text{ V}$ : maximum FMC\_CLK = 85 MHz at 15 pF

**Figure 38. SDRAM read access waveforms (CL = 1)**



**Table 74. SDRAM read timings<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
$t_w(\text{SDCLK})$	FMC_SDCLK period	$2T_{\text{fmc\_ker\_ck}} - 0.5$	$2T_{\text{fmc\_ker\_ck}} + 0.5$	ns
$t_{\text{su}}(\text{SDCLKH\_Data})$	Data input setup time	3	-	
$t_h(\text{SDCLKH\_Data})$	Data input hold time	1.5	-	
$t_d(\text{SDCLKL\_Add})$	Address valid time	-	2.0	
$t_d(\text{SDCLKL\_SDNE})$	Chip select valid time	-	1.5 <sup>(2)</sup>	
$t_h(\text{SDCLKL\_SDNE})$	Chip select hold time	0	-	
$t_d(\text{SDCLKL\_SDNRAS})$	SDNRAS valid time	-	1	
$t_h(\text{SDCLKL\_SDNRAS})$	SDNRAS hold time	0	-	
$t_d(\text{SDCLKL\_SDNCAS})$	SDNCAS valid time	-	2.0	
$t_h(\text{SDCLKL\_SDNCAS})$	SDNCAS hold time	0.5	-	

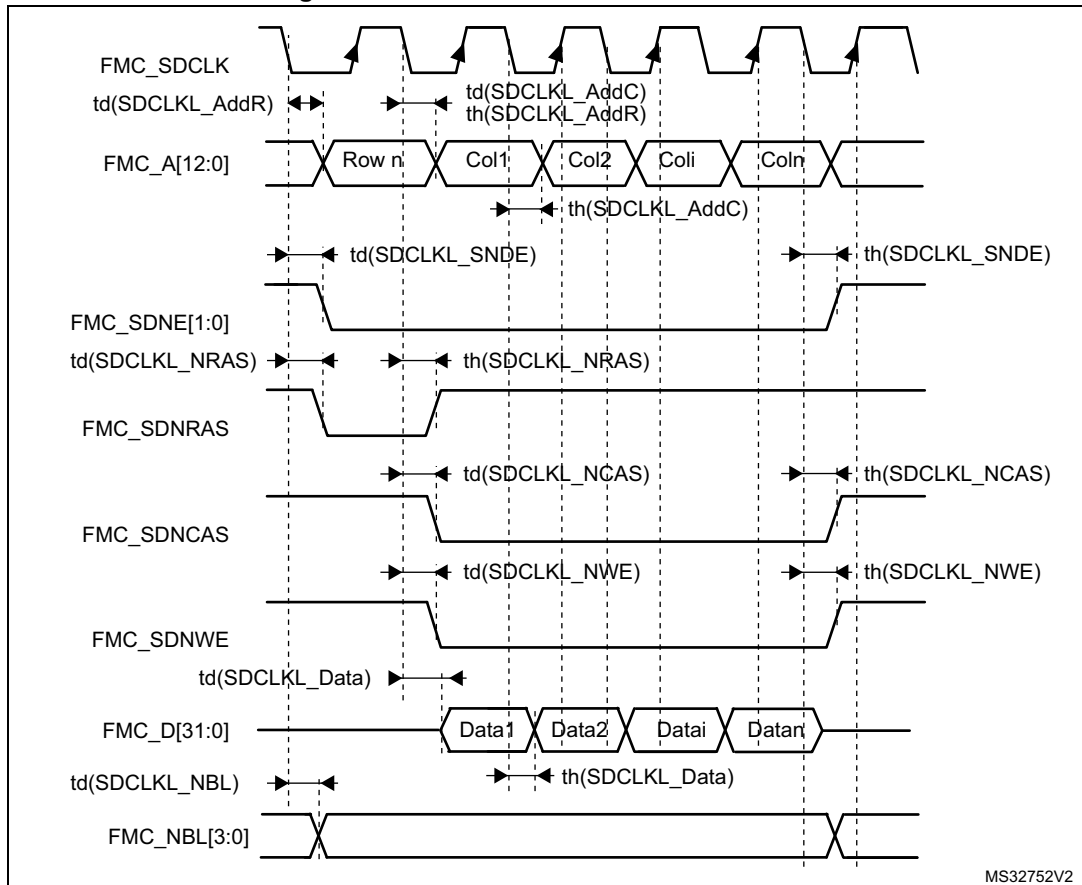
1. Guaranteed by characterization results.
2. Using PC2\_C I/O adds 4.5 ns to this timing.

**Table 75. LPSDR SDRAM read timings<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
$t_w(\text{SDCLK})$	FMC_SDCLK period	$2T_{\text{fmc\_ker\_ck}} - 0.5$	$2T_{\text{fmc\_ker\_ck}} + 0.5$	ns
$t_{\text{su}}(\text{SDCLKH\_Data})$	Data input setup time	3	-	
$t_h(\text{SDCLKH\_Data})$	Data input hold time	2.5	-	
$t_d(\text{SDCLKL\_Add})$	Address valid time	-	2	
$t_d(\text{SDCLKL\_SDNE})$	Chip select valid time	-	1.5 <sup>(2)(3)</sup>	
$t_h(\text{SDCLKL\_SDNE})$	Chip select hold time	0	-	
$t_d(\text{SDCLKL\_SDNRAS})$	SDNRAS valid time	-	1	
$t_h(\text{SDCLKL\_SDNRAS})$	SDNRAS hold time	0	-	
$t_d(\text{SDCLKL\_SDNCAS})$	SDNCAS valid time	-	2	
$t_h(\text{SDCLKL\_SDNCAS})$	SDNCAS hold time	0.5	-	

1. Guaranteed by characterization results.
2. Using PC2 I/O adds 4 ns to this timing.
3. Using PC2\_C I/O adds 16.5 ns to this timing.

Figure 39. SDRAM write access waveforms



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Table 76. SDRAM Write timings<sup>(1)</sup>

Symbol	Parameter	Min	Max	Unit
$t_w(\text{SDCLK})$	FMC_SDCLK period	$2T_{\text{fmc\_ker\_ck}} - 0.5$	$2T_{\text{fmc\_ker\_ck}} + 0.5$	ns
$t_d(\text{SDCLKL\_Data})$	Data output valid time	-	2	
$t_h(\text{SDCLKL\_Data})$	Data output hold time	0.5	-	
$t_d(\text{SDCLKL\_Add})$	Address valid time	-	2	
$t_d(\text{SDCLKL\_SDNWE})$	SDNWE valid time	-	2	
$t_h(\text{SDCLKL\_SDNWE})$	SDNWE hold time	0	-	
$t_d(\text{SDCLKL\_SDNE})$	Chip select valid time	-	1.5 <sup>(2)</sup>	
$t_h(\text{SDCLKL\_SDNE})$	Chip select hold time	0	-	
$t_d(\text{SDCLKL\_SDNRAS})$	SDNRAS valid time	-	1	
$t_h(\text{SDCLKL\_SDNRAS})$	SDNRAS hold time	0	-	
$t_d(\text{SDCLKL\_SDNCAS})$	SDNCAS valid time	-	2	
$t_d(\text{SDCLKL\_SDNCAS})$	SDNCAS hold time	0.5	-	

1. Guaranteed by characterization results.
2. Using PC2\_C I/O adds 4.5 ns to this timing.

**Table 77. LPSDR SDRAM Write timings<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
$t_w(\text{SDCLK})$	FMC_SDCLK period	$2T_{\text{fmc\_ker\_ck}} - 0.5$	$2T_{\text{fmc\_ker\_ck}} + 0.5$	ns
$t_d(\text{SDCLKL\_Data})$	Data output valid time	-	2	
$t_h(\text{SDCLKL\_Data})$	Data output hold time	0	-	
$t_d(\text{SDCLKL\_Add})$	Address valid time	-	2.5	
$t_d(\text{SDCLKL-SDNWE})$	SDNWE valid time	-	2	
$t_h(\text{SDCLKL-SDNWE})$	SDNWE hold time	0	-	
$t_d(\text{SDCLKL-SDNE})$	Chip select valid time	-	$1.5^{(2)(3)}$	
$t_h(\text{SDCLKL-SDNE})$	Chip select hold time	0	-	
$t_d(\text{SDCLKL-SDNRAS})$	SDNRAS valid time	-	1	
$t_h(\text{SDCLKL-SDNRAS})$	SDNRAS hold time	0	-	
$t_d(\text{SDCLKL-SDNCAS})$	SDNCAS valid time	-	2	
$t_d(\text{SDCLKL-SDNCAS})$	SDNCAS hold time	0.5	-	

1. Guaranteed by characterization results.
2. Using PC2 I/O adds 4 ns to this timing.
3. Using PC2\_C I/O adds 16.5 ns to this timing.

### 6.3.20 Octo-SPI interface characteristics

Unless otherwise specified, the parameters given in [Table 78](#) and [Table 80](#) for OCTOSPI are derived from tests performed under the ambient temperature,  $f_{\text{HCLK}}$  frequency and  $V_{\text{DD}}$  supply voltage conditions summarized in [Table 12: General operating conditions](#), with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 11
- Measurement points are done at CMOS levels:  $0.5V_{\text{DD}}$
- IO Compensation cell activated.
- HSLV activated when  $V_{\text{DD}} \leq 2.5 \text{ V}$
- VOS level set to VOS0

Refer to [Section 6.3.17: I/O port characteristics](#) for more details on the input/output alternate function characteristics.

**Table 78. OCTOSPI characteristics in SDR mode<sup>(1)(2)</sup>**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$F_{\text{(CLK)}}$	OCTOSPI clock frequency	$1.71 \text{ V} < V_{\text{DD}} < 3.6 \text{ V}$ , VOS0, $C_{\text{LOAD}} = 15 \text{ pF}$	-	-	92	MHz
		$1.71 \text{ V} < V_{\text{DD}} < 3.6 \text{ V}$ , VOS0, $C_{\text{LOAD}} = 20 \text{ pF}$	-	-	90	
		$2.7 \text{ V} < V_{\text{DD}} < 3.6 \text{ V}$ , VOS0, $C_{\text{LOAD}} = 20 \text{ pF}$	-	-	140	

Table 78. OCTOSPI characteristics in SDR mode<sup>(1)(2)</sup> (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$t_{w(CKH)}$	OCTOSPI clock high and low time, even division	PRESCALER[7:0] = n = 0,1,3,5	$t_{(CK)}/2$	-	$t_{(CK)}/2+1$	ns
$t_{w(CKL)}$			$t_{(CK)}/2-1$	-	$t_{(CK)}/2$	
$t_{w(CKH)}$	OCTOSPI clock high and low time, odd division	PRESCALER[7:0] = n = 2,4,6,8	$(n/2)*t_{(CK)}/(n+1)$	-	$(n/2)*t_{(CK)}/(n+1)+1$	
$t_{w(CKL)}$			$(n/2+1)*t_{(CK)}/(n+1)-1$	-	$(n/2+1)*t_{(CK)}/(n+1)$	
$t_{s(IN)}^{(3)}$	Data input setup time	-	3.0	-	-	
$t_{h(IN)}^{(3)}$	Data input hold time	-	1.5	-	-	
$t_{v(OUT)}$	Data output valid time	-	-	0.5	1 <sup>(4)</sup>	
$t_{h(OUT)}$	Data output hold time	-	0	-	-	

1. All values apply to Octal and Quad-SPI mode.
2. Guaranteed by characterization results.
3. Delay block bypassed.
4. Using PC2 or PC3 I/O in the data bus adds 4 ns to this timing value.

Figure 40. OCTOSPI SDR read/write timing diagram

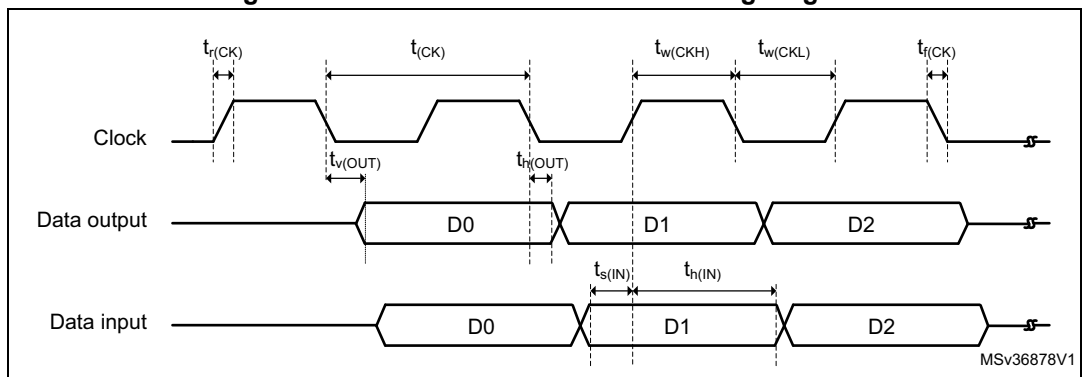




Table 79. OCTOSPI characteristics in DTR mode (no DQS)<sup>(1)(2)</sup>

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$F_{CK}^{(3)}$	OCTOSPI clock frequency	$1.71\text{ V} < V_{DD} < 3.6\text{ V}$ , $VOS0, C_{LOAD} = 15\text{ pF}$	-	-	90 <sup>(4)</sup>	MHz
		$1.71\text{ V} < V_{DD} < 3.6\text{ V}$ , $VOS0, C_{LOAD} = 20\text{ pF}$	-	-	87 <sup>(4)</sup>	
		$2.7\text{ V} < V_{DD} < 3.6\text{ V}$ , $VOS0, C_{LOAD} = 20\text{ pF}$	-	-	110	
$t_{w(CKH)}$	OCTOSPI clock high and low time, even division	PRESCALER[7:0] = n = 0,1,3,5	$t_{CK}/2$	-	$t_{CK}/2+1$	ns
$t_{w(CKL)}$			$t_{CK}/2-1$	-	$t_{CK}/2$	
$t_{w(CKH)}$	OCTOSPI clock high and low time, odd division	PRESCALER[7:0] = n = 2,4,6,8	$(n/2)*t_{CK}/(n+1)$	-	$(n/2)*t_{CK}/(n+1)+1$	
$t_{w(CKL)}$			$(n/2+1)*t_{CK}/(n+1)-1$	-	$(n/2+1)*t_{CK}/(n+1)$	
$t_{sr(IN)}$ $t_{sf(IN)}$ <sup>(5)</sup>	Data input setup time	-	3.0	-	-	
$t_{hr(IN)}$ $t_{hf(IN)}$ <sup>(5)</sup>	Data input hold time	-	1.50	-	-	
$t_{vr(OUT)}$ $t_{vf(OUT)}$	Data output valid time	DHQC = 0	-	6	7 <sup>(6)</sup>	
		DHQC = 1, Prescaler = 1,2 ...	-	$t_{pclk}/4+1$	$t_{pclk}/4+1.25$ <sup>(6)</sup>	
$t_{hr(OUT)}$ $t_{hf(OUT)}$	Data output hold time	DHQC = 0	4.5	-	-	
		DHQC = 1, Prescaler = 1,2 ...	$t_{pclk}/4$	-	-	

1. All values apply to Octal and Quad-SPI mode.
2. Guaranteed by characterization results.
3. DHQC must be set to reach the mentioned frequency.
4. Using PC2 or PC3 I/O in the data bus decreases the frequency to 47 MHz.
5. Delay block bypassed.
6. Using PC2 or PC3 I/O in the data bus adds 4 ns to this timing value.

Figure 41. OCTOSPI DTR mode timing diagram

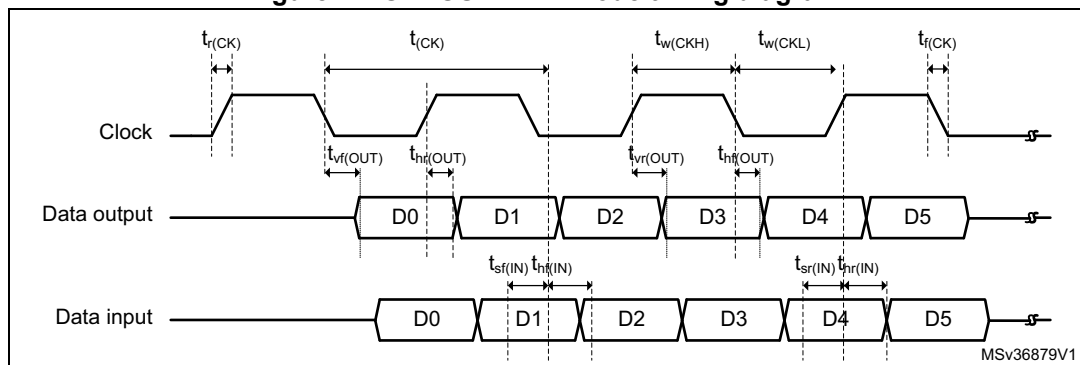


Table 80. OCTOSPI characteristics in DTR mode (with DQS)/Octal and Hyperbus<sup>(1)</sup>

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
F <sub>CK</sub> <sup>(2)(3)</sup>	OCTOSPI clock frequency	2,7 V < V <sub>DD</sub> < 3.6 V, VOS0, C <sub>LOAD</sub> = 20 pF	-	-	100	MHz
		1.71 V < V <sub>DD</sub> < 3.6 V, VOS0, C <sub>LOAD</sub> = 20 pF	-	-	100 <sup>(4)</sup>	
t <sub>w(CKH)</sub>	OCTOSPI clock high and low time, even division	PRESCALER[7:0] = n = 0,1,3,5	t <sub>CK</sub> /2	-	t <sub>CK</sub> /2+1	ns
t <sub>w(CKL)</sub>			t <sub>CK</sub> /2-1	-	t <sub>CK</sub> /2	
t <sub>w(CKH)</sub>	OCTOSPI clock high and low time, odd division	PRESCALER[7:0] = n = 2,4,6,8	(n/2)*t <sub>CK</sub> /(n+1)	-	(n/2)*t <sub>CK</sub> /(n+1)+1	ns
t <sub>w(CKL)</sub>			(n/2+1)*t <sub>CK</sub> /(n+1)-1	-	(n/2+1)*t <sub>CK</sub> /(n+1)	
t <sub>v(CK)</sub>	Clock valid time	-	-	-	t <sub>CK</sub> +1	
t <sub>h(CK)</sub>	Clock hold time	-	t <sub>CK</sub> /2	-	-	
V <sub>ODr(CK)</sub>	CK, $\overline{CK}$ crossing level on CK rising edge	VDD = 1.8 V	922	-	1229	mV
V <sub>ODf(CK)</sub>	CK, $\overline{CK}$ crossing level on CK falling edge	VDD = 1.8 V	1000	-	1277	
t <sub>w(CS)</sub>	Chip select high time	-	3*t <sub>CK</sub>	-	-	ns
t <sub>v(DQ)</sub>	Data input valid time	-	0	-	-	
t <sub>v(DS)</sub>	Data strobe input valid time	-	0	-	-	
t <sub>h(DS)</sub>	Data strobe input hold time	-	0	-	-	
t <sub>v(RWDS)</sub>	Data strobe output valid time	-	-	-	3 x t <sub>CK</sub>	
t <sub>sr(DQ)</sub>	Data input setup time	Rising edge	0	-	-	
t <sub>sf(DQ)</sub>		Falling edge	0	-	-	
t <sub>hr(DQ)</sub>	Data input hold time	Rising edge	1	-	-	
t <sub>hf(DQ)</sub>		Falling edge	1	-	-	
t <sub>vr(OUT)</sub>	Data output valid time rising edge	DHQC = 0	-	6	7 <sup>(5)</sup>	
		DHQC = 1, Prescaler = 1,2...	-	t <sub>pclk</sub> /4+1	t <sub>pclk</sub> /4+1.25 <sup>(5)</sup>	
t <sub>vf(OUT)</sub>	Data output valid time falling edge	DHQC = 0	-	5.5	6 <sup>(5)</sup>	
		DHQC = 1, Prescaler = 1,2...	-	t <sub>pclk</sub> /4+0.5	t <sub>pclk</sub> /4+0.75 <sup>(5)</sup>	
t <sub>hr(OUT)</sub>	Data output hold time rising edge	DHQC = 0	4.5	-	-	
		DHQC = 1, Prescaler = 1,2...	t <sub>pclk</sub> /4	-	-	
t <sub>hf(OUT)</sub>	Data output hold time falling edge	DHQC = 0	4.5	-	-	
		DHQC = 1, Prescaler = 1,2...	t <sub>pclk</sub> /4	-	-	

1. Guaranteed by characterization results.

2. Maximum frequency values are given for a RWDS to DQ skew of maximum +/-1.0 ns.
3. Activating DHQC is mandatory to reach this frequency
4. Using PC2 or PC3 I/O on data bus decreases the frequency to 47 MHz.
5. Using PC2 or PC3 I/O on the data bus adds 4 ns to this timing value.

Figure 42. OCTOSPI Hyperbus clock timing diagram

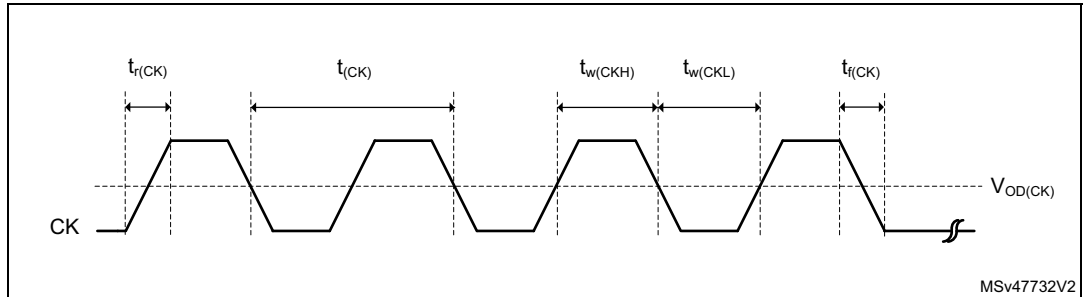


Figure 43. OCTOSPI Hyperbus read timing diagram

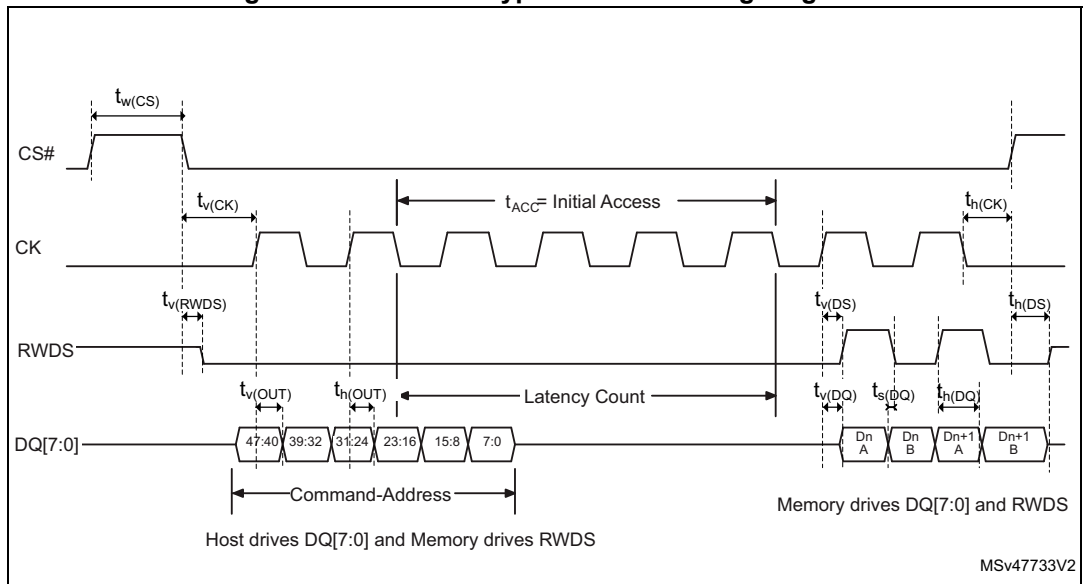
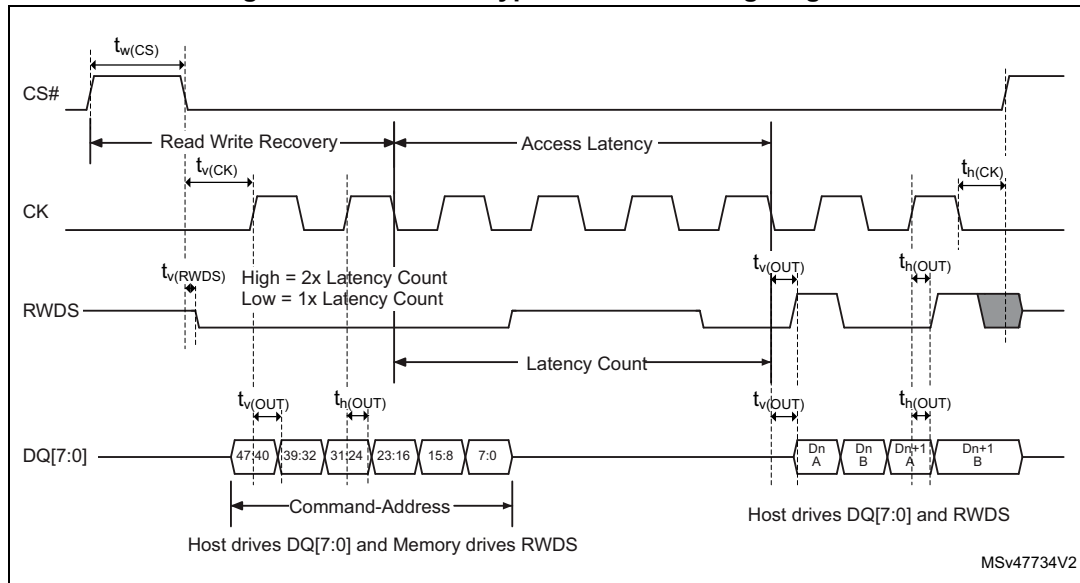


Figure 44. OCTOSPI Hyperbus write timing diagram



### 6.3.21 Delay block (DLYB) characteristics

Unless otherwise specified, the parameters given in [Table 81](#) for Delay Block are derived from tests performed under the ambient temperature,  $f_{\text{RCC\_C\_ck}}$  frequency and  $V_{\text{DD}}$  supply voltage summarized in [Table 12: General operating conditions](#), with the following configuration:

Table 81. Delay Block characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$t_{\text{init}}$	Initial delay	-	900	1300	1900	ps
$t_{\Delta}$	Unit Delay	-	28	33	41	-

### 6.3.22 16-bit ADC characteristics

Unless otherwise specified, the parameters given in [Table 82](#), [Table 83](#) and [Table 84](#) are derived from tests performed under the ambient temperature,  $f_{\text{PCLK2}}$  frequency and  $V_{\text{DDA}}$  supply voltage conditions summarized in [Table 12: General operating conditions](#).

Table 82. 16-bit ADC characteristics<sup>(1)(2)</sup>

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{\text{DDA}}$	Analog supply voltage for ADC ON	-	1.62	-	3.6	V
$V_{\text{REF+}}$	Positive reference voltage	$V_{\text{DDA}} \geq 2 \text{ V}$	1.62	-	$V_{\text{DDA}}$	
		$V_{\text{DDA}} < 2 \text{ V}$	$V_{\text{DDA}}$			
$V_{\text{REF-}}$	Negative reference voltage	-	$V_{\text{SSA}}$			

Table 82. 16-bit ADC characteristics<sup>(1)(2)</sup> (continued)

Symbol	Parameter	Conditions				Min	Typ	Max	Unit	
f <sub>ADC</sub>	ADC clock frequency	1.62 V ≤ V <sub>DDA</sub> ≤ 3.6 V				BOOST = 11	0.12	-	50	MHz
						BOOST = 10	0.12	-	25	
						BOOST = 01	0.12	-	12.5	
						BOOST = 00	-	-	6.25	
f <sub>s</sub> <sup>(3)</sup>	Sampling rate for Direct channels	Resolution = 16 bits, V <sub>DDA</sub> > 2.5 V	T <sub>J</sub> = 90 °C	f <sub>ADC</sub> = 36 MHz	SMP = 1.5	-	-	3.60	MSps	
		Resolution = 16 bits		f <sub>ADC</sub> = 37 MHz	SMP = 2.5	-	-	3.35		
		Resolution = 14 bits	T <sub>J</sub> = 125 °C	f <sub>ADC</sub> = 50 MHz	SMP = 2.5	-	-	5.00		
		Resolution = 12 bits		f <sub>ADC</sub> = 50 MHz	SMP = 2.5	-	-	5.50		
		Resolution = 10 bits		f <sub>ADC</sub> = 50 MHz	SMP = 1.5	-	-	7.10		
		Resolution = 8 bits		f <sub>ADC</sub> = 50 MHz	SMP = 1.5	-	-	8.30		
		Resolution = 14 bits	T <sub>J</sub> = 140 °C	f <sub>ADC</sub> = 49 MHz	SMP = 1.5	-	-	4.90		
		Resolution = 12 bits		f <sub>ADC</sub> = 50 MHz	SMP = 1.5	-	-	5.50		
		Resolution = 10 bits		f <sub>ADC</sub> = 50 MHz	SMP = 1.5	-	-	6.70		
		Resolution = 8 bits		f <sub>ADC</sub> = 50 MHz	SMP = 1.5	-	-	8.30		
		Sampling rate for Fast channels	Resolution = 16 bits, V <sub>DDA</sub> > 2.5 V	T <sub>J</sub> = 90 °C	f <sub>ADC</sub> = 32 MHz	SMP = 2.5	-	-		2.90
			Resolution = 16 bits		f <sub>ADC</sub> = 31 MHz	SMP = 2.5	-	-		2.80
	Resolution = 14 bits		T <sub>J</sub> = 125 °C	f <sub>ADC</sub> = 33 MHz	SMP = 2.5	-	-	3.30		
	Resolution = 12 bits			f <sub>ADC</sub> = 39 MHz	SMP = 2.5	-	-	4.30		
	Resolution = 10 bits			f <sub>ADC</sub> = 48 MHz	SMP = 2.5	-	-	6.00		
	Resolution = 8 bits			f <sub>ADC</sub> = 50 MHz	SMP = 2.5	-	-	7.10		
	Resolution = 12 bits		T <sub>J</sub> = 140 °C	f <sub>ADC</sub> = 37 MHz	SMP = 2.5	-	-	4.10		
	Resolution = 10 bits			f <sub>ADC</sub> = 46 MHz	SMP = 2.5	-	-	5.70		
	Resolution = 8 bits	f <sub>ADC</sub> = 50 MHz		SMP = 2.5	-	-	7.10			
	Sampling rate for Slow channels, BOOST = 0, f <sub>ADC</sub> = 10 MHz	Resolution = 16 bits	T <sub>J</sub> = 90 °C	f <sub>ADC</sub> = 10 MHz	SMP = 1.5	-	-	1.00		
		resolution = 14 bits				-	-			
		resolution = 12 bits				-	-			
		resolution = 10 bits				-	-			
		resolution = 8 bits	T <sub>J</sub> = 125 °C			-	-			
		resolution = 12 bits				-	-			
		resolution = 10 bits				-	-			
		resolution = 8 bits				-	-			
	t <sub>TRIG</sub>	External trigger period	Resolution = 16 bits				-	-		10
					0	-	V <sub>REF+</sub>	V		
V <sub>AIN</sub> <sup>(4)</sup>	Conversion voltage range					0	-	V <sub>REF+</sub>	V	
V <sub>CMIV</sub>	Common mode input voltage					V <sub>REF</sub> /2 - 10%	V <sub>REF</sub> /2	V <sub>REF</sub> /2 + 10%	V	

Table 82. 16-bit ADC characteristics<sup>(1)(2)</sup> (continued)

Symbol	Parameter	Conditions			Min	Typ	Max	Unit
R <sub>AIN</sub> <sup>(5)</sup>	External input impedance	Resolution = 16 bits, T <sub>J</sub> = 125 °C	-	-	-	-	170	Ω
		Resolution = 14 bits, T <sub>J</sub> = 125 °C	-	-	-	-	435	
		Resolution = 12 bits, T <sub>J</sub> = 125 °C	-	-	-	-	1,150	
		Resolution = 10 bits, T <sub>J</sub> = 125 °C	-	-	-	-	5,650	
		Resolution = 8 bits, T <sub>J</sub> = 125 °C	-	-	-	-	26,500	
C <sub>ADC</sub>	Internal sample and hold capacitor	-			-	4	-	pF
t <sub>ADCVREG_STUP</sub>	ADC LDO startup time	-			-	5	10	us
t <sub>STAB</sub>	ADC Power-up time	LDO already started			1	-	-	conversion cycle
t <sub>CAL</sub>	Offset and linearity calibration time	-			16,5010			1/f <sub>ADC</sub>
t <sub>OFF_CAL</sub>	Offset calibration time	-			1,280			1/f <sub>ADC</sub>
t <sub>LATR</sub>	Trigger conversion latency regular and injected channels without conversion abort	CKMODE = 00			1.5	2	2.5	1/f <sub>ADC</sub>
		CKMODE = 01			-	-	2.5	
		CKMODE = 10			-	-	2.5	
		CKMODE = 11			-	-	2.25	
t <sub>LATRINJ</sub>	Trigger conversion latency regular injected channels aborting a regular conversion	CKMODE = 00			2.5	3	3.5	1/f <sub>ADC</sub>
		CKMODE = 01			-	-	3.5	
		CKMODE = 10			-	-	3.5	
		CKMODE = 11			-	-	3.25	
t <sub>S</sub>	Sampling time	-			1.5	-	810.5	1/f <sub>ADC</sub>
t <sub>CONV</sub>	Total conversion time (including sampling time)	Resolution = N bits			ts + 0.5 + N/2	-	-	1/f <sub>ADC</sub>

Table 82. 16-bit ADC characteristics<sup>(1)(2)</sup> (continued)

Symbol	Parameter	Conditions			Min	Typ	Max	Unit
I <sub>DDA-D</sub> (ADC)	ADC consumption on V <sub>DDA</sub> , BOOST=11, Differential mode	Resolution = 16 bits, f <sub>ADC</sub> = 25 MHz	-	-	-	1,440	-	μA
		Resolution = 14 bits, f <sub>ADC</sub> = 30 MHz	-	-	-	1,350	-	
		Resolution = 12 bits, f <sub>ADC</sub> = 40 MHz	-	-	-	990	-	
	ADC consumption on V <sub>DDA</sub> , BOOST=10, Differential mode, f <sub>ADC</sub> = 25 MHz	Resolution = 16 bits	-	-	-	1,080	-	
		Resolution = 14 bits	-	-	-	810	-	
		Resolution = 12 bits	-	-	-	585	-	
	ADC consumption on V <sub>DDA</sub> , BOOST=01, Differential mode, f <sub>ADC</sub> = 12.5 MHz	Resolution = 16 bits	-	-	-	630	-	
		Resolution = 14 bits	-	-	-	432	-	
		Resolution = 12 bits	-	-	-	315	-	
	ADC consumption on V <sub>DDA</sub> , BOOST=00, Differential mode, f <sub>ADC</sub> = 6.25 MHz	Resolution = 16 bits	-	-	-	360	-	
		Resolution = 14 bits	-	-	-	270	-	
		Resolution = 12 bits	-	-	-	225	-	
I <sub>DDA-SE</sub> (ADC)	ADC consumption on V <sub>DDA</sub> , BOOST=11, Single-ended mode	Resolution = 16 bits, f <sub>ADC</sub> =25 MHz	-	-	-	720	-	
		Resolution = 14 bits, f <sub>ADC</sub> =30 MHz	-	-	-	675	-	
		Resolution = 12 bits, f <sub>ADC</sub> =40 MHz	-	-	-	495	-	
	ADC consumption on V <sub>DDA</sub> , BOOST=10, Single-ended mode, f <sub>ADC</sub> = 25 MHz	Resolution = 16 bits	-	-	-	540	-	
		Resolution = 14 bits	-	-	-	405	-	
		Resolution = 12 bits	-	-	-	292.5	-	
	ADC consumption on V <sub>DDA</sub> , BOOST=01, Single-ended mode, f <sub>ADC</sub> = 12.5 MHz	Resolution = 16 bits	-	-	-	315	-	
		Resolution = 14 bits	-	-	-	216	-	
		Resolution = 12 bits	-	-	-	157.5	-	
	ADC consumption on V <sub>DDA</sub> , BOOST=00, Single-ended mode, f <sub>ADC</sub> =6.25 MHz	Resolution = 16 bits	-	-	-	180	-	
		Resolution = 14 bits	-	-	-	135	-	
		Resolution = 12 bits	-	-	-	112.5	-	
I <sub>DD</sub> (ADC)	ADC consumption on V <sub>DD</sub>	f <sub>ADC</sub> =50 MHz	-	-	-	400	-	
		f <sub>ADC</sub> =25 MHz	-	-	-	220	-	
		f <sub>ADC</sub> =12.5 MHz	-	-	-	180	-	
		f <sub>ADC</sub> =6.25 MHz	-	-	-	120	-	
		f <sub>ADC</sub> =3.125 MHz	-	-	-	80	-	

1. Guaranteed by design.

2. The voltage booster on ADC switches must be used for V<sub>DDA</sub> < 2.4 V (embedded I/O switches).

3. These values are valid for TFBGA100, UFBGA169 and UFBGA176+25 packages and one ADC. The values for other packages and multiple ADCs may be different.
4. Depending on the package,  $V_{REF+}$  can be internally connected to  $V_{DDA}$  and  $V_{REF-}$  to  $V_{SSA}$ .
5. The tolerance is 10 LSBs for 16-bit resolution, 4 LSBs for 14-bit resolution, and 2 LSBs for 12-bit, 10-bit and 8-bit resolutions.

**Table 83. Minimum sampling time vs  $R_{AIN}$  (16-bit ADC)<sup>(1)(2)</sup>**

Resolution	$R_{AIN}$ ( $\Omega$ )	Minimum sampling time (s)		
		Direct channels <sup>(3)</sup>	Fast channels <sup>(4)</sup>	Slow channels <sup>(5)</sup>
16 bits	47	7.37E-08	1.14E-07	1.72E-07
14 bits	47	6.29E-08	9.74E-08	1.55E-07
	68	6.84E-08	1.02E-07	1.58E-07
	100	7.80E-08	1.12E-07	1.62E-07
	150	9.86E-08	1.32E-07	1.80E-07
	220	1.32E-07	1.61E-07	2.01E-07
12 bits	47	5.32E-08	8.00E-08	1.29E-07
	68	5.74E-08	8.50E-08	1.32E-07
	100	6.58E-08	9.31E-08	1.40E-07
	150	8.37E-08	1.10E-07	1.51E-07
	220	1.11E-07	1.34E-07	1.73E-07
	330	1.56E-07	1.78E-07	2.14E-07
	470	2.16E-07	2.39E-07	2.68E-07
680	3.01E-07	3.29E-07	3.54E-07	
10 bits	47	4.34E-08	6.51E-08	1.08E-07
	68	4.68E-08	6.89E-08	1.11E-07
	100	5.35E-08	7.55E-08	1.16E-07
	150	6.68E-08	8.77E-08	1.26E-07
	220	8.80E-08	1.08E-07	1.40E-07
	330	1.24E-07	1.43E-07	1.71E-07
	470	1.69E-07	1.89E-07	2.13E-07
	680	2.38E-07	2.60E-07	2.80E-07
	1000	3.45E-07	3.66E-07	3.84E-07
	1500	5.15E-07	5.35E-07	5.48E-07
	2200	7.42E-07	7.75E-07	7.78E-07
3300	1.10E-06	1.14E-06	1.14E-06	



**Table 83. Minimum sampling time vs R<sub>AIN</sub> (16-bit ADC)<sup>(1)(2)</sup> (continued)**

Resolution	R <sub>AIN</sub> (Ω)	Minimum sampling time (s)		
		Direct channels <sup>(3)</sup>	Fast channels <sup>(4)</sup>	Slow channels <sup>(5)</sup>
8 bits	47	3.32E-08	5.10E-08	8.61E-08
	68	3.59E-08	5.35E-08	8.83E-08
	100	4.10E-08	5.83E-08	9.22E-08
	150	5.06E-08	6.76E-08	9.95E-08
	220	6.61E-08	8.22E-08	1.11E-07
	330	9.17E-08	1.08E-07	1.32E-07
	470	1.24E-07	1.40E-07	1.63E-07
	680	1.74E-07	1.91E-07	2.12E-07
	1000	2.53E-07	2.70E-07	2.85E-07
	1500	3.73E-07	3.93E-07	4.05E-07
	2200	5.39E-07	5.67E-07	5.75E-07
	3300	8.02E-07	8.36E-07	8.38E-07
	4700	1.13E-06	1.18E-06	1.18E-06
	6800	1.62E-06	1.69E-06	1.68E-06
	10000	2.36E-06	2.47E-06	2.45E-06
15000	3.50E-06	3.69E-06	3.65E-06	

1. Guaranteed by design.
2. Data valid at up to 130 °C, with a 47 pF PCB capacitor, and V<sub>DDA</sub>=1.6 V.
3. Direct channels are connected to analog I/Os (PA0\_C, PA1\_C, PC2\_C and PC3\_C) to optimize ADC performance.
4. Fast channels correspond to PA6, PB1, PC4, PF11, PF13 for ADCx\_INPx, and to PA7, PB0, PC5, PF12, PF14 for ADCx\_INNx.
5. Slow channels correspond to all ADC inputs except for the Direct and Fast channels.

Table 84. 16-bit ADC accuracy<sup>(1)(2)</sup>

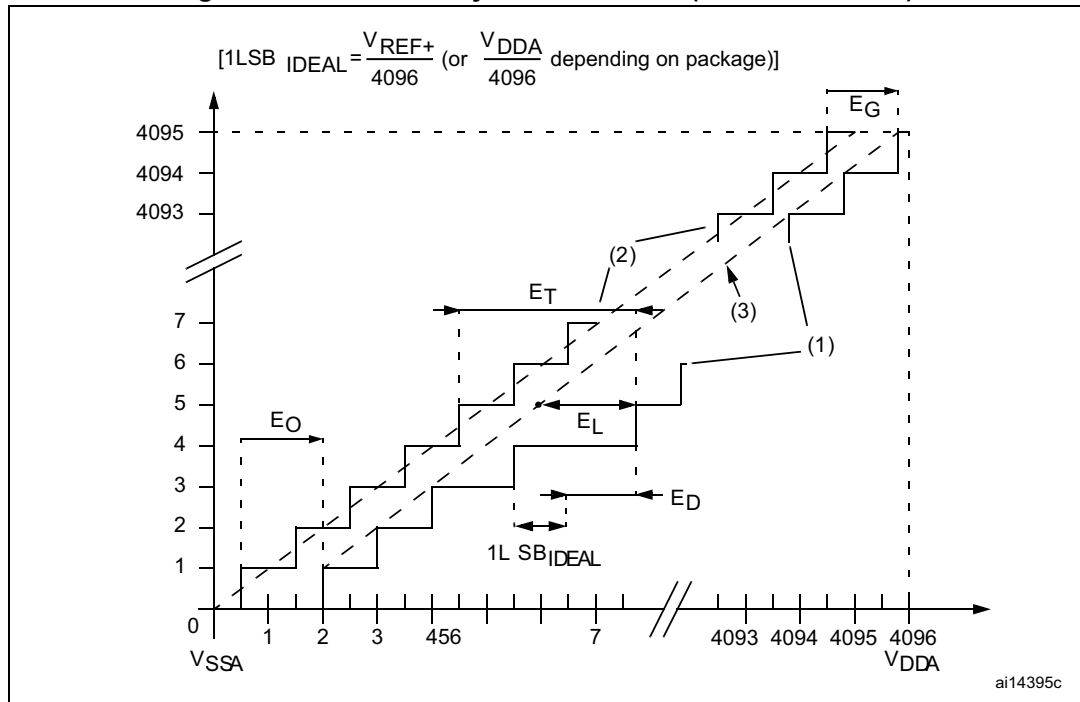
Symbol	Parameter	Conditions <sup>(3)</sup>		Min	Typ	Max	Unit
ET	Total undadjusted error	Direct channel	Single ended	-	+10/-20	-	LSB
			Differential	-	±15	-	
		Fast channel	Single ended	-	+10/-20	-	
			Differential	-	±15	-	
		Slow channel	Single ended	-	±10	-	
			Differential	-	±10	-	
EO	Offset error	-		-	±10	-	LSB
EG	Gain error	-		-	±15	-	
ED	Differential linearity error	Single ended		-	+3/-1	-	
		Differential		-	+4.5/-1	-	
EL	Integral linearity error	Direct channel	Single ended	-	±11	-	LSB
			Differential	-	±7	-	
		Fast channel	Single ended	-	±13	-	
			Differential	-	±7	-	
		Slow channel	Single ended	-	±10	-	
			Differential	-	±6	-	
ENOB	Effective number of bits	Single ended		-	12.2	-	Bits
		Differential		-	13.2	-	
SINAD	Signal-to-noise and distortion ratio	Single ended		-	75.2	-	dB
		Differential		-	81.2	-	
SNR	Signal-to-noise ratio	Single ended		-	77.0	-	
		Differential		-	81.0	-	
THD	Total harmonic distortion	Single ended		-	87	-	
		Differential		-	90	-	

1. Guaranteed by characterization results for BGA packages. The values for LQFP packages might differ.
2. ADC DC accuracy values are measured after internal calibration.
3. ADC clock frequency = 25 MHz, ADC resolution = 16 bits,  $V_{DDA}=V_{REF+}=3.3$  V, BOOST=11 and 16-bit mode.

Note: ADC accuracy vs. negative injection current: injecting a negative current on any analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative currents.

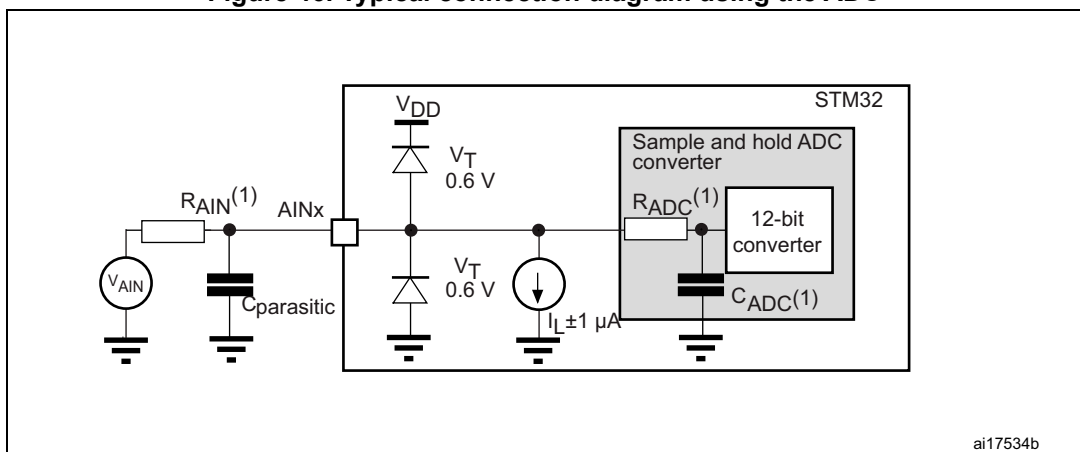
Any positive injection current within the limits specified for  $I_{INJ(PIN)}$  and  $\Sigma I_{INJ(PIN)}$  does not affect the ADC accuracy.

Figure 45. ADC accuracy characteristics (12-bit resolution)



1. Example of an actual transfer curve.
2. Ideal transfer curve.
3. End point correlation line.
4.  $E_T$  = Total Unadjusted Error: maximum deviation between the actual and the ideal transfer curves.  
 $E_O$  = Offset Error: deviation between the first actual transition and the first ideal one.  
 $E_G$  = Gain Error: deviation between the last ideal transition and the last actual one.  
 $E_D$  = Differential Linearity Error: maximum deviation between actual steps and the ideal one.  
 $E_L$  = Integral Linearity Error: maximum deviation between any actual transition and the end point correlation line.

Figure 46. Typical connection diagram using the ADC

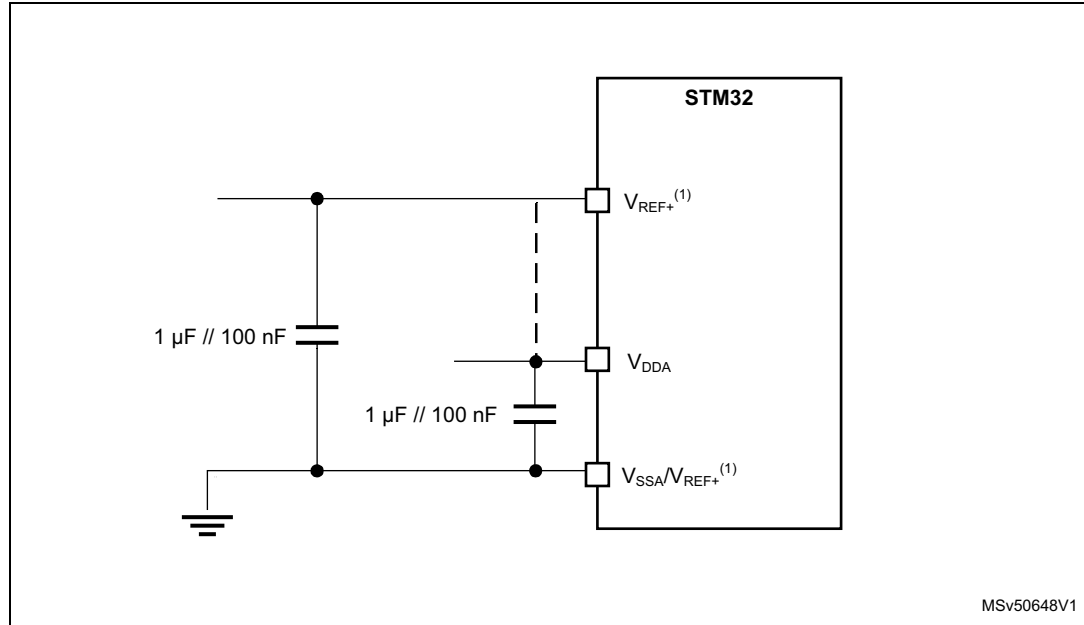


1. Refer to [Table 82](#) for the values of  $R_{AIN}$ ,  $R_{ADC}$  and  $C_{ADC}$ .
2.  $C_{parasitic}$  represents the capacitance of the PCB (dependent on soldering and PCB layout quality) plus the pad capacitance (roughly 5 pF). A high  $C_{parasitic}$  value downgrades conversion accuracy. To remedy this,  $f_{ADC}$  should be reduced.

**General PCB design guidelines**

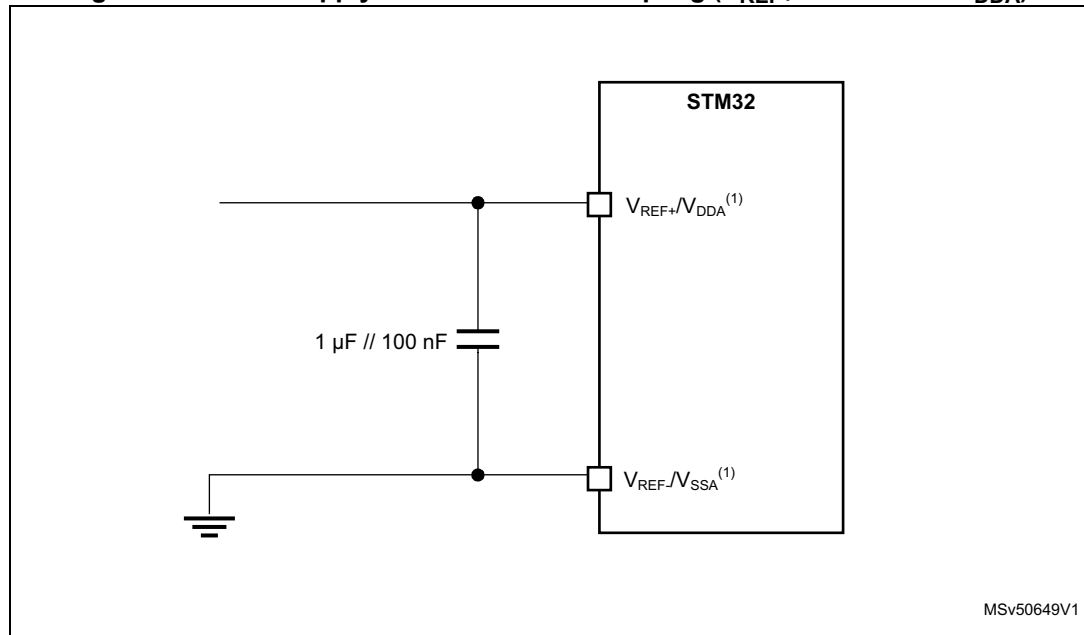
Power supply decoupling should be performed as shown in [Figure 47](#) or [Figure 48](#), depending on whether  $V_{REF+}$  is connected to  $V_{DDA}$  or not. The 100 nF capacitors should be ceramic (good quality). They should be placed them as close as possible to the chip.

**Figure 47. Power supply and reference decoupling ( $V_{REF+}$  not connected to  $V_{DDA}$ )**



1. When  $V_{REF+}$  and  $V_{REF-}$  inputs are not available, they are internally connected to  $V_{DDA}$  and  $V_{SSA}$ , respectively.

**Figure 48. Power supply and reference decoupling ( $V_{REF+}$  connected to  $V_{DDA}$ )**



1. When  $V_{REF+}$  and  $V_{REF-}$  inputs are not available, they are internally connected to  $V_{DDA}$  and  $V_{SSA}$ , respectively.

6.3.23 12-bit ADC characteristics

Unless otherwise specified, the parameters given in [Table 85](#), [Table 86](#) and [Table 87](#) are derived from tests performed under the ambient temperature and V<sub>D</sub> supply voltage conditions summarized in [Table 12: General operating conditions](#). In [Table 85](#), [Table 86](#) and [Table 87](#), f<sub>ADC</sub> refers to f<sub>adc\_ker\_ck</sub>.

Table 85. 12-bit ADC characteristics<sup>(1)(2)</sup>

Symbol	Parameter	Conditions				Min	Typ	Max	Unit				
V <sub>D</sub>	Analog power supply for ADC ON	-				1.62	-	3.6	V				
V <sub>REF+</sub> <sup>(3)</sup>	Positive reference voltage	V <sub>D</sub> ≥ V <sub>REF+</sub>				1.62	-	V <sub>D</sub>					
V <sub>REF-</sub>	Negative reference voltage	-				V <sub>SSA</sub>	-	-					
f <sub>ADC</sub>	ADC clock frequency	1,62 V ≤ V <sub>D</sub> ≤ 3,6 V				1.5	-	75	MHz				
f <sub>S</sub> <sup>(4)</sup>	Sampling rate for Direct channels	Resolution = 12 bits	Continuous and Discontinuous mode <sup>(5)</sup>	2.4 V ≤ V <sub>D</sub> ≤ 3.6 V	-40 °C ≤ T <sub>J</sub> ≤ 130 °C	f <sub>ADC</sub> = 75 MHz	SMP = 2.5	-	-	5	MSPS		
				1.6 V ≤ V <sub>D</sub> ≤ 3.6 V		f <sub>ADC</sub> = 60 MHz		-	-	4			
			Single mode	2.4 V ≤ V <sub>D</sub> ≤ 3.6 V		f <sub>ADC</sub> = 50 MHz <sup>(6)</sup>		-	-	3.33			
				1.6 V ≤ V <sub>D</sub> ≤ 3.6 V		f <sub>ADC</sub> = 38 MHz <sup>(6)</sup>		-	-	2.53			
		Resolution = 10 bits	Continuous and Discontinuous mode <sup>(5)</sup>	1.6 V ≤ V <sub>D</sub> ≤ 3.6 V		-40 °C ≤ T <sub>J</sub> ≤ 130 °C	f <sub>ADC</sub> = 75 MHz	SMP = 2.5	-	-		5.77	
				2.4 V ≤ V <sub>D</sub> ≤ 3.6 V			f <sub>ADC</sub> = 58 MHz <sup>(6)</sup>		-	-		4.46	
			Single mode	1.6 V ≤ V <sub>D</sub> ≤ 3.6 V			f <sub>ADC</sub> = 42 MHz <sup>(6)</sup>		-	-		3.23	
				Resolution = 8 bits			Continuous and Discontinuous mode <sup>(5)</sup>		1.6 V ≤ V <sub>D</sub> ≤ 3.6 V	-40 °C ≤ T <sub>J</sub> ≤ 130 °C		f <sub>ADC</sub> = 75 MHz	SMP = 2.5
		2.4 V ≤ V <sub>D</sub> ≤ 3.6 V	f <sub>ADC</sub> = 67 MHz <sup>(6)</sup>		-			-	6.09				
		Single mode	1.6 V ≤ V <sub>D</sub> ≤ 3.6 V		f <sub>ADC</sub> = 48 MHz <sup>(6)</sup>		-	-	4.36				
			Resolution = 6 bits		Continuous and Discontinuous mode <sup>(5)</sup>		1.6 V ≤ V <sub>D</sub> ≤ 3.6 V	-40 °C ≤ T <sub>J</sub> ≤ 130 °C	f <sub>ADC</sub> = 75 MHz			SMP = 2.5	
		2.4 V ≤ V <sub>D</sub> ≤ 3.6 V		f <sub>ADC</sub> = 75 MHz <sup>(6)</sup>			-		-				8.33
		Single mode		1.6 V ≤ V <sub>D</sub> ≤ 3.6 V	f <sub>ADC</sub> = 55 MHz <sup>(6)</sup>	-	-		6.11				

Table 85. 12-bit ADC characteristics<sup>(1)(2)</sup> (continued)

Symbol	Parameter	Conditions					Min	Typ	Max	Unit	
f <sub>S</sub> <sup>(4)</sup> (continued)	Sampling rate for fast channels (VIN[0:5])	Resolution = 12 bits	Continuous and Discontinuous mode <sup>(5)</sup>	2.4 V ≤ V <sub>DDA</sub> ≤ 3.6 V	-40 °C ≤ T <sub>J</sub> ≤ 130 °C	f <sub>ADC</sub> = 65 MHz	SMP = 2.5	-	-	4.33	MSPS
				1.6 V ≤ V <sub>DDA</sub> ≤ 3.6 V		f <sub>ADC</sub> = 58 MHz		-	-	3.87	
			Single mode	2.4 V ≤ V <sub>DDA</sub> ≤ 3.6 V		f <sub>ADC</sub> = 32 MHz <sup>(6)</sup>		-	-	2.13	
				1.6 V ≤ V <sub>DDA</sub> ≤ 3.6 V		f <sub>ADC</sub> = 26 MHz <sup>(6)</sup>		-	-	1.73	
		Resolution = 10 bits	Continuous and Discontinuous mode <sup>(5)</sup>	1.6 V ≤ V <sub>DDA</sub> ≤ 3.6 V	-40 °C ≤ T <sub>J</sub> ≤ 130 °C	f <sub>ADC</sub> = 75 MHz	SMP = 2.5	-	-	5.77	
				2.4 V ≤ V <sub>DDA</sub> ≤ 3.6 V		f <sub>ADC</sub> = 36 MHz <sup>(6)</sup>		-	-	2.77	
			Single mode	1.6 V ≤ V <sub>DDA</sub> ≤ 3.6 V		f <sub>ADC</sub> = 30 MHz <sup>(6)</sup>		-	-	2.31	
				Resolution = 8 bits		Continuous and Discontinuous mode <sup>(5)</sup>		1.6 V ≤ V <sub>DDA</sub> ≤ 3.6 V	-40 °C ≤ T <sub>J</sub> ≤ 130 °C	f <sub>ADC</sub> = 75 MHz	
		2.4 V ≤ V <sub>DDA</sub> ≤ 3.6 V	f <sub>ADC</sub> = 44 MHz <sup>(6)</sup>		-		-	4.00			
		Single mode	1.6 V ≤ V <sub>DDA</sub> ≤ 3.6 V		f <sub>ADC</sub> = 35 MHz <sup>(6)</sup>	-	-	3.18			
			Resolution = 6 bits		Continuous and Discontinuous mode <sup>(5)</sup>	1.6 V ≤ V <sub>DDA</sub> ≤ 3.6 V	-40 °C ≤ T <sub>J</sub> ≤ 130 °C	f <sub>ADC</sub> = 75 MHz		SMP = 2.5	
		2.4 V ≤ V <sub>DDA</sub> ≤ 3.6 V		f <sub>ADC</sub> = 56 MHz <sup>(6)</sup>		-		-	6.22		
	Single mode	1.6 V ≤ V <sub>DDA</sub> ≤ 3.6 V		f <sub>ADC</sub> = 42 MHz <sup>(6)</sup>	-	-		4.66			
		Sampling rate for slow channels		Resolution = 12 bits	-	-		-40 °C ≤ T <sub>J</sub> ≤ 130 °C	f <sub>ADC</sub> = 15 MHz <sup>(6)</sup>		
	Resolution = 10 bits		-	-			1.28				
	Resolution = 8 bits		-	-			1.63				
Resolution = 6 bits	-		-	2.08							
t <sub>TRIG</sub>	External trigger period	Resolution = 12 bits					-	-	15	1/f <sub>ADC</sub>	
V <sub>AIN</sub>	Conversion voltage range	-					0	-	V <sub>REF+</sub>	V	
V <sub>CMIV</sub>	Common mode input voltage	-					V <sub>REF</sub> /2 - 10%	V <sub>REF</sub> /2	V <sub>REF</sub> /2 + 10%		
R <sub>AIN</sub> <sup>(7)</sup>	External input impedance	Resolution = 12 bits, T <sub>J</sub> = 125 °C					-	-	220	Ω	
		Resolution = 10 bits, T <sub>J</sub> = 125 °C					-	-	2100		
		Resolution = 8 bits, T <sub>J</sub> = 125 °C					-	-	12000		
		Resolution = 6 bits, T <sub>J</sub> = 125 °C					-	-	80000		

Table 85. 12-bit ADC characteristics<sup>(1)(2)</sup> (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
C <sub>ADC</sub>	Internal sample and hold capacitor	-	-	5	-	pF
t <sub>ADCV</sub> REG_ STUP	ADC LDO startup time	-	-	5	10	μs
t <sub>STAB</sub>	ADC power-up time	LDO already started	1	-	-	conversion cycle
t <sub>OFF</sub> CAL	Offset calibration time	-	135	-	-	1/f <sub>ADC</sub>
t <sub>LATR</sub>	Trigger conversion latency for regular and injected channels without aborting the conversion	CKMODE = 00	1.5	2	2.5	
		CKMODE = 01	-	-	2.5	
		CKMODE = 10	-	-	2.5	
		CKMODE = 11	-	-	2.25	
t <sub>LATR</sub> INJ	Trigger conversion latency for regular and injected channels when a regular conversion is aborted	CKMODE = 00	2.5	3	3.5	
		CKMODE = 01	-	-	3.5	
		CKMODE = 10	-	-	3.5	
		CKMODE = 11	-	-	3.25	
t <sub>s</sub>	Sampling time	-	2.5	-	640.5	
t <sub>CONV</sub>	Total conversion time (including sampling time)	N-bits resolution	t <sub>s</sub> + 0.5 + N	-	-	
I <sub>DDA</sub> D(ADC)	ADC consumption on V <sub>DDA</sub> and V <sub>REF</sub> , Differential mode	f <sub>S</sub> = 5 MSPS	-	430	-	μA
		f <sub>S</sub> = 1 MSPS	-	133	-	
		f <sub>S</sub> = 0.1 MSPS	-	51	-	
I <sub>DDA</sub> SE (ADC)	ADC consumption on V <sub>DDA</sub> and V <sub>REF</sub> , Single-ended mode	f <sub>S</sub> = 5 MSPS	-	350	-	
		f <sub>S</sub> = 1 MSPS	-	122	-	
		f <sub>S</sub> = 0.1 MSPS	-	47	-	
I <sub>DD</sub> (ADC)	ADC consumption on V <sub>DD</sub> per f <sub>ADC</sub>	-	-	2.4	-	μA/MHz

1. Guaranteed by design.
2. The voltage booster on ADC switches must be used for V<sub>DDA</sub> < 2.4 V (embedded I/O switches).
3. Depending on the package, VREF+ can be internally connected to V<sub>DDA</sub> and VREF- to V<sub>SSA</sub>.
4. Guaranteed by characterization for BGA and CSP packages. The values for LQFP packages may be different.

- 5. The conversion of the first element in the group is excluded.
- 6.  $f_{ADC}$  value corresponds to the maximum frequency that can be reached considering a 2.5 sampling period. For other SMPy sampling periods, the maximum frequency is  $f_{ADC}$  value \* SMPy / 2.5 with a limitation to 75 MHz.
- 7. The tolerance is 2 LSBs for 12-bit, 10-bit and 8-bit resolutions. It is otherwise specified.

**Table 86. Minimum sampling time vs  $R_{AIN}$  (12-bit ADC)<sup>(1)(2)</sup>**

Resolution	$R_{AIN}$ ( $\Omega$ )	Minimum sampling time (s)		
		Direct channels <sup>(3)</sup>	Fast channels <sup>(4)</sup>	Slow channels <sup>(5)</sup>
12 bits	47	5.55E-08	7.04E-08	1.03E-07
	68	5.76E-08	7.22E-08	1.05E-07
	100	6.17E-08	7.65E-08	1.07E-07
	150	7.02E-08	8.45E-08	1.13E-07
	220	8.59E-08	1.00E-07	1.22E-07
	330	1.11E-07	1.26E-07	1.41E-07
	470	1.46E-07	1.61E-07	1.69E-07
	680	1.98E-07	2.17E-07	2.25E-07
10 bits	47	4.90E-08	6.06E-08	8.77E-08
	68	5.07E-08	6.27E-08	8.95E-08
	100	5.41E-08	6.67E-08	9.22E-08
	150	6.18E-08	7.50E-08	9.59E-08
	220	7.51E-08	8.70E-08	1.04E-07
	330	9.46E-08	1.07E-07	1.17E-07
	470	1.22E-07	1.34E-07	1.42E-07
	680	1.63E-07	1.77E-07	1.86E-07
	1000	2.27E-07	2.42E-07	2.43E-07
	1500	3.27E-07	3.40E-07	3.35E-07
	2200	4.53E-07	4.86E-07	4.73E-07
	3300	6.56E-07	6.93E-07	6.72E-07



Table 86. Minimum sampling time vs R<sub>AIN</sub> (12-bit ADC)<sup>(1)(2)</sup> (continued)

Resolution	R <sub>AIN</sub> (Ω)	Minimum sampling time (s)		
		Direct channels <sup>(3)</sup>	Fast channels <sup>(4)</sup>	Slow channels <sup>(5)</sup>
8 bits	47	4.35E-08	5.31E-08	7.36E-08
	68	4.47E-08	5.48E-08	7.47E-08
	100	4.72E-08	5.79E-08	7.63E-08
	150	5.33E-08	6.35E-08	7.88E-08
	220	6.26E-08	7.26E-08	8.47E-08
	330	7.84E-08	8.80E-08	9.48E-08
	470	9.80E-08	1.07E-07	1.14E-07
	680	1.28E-07	1.39E-07	1.43E-07
	1000	1.76E-07	1.88E-07	1.90E-07
	1500	2.49E-07	2.66E-07	2.64E-07
	2200	3.50E-07	3.63E-07	3.63E-07
	3300	5.09E-07	5.27E-07	5.24E-07
	4700	7.00E-07	7.28E-07	7.09E-07
	6800	9.84E-07	1.03E-06	1.00E-06
	10000	1.43E-06	1.48E-06	1.44E-06
15000	2.10E-06	2.18E-06	2.11E-06	
6 bits	47	3.79E-08	4.58E-08	5.74E-08
	68	3.88E-08	4.69E-08	5.81E-08
	100	4.09E-08	4.89E-08	5.93E-08
	150	4.48E-08	5.25E-08	6.14E-08
	220	5.07E-08	5.81E-08	6.58E-08
	330	6.04E-08	6.79E-08	7.46E-08
	470	7.37E-08	8.10E-08	8.60E-08
	680	9.31E-08	1.01E-07	1.04E-07
	1000	1.23E-07	1.32E-07	1.34E-07
	1500	1.71E-07	1.82E-07	1.82E-07
	2200	2.39E-07	2.50E-07	2.49E-07
	3300	3.43E-07	3.57E-07	3.49E-07
	4700	4.72E-07	4.92E-07	4.81E-07
	6800	6.65E-07	6.89E-07	6.68E-07
	10000	9.54E-07	9.88E-07	9.54E-07
15000	1.40E-06	1.45E-06	1.39E-06	

1. Guaranteed by design.
2. Data valid up to 130 °C, with a 22 pF PCB capacitor and V<sub>DDA</sub> = 1.62 V.



3. Direct channels are connected to analog I/Os (PA0\_C, PA1\_C, PC2\_C and PC3\_C) to optimize ADC performance.
4. Fast channels correspond to ADCx\_INx[0:5].
5. Slow channels correspond to all ADC inputs except for the Direct and Fast channels.

**Table 87. 12-bit ADC accuracy<sup>(1)(2)</sup>**

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
ET	Total unadjusted error	Direct channel	Single ended	-	3.5	5	±LSB
			Differential	-	2.5	3	
		Fast channel	Single ended	-	3.5	5	
			Differential	-	2.5	3	
		Slow channel	Single ended	-	3.5	5	
			Differential	-	2.5	3	
EO	Offset error	-		-	+/-2	+/-5	
EG	Gain error	-		-	TBD <sup>(3)</sup>	-	
ED	Differential linearity error	Single ended		-	+/-0.75	+1.5/-1	±LSB
		Differential		-	+/-0.5	+1.25/-1	
EL	Integral linearity error	Direct channel	Single ended	-	+/-1	+/-2.5	±LSB
			Differential	-	+/-1	+/-2	
		Fast channel	Single ended	-	+/-1	+/-2.5	
			Differential	-	+/-1	+/-2	
		Slow channel	Single ended	-	+/-1	+/-2.5	
			Differential	-	+/-1	+/-2	
ENOB	Effective number of bits	Single ended		-	11.2	-	bits
		Differential		-	11.5	-	
SINAD	Signal-to-noise and distortion ratio	Single ended		-	68.9	-	dB
		Differential		-	71.1	-	
SNR	Signal-to-noise ratio	Single ended		-	69.1	-	dB
		Differential		-	71.4	-	
THD	Total harmonic distortion	Single ended		-	-79.6	-	dB
		Differential		-	-81.8	-	

1. Guaranteed by characterization for BGA packages. The maximum values are preliminary data. The values for LQFP packages may be different.
2. ADC DC accuracy values are measured after internal calibration in Continuous and Discontinuous mode.
3. TBD stands for "to be defined".

6.3.24 DAC characteristics

Table 88. DAC characteristics<sup>(1)</sup>

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
V <sub>DDA</sub>	Analog supply voltage	-	1.8	3.3	3.6	V	
V <sub>REF+</sub>	Positive reference voltage	-	1.80	-	V <sub>DDA</sub>		
V <sub>REF-</sub>	Negative reference voltage	-	-	V <sub>SSA</sub>	-		
R <sub>L</sub>	Resistive Load	DAC output buffer ON	connected to V <sub>SSA</sub>	5	-	-	kΩ
			connected to V <sub>DDA</sub>	25	-	-	
R <sub>O</sub>	Output Impedance	DAC output buffer OFF		10.3	13	16	
R <sub>BON</sub>	Output impedance sample and hold mode, output buffer ON	DAC output buffer ON	V <sub>DD</sub> = 2.7 V	-	-	1.6	kΩ
			V <sub>DD</sub> = 2.0 V	-	-	2.6	
R <sub>BOFF</sub>	Output impedance sample and hold mode, output buffer OFF	DAC output buffer OFF	V <sub>DD</sub> = 2.7 V	-	-	17.8	kΩ
			V <sub>DD</sub> = 2.0 V	-	-	18.7	
C <sub>L</sub>	Capacitive Load	DAC output buffer OFF		-	-	50	pF
C <sub>SH</sub>		Sample and Hold mode		-	0.1	1	μF
V <sub>DAC_OUT</sub>	Voltage on DAC_OUT output	DAC output buffer ON		0.2	-	V <sub>DDA</sub> - 0.2	V
		DAC output buffer OFF		0	-	V <sub>REF+</sub>	
t <sub>SETTLING</sub>	Settling time (full scale: for a 12-bit code transition between the lowest and the highest input codes when DAC_OUT reaches the final value of ±0.5LSB, ±1LSB, ±2LSB, ±4LSB, ±8LSB)	Normal mode, DAC output buffer ON, C <sub>L</sub> ≤ 50 pF, R <sub>L</sub> ≥ 5 kΩ	±0.5 LSB	-	2.05	3	μs
			±1 LSB	-	1.97	2.87	
			±2 LSB	-	1.67	2.84	
			±4 LSB	-	1.66	2.78	
			±8 LSB	-	1.65	2.7	
		Normal mode, DAC output buffer OFF, ±1LSB C <sub>L</sub> =10 pF	-	1.7	2		
t <sub>WAKEUP</sub> <sup>(2)</sup>	Wakeup time from off state (setting the ENx bit in the DAC Control register) until the final value of ±1LSB is reached	Normal mode, DAC output buffer ON, C <sub>L</sub> ≤ 50 pF, R <sub>L</sub> = 5 kΩ		-	5	7.5	μs
		Normal mode, DAC output buffer OFF, C <sub>L</sub> ≤ 10 pF			2	5	
PSRR	DC V <sub>DDA</sub> supply rejection ratio	Normal mode, DAC output buffer ON, C <sub>L</sub> ≤ 50 pF, R <sub>L</sub> = 5 kΩ		-	-80	-28	dB

Table 88. DAC characteristics<sup>(1)</sup> (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
t <sub>SAMP</sub>	Sampling time in Sample and Hold mode C <sub>L</sub> =100 nF (code transition between the lowest input code and the highest input code when DAC_OUT reaches the ±1LSB final value)	MODE<2:0>_V12=100/101 (BUFFER ON)	-	0.7	2.6	ms	
		MODE<2:0>_V12=110 (BUFFER OFF)	-	11.5	18.7		
		MODE<2:0>_V12=111 (INTERNAL BUFFER OFF)	-	0.3	0.6	µs	
I <sub>leak</sub>	Output leakage current	-	(3)			nA	
C <sub>lint</sub>	Internal sample and hold capacitor	-	1.8	2.2	2.6	pF	
t <sub>TRIM</sub>	Middle code offset trim time	Minimum time to verify the each code	50	-	-	µs	
V <sub>offset</sub>	Middle code offset for 1 trim code step	V <sub>REF+</sub> = 3.6 V	-	850	-	µV	
		V <sub>REF+</sub> = 1.8 V	-	425	-		
I <sub>DDA(DAC)</sub>	DAC quiescent consumption from V <sub>DDA</sub>	DAC output buffer ON	No load, middle code (0x800)	-	360	-	µA
			No load, worst code (0xF1C)	-	490	-	
		DAC output buffer OFF	No load, middle/worst code (0x800)	-	20	-	
		Sample and Hold mode, C <sub>SH</sub> =100 nF	-	$\frac{360 \cdot T_{ON}}{(T_{ON} + T_{OFF})_{(4)}}$	-		
I <sub>DDV(DAC)</sub>	DAC consumption from V <sub>REF+</sub>	DAC output buffer ON	No load, middle code (0x800)	-	170	-	µA
			No load, worst code (0xF1C)	-	170	-	
		DAC output buffer OFF	No load, middle/worst code (0x800)	-	160	-	
		Sample and Hold mode, Buffer ON, C <sub>SH</sub> =100 nF (worst code)	-	$\frac{170 \cdot T_{ON}}{(T_{ON} + T_{OFF})_{(4)}}$	-		
		Sample and Hold mode, Buffer OFF, C <sub>SH</sub> =100 nF (worst code)	-	$\frac{160 \cdot T_{ON}}{(T_{ON} + T_{OFF})_{(4)}}$	-		

1. Guaranteed by design unless otherwise specified.

2. In buffered mode, the output can overshoot above the final value for low input code (starting from the minimum value).
3. Refer to [Table 53: I/O static characteristics](#).
4.  $T_{ON}$  is the refresh phase duration, while  $T_{OFF}$  is the hold phase duration. Refer to the product reference manual for more details.

**Table 89. DAC accuracy<sup>(1)</sup>**

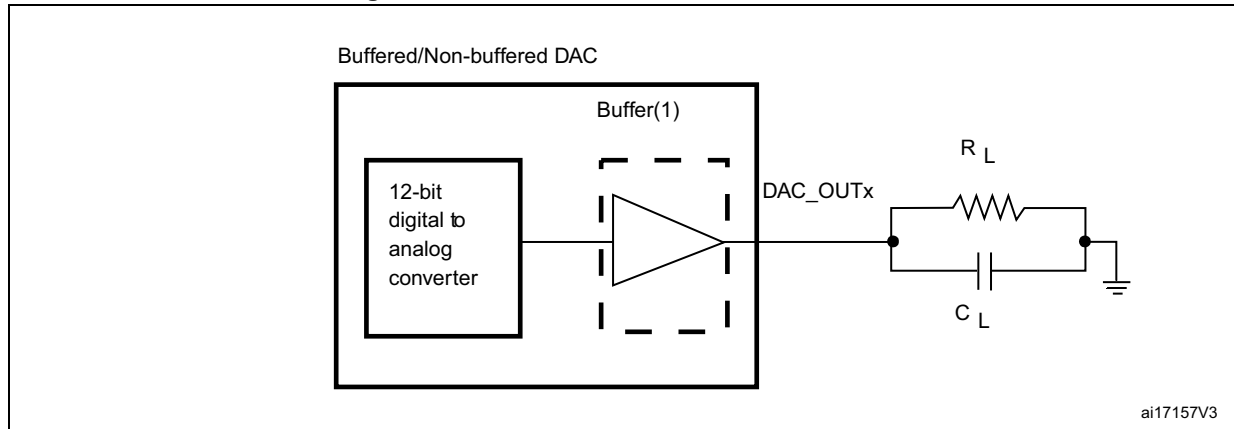
Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
DNL	Differential non linearity <sup>(2)</sup>	DAC output buffer ON	-2	-	2	LSB	
		DAC output buffer OFF	-2	-	2		
-	Monotonicity	10 bits	-	-	-	-	
INL	Integral non linearity <sup>(3)</sup>	DAC output buffer ON, $C_L \leq 50$ pF, $R_L \geq 5$ k $\Omega$	-4	-	4	LSB	
		DAC output buffer OFF, $C_L \leq 50$ pF, no $R_L$	-4	-	4		
Offset	Offset error at code 0x800 <sup>(3)</sup>	DAC output buffer ON, $C_L \leq 50$ pF, $R_L \geq 5$ k $\Omega$	$V_{REF+} = 3.6$ V	-	-	$\pm 12$	LSB
			$V_{REF+} = 1.8$ V	-	-	$\pm 25$	
		DAC output buffer OFF, $C_L \leq 50$ pF, no $R_L$	-	-	$\pm 8$		
Offset1	Offset error at code 0x001 <sup>(4)</sup>	DAC output buffer OFF, $C_L \leq 50$ pF, no $R_L$	-	-	$\pm 5$	LSB	
OffsetCal	Offset error at code 0x800 after factory calibration	DAC output buffer ON, $C_L \leq 50$ pF, $R_L \geq 5$ k $\Omega$	$V_{REF+} = 3.6$ V	-	-	$\pm 5$	LSB
			$V_{REF+} = 1.8$ V	-	-	$\pm 7$	
Gain	Gain error <sup>(5)</sup>	DAC output buffer ON, $C_L \leq 50$ pF, $R_L \geq 5$ k $\Omega$	-	-	$\pm 1$	%	
		DAC output buffer OFF, $C_L \leq 50$ pF, no $R_L$	-	-	$\pm 1$		
TUE	Total unadjusted error	DAC output buffer ON, $C_L \leq 50$ pF, $R_L \geq 5$ k $\Omega$	-	-	$\pm 30$	LSB	
		DAC output buffer OFF, $C_L \leq 50$ pF, no $R_L$	-	-	$\pm 12$		
TUECal	Total unadjusted error after calibration	DAC output buffer ON, $C_L \leq 50$ pF, $R_L \geq 5$ k $\Omega$	-	-	$\pm 23$		
SNR	Signal-to-noise ratio <sup>(6)</sup>	DAC output buffer ON, $C_L \leq 50$ pF, $R_L \geq 5$ k $\Omega$ , 1 kHz, BW = 500 KHz	-	67.8	-	dB	
		DAC output buffer OFF, $C_L \leq 50$ pF, no $R_L$ , 1 kHz, BW = 500 KHz	-	67.8	-		

**Table 89. DAC accuracy<sup>(1)</sup> (continued)**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
THD	Total harmonic distortion <sup>(6)</sup>	DAC output buffer ON, $C_L \leq 50$ pF, $R_L \geq 5$ k $\Omega$ , 1 kHz	-	-78.6	-	dB
		DAC output buffer OFF, $C_L \leq 50$ pF, no $R_L$ , 1 kHz	-	-78.6	-	
SINAD	Signal-to-noise and distortion ratio <sup>(6)</sup>	DAC output buffer ON, $C_L \leq 50$ pF, $R_L \geq 5$ k $\Omega$ , 1 kHz	-	67.5	-	dB
		DAC output buffer OFF, $C_L \leq 50$ pF, no $R_L$ , 1 kHz	-	67.5	-	
ENOB	Effective number of bits	DAC output buffer ON, $C_L \leq 50$ pF, $R_L \geq 5$ k $\Omega$ , 1 kHz	-	10.9	-	bits
		DAC output buffer OFF, $C_L \leq 50$ pF, no $R_L$ , 1 kHz	-	10.9	-	

1. Guaranteed by characterization results.
2. Difference between two consecutive codes minus 1 LSB.
3. Difference between the value measured at Code *i* and the value measured at Code *i* on a line drawn between Code 0 and last Code 4095.
4. Difference between the value measured at Code (0x001) and the ideal value.
5. Difference between the ideal slope of the transfer function and the measured slope computed from code 0x000 and 0xFFFF when the buffer is OFF, and from code giving 0.2 V and ( $V_{REF+} - 0.2$  V) when the buffer is ON.
6. Signal is -0.5dBFS with  $F_{sampling}=1$  MHz.

**Figure 49. 12-bit buffered /non-buffered DAC**



1. The DAC integrates an output buffer that can be used to reduce the output impedance and to drive external loads directly without the use of an external operational amplifier. The buffer can be bypassed by configuring the BOFFx bit in the DAC\_CR register.

6.3.25 Voltage reference buffer characteristics

Table 90. VREFBUF characteristics<sup>(1)</sup>

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
V <sub>DDA</sub>	Analog supply voltage	Normal mode, V <sub>DDA</sub> = 3.3 V	VSCALE = 000	2.8	3.3	3.6	V
			VSCALE = 001	2.4	-	3.6	
			VSCALE = 010	2.1	-	3.6	
			VSCALE = 011	1.8	-	3.6	
		Degraded mode <sup>(2)</sup>	VSCALE = 000	1.62	-	2.80	
			VSCALE = 001	1.62	-	2.40	
			VSCALE = 010	1.62	-	2.10	
			VSCALE = 011	1.62	-	1.80	
V <sub>REFBUF_OUT</sub>	Voltage Reference Buffer Output, at 30 °C, I <sub>load</sub> = 100 µA	Normal mode at 30 °C, I <sub>load</sub> = 100 µA	VSCALE = 000	2.4980	2.5000	2.5035	
			VSCALE = 001	2.0460	2.0490	2.0520	
			VSCALE = 010	1.8010	1.8040	1.8060	
			VSCALE = 011	1.4995	1.5015	1.5040	
		Degraded mode <sup>(2)</sup>	VSCALE = 000	V <sub>DDA</sub> - 150 mV	-	V <sub>DDA</sub>	
			VSCALE = 001	V <sub>DDA</sub> - 150 mV	-	V <sub>DDA</sub>	
			VSCALE = 010	V <sub>DDA</sub> - 150 mV	-	V <sub>DDA</sub>	
			VSCALE = 011	V <sub>DDA</sub> - 150 mV	-	V <sub>DDA</sub>	
TRIM	Trim step resolution	-	-	-	±0.05	±0.1	%
C <sub>L</sub>	Load capacitor	-	-	0.5	1	1.50	µF
esr	Equivalent Serial Resistor of C <sub>L</sub>	-	-	-	-	2	Ω
I <sub>LOAD</sub>	Static load current	-	-	-	-	4	mA
I <sub>line_reg</sub>	Line regulation	2.8 V ≤ V <sub>DDA</sub> ≤ 3.6 V	I <sub>load</sub> = 500 µA	-	200	-	ppm/V
			I <sub>load</sub> = 4 mA	-	100	-	
I <sub>load_reg</sub>	Load regulation	500 µA ≤ I <sub>LOAD</sub> ≤ 4 mA	Normal mode	-	50	-	ppm/mA
T <sub>coeff</sub>	Temperature coefficient	-40 °C < T <sub>J</sub> < +130 °C		-	-	T <sub>coeff</sub> V <sub>REFINT</sub> + 100	ppm/°C
PSRR	Power supply rejection	DC	-	-	60	-	dB
		100KHz	-	-	40	-	

**Table 90. VREFBUF characteristics<sup>(1)</sup> (continued)**

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
t <sub>START</sub>	Start-up time	C <sub>L</sub> =0.5 μF	-	-	300	-	μs
		C <sub>L</sub> =1 μF	-	-	500	-	
		C <sub>L</sub> =1.5 μF	-	-	650	-	
I <sub>INRUSH</sub>	Control of maximum DC current drive on V <sub>REFBUF_OUT</sub> during startup phase <sup>(3)</sup>	-		-	8	-	mA
I <sub>DDA</sub> (VREFBUF)	VREFBUF consumption from V <sub>DDA</sub>	I <sub>LOAD</sub> = 0 μA	-	-	15	25	μA
		I <sub>LOAD</sub> = 500 μA	-	-	16	30	
		I <sub>LOAD</sub> = 4 mA	-	-	32	50	

1. Guaranteed by design, unless otherwise specified.
2. In degraded mode, the voltage reference buffer cannot accurately maintain the output voltage (V<sub>DDA</sub>-drop voltage).
3. To properly control VREFBUF I<sub>INRUSH</sub> current during the startup phase and the change of scaling, V<sub>DDA</sub> voltage should be in the range of 1.8 V-3.6 V, 2.1 V-3.6 V, 2.4 V-3.6 V and 2.8 V-3.6 V for VSCALE = 011, 010, 001 and 000, respectively.

### 6.3.26 Analog temperature sensor characteristics

**Table 91. Temperature sensor characteristics**

Symbol	Parameter	Min	Typ	Max	Unit
T <sub>L</sub> <sup>(1)</sup>	V <sub>SENSE</sub> linearity with temperature	-	-	3	°C
Avg_Slope <sup>(2)</sup>	Average slope	-	2	-	mV/°C
V <sub>30</sub> <sup>(3)</sup>	Voltage at 30°C ± 5 °C	-	0.62	-	V
t <sub>start_run</sub>	Startup time in Run mode (buffer startup)	-	-	25.2	μs
t <sub>S_temp</sub> <sup>(1)</sup>	ADC sampling time when reading the temperature	9	-	-	
I <sub>sens</sub> <sup>(1)</sup>	Sensor consumption	-	0.18	0.31	μA
I <sub>sensbuf</sub> <sup>(1)</sup>	Sensor buffer consumption	-	3.8	6.5	

1. Guaranteed by design.
2. Guaranteed by characterization results.
3. Measured at V<sub>DDA</sub> = 3.3 V ± 10 mV. The V<sub>30</sub> ADC conversion result is stored in the TS\_CAL1 byte.

**Table 92. Temperature sensor calibration values**

Symbol	Parameter	Memory address
TS_CAL1	Temperature sensor raw data acquired value at 30 °C, V <sub>DDA</sub> =3.3 V	0x1FF1 E820 - 0x1FF1 E821
TS_CAL2	Temperature sensor raw data acquired value at 110 °C, V <sub>DDA</sub> =3.3 V	0x1FF1 E840 - 0x1FF1 E841



### 6.3.27 Digital temperature sensor characteristics

Table 93. Digital temperature sensor characteristics<sup>(1)</sup>

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{DTS}^{(2)}$	Output Clock frequency	-	500	750	1150	kHz
$T_{LC}^{(2)}$	Temperature linearity coefficient	VOS2	1660	2100	2750	Hz/°C
$T_{TOTAL\_ERROR}^{(2)}$	Temperature offset measurement, all VOS	$T_J = -40^{\circ}\text{C}$ to $30^{\circ}\text{C}$	-13	-	4	°C
		$T_J = 30^{\circ}\text{C}$ to $T_{jmax}$	-7	-	2	
$T_{VDD\_CORE}$	Additional error due to supply variation	VOS2	0	-	0	°C
		VOS0, VOS1, VOS3	-1	-	1	
$t_{TRIM}$	Calibration time	-	-	-	2	ms
$t_{WAKE\_UP}$	Wake-up time from off state until DTS ready bit is set	-	-	67	116.00	μs
$I_{DDCORE\_DTS}$	DTS consumption on VDD_CORE	-	8.5	30	70.0	μA

1. Guaranteed by design, unless otherwise specified.
2. Guaranteed by characterization results.

### 6.3.28 Temperature and $V_{BAT}$ monitoring

Table 94.  $V_{BAT}$  monitoring characteristics

Symbol	Parameter	Min	Typ	Max	Unit
R	Resistor bridge for $V_{BAT}$	-	26	-	KΩ
Q	Ratio on $V_{BAT}$ measurement	-	4	-	-
$E_r^{(1)}$	Error on Q	-10	-	+10	%
$t_{S\_vbat}^{(1)}$	ADC sampling time when reading $V_{BAT}$ input	9	-	-	μs
$V_{BAThigh}$	High supply monitoring	-	3.55	-	V
$V_{BATlow}$	Low supply monitoring	-	1.36	-	

1. Guaranteed by design.

Table 95.  $V_{BAT}$  charging characteristics

Symbol	Parameter	Condition	Min	Typ	Max	Unit
$R_{BC}$	Battery charging resistor	VBRS in PWR_CR3= 0	-	5	-	KΩ
		VBRS in PWR_CR3= 1	-	1.5	-	

**Table 96. Temperature monitoring characteristics**

Symbol	Parameter	Min	Typ	Max	Unit
TEMP <sub>high</sub>	High temperature monitoring	-	117	-	°C
TEMP <sub>low</sub>	Low temperature monitoring	-	-25	-	

**6.3.29 Voltage booster for analog switch**

**Table 97. Voltage booster for analog switch characteristics<sup>(1)</sup>**

Symbol	Parameter	Condition	Min	Typ	Max	Unit
V <sub>DD</sub>	Supply voltage	-	1.62	2.6	3.6	V
t <sub>SU(BOOST)</sub>	Booster startup time	-	-	-	50	µs
I <sub>DD(BOOST)</sub>	Booster consumption	1.62 V ≤ V <sub>DD</sub> ≤ 2.7 V	-	-	125	µA
		2.7 V < V <sub>DD</sub> < 3.6 V	-	-	250	

1. Guaranteed by characterization results.

**6.3.30 Comparator characteristics**

**Table 98. COMP characteristics<sup>(1)</sup>**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V <sub>DDA</sub>	Analog supply voltage	-	1.62	3.3	3.6	V
V <sub>IN</sub>	Comparator input voltage range	-	0	-	V <sub>DDA</sub>	
V <sub>BG</sub>	Scaler input voltage	-	(2)			
V <sub>SC</sub>	Scaler offset voltage	-	-	±5	±10	mV
I <sub>DDA(SCALER)</sub>	Scaler static consumption from V <sub>DDA</sub>	BRG_EN=0 (bridge disable)	-	0.2	0.3	µA
		BRG_EN=1 (bridge enable)	-	0.8	1	
t <sub>START_SCALER</sub>	Scaler startup time	-	-	140	250	µs
t <sub>START</sub>	Comparator startup time to reach propagation delay specification	High-speed mode	-	2	5	µs
		Medium mode	-	5	20	
		Ultra-low-power mode	-	15	80	
t <sub>D</sub> <sup>(3)</sup>	Propagation delay for 200 mV step with 100 mV overdrive	High-speed mode	-	50	80	ns
		Medium mode	-	0.5	0.9	µs
		Ultra-low-power mode	-	2.5	7	
	Propagation delay for step > 200 mV with 100 mV overdrive only on positive inputs	High-speed mode	-	50	120	µs
		Medium mode	-	0.5	1.2	
		Ultra-low-power mode	-	2.5	7	
V <sub>offset</sub>	Comparator offset error	Full common mode range	-	±5	±20	mV

Table 98. COMP characteristics<sup>(1)</sup> (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
$V_{\text{hys}}$	Comparator hysteresis	No hysteresis	-	0	-	mV	
		Low hysteresis	4	10	22		
		Medium hysteresis	8	20	37		
		High hysteresis	16	30	52		
$I_{\text{DDA}}(\text{COMP})$	Comparator consumption from $V_{\text{DDA}}$	Ultra-low-power mode	Static	-	400	600	nA
			With 50 kHz $\pm 100$ mV overdrive square signal	-	800	-	
		Medium mode	Static	-	5	7	$\mu\text{A}$
			With 50 kHz $\pm 100$ mV overdrive square signal	-	6	-	
		High-speed mode	Static	-	70	100	
			With 50 kHz $\pm 100$ mV overdrive square signal	-	75	-	

1. Guaranteed by design, unless otherwise specified.
2. Refer to [Table 20: Embedded reference voltage](#).
3. Guaranteed by characterization results.

### 6.3.31 Operational amplifier characteristics

Table 99. Operational amplifier characteristics<sup>(1)</sup>

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{\text{DDA}}$	Analog supply voltage Range	-	2	3.3	3.6	V
CMIR	Common Mode Input Range	-	0	-	$V_{\text{DDA}}$	
$V_{\text{I}}\text{OFFSET}$	Input offset voltage	25°C, no load on output	-	-	$\pm 1.5$	mV
		All voltages and temperature, no load	-	-	$\pm 2.5$	
$\Delta V_{\text{I}}\text{OFFSET}$	Input offset voltage drift	-	-	$\pm 3.0$	-	$\mu\text{V}/^\circ\text{C}$
TRIMOFFSETP TRIMLPOFFSETP	Offset trim step at low common input voltage ( $0.1 \cdot V_{\text{DDA}}$ )	-	-	1.1	1.5	mV
TRIMOFFSETN TRIMLPOFFSETN	Offset trim step at high common input voltage ( $0.9 \cdot V_{\text{DDA}}$ )	-	-	1.1	1.5	
$I_{\text{LOAD}}$	Drive current	-	-	-	500	$\mu\text{A}$
$I_{\text{LOAD\_PGA}}$	Drive current in PGA mode	-	-	-	270	

Table 99. Operational amplifier characteristics<sup>(1)</sup> (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
C <sub>LOAD</sub>	Capacitive load	-	-	-	50	pF	
CMRR	Common mode rejection ratio	-	-	80	-	dB	
PSRR	Power supply rejection ratio	C <sub>LOAD</sub> ≤ 50pf / R <sub>LOAD</sub> ≥ 4 kΩ <sup>(2)</sup> at 1 kHz, V <sub>com</sub> =V <sub>DDA</sub> /2	50	66	-	dB	
GBW	Gain bandwidth for high supply range	200 mV ≤ Output dynamic range ≤ V <sub>DDA</sub> - 200 mV	4	7.3	12.3	MHz	
SR	Slew rate (from 10% and 90% of output voltage)	Normal mode	-	3	-	V/μs	
		High-speed mode	-	24	-		
AO	Open loop gain	200 mV ≤ Output dynamic range ≤ V <sub>DDA</sub> - 200 mV	59	90	129	dB	
φ <sub>m</sub>	Phase margin	-	-	55	-	°	
GM	Gain margin	-	-	12	-	dB	
V <sub>OHSAT</sub>	High saturation voltage	I <sub>load</sub> =max or R <sub>LOAD</sub> =min, Input at V <sub>DDA</sub>	V <sub>DDA</sub> - 100 mV	-	-	mV	
V <sub>OLSAT</sub>	Low saturation voltage	I <sub>load</sub> =max or R <sub>LOAD</sub> =min, Input at 0 V	-	-	100		
t <sub>WAKEUP</sub>	Wake up time from OFF state	Normal mode	C <sub>LOAD</sub> ≤ 50pf, R <sub>LOAD</sub> ≥ 4 kΩ, follower configuration	-	0.8	3.2	μs
		High speed mode	C <sub>LOAD</sub> ≤ 50pf, R <sub>LOAD</sub> ≥ 4 kΩ, follower configuration	-	0.9	2.8	
PGA gain	Non inverting gain error value	PGA gain = 2	-1	-	1	%	
		PGA gain = 4	-2	-	2		
		PGA gain = 8	-2.5	-	2.5		
		PGA gain = 16	-3	-	3		
	Inverting gain error value	PGA gain = 2	-1	-	1		
		PGA gain = 4	-1	-	1		
		PGA gain = 8	-2	-	2		
		PGA gain = 16	-3	-	3		
	External non-inverting gain error value	PGA gain = 2	-1	-	1		
		PGA gain = 4	-3	-	3		
		PGA gain = 8	-3.5	-	3.5		
		PGA gain = 16	-4	-	4		

Table 99. Operational amplifier characteristics<sup>(1)</sup> (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
R <sub>network</sub>	R2/R1 internal resistance values in non-inverting PGA mode <sup>(3)</sup>	PGA Gain=2	-	10/10	-	kΩ/ kΩ	
		PGA Gain=4	-	30/10	-		
		PGA Gain=8	-	70/10	-		
		PGA Gain=16	-	150/10	-		
	R2/R1 internal resistance values in inverting PGA mode <sup>(3)</sup>	PGA Gain = -1	-	10/10	-		
		PGA Gain = -3	-	30/10	-		
		PGA Gain = -7	-	70/10	-		
		PGA Gain = -15	-	150/10	-		
Delta R	Resistance variation (R1 or R2)	-	-15	-	15	%	
PGA BW	PGA bandwidth for different non inverting gain	Gain=2	-	GBW/2	-	MHz	
		Gain=4	-	GBW/4	-		
		Gain=8	-	GBW/8	-		
		Gain=16	-	GBW/16	-		
	PGA bandwidth for different inverting gain	Gain = -1	-	5.00	-	MHz	
		Gain = -3	-	3.00	-		
		Gain = -7	-	1.50	-		
		Gain = -15	-	0.80	-		
en	Voltage noise density	at 1 KHz	output loaded with 4 kΩ	-	140	-	nV/ $\sqrt{\text{Hz}}$
		at 10 KHz		-	55	-	
I <sub>DDA(OPAMP)</sub>	OPAMP consumption from V <sub>DDA</sub>	Normal mode	no Load, quiescent mode, follower	-	570	1000	μA
		High-speed mode		-	610	1200	

1. Guaranteed by design, unless otherwise specified.
2. R<sub>LOAD</sub> is the resistive load connected to V<sub>SSA</sub> or to V<sub>DDA</sub>.
3. R2 is the internal resistance between the OPAMP output and the OPAMP inverting input. R1 is the internal resistance between the OPAMP inverting input and ground. PGA gain = 1 + R2/R1.

### 6.3.32 Digital filter for Sigma-Delta Modulators (DFSDM) characteristics

Unless otherwise specified, the parameters given in [Table 100](#) for DFSDM are derived from tests performed under the ambient temperature, fCLKx frequency and supply voltage conditions summarized in [Table 12: General operating conditions](#).

- Output speed is set to OSPEEDRy[1:0] = 10
- Capacitive load C<sub>L</sub> = 30 pF
- Measurement points are done at CMOS levels: 0.5V<sub>DD</sub>
- VOS level set to VOS0

Refer to [Section 6.3.17: I/O port characteristics](#) for more details on the input/output alternate function characteristics (DIFSDM\_CKINx, DFSDM\_DATINx, DFSDM\_CKOUT for DFSDM).

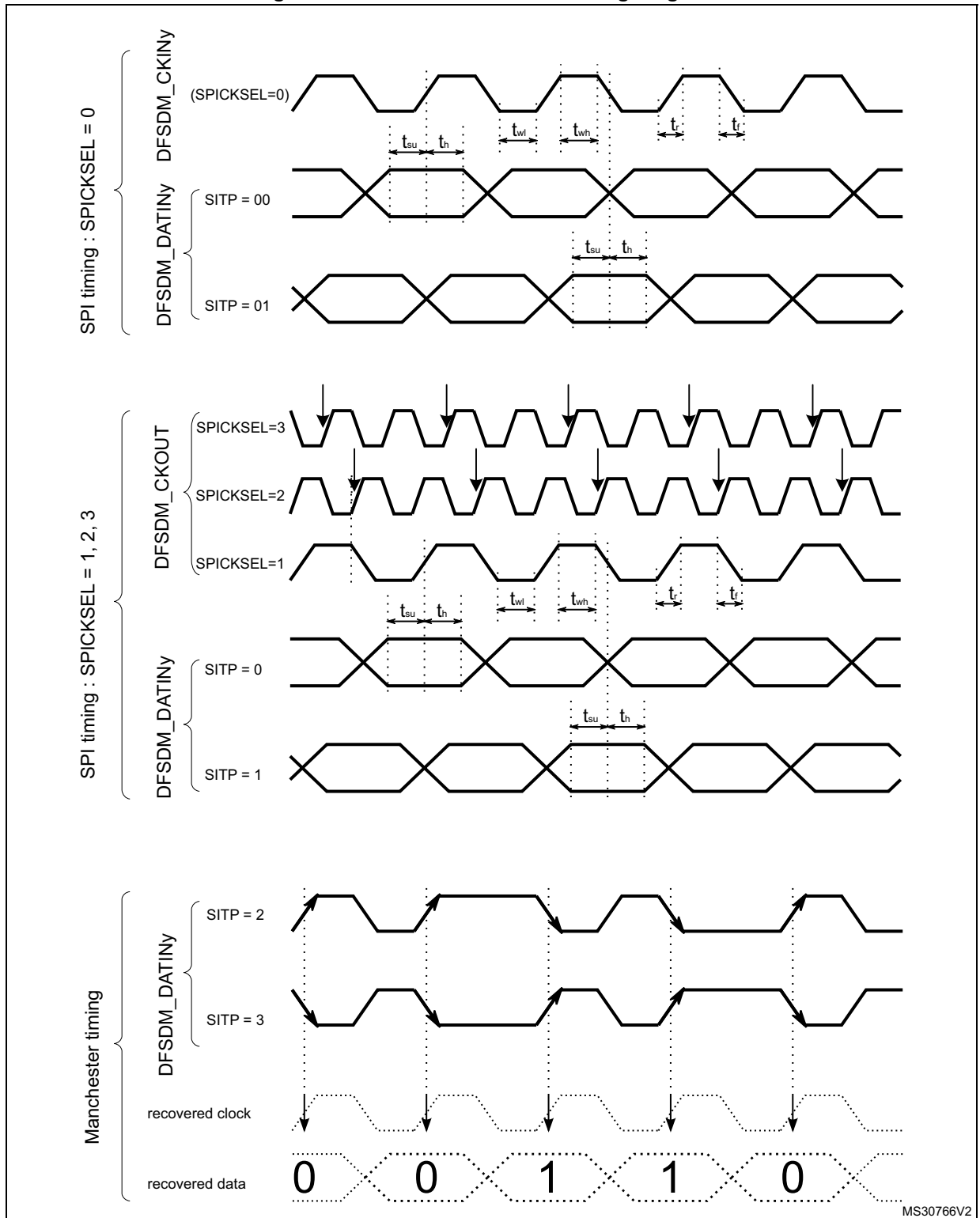
**Table 100. DFSDM measured timing**

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
f <sub>DFSDMCLK</sub>	DFSDM clock	1.62 < V <sub>DD</sub> < 3.6 V		-	-	f <sub>SYSCLK</sub>	
f <sub>CKIN</sub> (1/T <sub>CKIN</sub> )	Input clock frequency	SPI mode (SITP[1:0] = 0,1), External clock mode (SPICKSEL[1:0] = 0)		-	-	20	MHz
		SPI mode (SITP[1:0] = 0,1), Internal clock mode (SPICKSEL[1:0] ≠ 0)		-	-	20	
f <sub>CKOUT</sub>	Output clock frequency	1.62 < V <sub>DD</sub> < 3.6 V		-	-	20	
DuCy <sub>CKOUT</sub>	Output clock frequency duty cycle	1.62 < V <sub>DD</sub> < 3.6 V	Even division, CKOUTDIV = n, 1, 3, 5..	45	50	55	%
			Odd division, CKOUTDIV = n, 2, 4, 6..	$\frac{(n/2+1)}{(n+1)} * 100 - 5$	$\frac{(n/2+1)}{(n+1)} * 100$	$\frac{(n/2+1)}{(n+1)} * 100 + 5$	

Table 100. DFSDM measured timing (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$t_{wh(CKIN)}$ $t_{wl(CKIN)}$	Input clock high and low time	SPI mode (SITP[1:0] = 0,1), External clock mode (SPICKSEL[1:0] = 0)	$T_{CKIN}/2-0.5$	$T_{CKIN}/2$	-	ns
$t_{su}$	Data input setup time	SPI mode (SITP[1:0] = 0,1), External clock mode (SPICKSEL[1:0] = 0)	2	-	-	
$t_h$	Data input hold time	SPI mode (SITP[1:0] = 0,1), External clock mode (SPICKSEL[1:0] = 0)	1	-	-	
$T_{Manchester}$	Manchester data period (recovered clock period)	Manchester mode (SITP[1:0] = 2,3), Internal clock mode (SPICKSEL[1:0] ≠ 0)	$(CKOUTDIV+1)$ $* T_{DFSDMCLK}$	-	$(2*CKOUTDIV)$ $* T_{DFSDMCLK}$	

Figure 50. Channel transceiver timing diagrams





### 6.3.33 Camera interface (DCMI) timing specifications

Unless otherwise specified, the parameters given in [Table 101](#) for DCMI are derived from tests performed under the ambient temperature,  $f_{HCLK}$  frequency and VDD supply voltage summarized in [Table 12: General operating conditions](#), with the following configuration:

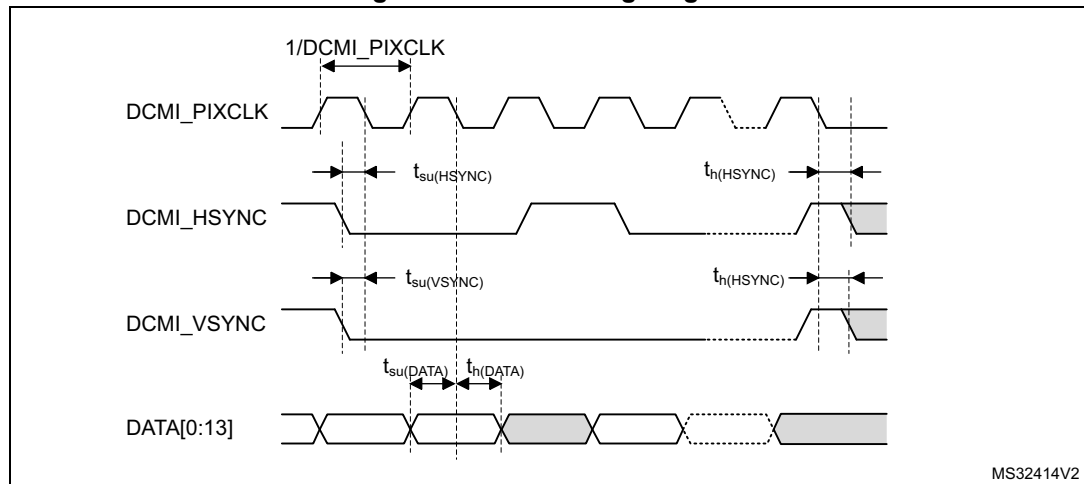
- DCMI\_PIXCLK polarity: falling
- DCMI\_VSYNC and DCMI\_HSYNC polarity: high
- Data formats: 14 bits
- Capacitive load  $C_L=30$  pF
- Measurement points are done at CMOS levels:  $0.5V_{DD}$
- VOS level set to VOS0

**Table 101. DCMI characteristics<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
-	Frequency ratio DCMI_PIXCLK/ $f_{HCLK}$	-	0.4	-
DCMI_PIXCLK	Pixel Clock input	-	110	MHz
$D_{pixel}$	Pixel Clock input duty cycle	30	70	%
$t_{su}(DATA)$	Data input setup time	2	-	ns
$t_h(DATA)$	Data hold time	1	-	
$t_{su}(HSYNC)$ , $t_{su}(VSYNC)$	DCMI_HSYNC/ DCMI_VSYNC input setup time	2	-	
$t_h(HSYNC)$ , $t_h(VSYNC)$	DCMI_HSYNC/ DCMI_VSYNC input hold time	1	-	

1. Guaranteed by characterization results.

**Figure 51. DCMI timing diagram**



### 6.3.34 Parallel synchronous slave interface (PSSI) characteristics

Unless otherwise specified, the parameters given in [Table 102](#) and [Table 103](#) for PSSI are derived from tests performed under the ambient temperature,  $f_{HCLK}$  frequency and VDD supply voltage summarized in [Table 12: General operating conditions](#).

**Table 102. PSSI transmit characteristics<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
-	Frequency ratio PSSI_PDCK/ $f_{HCLK}$	-	0.4	-
PSSI_PDCK	PSSI Clock input	-	50	MHz
		-	35 <sup>(2)</sup>	
$D_{pixel}$	PSSI Clock input duty cycle	30	70	%
$t_{ov}(DATA)$	Data output valid time	-	10	ns
-	-	-	14 <sup>(2)</sup>	
$t_{oh}(DATA)$	Data output hold time	4.5	-	
$t_{ov}(DE)$	DE output valid time	-	10	
$t_{oh}(DE)$	DE output hold time	4	-	
$t_{su}(RDY)$	RDY input setup time	0	-	
$t_h(RDY)$	RDY input hold time	0	-	

1. Guaranteed by characterization results.
2. This value is obtained by using PA9, PA10 or PH4 I/O.

**Table 103. PSSI receive characteristics<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
-	Frequency ratio PSSI_PDCK/ $f_{HCLK}$	-	0.4	-
PSSI_PDCK	PSSI Clock input	-	110	MHz
$D_{pixel}$	PSSI Clock input duty cycle	30	70	%
$t_{su}(DATA)$	Data input setup time	1.5	-	ns
$t_h(DATA)$	Data input hold time	0.5	-	
$t_{su}(DE)$	DE input setup time	2	-	
$t_h(DE)$	DE input hold time	1	-	
$t_{ov}(RDY)$	RDY output valid time	-	15	
$t_{oh}(RDY)$	RDY output hold time	5.5	-	

1. Guaranteed by characterization results.

### 6.3.35 LCD-TFT controller (LTDC) characteristics

Unless otherwise specified, the parameters given in [Table 104](#) for LCD-TFT are derived from tests performed under the ambient temperature,  $f_{HCLK}$  frequency and VDD supply voltage summarized in [Table 12: General operating conditions](#), with the following configuration:

- LCD\_CLK polarity: high
- LCD\_DE polarity: low
- LCD\_VSYNC and LCD\_HSYNC polarity: high
- Pixel formats: 24 bits
- Output speed is set to OSPEEDRy[1:0] = 11
- Capacitive load  $C_L=30$  pF
- Measurement points are done at CMOS levels: 0.5VDD
- IO Compensation cell activated.
- HSLV activated when  $V_{DD} \leq 2.7$  V
- VOS level set to VOS0

**Table 104. LTDC characteristics<sup>(1)</sup>**

Symbol	Parameter		Min	Max	Unit
$f_{CLK}$	LTDC clock output frequency	2.7<V <sub>DD</sub> <3.6 V, 20 pF	-	150	MHz
		2.7<V <sub>DD</sub> <3.6 V		133	
		1.62<V <sub>DD</sub> <3.6 V		90/76.5 <sup>(2)</sup>	
D <sub>CLK</sub>	LTDC clock output duty cycle		45	55	%
$t_{w(CLKH)}$ , $t_{w(CLKL)}$	Clock High time, low time		$t_{w(CLK)}/2-0.5$	$t_{w(CLK)}/2+0.5$	ns
$t_{v(DATA)}$	Data output valid time	2.7<V <sub>DD</sub> <3.6 V	-	2.0	
		1.62<V <sub>DD</sub> <3.6 V		2.5/6.5 <sup>(2)</sup>	
$t_{h(DATA)}$	Data output hold time		0	-	
$t_{v(HSYNC)}$ , $t_{v(VSYNC)}$ , $t_{v(DE)}$	HSYNC/VSYNC/DE output valid time	2.7<V <sub>DD</sub> <3.6 V	-	1.5	
		1.62<V <sub>DD</sub> <3.6 V	-	2.0	
$t_{h(HSYNC)}$ , $t_{h(VSYNC)}$ , $t_{h(DE)}$	HSYNC/VSYNC/DE output hold time		0	-	

1. Guaranteed by characterization results.
2. This value is valid when PA[9], PA[10], PA[11], PA[12], PA[15], PB[11], PH[4], PJ[8], PJ[9], PJ[10], PJ[11], PK[0], PK[1] or PK[2] is used.

Figure 52. LCD-TFT horizontal timing diagram

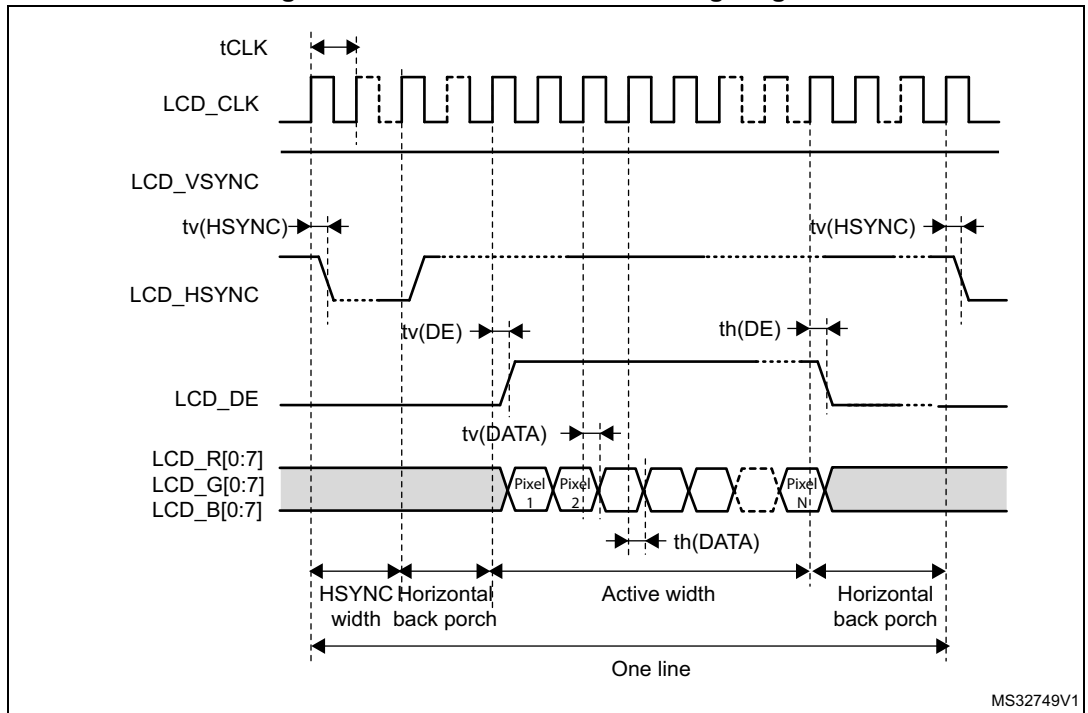
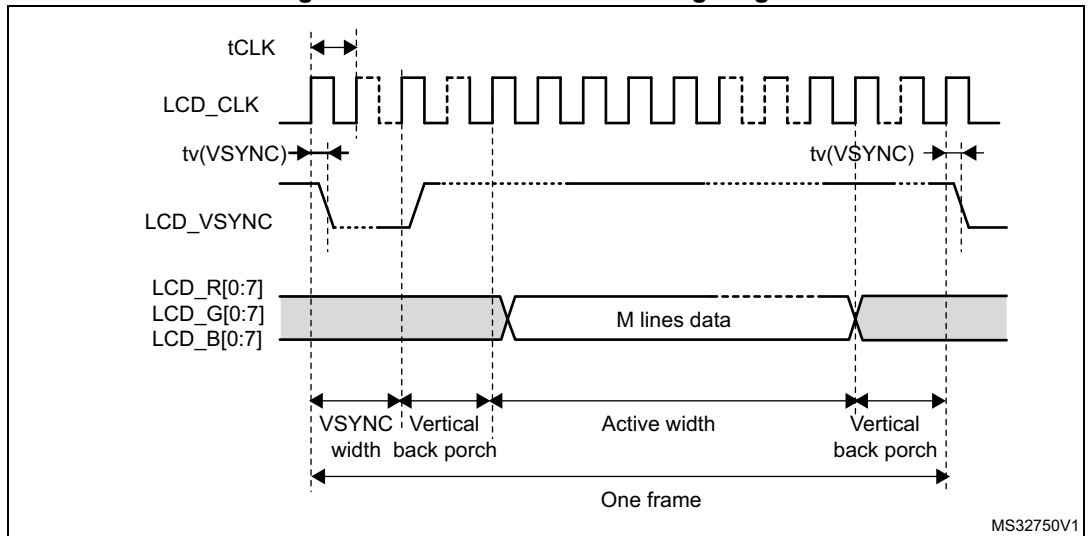


Figure 53. LCD-TFT vertical timing diagram



### 6.3.36 Timer characteristics

The parameters given in [Table 105](#) are guaranteed by design.

Refer to [Section 6.3.17: I/O port characteristics](#) for details on the input/output alternate function characteristics (output compare, input capture, external clock, PWM output).

**Table 105. TIMx characteristics<sup>(1)(2)</sup>**

Symbol	Parameter	Conditions <sup>(3)</sup>	Min	Max	Unit
t <sub>res(TIM)</sub>	Timer resolution time	AHB/APBx prescaler=1 or 2 or 4, f <sub>TIMxCLK</sub> = 275 MHz	1	-	t <sub>TIMxCLK</sub>
		AHB/APBx prescaler>4, f <sub>TIMxCLK</sub> = 137.5 MHz	1	-	t <sub>TIMxCLK</sub>
f <sub>EXT</sub>	Timer external clock frequency on CH1 to CH4	f <sub>TIMxCLK</sub> = 240 MHz	0	f <sub>TIMxCLK</sub> /2	MHz
Res <sub>TIM</sub>	Timer resolution		-	16/32	bit
t <sub>MAX_COUNT</sub>	Maximum possible count with 32-bit counter	-	-	65536 × 65536	t <sub>TIMxCLK</sub>

1. TIMx is used as a general term to refer to the TIM1 to TIM17 timers.
2. Guaranteed by design.
3. The maximum timer frequency on APB1 or APB2 is up to 275 MHz, by setting the TIMPRE bit in the RCC\_CFGR register, if APBx prescaler is 1 or 2 or 4, then TIMxCLK = rcc\_hclk1, otherwise TIMxCLK = 4 × F<sub>rcc\_pclkx1</sub> or TIMxCLK = 4 × F<sub>rcc\_pclkx2</sub>.

### 6.3.37 Low-power timer characteristics

The parameters given in [Table 106](#) are guaranteed by design.

Refer to [Section 6.3.17: I/O port characteristics](#) for details on the input/output alternate function characteristics (output compare, input capture, external clock, PWM output).

**Table 106. LPTIMx characteristics<sup>(1)(2)</sup>**

Symbol	Parameter	Min	Max	Unit
t <sub>res(TIM)</sub>	Timer resolution time	1	-	t <sub>TIMxCLK</sub>
f <sub>LPTIMxCLK</sub>	Timer kernel clock	0	137.5	MHz
f <sub>EXT</sub>	Timer external clock frequency on Input1 and Input2	0	f <sub>LPTIMxCLK</sub> /2	
Res <sub>TIM</sub>	Timer resolution	-	16	bit
t <sub>MAX_COUNT</sub>	Maximum possible count	-	65536	t <sub>TIMxCLK</sub>

1. LPTIMx is used as a general term to refer to the LPTIM1 to LPTIM5 timers.
2. Guaranteed by design.

### 6.3.38 Communication interfaces

#### I<sup>2</sup>C interface characteristics

The I<sup>2</sup>C interface meets the timings requirements of the I2C-bus specification and user manual revision 03 for:

- Standard-mode (Sm): with a bit rate up to 100 kbit/s
- Fast-mode (Fm): with a bit rate up to 400 kbit/s
- Fast-mode Plus (Fm+): with a bit rate up to 1 Mbit/s.

The I<sup>2</sup>C timings requirements are guaranteed by design when the I<sup>2</sup>C peripheral is properly configured (refer to RM0399 reference manual) and when the i2c\_ker\_ck frequency is greater than the minimum shown in the table below:

**Table 107. Minimum i2c\_ker\_ck frequency in all I<sup>2</sup>C modes**

Symbol	Parameter	Condition		Min	Unit
f(I2CCLK)	I2CCLK frequency	Standard-mode	-	2	MHz
		Fast-mode	Analog Filtre ON DNF=0	8	
			Analog Filtre OFF DNF=1	9	
		Fast-mode Plus	Analog Filtre ON DNF=0	17	
			Analog Filtre OFF DNF=1	16	-

The SDA and SCL I/O requirements are met with the following restrictions:

- The SDA and SCL I/O pins are not “true” open-drain. When configured as open-drain, the PMOS connected between the I/O pin and V<sub>DD</sub> is disabled, but still present.
- The 20 mA output drive requirement in Fast-mode Plus is not supported. This limits the maximum load C<sub>Load</sub> supported in Fm+, which is given by these formulas:

$$t_{r(SDA/SCL)} = 0.8473 \times R_P \times C_{Load}$$

$$R_{P(min)} = (V_{DD} - V_{OL(max)}) / I_{OL(max)}$$

Where R<sub>P</sub> is the I2C lines pull-up. Refer to [Section 6.3.17: I/O port characteristics](#) for the I<sup>2</sup>C I/Os characteristics.

All I<sup>2</sup>C SDA and SCL I/Os embed an analog filter. Refer to the table below for the analog filter characteristics:

**Table 108. I<sup>2</sup>C analog filter characteristics<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
t <sub>AF</sub>	Maximum pulse width of spikes that are suppressed by analog filter	50 <sup>(2)</sup>	80 <sup>(3)</sup>	ns

1. Guaranteed by characterization results.
2. Spikes with widths below t<sub>AF(min)</sub> are filtered.

- 3. Spikes with widths above  $t_{AF(max)}$  are not filtered.

**USART interface characteristics**

Unless otherwise specified, the parameters given in [Table 109](#) for USART are derived from tests performed under the ambient temperature,  $f_{PCLKx}$  frequency and  $V_{DD}$  supply voltage conditions summarized in [Table 12: General operating conditions](#), with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 11
- Capacitive load  $C_L = 30$  pF
- Measurement points are done at CMOS levels:  $0.5V_{DD}$
- IO Compensation cell activated.
- VOS level set to VOS0

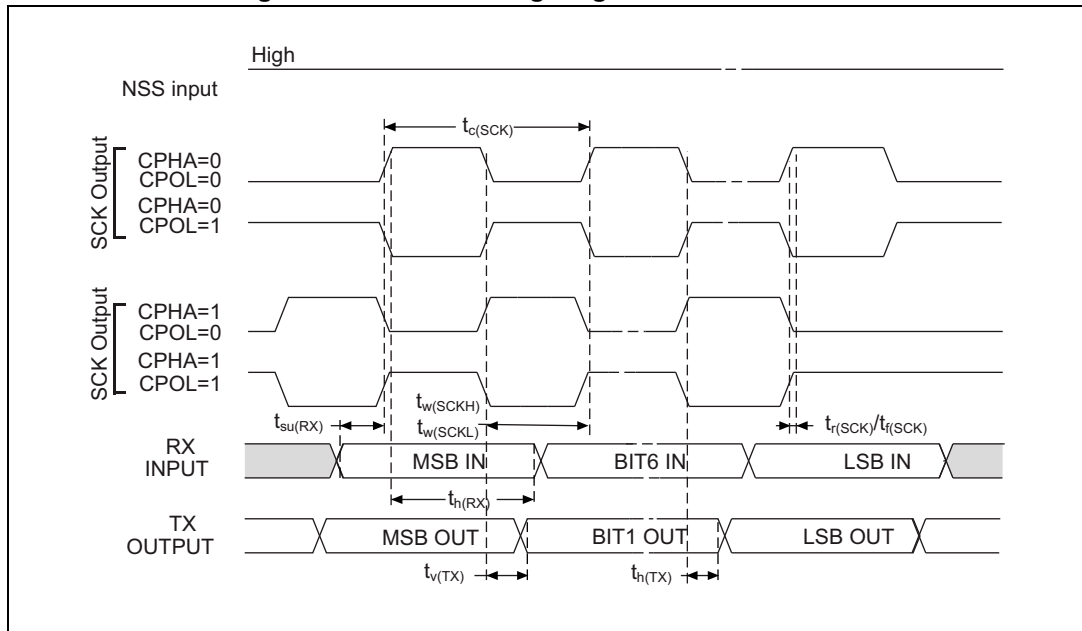
Refer to [Section 6.3.17: I/O port characteristics](#) for more details on the input/output alternate function characteristics (NSS, CK, TX, RX for USART).

**Table 109. USART characteristics<sup>(1)</sup>**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{CK}$	USART clock frequency	Master mode, $1.62\text{ V} < V_{DD} < 3.6\text{ V}$	-	-	17.0	MHz
		Slave receiver mode, $1.62\text{ V} < V_{DD} < 3.6\text{ V}$			45.0	
		Slave transmitter mode, $1.62\text{ V} < V_{DD} < 3.6\text{ V}$	-	-	27.0	
		Slave transmitter mode, $2.5\text{ V} < V_{DD} < 3.6\text{ V}$			37.0	
$t_{su(NSS)}$	NSS setup time	Slave mode	$t_{ker}+1$	-	-	ns
$t_h(NSS)$	NSS hold time	Slave mode	2	-	-	
$t_w(SCKH),$ $t_w(SCKL)$	CK high and low time	Master mode	$1/f_{CK}/2-2$	$1/f_{CK}/2$	$1/f_{CK}/2+2$	
$t_{su(RX)}$	Data input setup time	Master mode	16	-	-	
		Slave mode	1.0	-	-	
$t_h(RX)$	Data input hold time	Master mode	0	-	-	
		Slave mode	2.0	-	-	
$t_v(TX)$	Data output valid time	Slave mode, , $1.62\text{ V} < V_{DD} < 3.6\text{ V}$	-	12.0	18	
		Slave mode, , $2.5\text{ V} < V_{DD} < 3.6\text{ V}$	-	12.0	13.5	
		Master mode	-	0.5	1	
$t_h(TX)$	Data output hold time	Slave mode	9	-	-	
		Master mode	0	-	-	

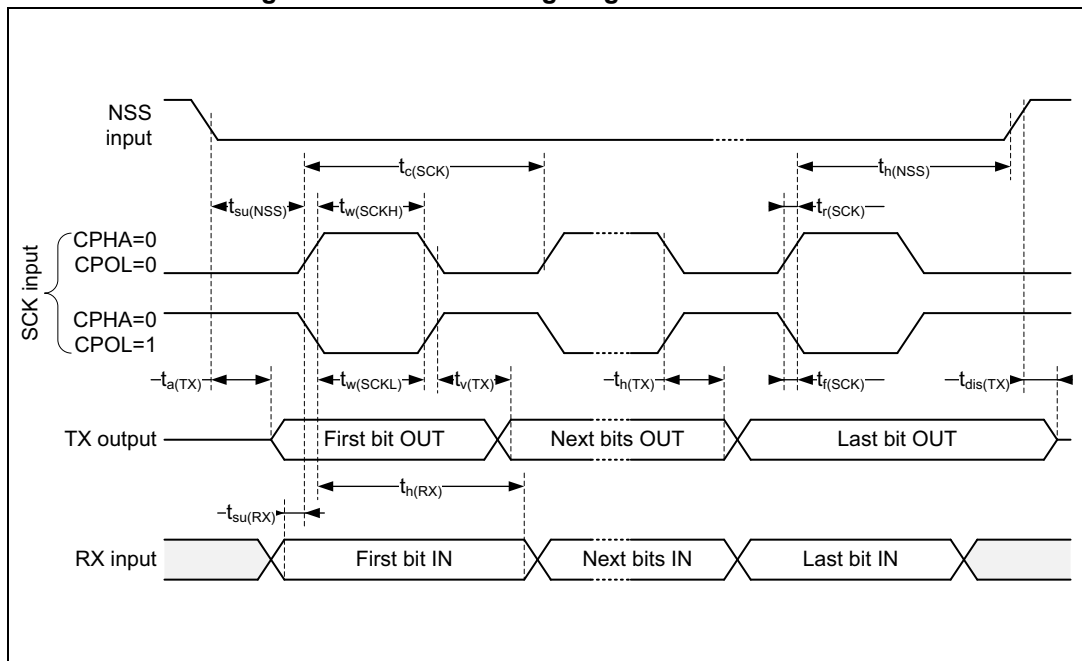
1. Guaranteed by characterization results.

Figure 54. USART timing diagram in Master mode



1. Measurement points are done at  $0.5V_{DD}$  and with external  $C_L = 30$  pF.

Figure 55. USART timing diagram in Slave mode





**SPI interface characteristics**

Unless otherwise specified, the parameters given in [Table 110](#) for SPI are derived from tests performed under the ambient temperature,  $f_{PCLKx}$  frequency and  $V_{DD}$  supply voltage conditions summarized in [Table 12: General operating conditions](#), with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 11
- Capacitive load  $C_L = 30$  pF
- Measurement points are done at CMOS levels:  $0.5V_{DD}$
- IO Compensation cell activated.
- HSLV activated when  $V_{DD} \leq 2.7$  V
- VOS level set to VOS0

Refer to [Section 6.3.17: I/O port characteristics](#) for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO for SPI).

**Table 110. SPI characteristics<sup>(1)(2)</sup>**

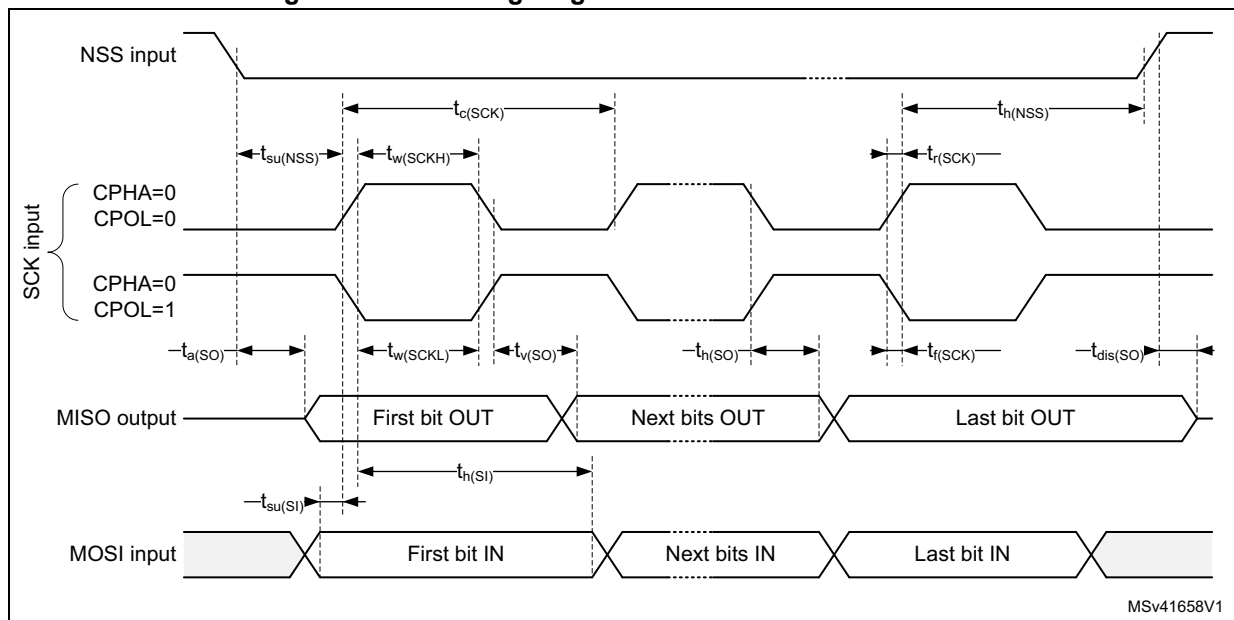
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{SCK}$	SPI clock frequency	Master mode, $2.7\text{ V} < V_{DD} < 3.6\text{ V}$ , SPI1, 2, 3	-	-	125	MHz
		Master mode, $1.62\text{ V} < V_{DD} < 3.6\text{ V}$ , SPI1, 2, 3			80/66 <sup>(3)</sup>	
		Master mode, $1.62\text{ V} < V_{DD} < 3.6\text{ V}$ , SPI4, 5, 6			68.5	
		Slave receiver mode, $1.62\text{ V} < V_{DD} < 3.6\text{ V}$ , SPI1, 2, 3			100	
		Slave receiver mode, $1.62\text{ V} < V_{DD} < 3.6\text{ V}$ , SPI4, 5, 6			68.5	
		Slave mode transmitter/full duplex, $2.7\text{ V} < V_{DD} < 3.6\text{ V}$			45	
		Slave mode transmitter/full duplex, $1.62\text{ V} < V_{DD} < 3.6\text{ V}$			42.5/31 <sup>(4)</sup>	
$t_{su(NSS)}$	NSS setup time	Slave mode	2	-	-	-
$t_{h(NSS)}$	NSS hold time	Slave mode	1	-	-	
$t_{w(SCKH)}$ , $t_{w(SCKL)}$	SCK high and low time	Master mode	$t_{SCK}/2-1^{(5)}$	$t_{SCK}/2^{(5)}$	$t_{SCK}/2+1^{(5)}$	

Table 110. SPI characteristics<sup>(1)(2)</sup> (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$t_{su(MI)}$	Data input setup time	Master mode	2.5	-	-	ns
$t_{su(SI)}$		Slave mode	1	-	-	
$t_{h(MI)}$	Data input hold time	Master mode	3	-	-	
$t_{h(SI)}$		Slave mode	1.5	-	-	
$t_{a(SO)}$	Data output access time	Slave mode	9	13	27	
$t_{dis(SO)}$	Data output disable time	Slave mode	0	1	5	
$t_{v(SO)}$	Data output valid time	Slave mode, 2.7 V < $V_{DD}$ < 3.6 V	-	7.5	11	
		Slave mode, 1.62 V < $V_{DD}$ < 3.6 V	-	7.5	12/16 <sup>(4)</sup>	
$t_{v(MO)}$		Master mode, 1.62 V < $V_{DD}$ < 3.6 V	-	1	1.5/5.5 <sup>(6)</sup>	
$t_{h(SO)}$	Data output hold time	Slave mode	7	-	-	
$t_{h(MO)}$		Master mode	0.5	-	-	

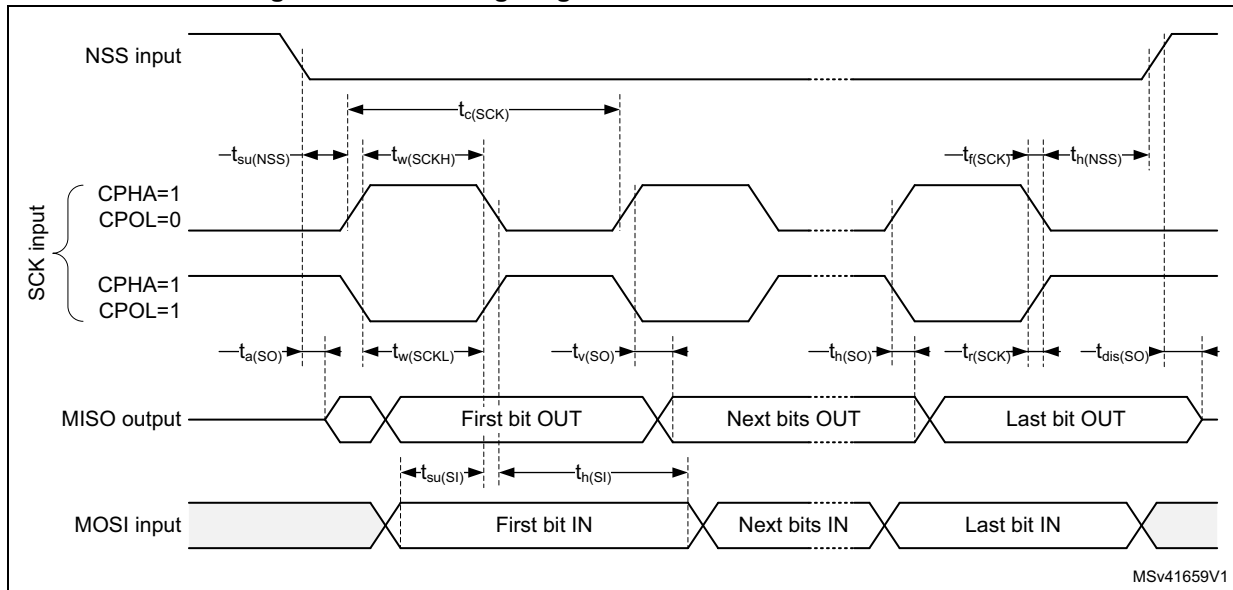
1. Guaranteed by characterization results.
2. The values given in the above table might be degraded when PC3\_C/PC2\_C I/Os are used (not available on all packages).
3. This value is obtained by using PA9 or PA12 I/O.
4. This value is obtained by using PC2 or PJ11 I/O.
5.  $t_{SCK} = t_{ker\_ck} * \text{baud rate prescaler}$ .
6. This value is obtained by using PC3 or PJ10 I/O.

Figure 56. SPI timing diagram - slave mode and CPHA = 0



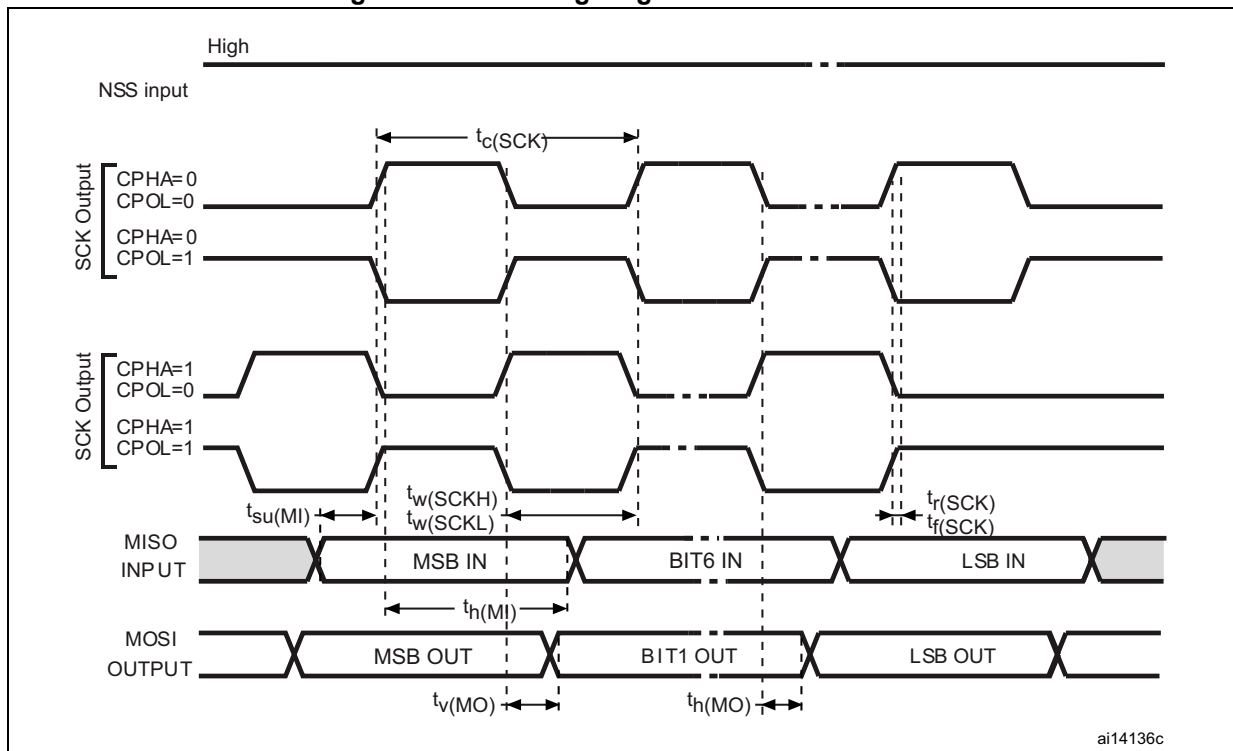
MSv41658V1

Figure 57. SPI timing diagram - slave mode and CPHA = 1<sup>(1)</sup>



1. Measurement points are done at 0.5V<sub>DD</sub> and with external C<sub>L</sub> = 30 pF.

Figure 58. SPI timing diagram - master mode<sup>(1)</sup>



1. Measurement points are done at 0.5V<sub>DD</sub> and with external C<sub>L</sub> = 30 pF.

### I<sup>2</sup>S Interface characteristics

Unless otherwise specified, the parameters given in [Table 111](#) for I<sup>2</sup>S are derived from tests performed under the ambient temperature,  $f_{PCLKx}$  frequency and  $V_{DD}$  supply voltage conditions summarized in [Table 12: General operating conditions](#), with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 11
- Capacitive load  $C_L = 30$  pF
- Measurement points are done at CMOS levels:  $0.5V_{DD}$
- IO Compensation cell activated.
- HSLV activated when  $V_{DD} \leq 2.7$  V
- VOS level set to VOS0

Refer to [Section 6.3.17: I/O port characteristics](#) for more details on the input/output alternate function characteristics (CK,SD,WS).

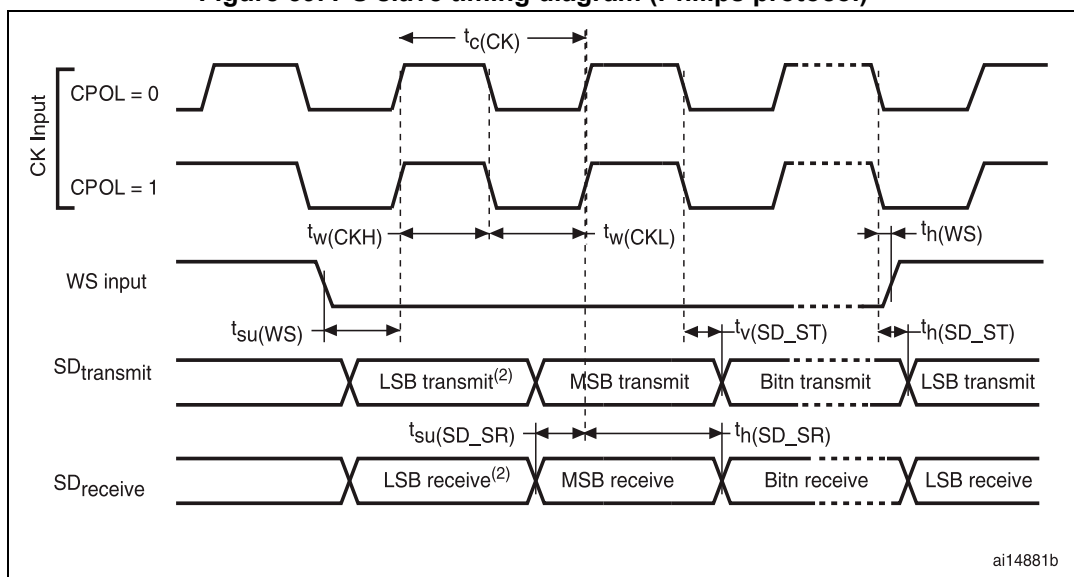
**Table 111. I<sup>2</sup>S dynamic characteristics<sup>(1)</sup>**

Symbol	Parameter	Conditions	Min	Max	Unit
$f_{MCK}$	I <sup>2</sup> S main clock output	-	-	50	MHz
		Master transmitter	-	50/40 <sup>(2)</sup>	
		Master receiver	-	50/40 <sup>(2)</sup>	
		Slave transmitter	-	41.5/31 <sup>(3)</sup>	
		Slave receiver	-	50	
$t_{v(WS)}$	WS valid time	Master mode	-	2/6 <sup>(4)</sup>	ns
$t_{h(WS)}$	WS hold time		1	-	
$t_{su(WS)}$	WS setup time	Slave mode	3	-	
$t_{h(WS)}$	WS hold time		1	-	
$t_{su(SD\_MR)}$	Data input setup time	Master receiver	2.5	-	
$t_{su(SD\_SR)}$		Slave receiver	1	-	
$t_{h(SD\_MR)}$	Data input hold time	Master receiver	3	-	
$t_{h(SD\_SR)}$		Slave receiver	1.5	-	
$t_{v(SD\_ST)}$	Data output valid time	Slave transmitter (after enable edge)	-	12/16 <sup>(3)</sup>	
$t_{v(SD\_MT)}$		Master transmitter (after enable edge)	-	2/6 <sup>(5)</sup>	
$t_{h(SD\_ST)}$	Data output hold time	Slave transmitter (after enable edge)	6.5	-	
$t_{h(SD\_MT)}$		Master transmitter (after enable edge)	0.5	-	

1. Guaranteed by characterization results.
2. This value is obtained when PA9 or PA12 are used.
3. This value is obtained when PC2 is used.
4. This value is obtained when PA11 or PA15 are used.

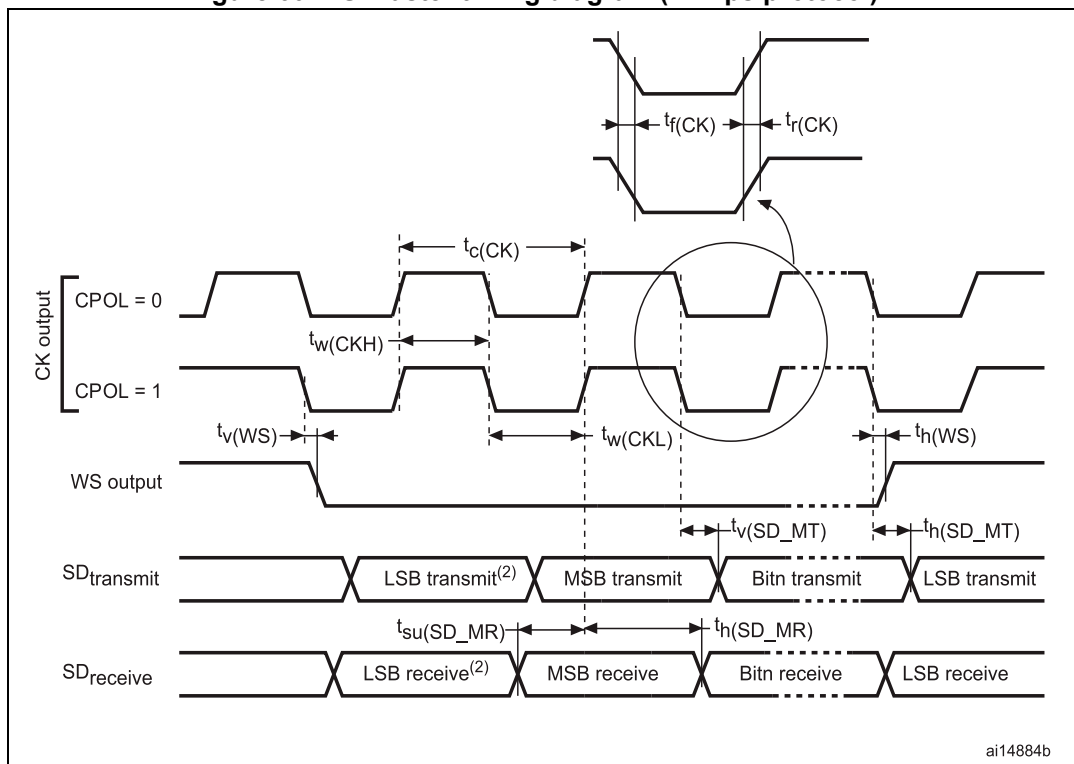
5. This value is obtained when PC3 is used.

**Figure 59. I<sup>2</sup>S slave timing diagram (Philips protocol)<sup>(1)</sup>**



1. LSB transmit/receive of the previously transmitted byte. No LSB transmit/receive is sent before the first byte.

**Figure 60. I<sup>2</sup>S master timing diagram (Philips protocol)<sup>(1)</sup>**



1. LSB transmit/receive of the previously transmitted byte. No LSB transmit/receive is sent before the first byte.

### SAI characteristics

Unless otherwise specified, the parameters given in [Table 112](#) for SAI are derived from tests performed under the ambient temperature,  $f_{PCLKx}$  frequency and VDD supply voltage conditions summarized in [Table 12: General operating conditions](#), with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 10
- Capacitive load  $C_L = 30$  pF
- IO Compensation cell activated.
- Measurement points are done at CMOS levels:  $0.5V_{DD}$
- VOS level set to VOS0

Refer to [Section 6.3.17: I/O port characteristics](#) for more details on the input/output alternate function characteristics (SCK,SD,WS).

**Table 112. SAI characteristics<sup>(1)</sup>**

Symbol	Parameter	Conditions	Min	Max	Unit
$f_{MCK}$	SAI Main clock output	-	-	50	MHz
$f_{CK}$	SAI clock frequency <sup>(2)</sup>	Master transmitter, $2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$	-	45	
		Master transmitter, $1.62\text{ V} \leq V_{DD} \leq 3.6\text{ V}$	-	32	
		Master receiver, $1.62\text{ V} \leq V_{DD} \leq 3.6\text{ V}$	-	32	
		Slave transmitter, $2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$	-	47.5	
		Slave transmitter, $1.62\text{ V} \leq V_{DD} \leq 3.6\text{ V}$	-	41.5	
		Slave receiver, $1.62\text{ V} \leq V_{DD} \leq 3.6\text{ V}$	-	50	

Table 112. SAI characteristics<sup>(1)</sup> (continued)

Symbol	Parameter	Conditions	Min	Max	Unit
$t_{v(FS)}$	$F_S$ valid time	Master mode, $2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$	-	11	ns
		Master mode, $1.62\text{ V} \leq V_{DD} \leq 3.6\text{ V}$	-	15.5	
$t_{su(FS)}$	$F_S$ setup time	Slave mode	2.5	-	
$t_{h(FS)}$	$F_S$ hold time	Master mode	6	-	
		Slave mode	0.5	-	
$t_{su(SD\_A\_MR)}$	Data input setup time	Master receiver	3	-	
$t_{su(SD\_B\_SR)}$		Slave receiver	3.5	-	
$t_{h(SD\_A\_MR)}$	Data input hold time	Master receiver	3.5	-	
$t_{h(SD\_B\_SR)}$		Slave receiver	0	-	
$t_{v(SD\_B\_ST)}$	Data output valid time	Slave transmitter (after enable edge), $2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$	-	10.5	
		Slave transmitter (after enable edge), $1.62\text{ V} \leq V_{DD} \leq 3.6\text{ V}$	-	12	
$t_{h(SD\_B\_ST)}$	Data output hold time	Slave transmitter (after enable edge)	6.5	-	
$t_{v(SD\_A\_MT)}$	Data output valid time	Master transmitter (after enable edge), $2.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$	-	10.5	
		Master transmitter (after enable edge), $1.62\text{ V} \leq V_{DD} \leq 3.6\text{ V}$	-	14.5	
$t_{h(SD\_A\_MT)}$	Data output hold time	Master transmitter (after enable edge)	6	-	

1. Guaranteed by characterization results.
2. APB clock frequency must be at least twice SAI clock frequency.

Figure 61. SAI master timing waveforms

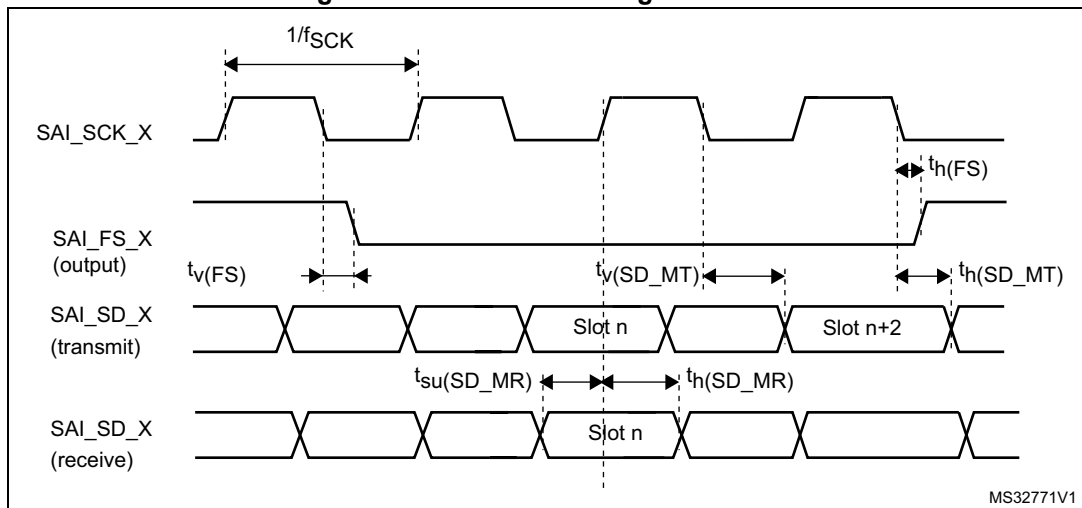
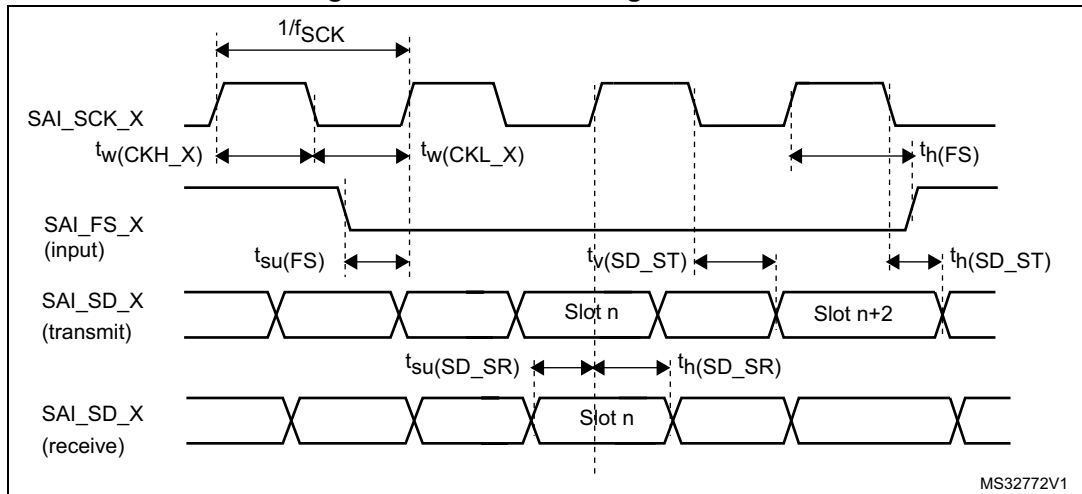


Figure 62. SAI slave timing waveforms



**MDIO characteristics**

Unless otherwise specified, the parameters given in [Table 113](#) for the MDIO are derived from tests performed under the ambient temperature,  $f_{PCLKx}$  frequency and VDD supply voltage conditions summarized in [Table 12: General operating conditions](#), with the following configuration:

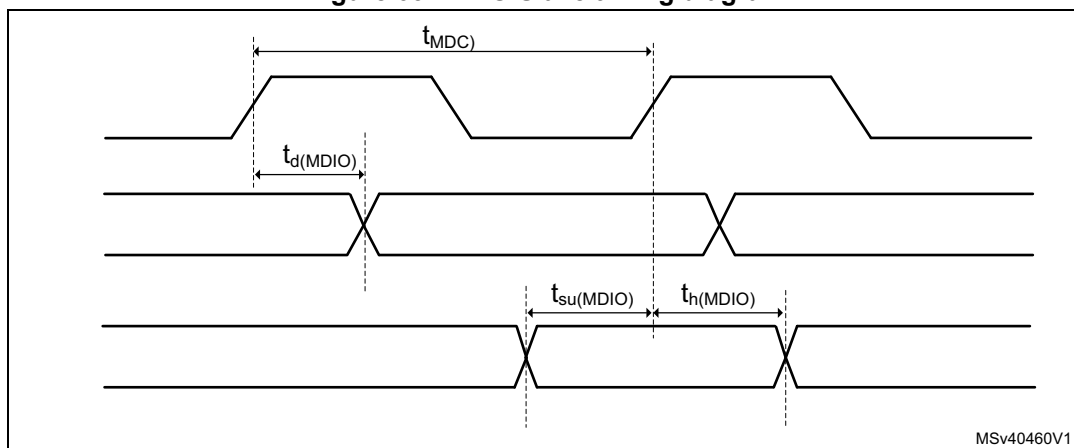
- Output speed is set to OSPEEDRy[1:0] = 10
- I/O Compensation cell activated.
- Measurement points are done at CMOS levels:  $0.5V_{DD}$
- HSLV activated when  $V_{DD} \leq 2.7 V$
- VOS level set to VOS0

Table 113. MDIO Slave timing parameters

Symbol	Parameter	Min	Typ	Max	Unit
$F_{MDC}$	Management Data Clock	-	-	30	MHz
$t_d(MDIO)$	Management Data Input/output output valid time	8	10	18	ns
$t_{su}(MDIO)$	Management Data Input/output setup time	1	-	-	
$t_h(MDIO)$	Management Data Input/output hold time	1	-	-	



Figure 63. MDIO Slave timing diagram



**SD/SDIO MMC card host interface (SDMMC) characteristics**

Unless otherwise specified, the parameters given in [Table 114](#) and [Table 115](#) for SDIO are derived from tests performed under the ambient temperature,  $f_{PCLKx}$  frequency and VDD supply voltage summarized in [Table 12: General operating conditions](#), with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 11
- Capacitive load  $C_L=30$  pF
- Measurement points are done at CMOS levels:  $0.5V_{DD}$
- IO Compensation cell activated.
- HSLV activated when  $V_{DD} \leq 2.7$  V
- VOS level set to VOS0

Refer to [Section 6.3.17: I/O port characteristics](#) for more details on the input/output characteristics.

**Table 114. Dynamics characteristics: SD / MMC characteristics,  $V_{DD}=2.7$  to  $3.6$  V<sup>(1)(2)</sup>**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{PP}$	Clock frequency in data transfer mode	-	0	-	120	MHz
-	SDIO_CK/fPCLK2 frequency ratio	-	-	-	8/3	-
$t_{W(CKL)}$	Clock low time	$f_{PP} = 52\text{MHz}$	8.5	9.5	-	ns
$t_{W(CKH)}$	Clock high time		8.5	9.5	-	
<b>CMD, D inputs (referenced to CK) in eMMC legacy/SDR/DDR and SD HS/SDR/DDR mode</b>						
$t_{ISU}$	Input setup time HS	-	2.5	-	-	ns
$t_{IH}$	Input hold time HS	-	0.5	-	-	
$t_{IDW}^{(3)}$	Input valid window (variable window)	-	1.5	-	-	
<b>CMD, D outputs (referenced to CK) in eMMC legacy/SDR/DDR and SD HS/SDR/DDR mode</b>						
$t_{OV}$	Output valid time HS	-	-	5.5	6	ns
$t_{OH}$	Output hold time HS	-	4.5	-	-	

**Table 114. Dynamics characteristics: SD / MMC characteristics,  $V_{DD}=2.7$  to  $3.6$  V<sup>(1)(2)</sup>**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>CMD, D inputs (referenced to CK) in SD default mode</b>						
$t_{ISUD}$	Input setup time SD	-	1.5		-	ns
$t_{IHD}$	Input hold time SD	-	0.5		-	
<b>CMD, D outputs (referenced to CK) in SD default mode</b>						
$t_{OVD}$	Output valid default time SD	-	-	1	1	ns
$t_{OHD}$	Output hold default time SD	-	0	-	-	

1. Guaranteed by characterization results.
2. Above 100 MHz,  $C_L = 20$  pF.
3. The minimum window of time where the data needs to be stable for proper sampling in tuning mode.

**Table 115. Dynamics characteristics: eMMC characteristics  $V_{DD}=1.71V$  to  $1.9V$ <sup>(1)(2)</sup>**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{PP}$	Clock frequency in data transfer mode	-	0	-	85	MHz
-	SDIO_CK/fPCLK2 frequency ratio	-	-	-	8/3	-
$t_{W(CKL)}$	Clock low time	$f_{PP} = 52$ MHz	8.5	9.5	-	ns
$t_{W(CKH)}$	Clock high time		8.5	9.5	-	
<b>CMD, D inputs (referenced to CK) in eMMC mode</b>						
$t_{ISU}$	Input setup time HS	-	1.5	-	-	ns
$t_{IH}$	Input hold time HS	-	1.5	-	-	
$t_{IDW}^{(3)}$	Input valid window (variable window)	-	3.5	-	-	
<b>CMD, D outputs (referenced to CK) in eMMC mode</b>						
$t_{OVD}$	Output valid time HS	-	-	6	6.5	ns
$t_{OHD}$	Output hold time HS	-	5.5	-	-	

1. Guaranteed by characterization results.
2.  $C_L = 20$  pF.
3. The minimum window of time where the data needs to be stable for proper sampling in tuning mode.

Figure 64. SDIO high-speed mode

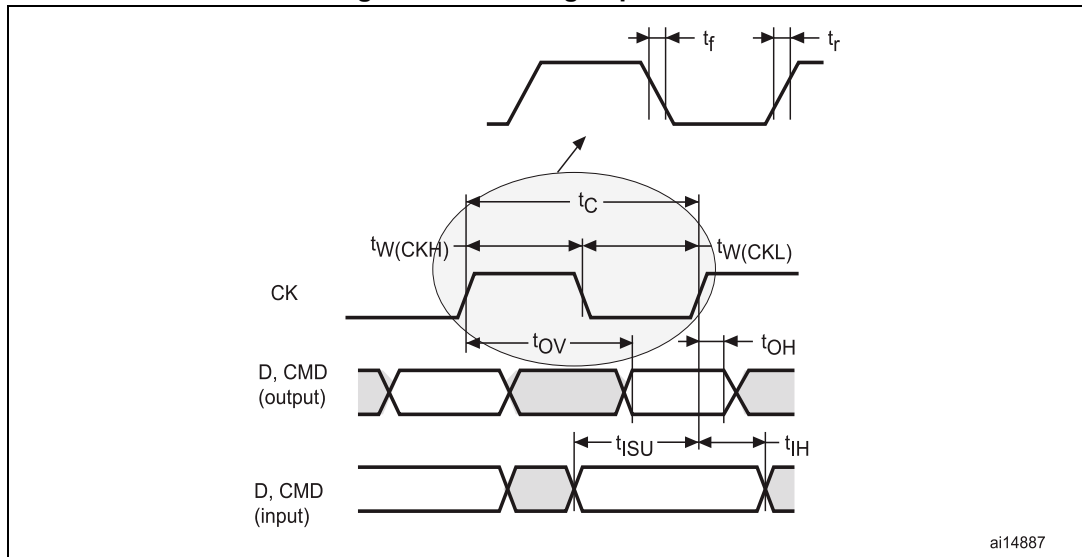


Figure 65. SD default mode

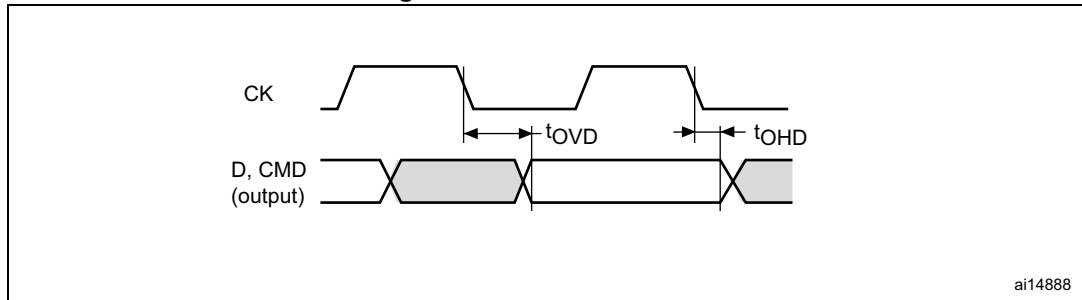
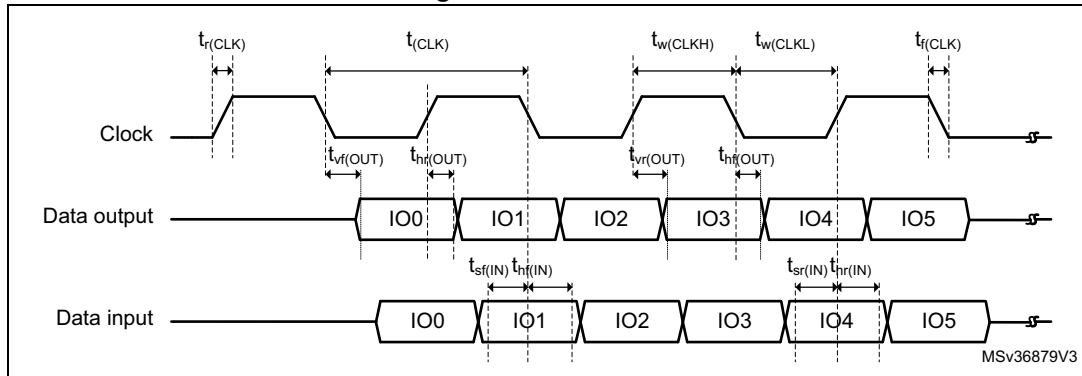


Figure 66. DDR mode



### USB OTG\_FS characteristics

Unless otherwise specified, the parameters given in [Table 117](#) for ULPI are derived from tests performed under the ambient temperature,  $f_{PCLKx}$  frequency and  $V_{DD}$  supply voltage summarized in [Table 12: General operating conditions](#), with the following configuration:

- Output speed is set to  $OSPEEDRy[1:0] = 11$
- Capacitive load  $C_L = 20$  pF
- Measurement points are done at CMOS levels:  $0.5V_{DD}$
- IO Compensation cell activated.
- VOS level set to VOS0

Refer to [Section 6.3.17: I/O port characteristics](#) for more details on the input/output characteristics.

**Table 116. USB OTG\_FS electrical characteristics**

Symbol	Parameter	Condition	Min	Typ	Max	Unit
$V_{DD33USB}$	USB transceiver operating voltage	-	3.0 <sup>(1)</sup>	-	3.6	V
$R_{PUI}$	Embedded USB_DP pull-up value during idle	-	900	1250	1600	Ω
$R_{PUR}$	Embedded USB_DP pull-up value during reception	-	1400	2300	3200	
$Z_{DRV}$	Output driver impedance <sup>(2)</sup>	Driver high and low	28	36	44	

1. The USB functionality is ensured down to 2.7 V. However, not all USB electrical characteristics are degraded in the 2.7 to 3.0 V voltage range.
2. No external termination series resistors are required on USB\_DP (D+) and USB\_DM (D-); the matching impedance is already included in the embedded driver.

### USB OTG\_HS characteristics

Unless otherwise specified, the parameters given in [Table 117](#) for ULPI are derived from tests performed under the ambient temperature,  $f_{PCLKx}$  frequency and  $V_{DD}$  supply voltage summarized in [Table 12: General operating conditions](#), with the following configuration:

- Output speed is set to  $OSPEEDRy[1:0] = 11$
- Capacitive load  $C_L = 20$  pF
- Measurement points are done at CMOS levels:  $0.5V_{DD}$
- IO Compensation cell activated.
- VOS level set to VOS0

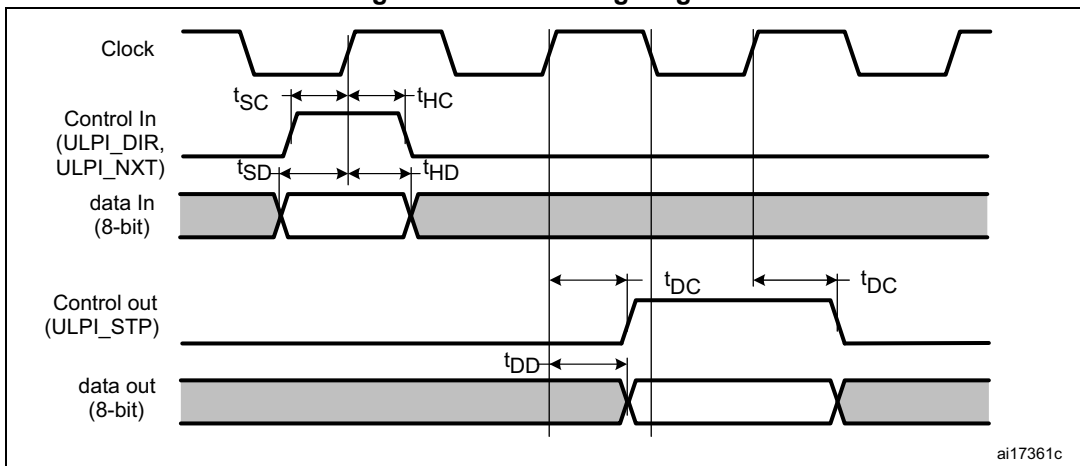
Refer to [Section 6.3.17: I/O port characteristics](#) for more details on the input/output characteristics.

Table 117. Dynamics characteristics: USB ULPI<sup>(1)</sup>

Symbol	Parameter	Condition	Min	Typ	Max	Unit
$t_{SC}$	Control in (ULPI_DIR , ULPI_NXT) setup time	-	5.5	-	-	ns
$t_{HC}$	Control in (ULPI_DIR, ULPI_NXT) hold time	-	0	-	-	
$t_{SD}$	Data in setup time	-	2.5	-	-	
$t_{HD}$	Data in hold time	-	0	-	-	
$t_{DC}/t_{DD}$	Control/Data output delay	$2.7\text{ V} < V_{DD} < 3.6\text{ V}, C_L = 20\text{ pF}$	-	6.0	8.0	
		$1.71\text{ V} < V_{DD} < 3.6\text{ V}, C_L = 15\text{ pF}$	-	6.0	12	

1. Guaranteed by characterization results.

Figure 67. ULPI timing diagram



**Ethernet interface characteristics**

Unless otherwise specified, the parameters given in [Table 118](#), [Table 119](#) and [Table 120](#) for SMI, RMII and MII are derived from tests performed under the ambient temperature,  $f_{\text{rcc\_c\_ck}}$  frequency and  $V_{\text{DD}}$  supply voltage conditions summarized in [Table 12: General operating conditions](#), with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 10
- Capacitive load  $C_L=20$  pF
- Measurement points are done at CMOS levels:  $0.5V_{\text{DD}}$
- IO Compensation cell activated.
- HSLV activated when  $V_{\text{DD}} \leq 2.7$  V
- VOS level set to VOS1

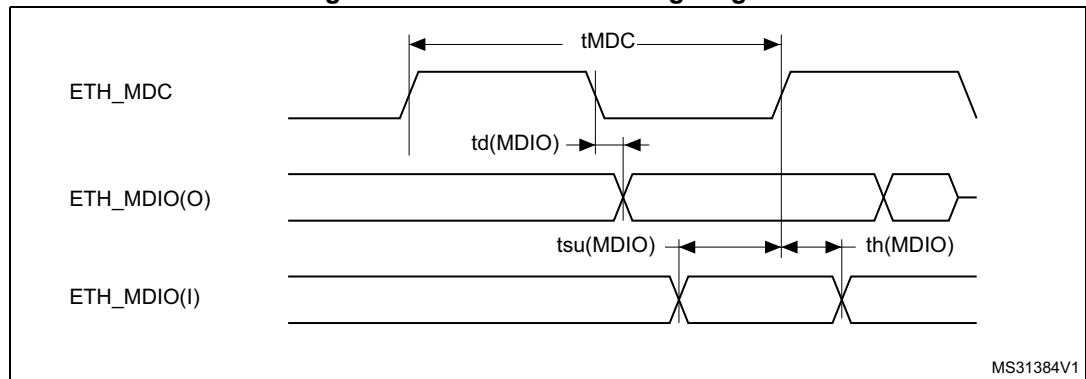
Refer to [Section 6.3.17: I/O port characteristics](#) for more details on the input/output characteristics:

**Table 118. Dynamics characteristics: Ethernet MAC signals for SMI <sup>(1)</sup>**

Symbol	Parameter	Min	Typ	Max	Unit
$t_{\text{MDC}}$	MDC cycle time( 2.5 MHz)	400	400	403	ns
$T_{\text{d(MDIO)}}$	Write data valid time	0.5	1.5	4	
$t_{\text{su(MDIO)}}$	Read data setup time	12.5	-	-	
$t_{\text{h(MDIO)}}$	Read data hold time	0	-	-	

1. Guaranteed by characterization results.

**Figure 68. Ethernet SMI timing diagram**



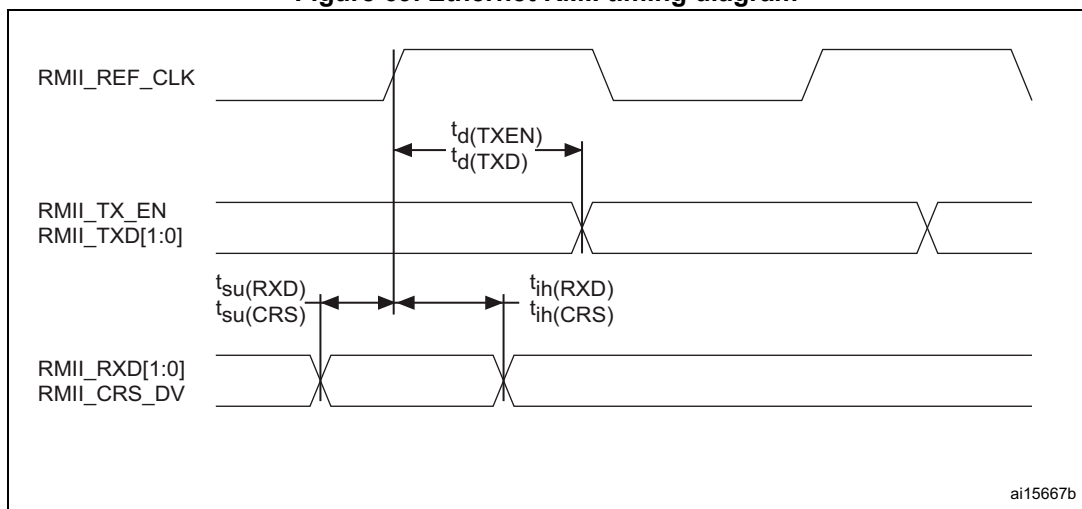
MS31384V1

**Table 119. Dynamics characteristics: Ethernet MAC signals for RMII <sup>(1)</sup>**

Symbol	Parameter	Min	Typ	Max	Unit
$t_{su}(RXD)$	Receive data setup time	2	-	-	ns
$t_{ih}(RXD)$	Receive data hold time	2	-	-	
$t_{su}(CRS)$	Carrier sense setup time	1.5	-	-	
$t_{ih}(CRS)$	Carrier sense hold time	1.5	-	-	
$t_d(TXEN)$	Transmit enable valid delay time	8	0	10.5	
$t_d(TXD)$	Transmit data valid delay time	7	8	9.5	

1. Guaranteed by characterization results.

**Figure 69. Ethernet RMII timing diagram**



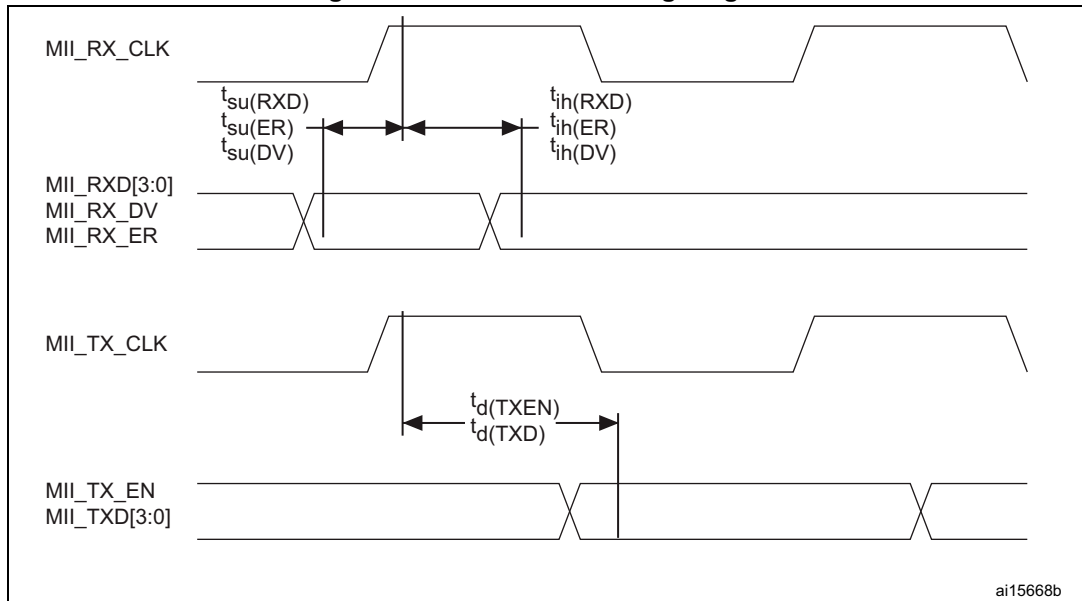
ai15667b

**Table 120. Dynamics characteristics: Ethernet MAC signals for MII <sup>(1)</sup>**

Symbol	Parameter	Min	Typ	Max	Unit
$t_{su}(RXD)$	Receive data setup time	2.0	-	-	ns
$t_{ih}(RXD)$	Receive data hold time	2.0	-	-	
$t_{su}(DV)$	Data valid setup time	1.5	-	-	
$t_{ih}(DV)$	Data valid hold time	1.5	-	-	
$t_{su}(ER)$	Error setup time	1.5	-	-	
$t_{ih}(ER)$	Error hold time	0.5	-	-	
$t_d(TXEN)$	Transmit enable valid delay time	9.0	11	19	
$t_d(TXD)$	Transmit data valid delay time	8.5	10	19	

1. Guaranteed by characterization results.

Figure 70. Ethernet MII timing diagram



JTAG/SWD interface characteristics

Unless otherwise specified, the parameters given in [Table 121](#) and [Table 122](#) for JTAG/SWD are derived from tests performed under the ambient temperature,  $f_{rcc\_c\_ck}$  frequency and  $V_{DD}$  supply voltage summarized in [Table 12: General operating conditions](#), with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 11
- Capacitive load  $C_L=30$  pF
- Measurement points are done at CMOS levels:  $0.5V_{DD}$
- VOS level set to VOS0

Refer to [Section 6.3.17: I/O port characteristics](#) for more details on the input/output characteristics:

Table 121. Dynamics JTAG characteristics

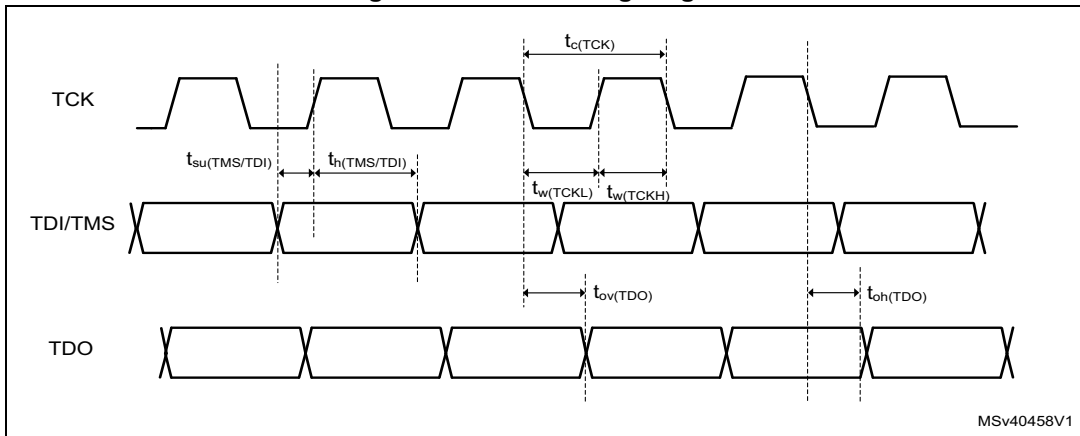
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$F_{pp}$	T <sub>CK</sub> clock frequency	2.7V < V <sub>DD</sub> < 3.6 V	-	-	37	MHz
$1/t_c(TCK)$		1.62 < V <sub>DD</sub> < 3.6 V	-	-	27.5	
$t_{su}(TMS)$	TMS input setup time	-	2.5	-	-	-
$t_{h}(TMS)$	TMS input hold time	-	1	-	-	-
$t_{su}(TDI)$	TDI input setup time	-	1.5	-	-	-
$t_{h}(TDI)$	TDI input hold time	-	1	-	-	-
$t_{ov}(TDO)$	TDO output valid time	2.7V < V <sub>DD</sub> < 3.6 V	-	8	13.5	-
		1.62 < V <sub>DD</sub> < 3.6 V	-	8	18	-
$t_{oh}(TDO)$	TDO output hold time	-	7	-	-	-



Table 122. Dynamics SWD characteristics

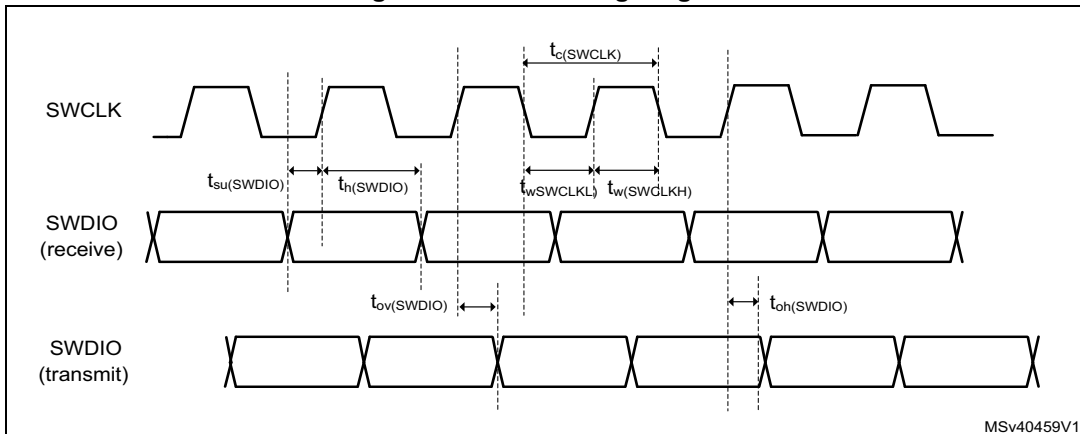
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$F_{pp}$	SWCLK clock frequency	$2.7V < V_{DD} < 3.6 V$	-	-	71	MHz
$1/t_c(SWCLK)$		$1.62 < V_{DD} < 3.6 V$	-	-	52.5	
$t_{i_{su}}(SWDIO)$	SWDIO input setup time	-	2.5	-	-	-
$t_{i_h}(SWDIO)$	SWDIO input hold time	-	1	-	-	-
$t_{ov}(SWDIO)$	SWDIO output valid time	$2.7V < V_{DD} < 3.6 V$	-	8.5	14	-
		$1.62 < V_{DD} < 3.6 V$	-	8.5	19	-
$t_{oh}(SWDIO)$	SWDIO output hold time	-	8	-	-	-

Figure 71. JTAG timing diagram



MSv40458V1

Figure 72. SWD timing diagram



MSv40459V1

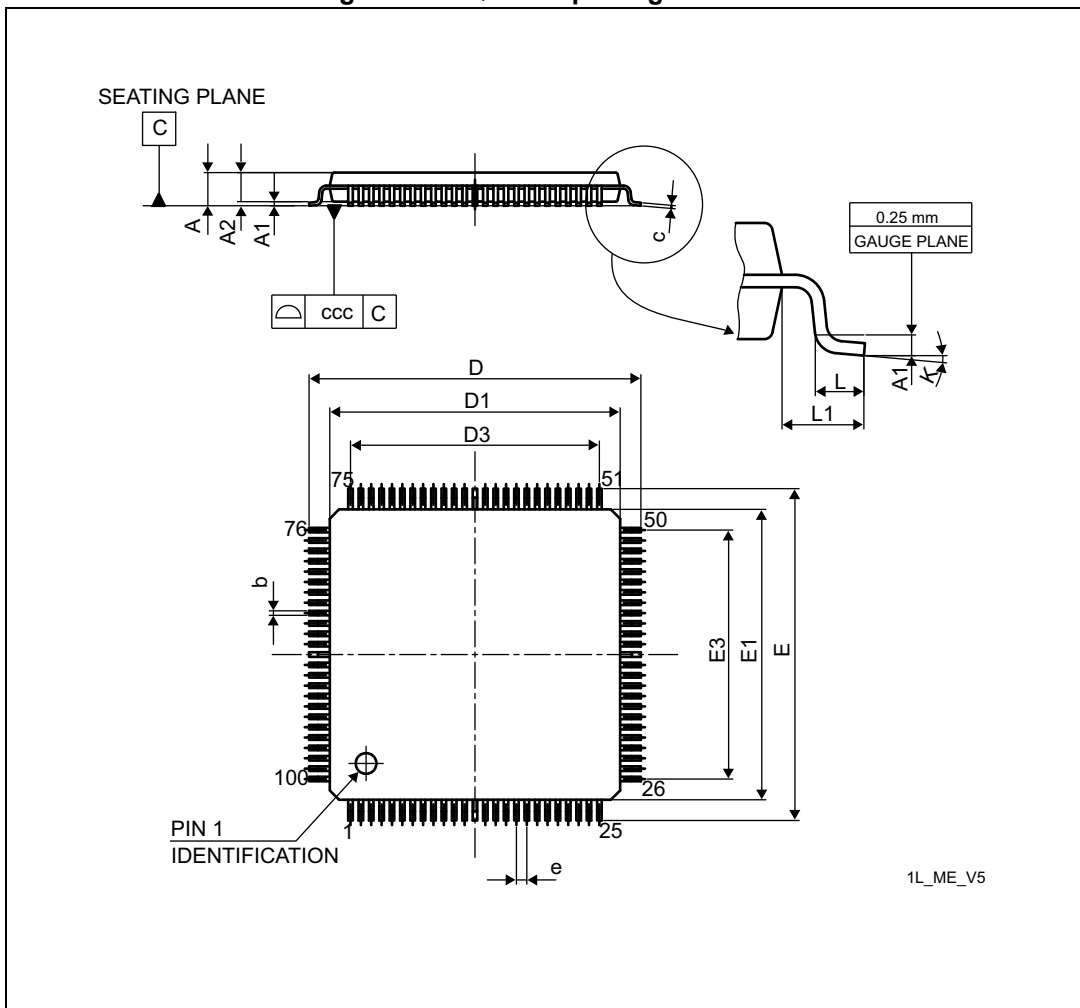
# 7 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status *are available at [www.st.com](http://www.st.com)*. ECOPACK is an ST trademark.

## 7.1 LQFP100 package information

LQFP100 is a 100-pin, 14 x 14 mm low-profile quad flat package.

Figure 73. LQFP100 package outline



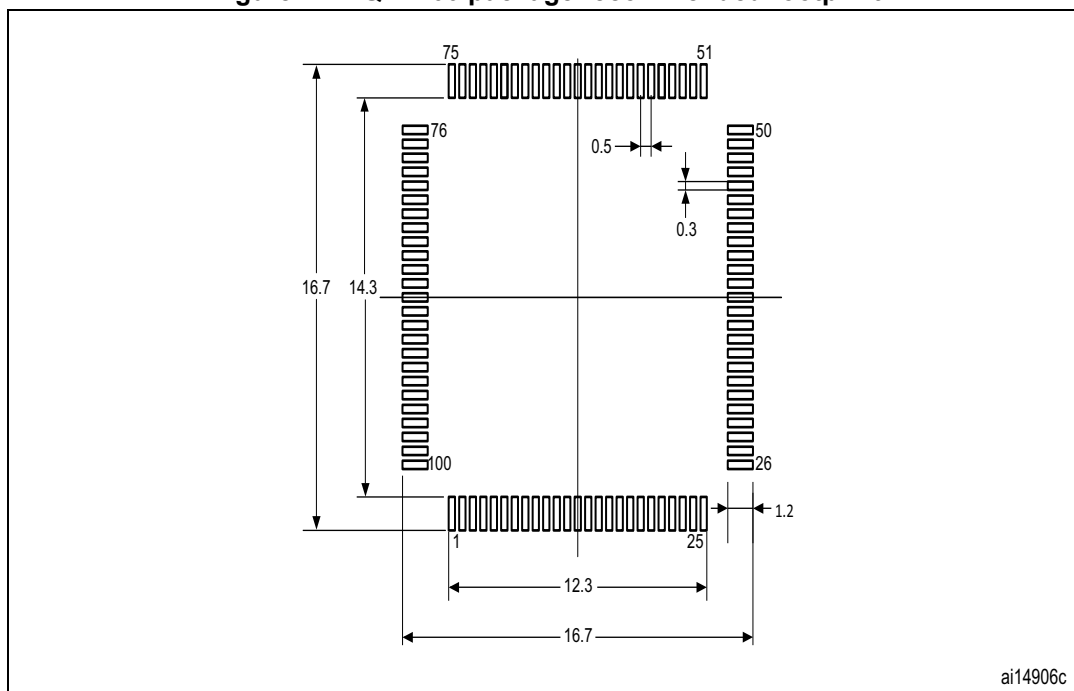
1. Drawing is not to scale.

Table 123. LQPF100 package mechanical data

Symbol	millimeters			inches <sup>(1)</sup>		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	15.800	16.000	16.200	0.6220	0.6299	0.6378
D1	13.800	14.000	14.200	0.5433	0.5512	0.5591
D3	-	12.000	-	-	0.4724	-
E	15.800	16.000	16.200	0.6220	0.6299	0.6378
E1	13.800	14.000	14.200	0.5433	0.5512	0.5591
E3	-	12.000	-	-	0.4724	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0.0°	3.5°	7.0°	0.0°	3.5°	7.0°
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 74. LQFP100 package recommended footprint



1. Dimensions are expressed in millimeters.

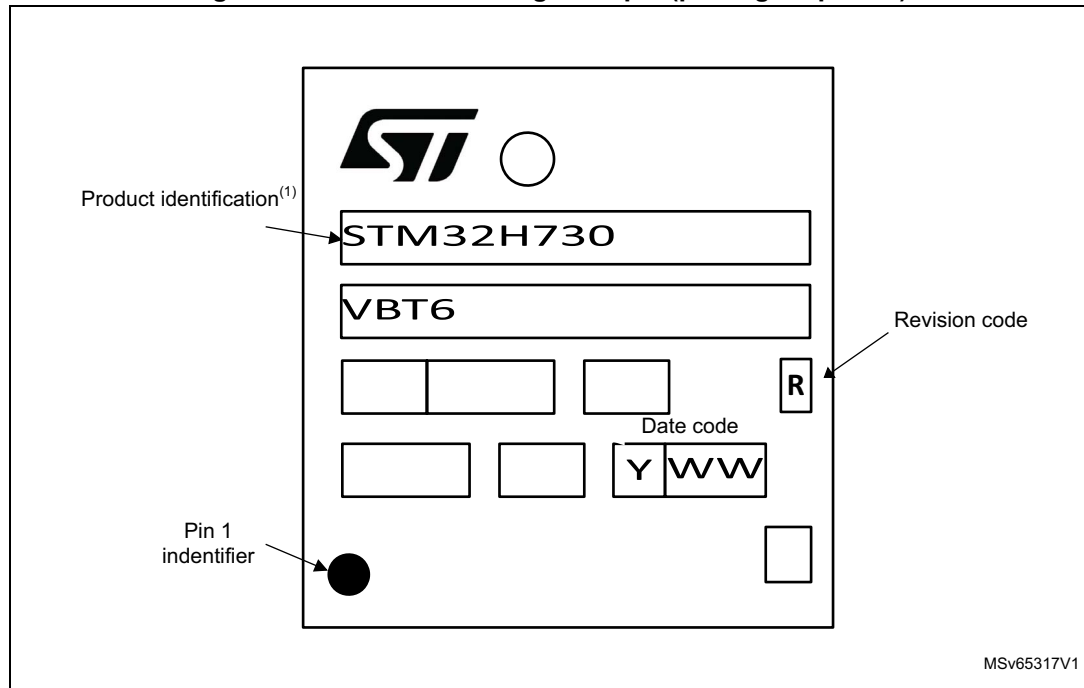
**Device marking for LQFP100**

The following figure gives an example of topside marking versus pin 1 position identifier location.

The printed markings may differ depending on the supply chain.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

**Figure 75. LQFP100 marking example (package top view)**

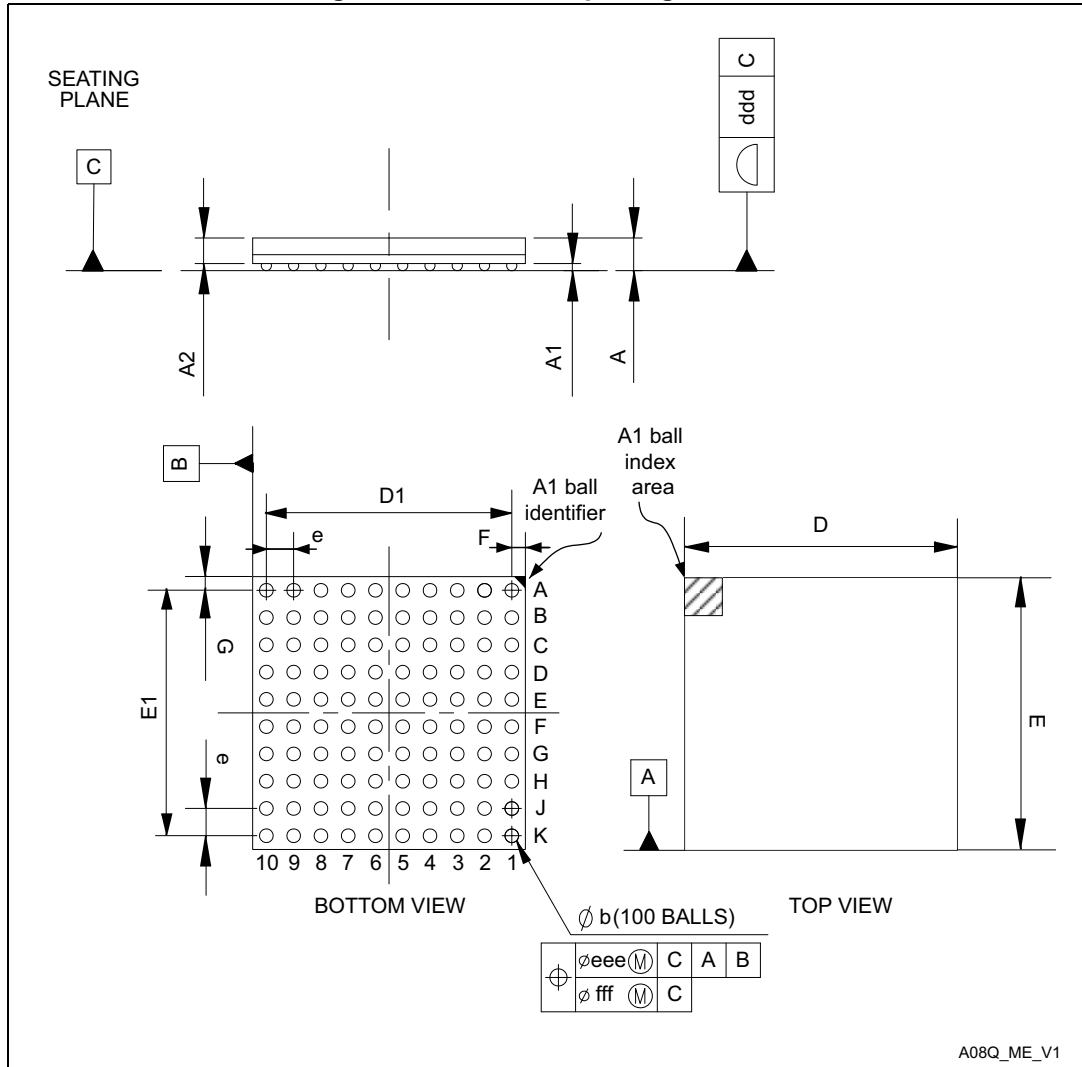


1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST's Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

## 7.2 TFBGA100 package information

TFBGA100 is a 100-ball, 8 x 8 mm, 0.8 mm pitch, thin fine-pitch ball grid array package.

Figure 76. TFBGA100 package outline



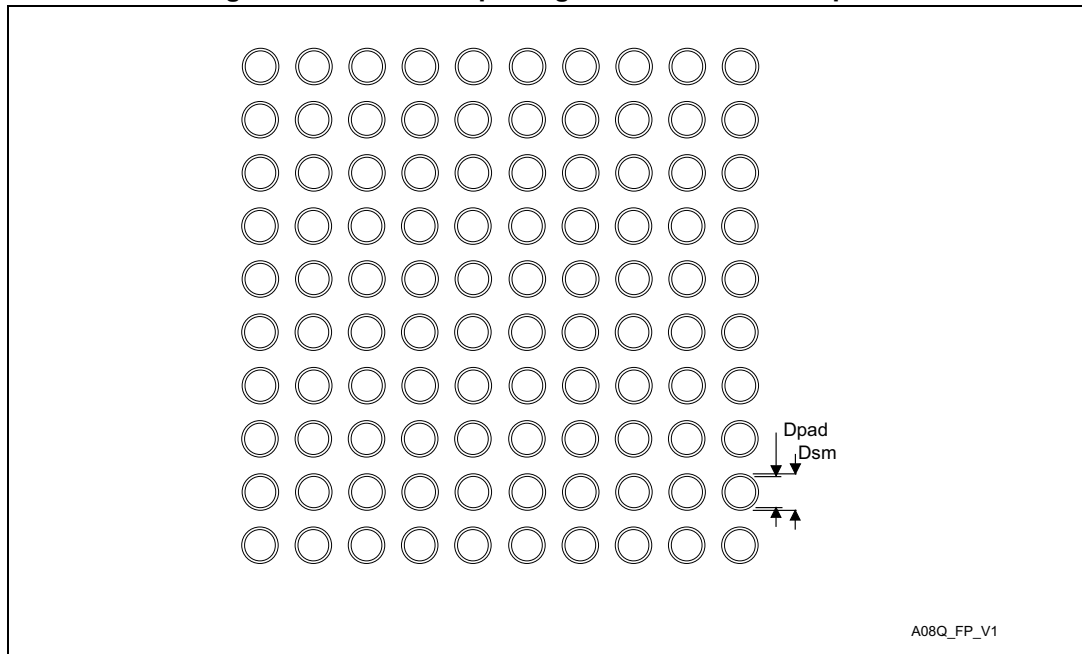
1. Drawing is not to scale.

**Table 124. TFBGA100 package mechanical data**

Symbol	millimeters			inches <sup>(1)</sup>		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.100	-	-	0.0433
A1	0.150	-	-	0.0059	-	-
A2	-	0.760	-	-	0.0299	-
b	0.350	0.400	0.450	0.0138	0.0157	0.0177
D	7.850	8.000	8.150	0.3091	0.3150	0.3209
D1	-	7.200	-	-	0.2835	-
E	7.850	8.000	8.150	0.3091	0.3150	0.3209
E1	-	7.200	-	-	0.2835	-
e	-	0.800	-	-	0.0315	-
F	-	0.400	-	-	0.0157	-
G	-	0.400	-	-	0.0157	-
ddd	-	-	0.100	-	-	0.0039
eee	-	-	0.150	-	-	0.0059
fff	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

**Figure 77. TFBGA100 package recommended footprint**



1. Dimensions are expressed in millimeters.

**Table 125. TFBGA100 recommended PCB design rules (0.8 mm pitch BGA)**

Dimension	Recommended values
Pitch	0.8
Dpad	0.400 mm
Dsm	0.470 mm typ (depends on the soldermask registration tolerance)
Stencil opening	0.400 mm
Stencil thickness	Between 0.100 mm and 0.125 mm
Pad trace width	0.120 mm

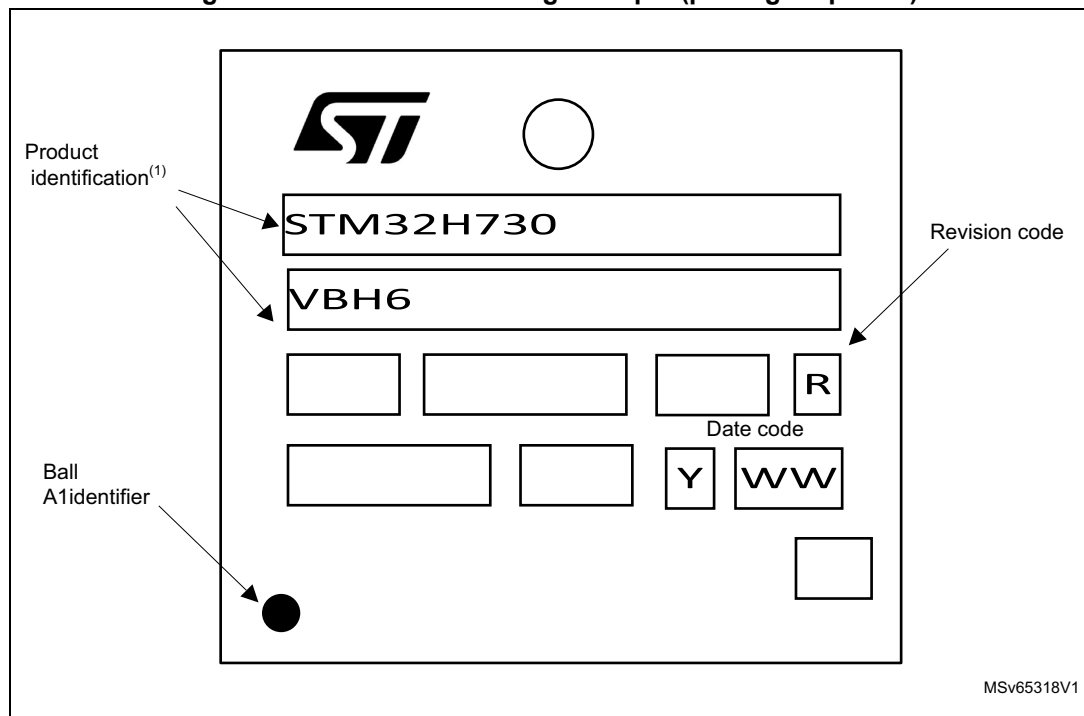
**Device marking for TFBGA100**

The following figure gives an example of topside marking versus pin 1 position identifier location.

The printed markings may differ depending on the supply chain.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

**Figure 78. TFBGA100 marking example (package top view)**



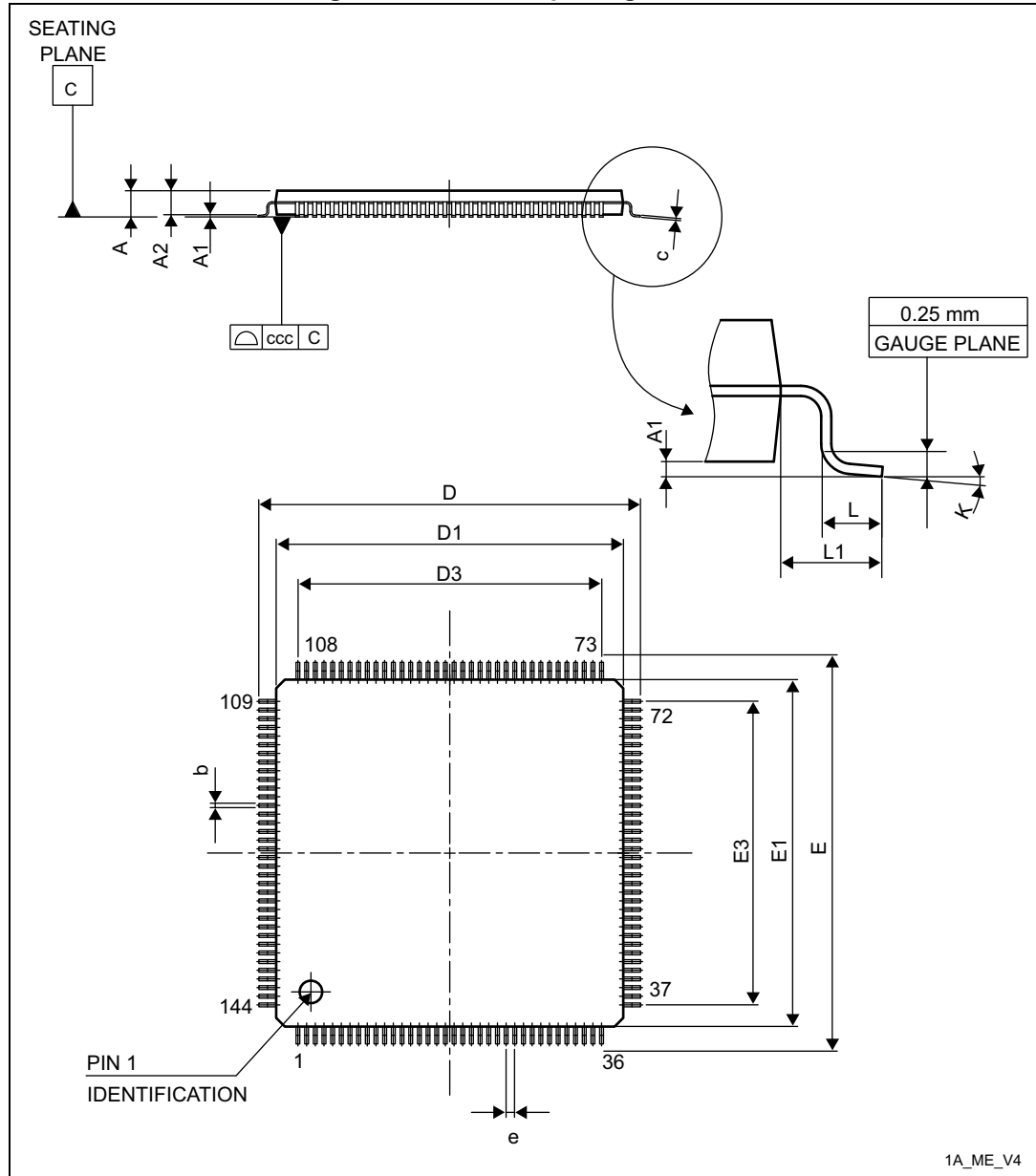
1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST’s Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.



### 7.3 LQFP144 package information

LQFP144 is a 144-pin, 20 x 20 mm low-profile quad flat package.

Figure 79. LQFP144 package outline



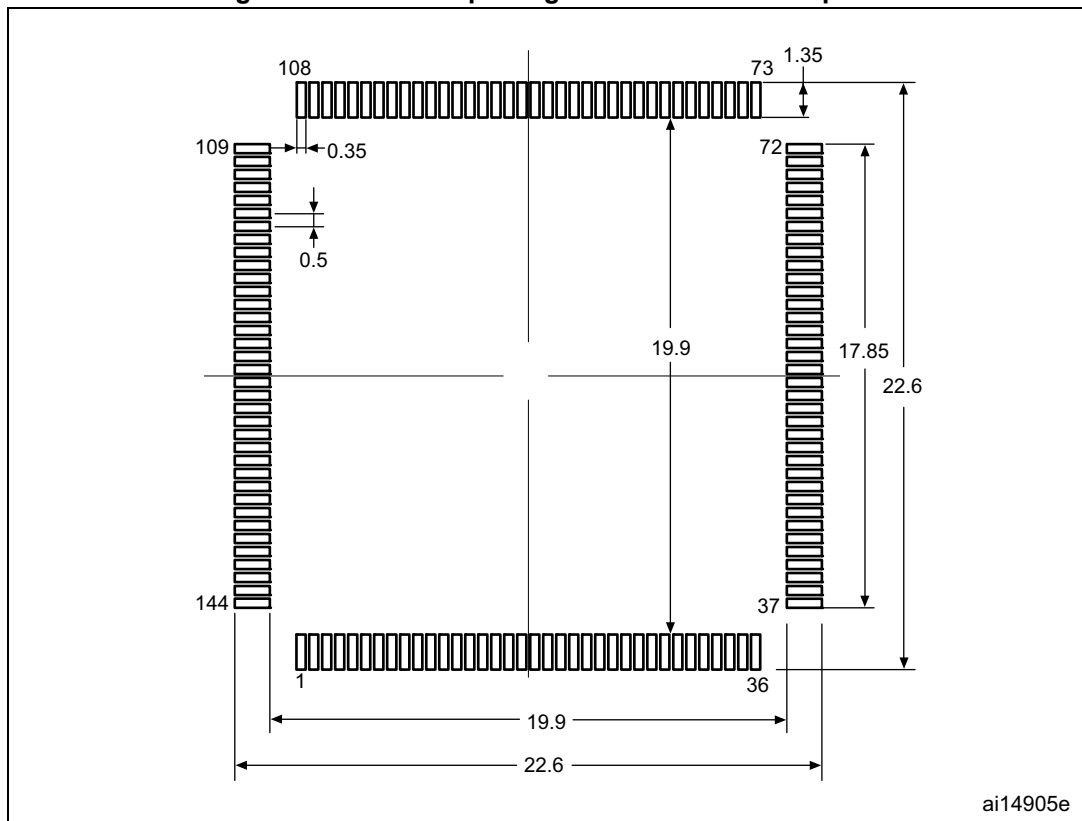
1. Drawing is not to scale.

Table 126. LQFP144 package mechanical data

Symbol	millimeters			inches <sup>(1)</sup>		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	21.800	22.000	22.200	0.8583	0.8661	0.8740
D1	19.800	20.000	20.200	0.7795	0.7874	0.7953
D3	-	17.500	-	-	0.6890	-
E	21.800	22.000	22.200	0.8583	0.8661	0.8740
E1	19.800	20.000	20.200	0.7795	0.7874	0.7953
E3	-	17.500	-	-	0.6890	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 80. LQFP144 package recommended footprint



1. Dimensions are expressed in millimeters.

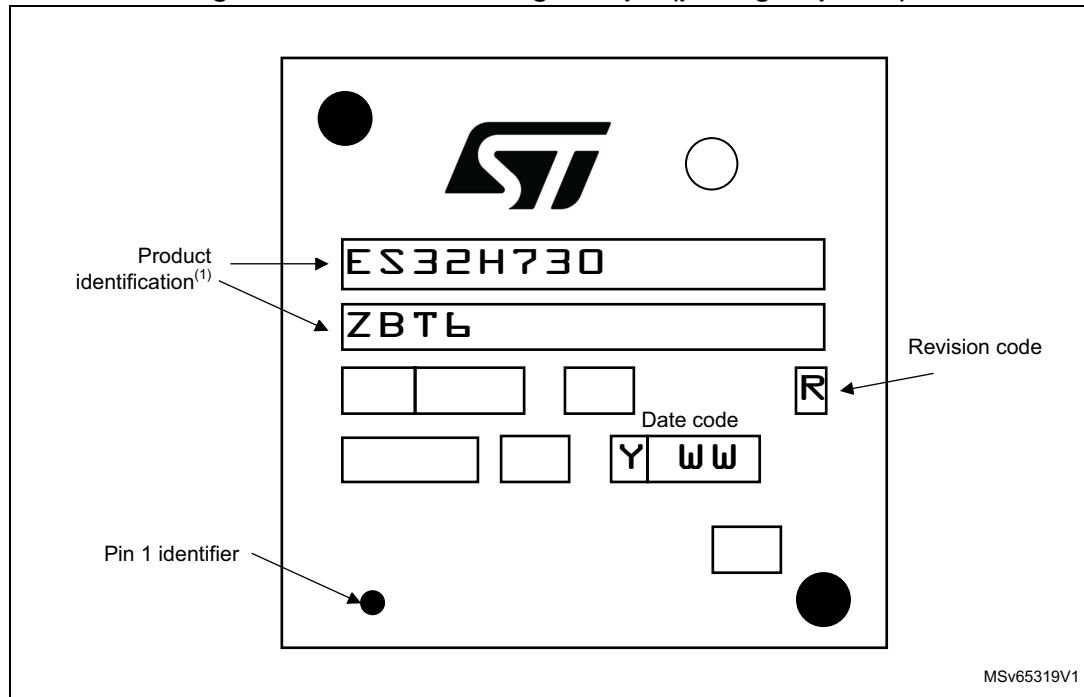
### Device marking for LQFP144

The following figure gives an example of topside marking versus pin 1 position identifier location.

The printed markings may differ depending on the supply chain.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

**Figure 81. LQFP144 marking example (package top view)**

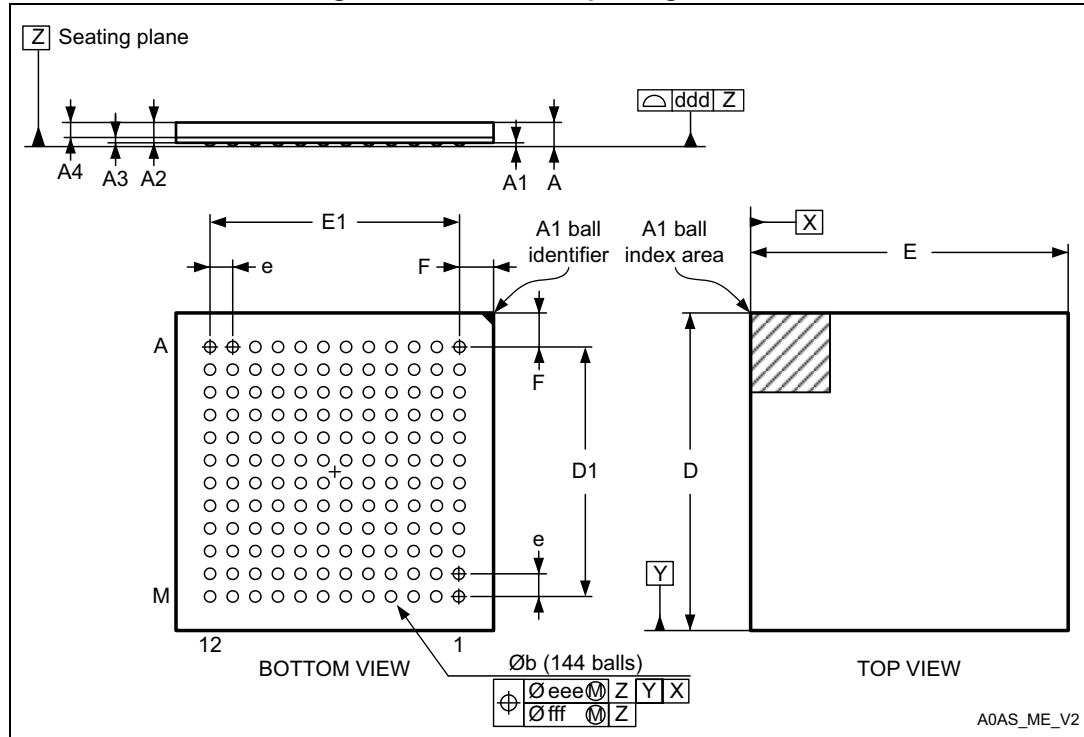


1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST’s Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

### 7.4 UFBGA144 package information

UFBGA144 is a 144-ball, 7 x 7 mm, 0.50 mm pitch, ultra fine pitch ball grid array package.

Figure 82. UFBGA144 package outline



1. Drawing is not to scale.

Table 127. UFBGA144 package mechanical data

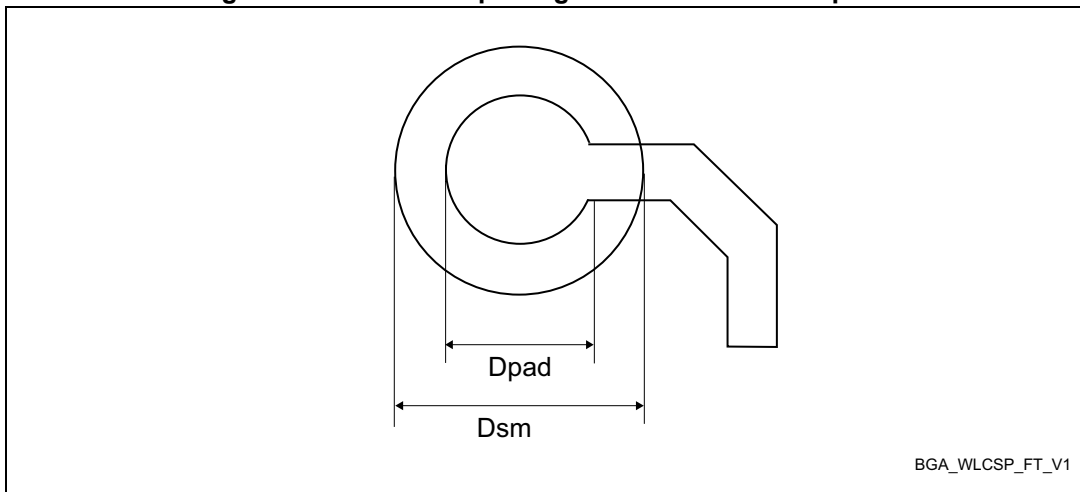
Symbol	millimeters			inches <sup>(1)</sup>		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	0.460	0.530	0.600	0.0181	0.0209	0.0236
A1	0.050	0.080	0.110	0.0020	0.0031	0.0043
A2	0.400	0.450	0.500	0.0157	0.0177	0.0197
A3	-	0.130	-	-	0.0051	-
A4	0.270	0.320	0.370	0.0106	0.0126	0.0146
b	0.230	0.280	0.320	0.0091	0.0110	0.0126
D	6.950	7.000	7.050	0.2736	0.2756	0.2776
D1	5.450	5.500	5.550	0.2146	0.2165	0.2185
E	6.950	7.000	7.050	0.2736	0.2756	0.2776
E1	5.450	5.500	5.550	0.2146	0.2165	0.2185
e	-	0.500	-	-	0.0197	-
F	0.700	0.750	0.800	0.0276	0.0295	0.0315

**Table 127. UFBGA144 package mechanical data (continued)**

Symbol	millimeters			inches <sup>(1)</sup>		
	Min.	Typ.	Max.	Min.	Typ.	Max.
ddd	-	-	0.100	-	-	0.0039
eee	-	-	0.150	-	-	0.0059
fff	-	-	0.050	-	-	0.0020

1. Values in inches are converted from mm and rounded to 4 decimal digits.

**Figure 83. UFBGA144 package recommended footprint**



**Table 128. UFBGA144 recommended PCB design rules (0.50 mm pitch BGA)**

Dimension	Recommended values
Pitch	0.50 mm
$D_{pad}$	0.280 mm
$D_{sm}$	0.370 mm typ. (depends on the soldermask registration tolerance)
Stencil opening	0.280 mm
Stencil thickness	Between 0.100 mm and 0.125 mm
Pad trace width	0.120 mm

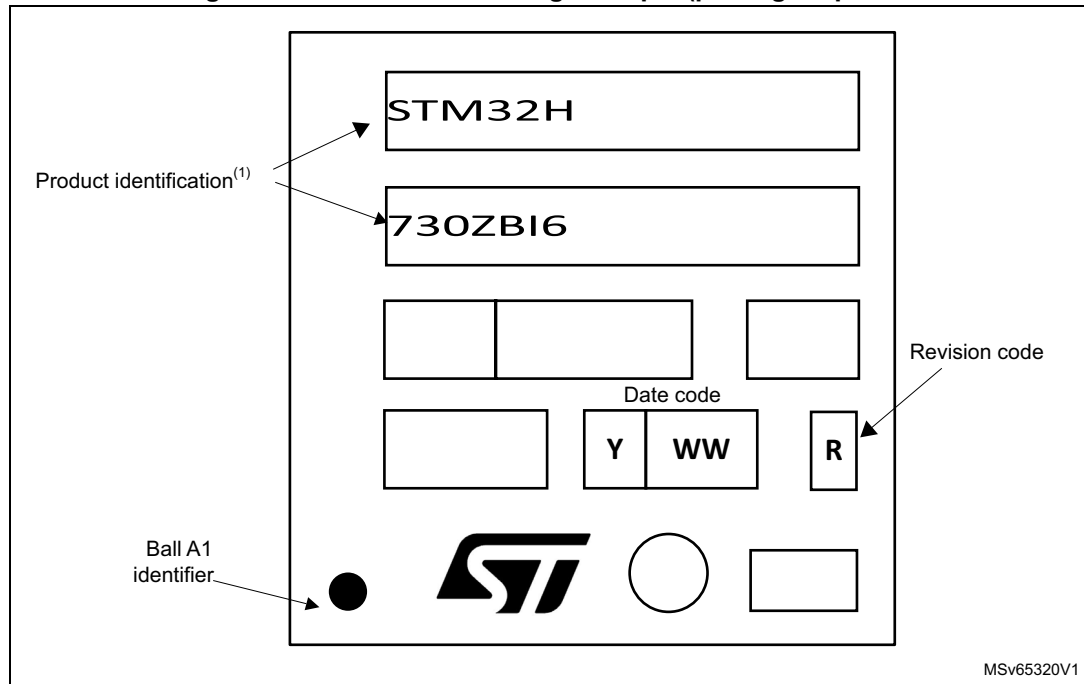
**Device marking for UFBGA144**

The following figure gives an example of topside marking versus pin 1 position identifier location.

The printed markings may differ depending on the supply chain.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

**Figure 84. UFBGA144 marking example (package top view)**

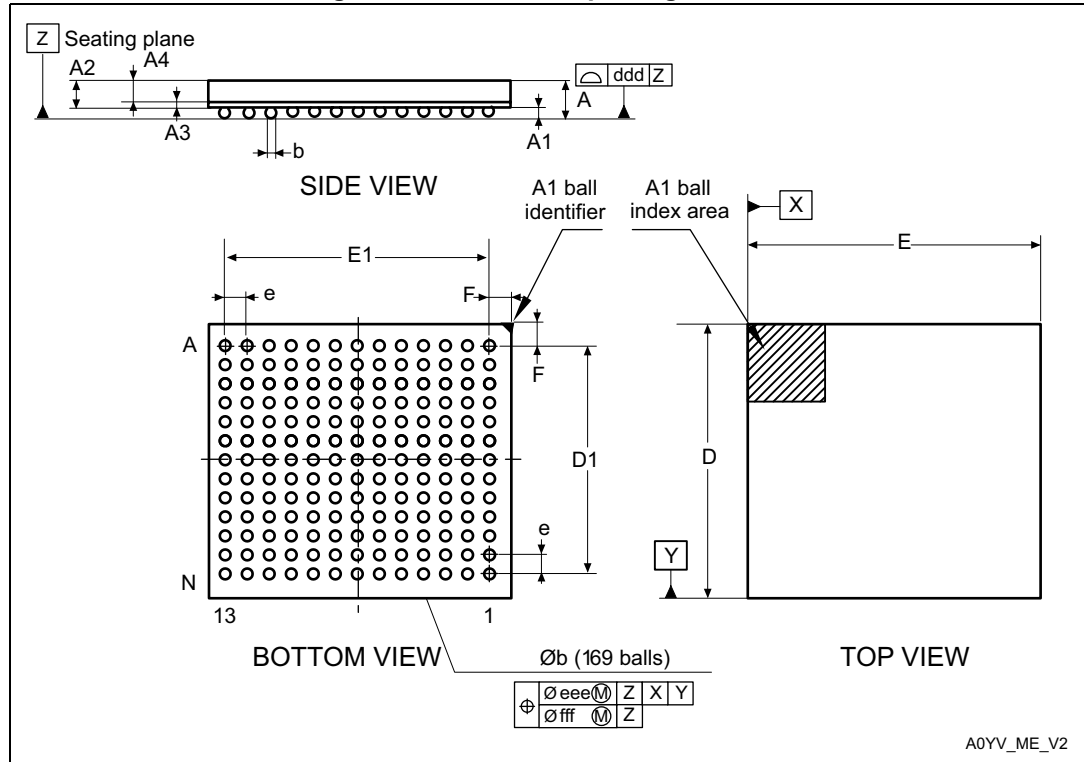


1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST’s Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

### 7.5 UFBGA169 package information

UFBGA169 is a 169-pin, 7 x 7 mm, 0.50 mm pitch, ultra fine pitch ball grid array package.

Figure 85. UFBGA169 package outline



1. Drawing is not in scale.

Table 129. UFBGA169 package mechanical data

Symbol	millimeters			inches <sup>(1)</sup>		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	0.460	0.530	0.600	0.0181	0.0209	0.0236
A1	0.050	0.080	0.110	0.0020	0.0031	0.0043
A2	0.400	0.450	0.500	0.0157	0.0177	0.0197
A3	-	0.130	-	-	0.0051	-
A4	0.270	0.320	0.370	0.0106	0.0126	0.0146
b	0.230	0.280	0.330	0.0091	0.0110	0.0130
D	6.950	7.000	7.050	0.2736	0.2756	0.2776
D1	5.950	6.000	6.050	0.2343	0.2362	0.2382
E	6.950	7.000	7.050	0.2736	0.2756	0.2776
E1	5.950	6.000	6.050	0.2343	0.2362	0.2382
e	-	0.500	-	-	0.0197	-
F	0.450	0.500	0.550	0.0177	0.0197	0.0217

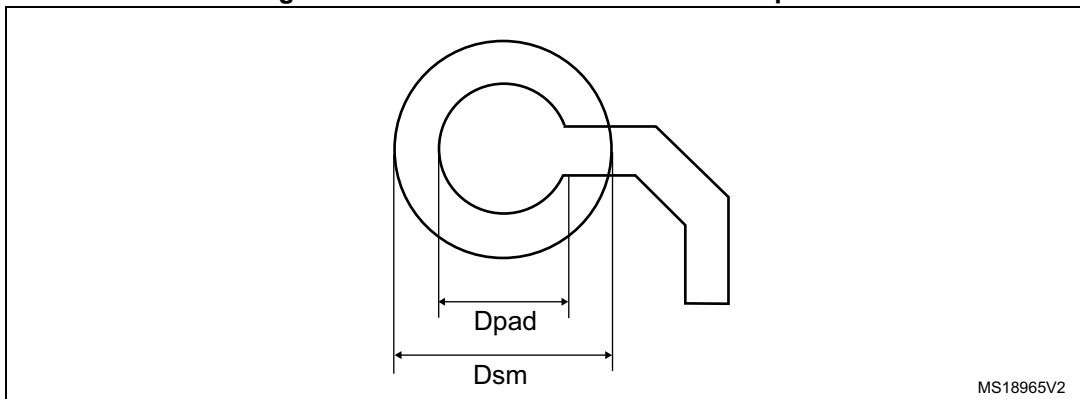


**Table 129. UFBGA169 package mechanical data (continued)**

Symbol	millimeters			inches <sup>(1)</sup>		
	Min.	Typ.	Max.	Min.	Typ.	Max.
ddd	-	-	0.100	-	-	0.0039
eee	-	-	0.150	-	-	0.0059
fff	-	-	0.050	-	-	0.0020

1. Values in inches are converted from mm and rounded to 4 decimal digits.

**Figure 86. UFBGA169 recommended footprint**



**Table 130. UFBGA169 recommended PCB design rules (0.5 mm pitch BGA)**

Dimension	Recommended values
Pitch	0.5
Dpad	0.27 mm
Dsm	0.35 mm typ. (depends on the soldermask registration tolerance)
Solder paste	0.27 mm aperture diameter.

*Note:* Non-solder mask defined (NSMD) pads are recommended.

*Note:* 4 to 6 mils solder paste screen printing process.

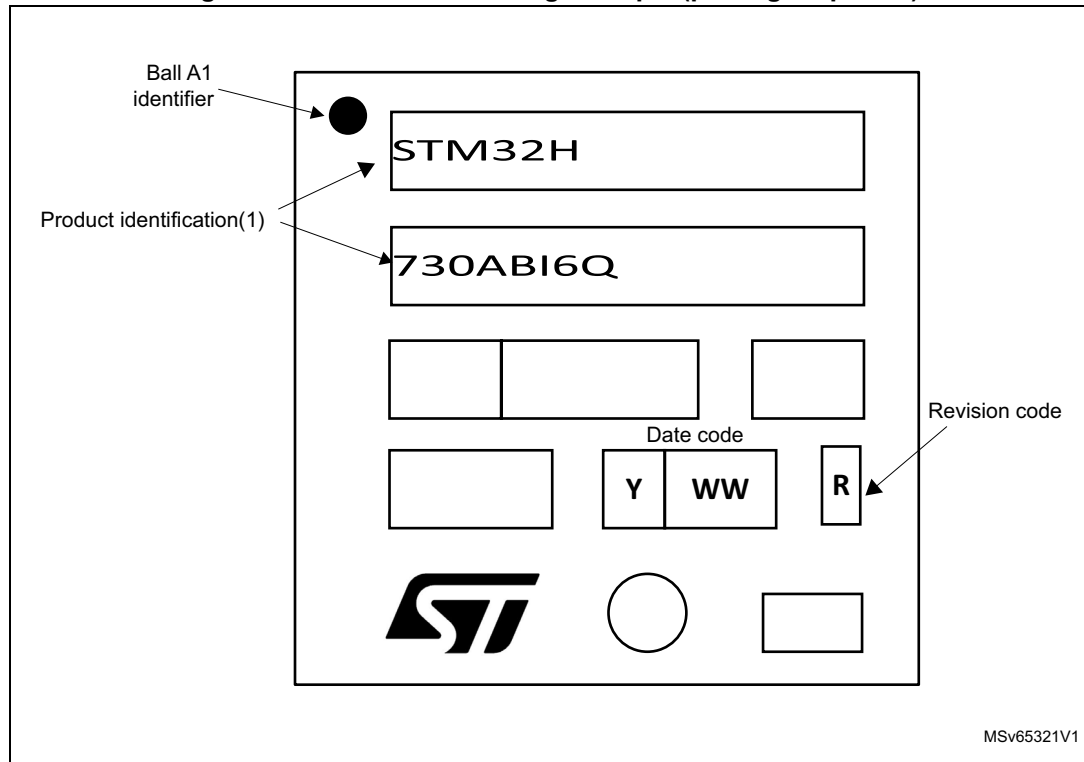
### Device marking for UFBGA169

The following figure gives an example of topside marking versus ball A1 position identifier location.

The printed markings may differ depending on the supply chain.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

**Figure 87. UFBGA169 marking example (package top view)**

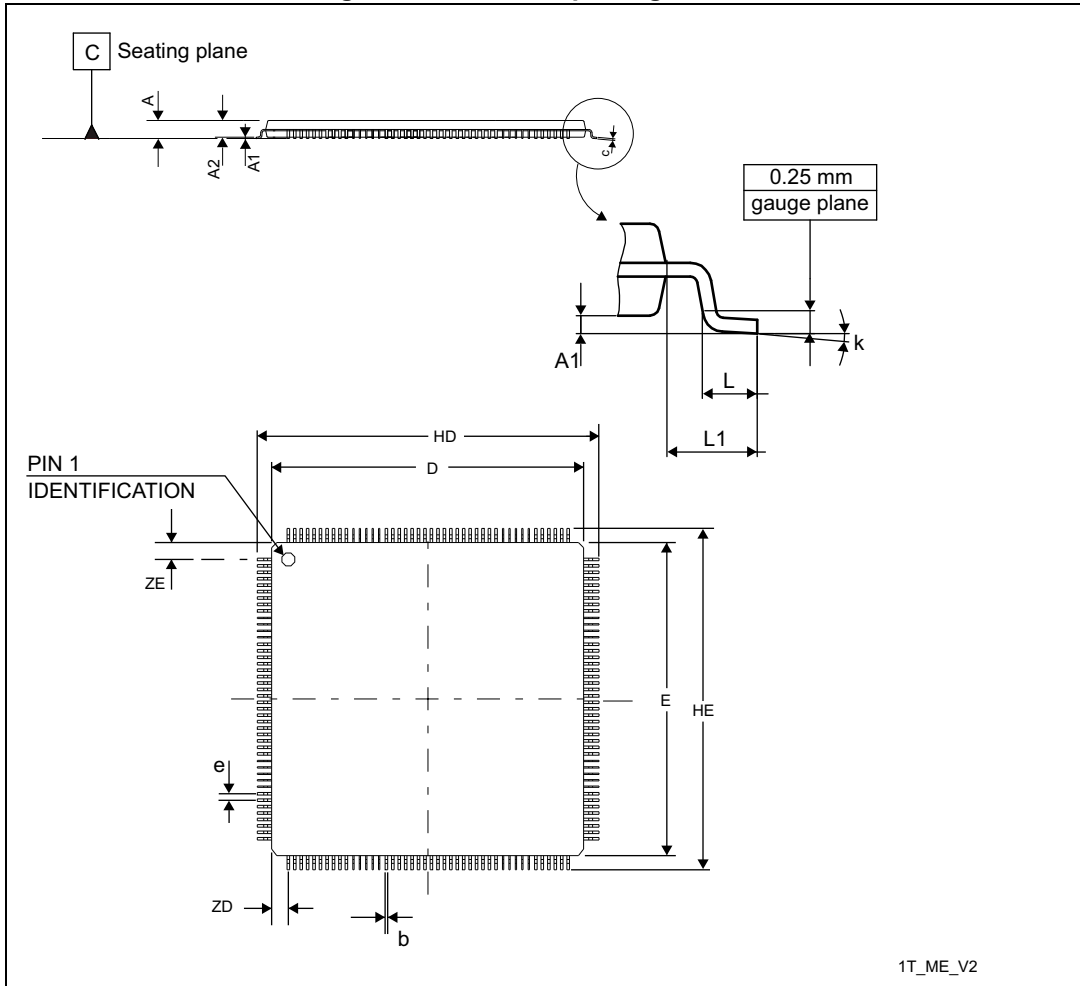


1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST’s Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

### 7.6 LQFP176 package information

LQFP176 is a 176-pin, 24 x 24 mm low profile quad flat package.

Figure 88. LQFP176 package outline



1T\_ME\_V2

1. Drawing is not to scale.

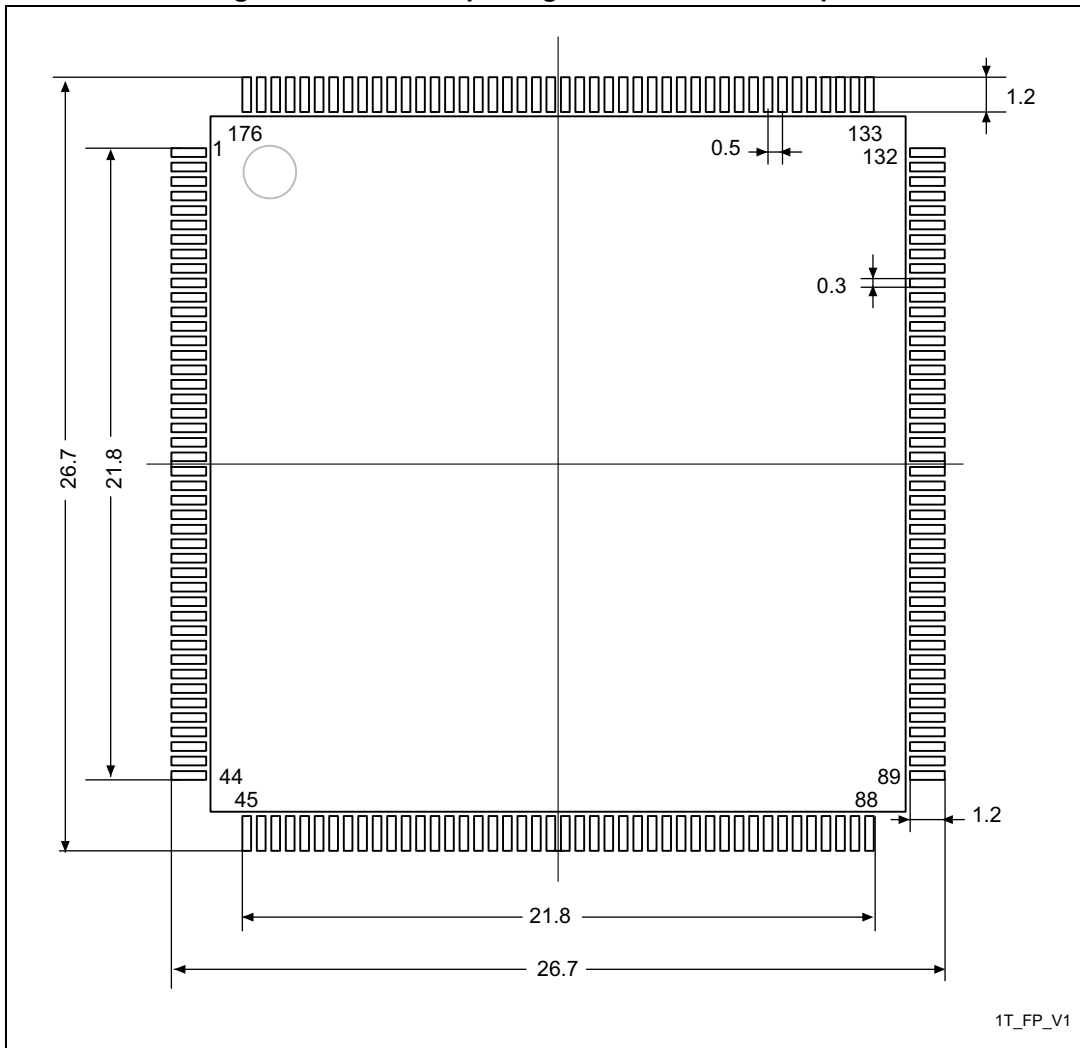
Table 131. LQFP176 package mechanical data

Ref.	Dimensions					
	Millimeters			Inches <sup>(1)</sup>		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	-	1.450	0.0531	-	0.0571
b	0.170	-	0.270	0.0067	-	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	23.900	-	24.100	0.9409	-	0.9488
HD	25.900	-	26.100	1.0197	-	1.0276
ZD	-	1.250	-	-	0.0492	-
E	23.900	-	24.100	0.9409	-	0.9488
HE	25.900	-	26.100	1.0197	-	1.0276
ZE	-	1.250	-	-	0.0492	-
e	-	0.500	-	-	0.0197	-
L <sup>(2)</sup>	0.450	-	0.750	0.0177	-	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	-	7°	0°	-	7°
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

2. L dimension is measured at gauge plane at 0.25 mm above the seating plane.

Figure 89. LQFP176 package recommended footprint



1. Dimensions are expressed in millimeters.

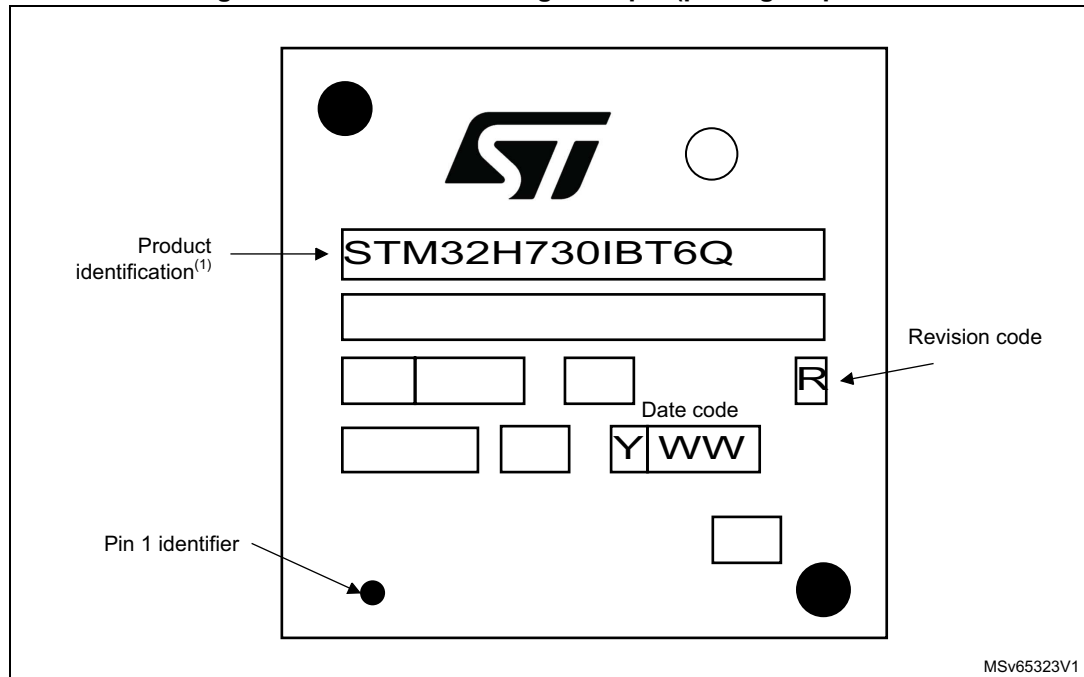
**Device marking for LQFP176**

The following figure gives an example of topside marking versus pin 1 position identifier location.

The printed markings may differ depending on the supply chain.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

**Figure 90. LQFP176 marking example (package top view)**

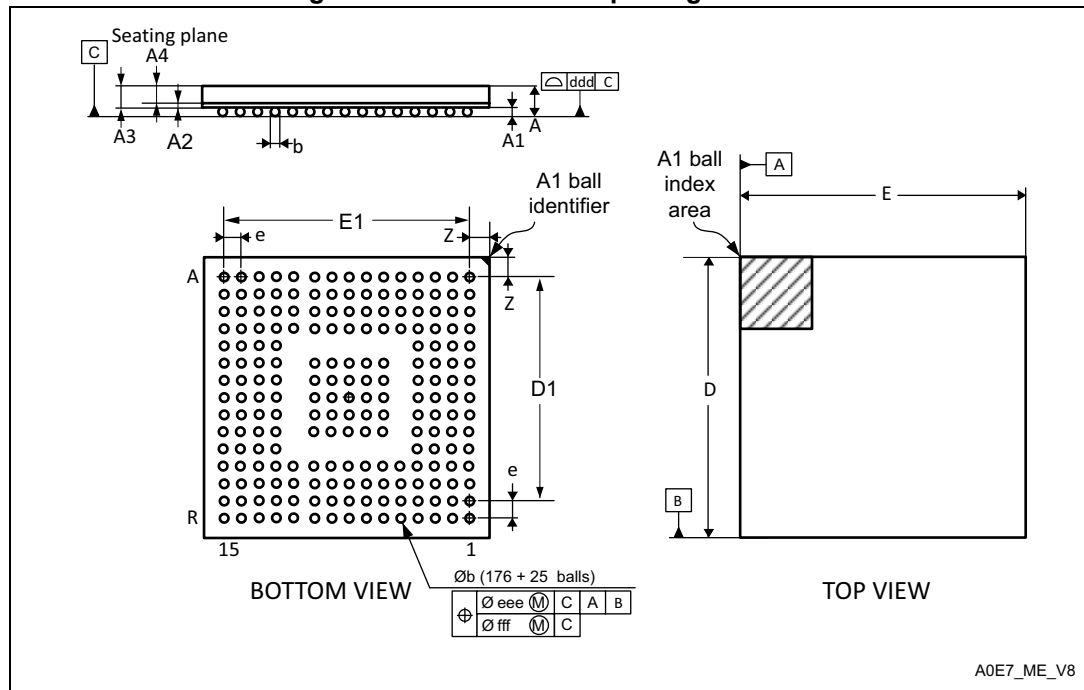


1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST’s Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

### 7.7 UFBGA176+25 package information

UFBGA176+25 is a 201-ball, 10 x 10 mm, 0.65 mm pitch, ultra fine pitch ball grid array package.

Figure 91. UFBGA176+25 package outline



1. Drawing is not to scale.

Table 132. UFBGA176+25 package mechanical data

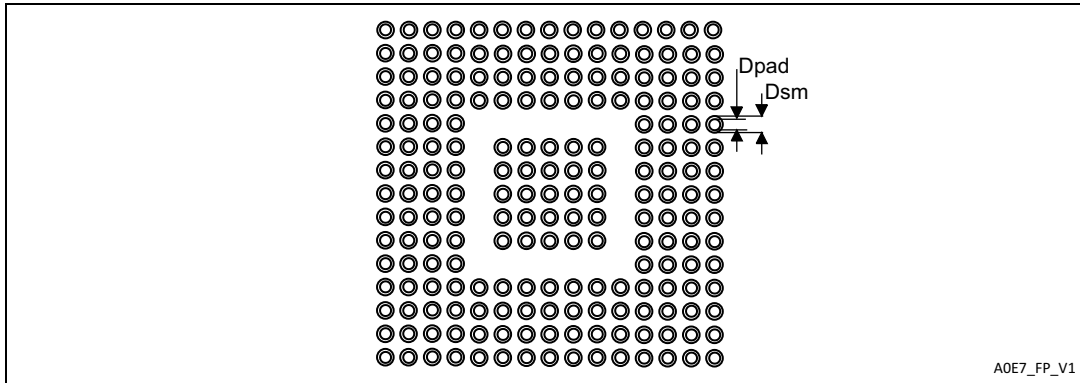
Symbol	millimeters			inches <sup>(1)</sup>		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	-	-	0.600	-	-	0.0236
A1	-	-	0.110	-	-	0.0043
A2	-	0.130	-	-	0.0051	-
A3	-	0.450	-	-	0.0177	-
A4	-	0.320	-	-	0.0126	-
b	0.240	0.290	0.340	0.0094	0.0114	0.0134
D	9.850	10.000	10.150	0.3878	0.3937	0.3996
D1	-	9.100	-	-	0.3583	-
E	9.850	10.000	10.150	0.3878	0.3937	0.3996
E1	-	9.100	-	-	0.3583	-
e	-	0.650	-	-	0.0256	-
Z	-	0.450	-	-	0.0177	-
ddd	-	-	0.080	-	-	0.0031

**Table 132. UFBGA176+25 package mechanical data (continued)**

Symbol	millimeters			inches <sup>(1)</sup>		
	Min.	Typ.	Max.	Min.	Typ.	Max.
eee	-	-	0.150	-	-	0.0059
fff	-	-	0.050	-	-	0.0020

1. Values in inches are converted from mm and rounded to 4 decimal digits.

**Figure 92. UFBGA176+25 package recommended footprint**



**Table 133. UFBGA176+25 recommended PCB design rules (0.65 mm pitch BGA)**

Dimension	Recommended values
Pitch	0.65 mm
Dpad	0.300 mm
Dsm	0.400 mm typ. (depends on the soldermask registration tolerance)
Stencil opening	0.300 mm
Stencil thickness	Between 0.100 mm and 0.125 mm
Pad trace width	0.100 mm



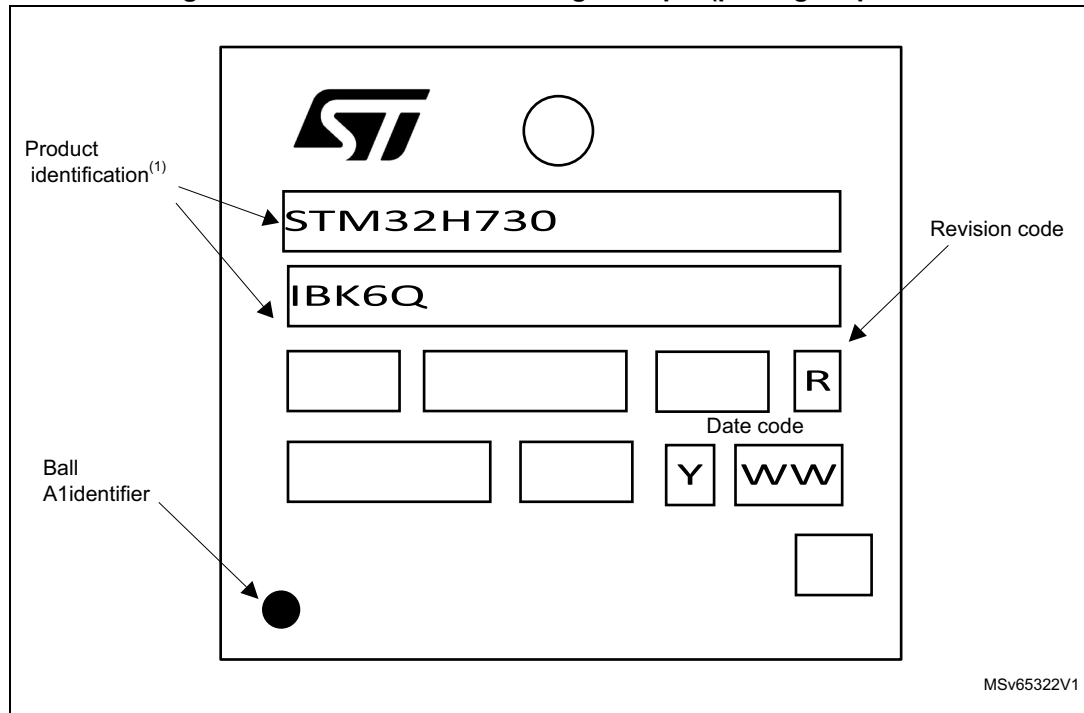
**Device marking for UFBGA176+25**

The following figure gives an example of topside marking versus ball A1 position identifier location.

The printed markings may differ depending on the supply chain.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

**Figure 93. UFBGA176+25 marking example (package top view)**



1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST’s Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

## 7.8 Thermal characteristics

The maximum chip-junction temperature,  $T_J \text{ max}$ , in degrees Celsius, may be calculated using the following equation:

$$T_J \text{ max} = T_A \text{ max} + (P_D \text{ max} \times \Theta_{JA})$$

Where:

- $T_A \text{ max}$  is the maximum ambient temperature in °C,
- $\Theta_{JA}$  is the package junction-to-ambient thermal resistance, in °C/W,
- $P_D \text{ max}$  is the sum of  $P_{INT \text{ max}}$  and  $P_{I/O \text{ max}}$  ( $P_D \text{ max} = P_{INT \text{ max}} + P_{I/O \text{ max}}$ ),
- $P_{INT \text{ max}}$  is the product of  $I_{DD}$  and  $V_{DD}$ , expressed in Watts. This is the maximum chip internal power.

$P_{I/O \text{ max}}$  represents the maximum power dissipation on output pins where:

$$P_{I/O \text{ max}} = \Sigma (V_{OL} \times I_{OL}) + \Sigma (V_{DD} - V_{OH}) \times I_{OH},$$

taking into account the actual  $V_{OL} / I_{OL}$  and  $V_{OH} / I_{OH}$  of the I/Os at low and high level in the application.

**Table 134. Thermal characteristics**

Symbol	Definition	Parameter	Value	Unit
$\Theta_{JA}$	Thermal resistance junction-ambient	<b>Thermal resistance junction-ambient</b> LQFP100 - 14 x 14 mm /0.5 mm pitch	43.8	°C/W
		<b>Thermal resistance junction-ambient</b> TFBGA100 - 8 x 8 mm /0.8 mm pitch	43.2	
		<b>Thermal resistance junction-ambient</b> LQFP144 - 20 x 20 mm /0.5 mm pitch	44.8	
		<b>Thermal resistance junction-ambient</b> UFBGA144 - 7 x 7 mm /0.5 mm pitch	TBD	
		<b>Thermal resistance junction-ambient</b> UFBGA169 - 7 x 7 mm / 0.5 mm pitch	38	
		<b>Thermal resistance junction-ambient</b> LQFP176 - 24 x 24 mm / 0.5 mm pitch	48.3	
		<b>Thermal resistance junction-ambient</b> UFBGA176+25 - 10 x 10 mm / 0.65 mm pitch	38	

Table 134. Thermal characteristics (continued)

Symbol	Definition	Parameter	Value	Unit
$\Theta_{JB}$	Thermal resistance junction-board	<b>Thermal resistance junction-ambient</b> LQFP100 - 14 x 14 mm /0.5 mm pitch	19.8	°C/W
		<b>Thermal resistance junction-ambient</b> TFBGA100 - 8 x 8 mm /0.8 mm pitch	24.8	
		<b>Thermal resistance junction-ambient</b> LQFP144 - 20 x 20 mm /0.5 mm pitch	24.4	
		<b>Thermal resistance junction-ambient</b> UFBGA144 - 7 x 7 mm /0.5 mm pitch	TBD	
		<b>Thermal resistance junction-ambient</b> UFBGA169 - 7 x 7 mm / 0.5 mm pitch	18	
		<b>Thermal resistance junction-ambient</b> LQFP176 - 24 x 24 mm / 0.5 mm pitch	29.1	
		<b>Thermal resistance junction-ambient</b> UFBGA176+25 - 10 x 10 mm / 0.65 mm pitch	20	
$\Theta_{JC}$	Thermal resistance junction-case	<b>Thermal resistance junction-ambient</b> LQFP100 - 14 x 14 mm /0.5 mm pitch	7.3	°C/W
		<b>Thermal resistance junction-ambient</b> TFBGA100 - 8 x 8 mm /0.8 mm pitch	13.2	
		<b>Thermal resistance junction-ambient</b> LQFP144 - 20 x 20 mm /0.5 mm pitch	7.4	
		<b>Thermal resistance junction-ambient</b> UFBGA144 - 7 x 7 mm /0.5 mm pitch	TBD	
		<b>Thermal resistance junction-ambient</b> UFBGA169 - 7 x 7 mm / 0.5 mm pitch	11	
		<b>Thermal resistance junction-ambient</b> LQFP176 - 24 x 24 mm / 0.5 mm pitch	7.9	
		<b>Thermal resistance junction-ambient</b> UFBGA176+25 - 10 x 10 mm / 0.65 mm pitch	24	

### 7.8.1 Reference documents

- JESD51-2 Integrated Circuits Thermal Test Method Environment Conditions - Natural Convection (Still Air). Available from [www.jedec.org](http://www.jedec.org).
- For information on thermal management, refer to application note “*Thermal management guidelines for STM32 applications*” (AN5036) available from [www.st.com](http://www.st.com).

## 8 Ordering information

Example:	STM32	H	730	V	B	T	6	Q	TR
Device family	STM32 = Arm-based 32-bit microcontroller								
Product type	H = High performance								
Device subfamily	730 = STM32H730								
Pin count	V = 100 pins Z = 144 pins A = 169 pins I = 176 pins/balls								
Flash memory size	B = 128 Kbytes								
Package	T = LQFP ECOPACK2 K = UFBGA pitch 0.65 mm ECOPACK2 I = UFBGA pitch 0.5 mm ECOPACK2 H = TFBGA ECOPACK2								
Temperature range	6 = -40 to 85 °C								
Option	Q = with SMPS Blank = without SMPS								
Packing	TR = tape and reel No character = tray or tube								

For a list of available options (speed, package, etc.) or for further information on any aspect of this device, please contact your nearest ST sales office.

## 9 Revision history

**Table 135. Document revision history**

Date	Revision	Changes
10-Jul-2020	1	Initial release.
03-Sep-2020	2	<p>Renamed <a href="#">Section 3.31</a> into <a href="#">True random number generator (RNG)</a>.</p> <p>Replaced <math>V_{DDIOx}</math> by <math>V_{DD}</math> in <a href="#">Section 6: Electrical characteristics</a>.</p> <p>Updated <math>I_{IO}</math> in <a href="#">Table 10: Current characteristics</a> and <a href="#">Table 17: Inrush current and inrush electric charge characteristics for LDO and SMPS</a>.</p> <p>Removed <a href="#">Table 13: Supply voltage and maximum temperature configuration</a>.</p> <p>Updated <a href="#">Table 27: Typical current consumption in Autonomous mode</a>, <a href="#">Table 30: Typical current consumption in Standby mode</a> and <a href="#">Table 31: Typical and maximum current consumption in VBAT mode</a>.</p> <p>Added <a href="#">Section 6.3.16: I/O current injection characteristics</a>.</p> <p>Removed reference to PI8 in <a href="#">Table 54: Output voltage characteristics for all I/Os except PC13, PC14 and PC15</a> and <a href="#">Table 55: Output voltage characteristics for PC13, PC14 and PC15</a>.</p> <p>Added <a href="#">Section : Analog switch between ports Pxy_C and Pxy</a>.</p> <p>Added <a href="#">Figure 89: LQFP176 package recommended footprint</a> and <a href="#">Table 130: UFBGA169 recommended PCB design rules (0.5 mm pitch BGA)</a>.</p>

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